

INTERNATIONAL STANDARD



GROUP SAFETY PUBLICATION

**Safety requirements for electrical equipment for measurement, control and laboratory use –
Part 031: Safety requirements for hand-held probe assemblies for electrical measurement and test**



THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2015 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
Fax: +41 22 919 03 00
info@iec.ch
www.iec.ch

About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigenda or an amendment might have been published.

IEC Catalogue - webstore.iec.ch/catalogue

The stand-alone application for consulting the entire bibliographical information on IEC International Standards, Technical Specifications, Technical Reports and other documents. Available for PC, Mac OS, Android Tablets and iPad.

IEC publications search - www.iec.ch/searchpub

The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, replaced and withdrawn publications.

IEC Just Published - webstore.iec.ch/justpublished

Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and also once a month by email.

Electropedia - www.electropedia.org

The world's leading online dictionary of electronic and electrical terms containing more than 30 000 terms and definitions in English and French, with equivalent terms in 15 additional languages. Also known as the International Electrotechnical Vocabulary (IEV) online.

IEC Glossary - std.iec.ch/glossary

More than 60 000 electrotechnical terminology entries in English and French extracted from the Terms and Definitions clause of IEC publications issued since 2002. Some entries have been collected from earlier publications of IEC TC 37, 77, 86 and CISPR.

IEC Customer Service Centre - webstore.iec.ch/csc

If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: csc@iec.ch.

IECNORM.COM : Click to view the full text of IEC 60310-031:2015 PLV



IEC 61010-031

Edition 2.0 2015-05
REDLINE VERSION

INTERNATIONAL STANDARD



**Safety requirements for electrical equipment for measurement, control and laboratory use –
Part 031: Safety requirements for hand-held probe assemblies for electrical measurement and test**

INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

ICS 19.080

ISBN 978-2-8322-2723-7

Warning! Make sure that you obtained this publication from an authorized distributor.

CONTENTS

FOREWORD.....	7
1 Scope and object.....	10
1.1 Scope	10
1.1.1 Probe assemblies included in scope	10
1.1.2 Probe assemblies excluded from scope	13
1.2 Object.....	13
1.2.1 Aspects included in scope	13
1.2.2 Aspects excluded from scope	13
1.3 Verification.....	13
1.4 Environmental conditions	13
1.4.1 Normal environmental conditions	13
1.4.2 Extended environmental conditions	14
2 Normative references	14
3 Terms and definitions	14
3.1 Parts and accessories.....	15
3.2 ~~Electrical~~ Quantities	16
3.3 Tests	17
3.4 Safety terms	17
3.5 Insulation	18
4 Tests	20
4.1 General.....	20
4.2 Sequence of tests	20
4.3 Reference test conditions.....	21
4.3.1 Environmental conditions.....	21
4.3.2 State of probe assemblies.....	21
4.3.3 Position of the probe assembly	21
4.3.4 Accessories.....	21
4.3.5 Covers and removable parts	21
4.3.6 Input and output voltages	21
4.3.7 Controls.....	21
4.3.8 Connections	21
4.3.9 Duty cycle.....	22
4.4 Testing in SINGLE FAULT CONDITION.....	22
4.4.1 General	22
4.4.2 Application of fault conditions	22
4.4.3 Duration of tests	23
4.4.4 Conformity after application of ~~single~~ fault conditions	23
4.5 Tests in REASONABLY FORESEEABLE MISUSE	24
4.5.1 General	24
4.5.2 Fuses	24
5 Marking and documentation.....	24
5.1 Marking.....	24
5.1.1 General	24
5.1.2 Identification	24
5.1.3 Fuses	25
5.1.4 ~~Terminals~~ CONNECTORS and operating devices.....	26

~~5.1.5~~	~~PARTS PROTECTED by double insulation or reinforced insulation~~	
5.1.5	RATING	26
5.2	Warning markings	26
5.3	Durability of markings	27
5.4	Documentation	27
5.4.1	General	27
5.4.2	~~Ratings~~ Probe assembly rating	27
5.4.3	~~Probe assembly~~ operation	27
5.4.4	~~MAINTENANCE~~ Probe assembly maintenance and service	28
6	Protection against electric shock	29
6.1	General	29
~~6.1.1~~	~~EXCEPTIONS~~	
6.2	Determination of ACCESSIBLE parts	29
6.2.1	General	29
6.2.2	~~General~~ Examination	29
6.2.3	Openings for pre-set controls	31
6.3	~~Permissible limits~~ Limit values for ACCESSIBLE parts	31
6.3.1	General	31
6.3.2	~~VALUES~~ Levels in NORMAL CONDITION	32
6.3.3	~~VALUES~~ Levels in SINGLE FAULT CONDITION	32
6.3.4	Measurement of voltage and touch current	35
6.4	~~Insulation requirements for~~ Means of protection against electric shock	38
6.4.1	General	38
6.4.2	CONNECTORS	39
~~6.4.2~~	~~HAND-HELD parts other than CONNECTORS~~	
~~6.4.3~~	~~Cables~~	
6.4.4	Impedance	46
~~6.4.5~~	~~Double insulation and reinforced insulation~~	
6.4.5	PROTECTIVE IMPEDANCE	46
6.4.6	BASIC INSULATION, SUPPLEMENTARY INSULATION, DOUBLE INSULATION and REINFORCED INSULATION	47
~~6.5~~	~~CLEARANCES and CREEPAGE DISTANCES~~	
6.5	Insulation requirements	47
6.5.1	The nature of insulation	47
6.5.2	~~Measuring circuits~~ Insulation requirements for probe assemblies	52
6.6	~~Dielectric strength tests~~ Procedure for voltage tests	59
6.6.1	~~REFERENCE TEST EARTH~~ General	59
6.6.2	Humidity preconditioning	59
6.6.3	Conduct of tests	59
6.6.4	~~VOLTAGE TESTS~~ Test voltages	60
6.6.5	Test procedures	62
6.7	Constructional requirements for protection against electric shock	63
6.7.1	General	63
6.7.2	Insulating materials	63
6.7.3	ENCLOSURES of probe assemblies with DOUBLE INSULATION or REINFORCED INSULATION	63
~~6.7.3~~	~~CORONA and PARTIAL DISCHARGES~~	
6.7.4	~~CABLE PROBE WIRE~~ attachment	64
7	Protection against mechanical HAZARDS	67

8	~~Mechanical resistance to shock and impact~~ Resistance to mechanical stresses	67
8.1	General	67
8.2	Rigidity test	68
8.3	Drop test	68
8.4	Impact swing test	68
9	Temperature limits and protection against the spread of fire	69
9.1	General	69
9.2	Temperature tests	70
10	Resistance to heat	70
10.1	Integrity of ~~CLEARANCES AND CREEPAGE DISTANCES SPACINGS~~	70
10.2	Resistance to heat	70
11	Protection against HAZARDS from fluids	71
11.1	General	71
11.2	Cleaning	71
11.3	Specially protected probe assemblies	71
12	Components	71
12.1	General	71
12.2	Fuses	72
~~12.3~~	~~High integrity components~~	
12.3	PROBE WIRE	73
13	Prevention of HAZARD from arc flash and short-circuits	78
13.1	General	78
13.2	Exposed conductive parts	78
Annex A (normative)	Measuring circuits for ~~ACCESSIBLE~~ touch current (see 6.3)	80
A.1	Measuring circuits for a.c. with frequencies up to 1 MHz and for d.c	80
A.2	Measuring circuits for a.c. with sinusoidal frequencies up to 100 Hz and for d.c.	81
A.3	Current measuring circuit for electrical burns at ~~high~~ frequencies ~~above~~ 100 kHz	81
A.4	Current measuring circuit for WET ~~contact~~ LOCATIONS	83
Annex B (normative)	Standard test fingers ~~(see 6.2)~~	84
Annex C (normative)	Measurement of CLEARANCES and CREEPAGE DISTANCES	87
Annex D (normative)	Routine spark tests on PROBE WIRE	91
D.1	General	91
D.2	Spark test procedure	91
D.3	Routine spark test method for PROBE WIRE	93
Annex E (informative)	4 mm CONNECTORS	95
E.1	General	95
E.2	Dimensions	95
Annex F (normative)	Measurement Categories	97
F.1	General	97
F.2	MEASUREMENT CATEGORIES	97
Annex G	Index of defined terms	99
Bibliography		101

Figure 1 — Examples of type A and C probe assemblies

Figure 1 – Examples of type A probe assemblies	11
--	----

Figure 2 – Examples of type B probe assemblies	11
Figure 3 – Examples of type C probe assemblies	12
~~Figure 4 – Example of application of metal foil for ACCESSIBLE current measurement~~	~~12~~
Figure 4 – Examples of type D probe assemblies	12
Figure 5 – Example of a STACKABLE CONNECTOR with a male CONNECTOR and a female TERMINAL	16
~~Figure 6 – Protection against touching a PROBE TIP (see 6.4.4)~~	~~16~~
Figure ~~3~~ 6 – Methods for determination of ACCESSIBLE parts (see 6.2) and for voltage tests of (see 6.4.2)	30
Figure ~~5~~ 7 – ~~Charged~~ Capacitance level versus voltage in NORMAL CONDITION AND SINGLE-FAULT CONDITION (see ~~6.3.2.3~~ 6.3.2 c) and 6.3.3 c))	34
Figure 8 – Voltage and touch current measurement	35
Figure 9 – Voltage and touch current measurement for the reference CONNECTOR	36
Figure 10 – Voltage and touch current measurement with shielded test probe	37
Figure 11 – Maximum test probe input voltage for 70 mA touch current	38
Figure 12 – Protection by a PROTECTIVE FINGERGUARD	43
Figure 13 – Protection by distance	45
Figure 14 – Protection by tactile indicator	45
Figure 15 – Distance between conductors on an interface between two layers	50
Figure 16 – Distance between adjacent conductors along an interface of two layers	51
Figure 17 – Distance between adjacent conductors located between the same two layers	52
Figure 18 – Example of recurring peak voltage	56
Figure ~~7~~ 19 – Flexing test	65
Figure ~~8~~ 20 – Rotational flexing test for cable used in PROBE ASSEMBLIES (see 6.7.4)	67
Figure ~~9~~ 21 – Impact swing test	69
Figure 22 – Indentation device	74
Figure A.1 – Measuring circuit for a.c. with frequencies up to 1 MHz and for d.c.	80
Figure A.2 – Measuring circuits for a.c. with sinusoidal frequencies up to 100 Hz and for d.c.	81
Figure A.3 – Current measuring circuit for electrical burns	82
Figure A.4 – Current measuring circuit for high frequency test probes	82
Figure ~~A.4~~ A.5 – Current measuring circuit for WET ~~contact~~ LOCATIONS	83
Figure B.1 – Rigid test finger	84
Figure B.2 – Jointed test finger	85
Figure D.1 – Bead Chain Configuration (if applicable)	92
Figure E.1 – Recommended dimensions of 4 mm CONNECTORS	95
Figure F.1 – Example to identify the locations of MEASUREMENT CATEGORIES	98
Table 1 – Symbols	25
Table 2 – SPACINGS for unmated CONNECTORS RATED up to 1 000 V a.c. or 1 500 V d.c. with HAZARDOUS LIVE conductive parts	40
Table ~~2~~ 3 – Multiplication factors for CLEARANCES of probe assembly rated for operation at altitudes up to 5 000 m	46
Table 4 – Test voltages for testing solid insulation	50

Table 5 – Minimum values for distance or thickness.....	51
Table ~~3~~ 6 – CLEARANCES ~~for probe assemblies~~ of MEASUREMENT CATEGORIES II, III and IV	52
Table ~~4~~ 7 – CLEARANCE values for the calculation of 6.5.2. 3.2.....	55
Table 8 – CLEARANCES for BASIC INSULATION in probe assemblies subjected to recurring peak voltages or WORKING VOLTAGES with frequencies above 30 kHz.....	57
Table ~~5~~ 9 – CREEPAGE DISTANCES ~~for basic insulation or supplementary insulation~~	57
Table ~~6~~ 10 – Test voltages ~~for BASIC INSULATION~~ based on clearances.....	61
Table ~~7~~ 11 – Correction factors according to test site altitude for test voltages ~~for clearances~~	62
Table ~~8~~ 12 – Pull forces for ~~cable~~ PROBE WIRE attachment tests	66
Table 13 – Diameter of mandrel and numbers of turns	75
Table C.1 – ~~Relation between POLLUTION degrees and width of grooves~~ Dimension of X	87
Table D.1 – Maximum centre-to-centre spacings of bead chains	91
Table D.2 – Formula for maximum speed of wire in terms of electrode length L of link- or bead-chain electrode	93
Table F.1 – Characteristics of MEASUREMENT CATEGORIES	98

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT
FOR MEASUREMENT, CONTROL AND LABORATORY USE –****Part 031: Safety requirements for hand-held
probe assemblies for electrical measurement and test**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

This redline version of the official IEC Standard allows the user to identify the changes made to the previous edition. A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text.

International Standard IEC 61010-031 has been prepared by IEC technical committee 66: Safety of measuring, control and laboratory equipment.

It has the status of a group safety publication in accordance with IEC GUIDE 104.

IEC 61010-031 is a stand-alone standard. This second edition cancels and replaces the first edition published in 2002 and Amendment 1:2008. This edition constitutes a technical revision.

This edition includes the following significant changes from the first edition, as well as numerous other changes:

- a) Voltages above the levels of 30 V r.m.s., 42,4 V peak, or 60 V d.c. are deemed to be HAZARDOUS LIVE instead of 33 V r.m.s., 46,7 V peak, or 70 V d.c.
- b) Servicing is now included within the scope.
- c) Extended environmental conditions are included within the scope.
- d) New terms have been defined.
- e) Tests for REASONABLY FORESEEABLE MISUSE have been added, in particular for fuses.
- f) Additional instruction requirements for probe assembly operation have been specified.
- g) Limit values for ACCESSIBLE parts and for measurement of voltage and touch current have been modified.
- h) SPACINGS requirements for mating of CONNECTORS have been modified.
- i) PROBE TIPS and SPRING-LOADED CLIPS requirements have been modified. The PROTECTIVE FINGERGUARD replace the BARRIER with new requirements.
- j) Insulation requirements (6.5) and test procedures (6.6.5) have been rewritten and aligned when relevant with Part 1. Specific requirements have been added for solid insulation and thin-film insulation.
- k) The terminology for MEASUREMENT CATEGORY I has been replaced with the designation “not RATED for measurements within MEASUREMENT CATEGORIES II, III, or IV”.
- l) The flexing/pull test (6.7.4.3) has been partially rewritten.
- m) Surface temperature limits (Clause 10) have been modified to conform to the limits of IEC Guide 117.
- n) Requirements for resistance of PROBE WIRES to mechanical stresses have been added in Clause 12 and a new Annex D.
- o) Requirements have been added regarding the prevention of HAZARD from arc flash and short-circuits for SPRING-LOADED CLIPS.
- p) A new informative Annex E defines the dimension of the 4 mm banana CONNECTORS.

The text of this standard is based on the following documents:

FDIS	Report on voting
66/569/FDIS	66/571/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 61010 series, under the general title, *Safety requirements for electrical equipment for measurement, control, and laboratory use*, may be found on the IEC website.

In this standard, the following print types are used:

- requirements and definitions: in roman type;
- NOTES and EXAMPLES: in smaller roman type;
- *conformity and tests: in italic type;*
- terms used throughout this standard which have been defined in Clause 3: SMALL ROMAN CAPITALS.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL AND LABORATORY USE –

Part 031: Safety requirements for hand-held probe assemblies for electrical measurement and test

1 Scope and object

1.1 Scope

1.1.1 Probe assemblies included in scope

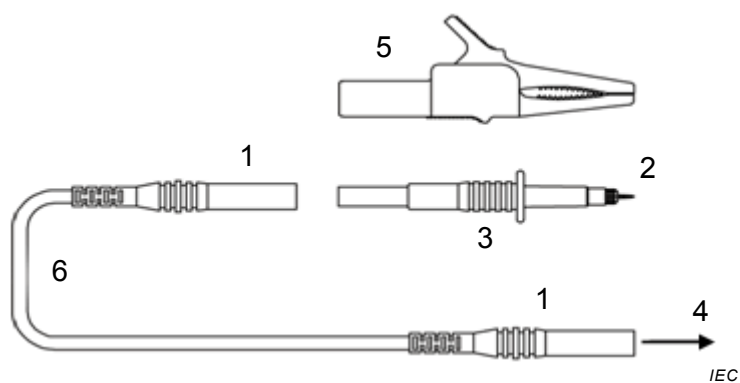
This part of IEC 61010 ~~applies to~~ specifies safety requirements for hand-held and hand-manipulated probe assemblies of the types described below, and ~~their~~ related accessories ~~which are intended for professional, industrial process, and educational use~~. These probe assemblies are for ~~use in the interface between an direct electrical phenomenon and connection between a part and electrical test or~~ and measurement equipment. They may be fixed to the equipment or be detachable accessories for the equipment.

- a) Type A: low-voltage and high-voltage, non-attenuating probe assemblies. Non-attenuating probe assemblies that are RATED for direct connection to voltages exceeding ~~33~~ 30 V r.m.s. ~~or 46,7, 42,4 V peak, or 70 60 V d.c.~~, but not exceeding 63 kV. They do not incorporate ~~active~~ components, ~~nor which~~ are they intended to provide a voltage divider function or a signal conditioning function, but they may contain ~~passive~~ non-attenuating components such as fuses (see Figure 1).
- b) Type B: high-voltage attenuating or divider probe assemblies. Attenuating or divider probe assemblies that are RATED for direct connection to secondary voltages exceeding 1 kV r.m.s. ~~or 1,5 kV d.c.~~ but not exceeding 63 kV r.m.s. ~~or d.c.~~ The divider function may be carried out wholly within the probe assembly, or partly within the test or measurement equipment to be used with the probe assembly (see Figure 2).
- c) Type C: low-voltage attenuating or divider probe assemblies. Attenuating ~~or divider or other signal conditioning~~ probe assemblies for direct connection to voltages ~~exceeding 33 V r.m.s. or 46,7 V peak or 70 V d.c., but~~ not exceeding 1 kV r.m.s. or 1,5 kV d.c. The signal conditioning function may be carried out wholly within the probe assembly, or partly within the test or measurement equipment intended to be used with the probe assembly (see Figure 3).
- d) Type D: low-voltage attenuating, non-attenuating or other signal conditioning probe assemblies, that are RATED for direct connection only to voltages not exceeding 30 V r.m.s., or 42,4 V peak, or 60 V d.c., and are suitable for currents exceeding 8 A (see Figure 4).

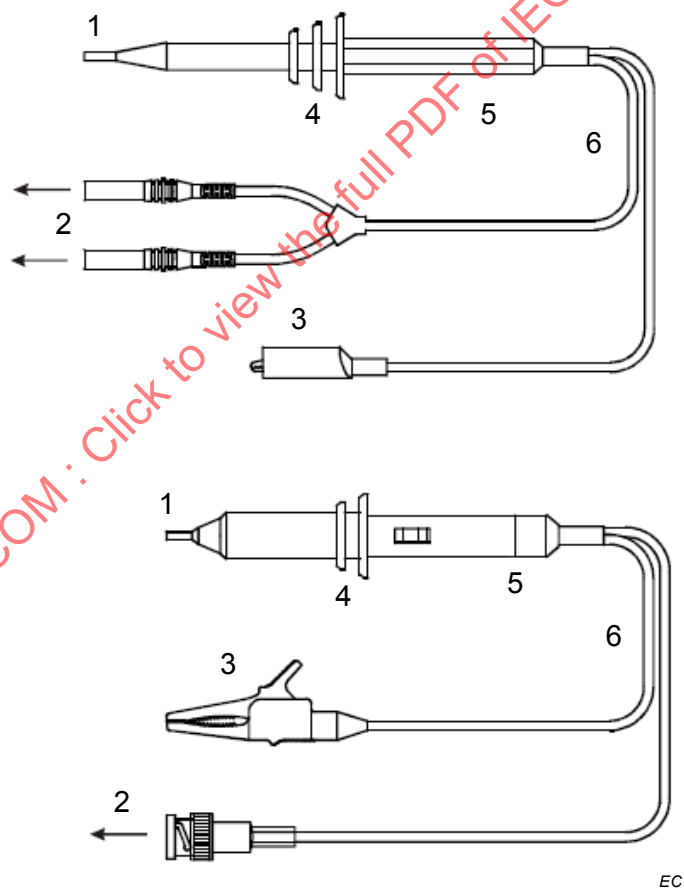
NOTE – PROBE ASSEMBLIES which

- are not within the definitions of types A, B or C, or,
 - which are designed to be powered from a low-voltage mains supply, or
 - include other features not specifically addressed in this standard
- may also need to meet the relevant requirements of other parts of IEC 61010 [6]^{†)}.

^{†)} Figures in square brackets refer to the bibliography.

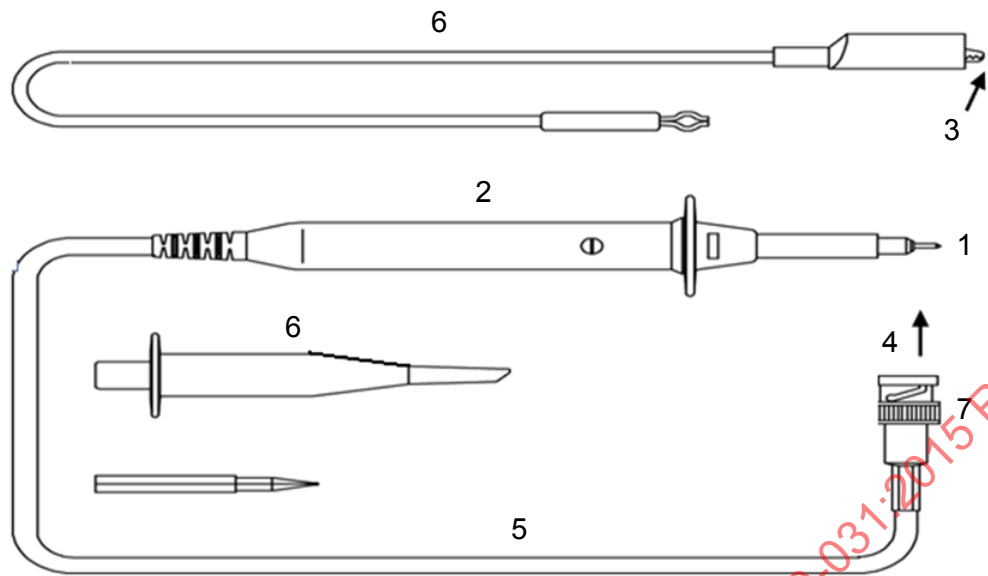
**Key**

- | | |
|----------------------|-------------------------------------|
| 1 typical connectors | 4 to equipment |
| 2 PROBE TIP | 5 Crocodile clip SPRING-LOADED CLIP |
| 3 probe body | 6 PROBE WIRE |

Figure 1 – Examples of type A probe assemblies**Key**

- | | |
|-----------------------|----------------------------------|
| 1 PROBE TIP | 4 BARRIER PROTECTIVE FINGERGUARD |
| 2 to equipment | 5 hand-held area of probe body |
| 3 reference CONNECTOR | 6 PROBE WIRE |

Figure 2 – Examples of type B probe assemblies

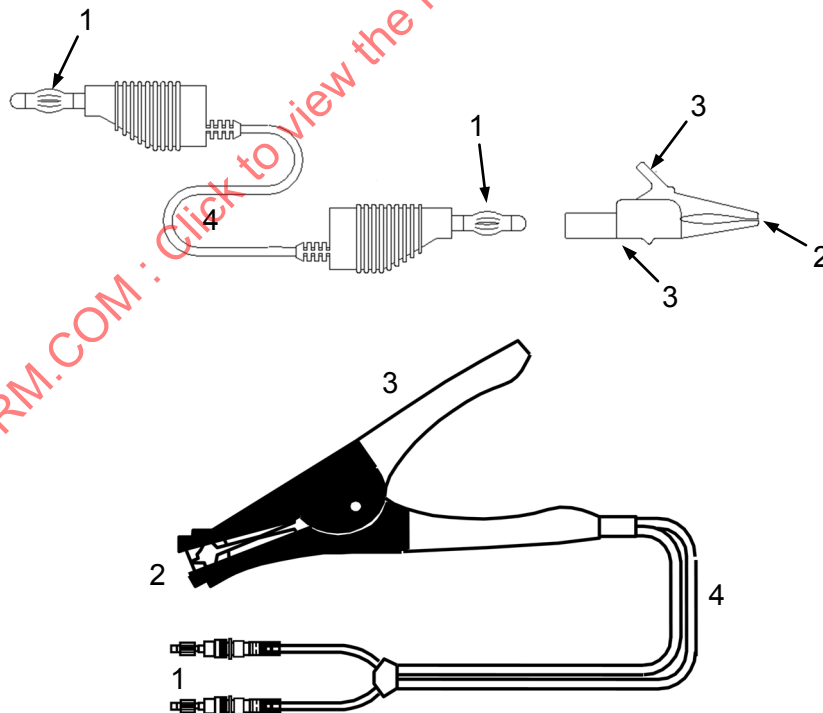


IEC

Key

- | | |
|-----------------------|---------------------------|
| 1 PROBE TIP | 5 PROBE WIRE |
| 2 probe body | 6 examples of accessories |
| 3 reference CONNECTOR | 7 BNC CONNECTOR |
| 4 to equipment | |

Figure 3 – Examples of type C probe assemblies



IEC

Key

- | | |
|-------------|---|
| 1 CONNECTOR | 3 hand-held area of SPRING-LOADED CLIP or clamp |
| 2 PROBE TIP | 4 PROBE WIRE |

Figure 4 – Examples of type D probe assemblies

1.1.2 Probe assemblies excluded from scope

This standard does not apply to current sensors within the scope of IEC 61010-2-032 (Hand-held and hand-manipulated current sensors), but may apply to their input measuring circuit leads and accessories.

1.2 Object

1.2.1 Aspects included in scope

The purpose of the requirements of this standard is to ensure that ~~the design and methods of construction used provide adequate protection for~~ HAZARDS to the OPERATOR and the surrounding area ~~against~~ are reduced to a tolerable level.

Requirements for protection against particular types of HAZARDS are given in Clauses 6 to 13, as follows:

- a) electric shock or burn (see Clauses 6, 10 and 11);
- b) mechanical HAZARDS (see Clauses 7, 8 and 11);
- c) excessive temperature (see Clause 9);
- d) spread of fire from the probe assembly (see Clause 9);
- e) arc flash (see Clause 13).

Additional requirements for probe assemblies which are designed to be powered from a low-voltage mains supply, or include other features not specifically addressed in this standard are in other parts of IEC 61010.

NOTE Attention is drawn to the possible existence of additional requirements ~~which may be specified by national authorities responsible for~~ regarding the health and safety of labour forces.

1.2.2 Aspects excluded from scope

This standard does not cover:

- a) reliable function, performance, or other properties of the probe assembly;
- b) effectiveness of transport packaging.
- ~~c) servicing (repair);~~
- ~~d) protection of servicing (repair) personnel.~~

NOTE ~~Servicing personnel are expected to be reasonably careful in dealing with obvious HAZARDS, but the design should protect against mishap in an appropriate manner, and the service documentation should point out any residual HAZARDS.~~

1.3 Verification

This standard also specifies methods of verifying that the probe assembly meets the requirements of this standard, through inspection, TYPE TESTS, and ROUTINE TESTS.

1.4 Environmental conditions

1.4.1 Normal environmental conditions

This standard applies to probe assemblies designed to be safe at least under the following conditions:

- a) altitude up to 2 000 m, ~~or above 2 000 m if specified by the manufacturer;~~
- b) ambient temperature of 5 °C to 40 °C; ~~or below 5 °C or above 40 °C if specified by the manufacturer;~~

- c) maximum relative humidity of 80 % for temperatures up to 31 °C decreasing linearly to 50 % relative humidity at 40 °C;
- d) applicable ~~RATED~~ POLLUTION DEGREE of the intended environment.

1.4.2 Extended environmental conditions

This standard applies to probe assemblies designed to be safe not only in the environmental conditions specified in 1.4.1, but also in any of the following conditions as RATED by the manufacturer of the probe assemblies:

- a) outdoor use;
- b) altitudes above 2 000 m;
- c) ambient temperatures below 5 °C or above 40 °C;
- d) relative humidities above the levels specified in 1.4.1;
- e) WET LOCATIONS.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letters symbols to be used in electrical technology*

~~IEC 60060 (all parts), *High-voltage test techniques*~~

~~IEC 60417 (all parts), *Graphical symbols for use on equipment*~~

IEC 60529, *Degrees of protection provided by enclosures (IP Code)*

~~IEC 60664-3, *Insulation coordination for equipment within low-voltage systems – Part 3: Use of coatings to achieve insulation coordination of printed board assemblies*~~

IEC 61010-1:2010, *Safety requirements for electrical equipment for measurement, control, and laboratory use – Part 1: General requirements*

IEC 61180-1:1992, *High-voltage test techniques for low voltage equipment – Part 1: Definitions, test and procedure requirements*

IEC 61180-2, *High-voltage test techniques for low-voltage equipment – Part 2: Test equipment*

IEC GUIDE 104, *The preparation of safety publications and the use of basic safety publications and group safety publications*

ISO/IEC GUIDE 51, *Safety aspects – Guidelines for their inclusion in standards*

~~ISO 7000, *Graphical symbols for use on equipment – Index and synopsis*~~

3 Terms and definitions

For the purposes of this document, the following **terms and** definitions apply.

~~Unless otherwise specified, the terms "voltage" and "current" mean the r.m.s. values of an alternating, direct or composite voltage or current. Where the term "mains" is used, it refers to the low voltage electricity supply system (above the values of 6.3.2.1).~~

3.1 Parts and accessories

3.1.1

TERMINAL

component provided for the connection of a device (equipment) to external conductors

Note 1 to entry: TERMINALS can contain one or several contacts and the term includes sockets, pins, connectors, etc.

3.1.2

ENCLOSURE

part providing protection of ~~equipment~~ **a probe assembly** against certain external influences and, in any direction, protection against direct contact

3.1.3

BARRIER

~~part providing protection against direct contact from any usual direction of access~~

~~NOTE ENCLOSURES and BARRIERS may provide protection against the spread of fire (see 9.1).~~

3.1.4

PROBE ASSEMBLY

~~device for making temporary contact between test or measurement equipment and a point on an electrical circuit being measured or tested. It includes the cable and the means for making a connection with the test or measurement equipment~~

~~NOTE See figures 1 and 2 for examples of PROBE ASSEMBLIES and an explanation of the function of their parts.~~

3.1.3

PROTECTIVE FINGERGUARD

part of the ENCLOSURE that indicates the limit of safe access and that reduces the risk of the OPERATOR touching HAZARDOUS LIVE parts

3.1.4

PROBE TIP

part of a probe assembly ~~or accessory~~ which makes a connection to the point being measured or tested

Note 1 to entry: The term "PROBE TIP" includes the conductive parts of the jaws or hooks of SPRING-LOADED CLIPS.

3.1.6

REFERENCE CONNECTOR

~~device used to connect a reference point in the test or measurement equipment (usually the functional earth TERMINAL) to a reference point on the electrical circuit being measured or tested~~

3.1.5

CONNECTOR

component which is attached to the PROBE WIRE, to connect to a TERMINAL of the equipment or to a CONNECTOR of another probe assembly

3.1.6

TOOL

external device, including a key or coin, used to aid a person performing a mechanical function

3.1.7

PROBE WIRE

flexible wire or cable used as part of the probe assembly or its accessories, consisting of one or more conductors and associated insulation

3.1.8

SPRING-LOADED CLIP

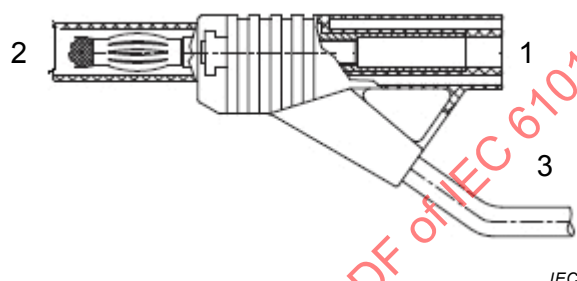
probe or probe accessory with one or more hooks or jaws forced by a spring to grip the part being measured or tested

3.1.9

STACKABLE CONNECTOR

CONNECTOR assembly which contains an additional TERMINAL

EXAMPLE: Figure 5 is an example of a STACKABLE CONNECTOR with a male CONNECTOR and a female TERMINAL.



Key

- 1 TERMINAL for additional CONNECTOR
- 2 CONNECTOR
- 3 PROBE WIRE

Figure 5 – Example of a STACKABLE CONNECTOR with a male CONNECTOR and a female TERMINAL

3.2 ~~Electrical~~ Quantities

3.2.1

RATED (condition or value)

condition or quantity value assigned, generally by a manufacturer, for a specified operating condition of a component, device, or ~~equipment~~ probe assembly

~~[IEV 151-04-03]~~

3.2.2

RATING

set of RATED values and operating conditions

~~[IEV 151-04-04]~~ SOURCE: IEC 60050-151:2001, 151-16-11]

3.2.3

WORKING VOLTAGE

highest r.m.s. value of the a.c. or d.c. voltage across any particular insulation which can continuously appear during NORMAL USE

Note 1 to entry: ~~Both open-circuit conditions and normal operating conditions are taken into account. Transients and voltage fluctuations are not considered to be part of the WORKING VOLTAGE~~

3.3 Tests

3.3.1

TYPE TEST

test of one or more samples of ~~equipment~~ a probe assembly (or parts of ~~equipment~~ a probe assembly) made to a particular design, to show that the design and construction meet ~~one or more the~~ requirements of this standard

Note 1 to entry: This is an amplification of the ~~IEV 151-04-15~~ IEC 60050-151:2001, 151-16-16 definition to cover design as well as construction ~~requirements~~.

3.3.2

ROUTINE TEST

conformity test made on each individual item during or after manufacture

[SOURCE: IEC 60050-151:2001, 151-16-17]

3.4 Safety terms

3.4.1

ACCESSIBLE ~~(of a part)~~

able to be touched with a standard test finger or test pin, when used as specified in 6.2

3.4.2

HAZARDOUS LIVE

capable of rendering an electric shock or electric burn ~~in NORMAL CONDITION or SINGLE FAULT CONDITION (see 6.3.1 for values applicable to NORMAL CONDITION and 6.3.2 for the higher values deemed to be appropriate in SINGLE FAULT CONDITION)~~

3.4.3

HIGH INTEGRITY

~~not liable to become defective in such a manner as to cause a risk of HAZARD; a HIGH INTEGRITY part is considered as not subject to failure when tests under fault conditions are made~~

3.4.3

HAZARD

potential source of harm

3.4.4

PROTECTIVE IMPEDANCE

~~component, assembly of components or the combination of BASIC INSULATION and a current or voltage limiting device, the impedance, construction and reliability of which are such that when connected between parts which are HAZARDOUS LIVE and ACCESSIBLE conductive parts, it provides protection to the extent required by this standard in NORMAL CONDITION and SINGLE FAULT CONDITION~~

component or assembly of components whose impedance, construction and reliability are suitable to provide protection against electric shock

3.4.5

NORMAL USE

operation, including stand-by, according to the instructions for use or for the obvious intended purpose

NOTE ~~In most cases, NORMAL USE also implies NORMAL CONDITION, because the instructions for use will warn against using the equipment when it is not in NORMAL CONDITION.~~

3.4.6

NORMAL CONDITION

condition in which all means for protection against HAZARDS are intact

3.4.7

SINGLE FAULT CONDITION

condition in which one means for protection against a HAZARD is defective or one fault is present which could cause a HAZARD

~~NOTE If a SINGLE FAULT CONDITION results unavoidably in another SINGLE FAULT CONDITION, the two failures are considered as one SINGLE FAULT CONDITION.~~

3.4.8

OPERATOR

person operating ~~equipment~~ the probe assembly for its intended purpose

~~NOTE The OPERATOR should have received training appropriate for this purpose.~~

3.4.9

RESPONSIBLE BODY

individual or group responsible for the safe use and maintenance of ~~equipment, and for ensuring that OPERATORS are adequately trained~~ probe assemblies

3.4.10

WET LOCATION

location where water or another conductive liquid may be present and is likely to cause reduced human body impedance due to wetting of the contact between the human body and the ~~equipment~~ probe assembly, or wetting of the contact between the human body and the environment

3.4.11

HAZARD

~~potential source of harm (see 1.2)~~

3.4.11

MEASUREMENT CATEGORY

classification of testing and measuring circuits according to the types of mains circuits to which they are intended to be connected

3.4.12

REASONABLY FORESEEABLE MISUSE

use of a product in a way not intended by the supplier, but which may result from readily predictable human behaviour

3.5 Insulation

3.5.1

BASIC INSULATION

insulation ~~the failure of~~ HAZARDOUS LIVE parts which ~~could cause a risk of electric shock~~ provides basic protection

~~NOTE BASIC INSULATION may serve also for functional purposes.~~

[SOURCE: IEC 60050-195:1998, 195-06-06]

3.5.2

SUPPLEMENTARY INSULATION

independent insulation applied in addition to BASIC INSULATION in order to provide protection against electric shock in the event of a failure of BASIC INSULATION

3.5.3

DOUBLE INSULATION

insulation comprising both BASIC INSULATION and SUPPLEMENTARY INSULATION

[SOURCE: IEC 60050-195:1998, 195-06-08]

3.5.4

REINFORCED INSULATION

insulation which provides a degree of protection against electric shock not less than that provided by DOUBLE INSULATION

~~NOTE REINFORCED INSULATION may comprise several layers which cannot be tested singly as SUPPLEMENTARY INSULATION or BASIC INSULATION.~~

3.5.5

POLLUTION

addition of foreign matter, solid, liquid or gaseous (ionized gases), that may produce a reduction of dielectric strength or surface ~~resistivity~~ resistivity

3.5.6

POLLUTION DEGREE

~~for the purpose of evaluating CLEARANCES one of three degrees of POLLUTION in the micro-environment, which are recognized for use with this International Standard~~
numeral indicating the level of POLLUTION that may be present in the environment

3.5.7

POLLUTION DEGREE 1

no POLLUTION or only dry, non-conductive POLLUTION occurs, which has no influence

~~NOTE The POLLUTION has no influence.~~

3.5.8

POLLUTION DEGREE 2

only non-conductive POLLUTION. ~~Occasionally, however, a temporary conductivity caused by condensation must be expected~~ occurs except that occasionally a temporary conductivity caused by condensation is expected

3.5.9

POLLUTION DEGREE 3

conductive POLLUTION occurs, or dry, non-conductive POLLUTION occurs which becomes conductive due to condensation which is expected

3.5.10

CLEARANCE

shortest distance in air between two conductive parts

3.5.11

CREEPAGE DISTANCE

shortest distance along the surface of a solid insulating material between two conductive parts

~~[IEV 151-03-37 SOURCE: IEC 60050-151:2001, 151-15-50]~~

3.5.12

SPACING

any combination of CLEARANCES and CREEPAGE DISTANCES

4 Tests

4.1 General

Tests in this standard are TYPE TESTS to be carried out on samples of probe assemblies or their parts. Their only purpose is to check that the design and construction ensure conformity with this standard. **In addition, the ROUTINE TESTS of Annex D shall be performed on the PROBE WIRE.**

The probe assembly shall at least meet the requirements of this standard. It is permissible to exceed the requirements. If, in this standard, a lower limit is specified for a conformity value, then the probe assembly may demonstrate a larger value. If an upper limit is specified for a conformity value, the probe assembly may demonstrate a lower value. Manufacturing variations and tolerances shall be taken into account.

Tests on components or parts of the probe assembly meeting the requirements of the relevant standards, **specified in this standard, and used in accordance with them,** need not be repeated during TYPE TESTS of the whole probe assembly.

If a probe assembly is of more than one probe type (see 1.1.1), each type shall be tested according to its applicable requirements.

*Conformity with the requirements of this standard is checked by carrying out all applicable tests, except that a test may be omitted if examination of the probe assembly **and design documentation** demonstrates conclusively that it would pass the test. Tests are carried out both under reference test conditions (see 4.3) and fault conditions (see 4.4).*

Where conformity statements in this standard require inspection, this may include examination of the probe assembly by measurement, examination of the markings on the probe assembly, examination of the instructions supplied with the probe assembly, examination of the data sheets of the materials or components from which the probe assembly is manufactured, etc. In each case, the inspection will either demonstrate that the probe assembly meets the applicable requirements, or will indicate that further testing is required.

NOTE 2 If when carrying out a conformity test, there is any uncertainty about the exact value of the applied or measured quantity (for example, voltage) due to the tolerance,

- a) the manufacturer should ensure that at least the specified test value is applied;
- b) the test house should ensure that no more than the specified test value is applied.

NOTE 4 If the RATED range of environmental conditions for probe assemblies is wider than that stated in 1.4.1, the manufacturer should make sure (for example, by suitable alteration of test requirements or additional tests) that the safety requirements of this standard are still fulfilled.

NOTE 3 Probe assemblies which have been type tested may no longer be suitable for their intended function because of the residual effect of stresses resulting from tests. ~~For this reason TYPE TESTS should never be carried out (for example, by the RESPONSIBLE BODY) after the PROBE ASSEMBLIES have left the manufacturer. A probe assembly which has undergone TYPE TESTS shall not then be put into use.~~

4.2 Sequence of tests

The sequence of tests is optional unless otherwise specified ~~in the standard~~. The probe assemblies under test shall be carefully inspected after each test. If the result of a test causes doubt whether any earlier tests would have ~~been~~ passed if the sequence had been reversed, these earlier tests shall be repeated. ~~Tests under fault conditions may be destructive and may follow those under reference test conditions.~~

4.3 Reference test conditions

4.3.1 Environmental conditions

Unless otherwise specified in this standard, the following environmental conditions (but not conflicting with those of 1.4.1, shall exist in the test location:

- a) a temperature of 15 °C to 35 °C;
- b) a relative humidity of not more than 75 %;
- c) an air pressure of 75 kPa to 106 kPa;
- d) no hoarfrost, dew, percolating water, rain, solar irradiation, etc.

4.3.2 State of probe assemblies

Unless otherwise specified, tests shall be carried out on the probe assemblies assembled for NORMAL USE and under the least favourable combination of the conditions given in 4.3.3 to 4.3.9.

In case of doubt, tests shall be performed in more than one combination of conditions.

If dimensions or mass make it unsuitable to carry out particular tests on a complete probe assembly, tests on sub-assemblies are allowed, provided it is verified that the assembled probe assembly will meet the requirements of this standard.

4.3.3 Position of the probe assembly

~~The probe assembly shall be in any position of NORMAL USE and with any ventilation unimpeded.~~ All possible orientations of the probe assembly are considered to be positions of NORMAL USE.

4.3.4 Accessories

Accessories and OPERATOR-interchangeable parts available from, or recommended by, the manufacturer for use with the probe assembly under test shall be either connected or not connected.

4.3.5 Covers and removable parts

Covers or parts which can be removed without using a TOOL shall be removed or not removed ~~whichever is the worst condition.~~

4.3.6 Input and output voltages

Input and output voltages, including floating voltages shall be set to any voltage within the RATED voltage range.

4.3.7 Controls

Controls which the OPERATOR can adjust ~~by hand without the use of a TOOL~~ shall be set to any position except for combinations of settings prohibited by the ~~manufacturer, as shown by~~ manufacturer's marking on the probe assembly.

4.3.8 Connections

The probe assembly shall be connected for ~~its intended purpose,~~ NORMAL USE or not connected ~~whichever is the worst condition.~~

4.3.9 Duty cycle

Probe assemblies for short-term or intermittent operation shall be operated for the longest **RATED** period and **shall** have the shortest **RATED** recovery period consistent with the manufacturer's instructions.

4.4 Testing in SINGLE FAULT CONDITION

4.4.1 General

The following requirements apply.

- a) Examination of the probe assembly and its circuit diagram will generally show the fault conditions which are liable to result in HAZARDS ~~within the meaning of this standard~~ and which, therefore, shall be applied.
- b) Fault tests shall be made **as specified for checking conformity**, unless it can be demonstrated that no HAZARD could arise from a particular fault condition.
- c) The probe assembly shall be operated under the least favourable combination of reference test conditions (see 4.3). These combinations may be different for different faults and they ~~should~~ **shall** be recorded for each test.

4.4.2 Application of fault conditions

4.4.2.1 General

Fault conditions shall include those specified in 4.4.2.2 to 4.4.2.5. They shall be applied only one at a time and shall be applied in turn in the most convenient order. Multiple simultaneous faults shall not be applied unless they are a consequence of an applied fault.

After each application of a fault condition, the probe assembly or part shall pass the applicable tests of 4.4.4.

4.4.2.2 PROTECTIVE IMPEDANCE

The following requirements apply.

- a) If a PROTECTIVE IMPEDANCE is formed by a combination of components, each component shall be short-circuited or disconnected, whichever is less favourable.
- b) If a PROTECTIVE IMPEDANCE is formed with a single component that meets the requirements of 6.4.5, it need not be short-circuited or disconnected.

4.4.2.3 Probe assemblies or parts for short-term or intermittent operation

These shall be operated continuously if continuous operation could occur in a SINGLE FAULT CONDITION.

4.4.2.4 Outputs

Outputs of Type B and Type C probe assemblies shall be short-circuited ~~one at a time~~.

4.4.2.5 Insulation between circuits and parts

Insulation between circuits and parts which is below the level specified for BASIC INSULATION shall be bridged to check against the spread of fire **if the method of 9.1 is used**.

NOTE—See 9.1 for an alternative method of checking protection against spread of fire.

4.4.2.4 COMPONENTS

~~Components (except HIGH INTEGRITY components) of type B and type C PROBE ASSEMBLIES shall be short-circuited or open-circuited, whichever is less favourable.~~

4.4.3 Duration of tests

The probe assembly shall be operated until further change as a result of the applied fault is unlikely. Each test is normally limited to 1 h since a secondary fault arising from a SINGLE FAULT CONDITION will usually manifest itself within that time. ~~If at the end of 1 h there is an indication that a risk HAZARD of electric shock, spread of fire or injury to persons may eventually occur, the test shall be continued until one of these HAZARDS does occur or for a maximum period of 4 h.~~

~~If a fault is terminated by the opening of a fuse and if the fuse does not operate within approximately 1 s, the current through the fuse under the relevant fault condition shall be measured. Evaluation with the pre-arcing time/current characteristics shall be made to find out whether the minimum operating current of the fuse is reached or exceeded and what is the maximum time before the fuse operates. The current through the fuse may vary as a function of time. If the minimum operating current of the fuse is not reached in the test, the equipment shall be operated for a period corresponding to the maximum fusing time or continuously for the duration specified in 4.4.3.1.~~

4.4.4 Conformity after application of single fault conditions

4.4.4.1 Electric shock

Conformity with requirements for protection against electric shock after the application of single faults is checked as follows:

- by making the measurements of 6.3.3 to check that no ACCESSIBLE conductive parts have become HAZARDOUS LIVE, except as permitted by 6.1;
- by performing a voltage test on DOUBLE INSULATION or REINFORCED INSULATION to check that ~~there the protection~~ is still ~~one at least at the level of protection by BASIC INSULATION~~. The voltage tests are made as specified in 6.6 (without humidity preconditioning) with the test voltage for BASIC INSULATION.

4.4.4.2 Temperature

Conformity with requirements for temperature protection is checked by determining the temperature of the outer surface of the probe assembly (see Clause 9).

~~The temperature of the outer surface shall not exceed 105 °C at maximum RATED ambient temperature.~~

This temperature is determined by measuring the temperature rise of the surface or part and adding it to the maximum RATED ambient temperature.

4.4.4.3 Spread of fire

Conformity with requirements for protection against the spread of fire is checked by placing the probe assembly on white tissue-paper covering a softwood surface and covering the probe assembly with cheesecloth. No molten metal, burning insulation, flaming particles, etc. shall fall on the surface on which the probe assembly stands and there shall be no charring, glowing, or flaming of the tissue paper or cheesecloth. Melting of insulation material shall be ignored ~~if the molten material could not contribute to starting a fire, and if it would be obvious to the operator that the PROBE ASSEMBLY needs to be de-energized and allowed to cool before it is touched no HAZARD could arise.~~

4.4.4.4 Other HAZARDS

Conformity with the requirements for protection against other HAZARDS is checked as specified in Clauses 7 to 13.

4.5 Tests in REASONABLY FORESEEABLE MISUSE

4.5.1 General

Tests needed to support a risk assessment pertaining to REASONABLY FORESEEABLE MISUSE are carried out in the combinations of conditions and operations determined during the risk assessment.

4.5.2 Fuses

Fused probe assemblies are used where insufficient protection may be provided by the equipment to which the hand manipulated probe assemblies are connected in particular under the REASONABLY FORESEEABLE MISUSE conditions associated with the equipment that could lead to fire or arc explosion.

For the purposes of this test, it is assumed that the equipment to which the probe assemblies are connected represents a short circuit condition. It is further assumed that the fused probe assembly may be connected to any voltage source within the RATING of the probe assembly. This leads to a test condition where any current level up to the maximum prospective short circuit current may be applied. With respect to prospective short circuit currents associated with MAINS installations, the fuse shall be RATED according to 12.2 and no additional testing related to the interrupt current RATING is necessary. However, testing is necessary at current levels near the RATING of fuse which could potentially lead to excessive temperature rise on hand held parts as well as damage to insulating parts, ENCLOSURES, and barriers.

It shall be demonstrated that the maximum fuse temperature under any current load condition up to 5 times the fuse RATING through the fused probe assembly does not lead to a HAZARD.

Conformity is checked by inspection and measurement.

5 Marking and documentation

5.1 Marking

5.1.1 General

Probe assemblies shall bear markings in accordance with 5.1.2 to 5.2. Markings applying to a probe assembly as a whole shall not be put on parts which can be removed by an OPERATOR without the use of a TOOL.

Letter symbols for quantities and units shall be in accordance with IEC 60027. Graphic symbols shall be in accordance with Table 1 if applicable. There are no requirements for size or colour. If there is no applicable symbol in Table 1, any other graphic symbol may be used on a probe assembly provided the symbol is explained in the accompanying documentation (see 5.4.1).

If it is not possible to put all of the required markings on the part, the necessary information shall be included in the documentation. Symbol 7 of Table 1 may also be used.

Conformity is checked by inspection.

5.1.2 Identification

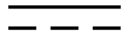
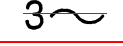
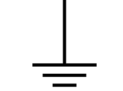
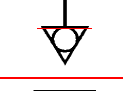
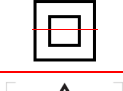
Each probe assembly and ~~separable mating part of a PROBE ASSEMBLY~~, when possible, its accessories shall, ~~as a minimum~~, be marked with:

- the name or registered trade mark of the manufacturer or supplier;
- in addition for Type B and Type C only, the model number or name or other means of identifying the probe assembly or part.

If a probe assembly is designed for use only with a specific model of equipment, this shall be made clear, and the specific equipment or model shall be identified, either by marking on the probe assembly or in the accompanying documentation.

Conformity is checked by inspection.

Table 1 – Symbols

Number	Symbol	Reference	Description
1		IEC 60417-5031 (2002-10)	Direct current
2		IEC 60417-5032 (2002-10)	Alternating current
3		IEC 60417-5033 (2002-10)	Both direct and alternating current
4			Three-phase alternating current
4		IEC 60417-5017 (2006-08)	Earth (ground) TERMINAL
6		IEC 60417-5024	Equipotentiality
7		IEC 60417-5172	Part protected throughout by DOUBLE INSULATION OR REINFORCED INSULATION
5		IEC 60417-6042 (2010-11)	Caution, risk possibility of electric shock
6		IEC 60417-5041 (2002-10)	Caution, hot surface
7		ISO 7000-0434 (2004-01)	Caution, risk of danger (see note 1) ^a
NOTE 1 ^a See 5.4.1 which requires manufacturers to state that documentation must be consulted in all cases where this symbol is marked.			
NOTE 2 There are no requirements for sizes or colours (see 5.1.1).			

5.1.3 Fuses

Probe assemblies which contain fuses intended to be replaced by an OPERATOR shall be marked with all the details necessary for the OPERATOR to obtain the correct fuse. These shall include the voltage RATING and the breaking capacity (the maximum current that the fuse can safely interrupt at the highest RATED voltage). If ~~the OPERATOR has to select a fuse according to the particular application~~, there is not sufficient room, Symbol 7 of Table 1 shall be marked on the probe assembly and the necessary information shall be included in the documentation.

Conformity is checked by inspection.

5.1.4 **Terminals CONNECTORS and operating devices**

If necessary for safety, an indication shall be given of the purpose of CONNECTORS, TERMINALS, and controls, including any sequence of operations.

Conformity is checked by inspection.

~~5.1.5 PARTS PROTECTED BY double insulation OR reinforced insulation~~

~~Parts protected throughout by DOUBLE INSULATION OR REINFORCED INSULATION shall be marked with symbol 7 of table 1.~~

~~Parts which are only partially protected by DOUBLE INSULATION OR REINFORCED INSULATION shall not bear symbol 7 of table 1.~~

~~*Conformity is checked by inspection.*~~

5.1.5 **RATING**

The RATING of probe assemblies shall be marked as follows.

- a) Probe assemblies ~~which do not have a RATING for measurements within category I~~ MEASUREMENT CATEGORIES II, III, or IV (see 6.5.2) shall be marked with the RATED voltage to earth and with Symbol 7 of Table 1 (see also 5.4.3 f) and g)).
- b) Probe assemblies for measurements within MEASUREMENT CATEGORIES II, III and IV (see 6.5.2) shall be marked with the RATED voltages to earth and the relevant MEASUREMENT CATEGORIES. The MEASUREMENT CATEGORY markings shall be "CAT II", "CAT III" or "CAT IV" as applicable.

Marking on a probe assembly shall preferably be on the probe body. The nature of the voltage (a.c., d.c., etc.) shall also be marked, unless the voltage marking applies to both a.c. r.m.s. and d.c. If a reference CONNECTOR is intended for connection to points at a voltage level exceeding the values of 6.3.2, ~~its~~ the RATED voltage ~~RATING~~ shall be marked, ~~preferably~~ on the CONNECTOR or as close to the CONNECTOR as is practicable.

For Type A ~~and Type D~~ probe assemblies only, the ~~maximum~~ RATED current of the probe assembly shall be marked together with the ~~maximum RATED circuit-to-earth~~ RATED voltage to earth. The ~~maximum~~ RATED current does not need to be marked on probe assemblies which are specified for use only in conjunction with equipment which has high-impedance inputs or limited-current outputs.

Conformity is checked by inspection.

5.2 **Warning markings**

Warning markings shall be ~~visible legible~~ when the probe assembly is ready for NORMAL USE.

If it is necessary for the OPERATOR to refer to the instruction manual to preserve the protection afforded by the probe assembly, the probe assembly shall be marked with the Symbol 7 of Table 1. If a warning applies to a particular part of the probe assembly, the marking shall be placed on or near this part.

If the instructions for use state that an OPERATOR is permitted to gain access, using a TOOL, to any part which in NORMAL USE may be HAZARDOUS LIVE, there shall be a warning marking which states that the probe assembly must be isolated or disconnected from the HAZARDOUS LIVE voltage before access, or Symbol 7 of Table 1 may be used provided that the information is included in the instructions for use.

Unless their heated state is self-evident or is obvious from the function of the probe assembly, parts which are easily touched and are also permitted by 9.1 to exceed the temperature limits of 9.1 shall be marked with Symbol 6 of Table 1.

Conformity is checked by inspection.

5.3 Durability of markings

Required markings ~~in accordance with 5.1.2 to 5.2~~ shall remain clear and legible under conditions of NORMAL USE and **shall** resist the effects of cleaning agents specified by the manufacturer.

*Conformity is checked ~~by inspection and~~ by performing the following test for durability of markings on the outside of the probe assembly. The markings are rubbed by hand, without undue pressure, for 30 s with a cloth soaked with each specified cleaning agent, **one at a time**, or, if not specified, with **a solution containing a minimum of 70 % isopropyl alcohol in water**.*

After the above treatment the markings shall be clearly legible and adhesive labels shall not have worked loose or become curled at the edges.

5.4 Documentation

5.4.1 General

Probe assemblies shall be accompanied by documentation when necessary for safety purposes. Such documentation shall include as a minimum:

- a) technical specification;
- b) instructions for use;
- c) name and address of manufacturer or supplier from whom technical assistance may be obtained;
- d) the information specified in 5.4.2 to 5.4.4.

If applicable, warning statements and a clear explanation of warning symbols marked on the probe assembly shall be provided in the documentation or shall be durably and legibly marked on the probe assembly. In particular, there shall be a statement that documentation needs to be consulted in all cases where Symbol 7 of Table 1 is used, in order to find out the nature of the potential HAZARD and any actions which have to be taken.

Conformity is checked by inspection.

5.4.2 **Ratings Probe assembly RATING**

Documentation shall include the ~~maximum~~ voltage and current RATING (as appropriate), **and the MEASUREMENT CATEGORY** as well as a statement of the range of environmental conditions for which the probe assembly is designed (see 1.4 ~~and note 1 of 4.1~~).

Conformity is checked by inspection.

5.4.3 **Probe assembly operation**

Instructions for use shall include, **if applicable**:

- a) identification of operating controls and their use in all operating modes;
- b) for probe assemblies designed for use only with a specific model of equipment, a clear identification of the equipment;**

- c) an explanation of symbols ~~required by this standard and related to safety~~ which are used on the probe assembly;
- d) a definition of the relevant MEASUREMENT CATEGORY if marking is required on the probe assembly (see 5.1.5);
- e) a specification of limits for intermittent operation, if applicable;
- f) instructions for interconnection to accessories and other equipment, including indication of suitable accessories, detachable parts and any special materials;
- g) instructions for cleaning ~~if necessary (see 11.2)~~;
- h) instructions for replacement of consumable materials;
- i) for PROBE ASSEMBLIES ~~intended for use within measurement category I, a warning shall be given not to use the PROBE ASSEMBLIES for measurements within the other measurement categories, and there shall be a detailed RATING, including RATED transient overvoltages, in the documentation~~ which do not have PROBE WIRE with a wear indicator, instructions to periodically inspect the PROBE WIRE;
- j) for probe assemblies which do have PROBE WIRE with a wear indicator, a warning not to use the probe assembly if the wear indicator has become visible (see 12.3.2);
- k) for probe assemblies which do not have a RATING for MEASUREMENT CATEGORIES II, III, or IV, a warning not to use the probe assemblies for measurements on mains circuits;
- l) for Type B probe assemblies, if the RATED voltage of the PROBE WIRE is lower than the RATED voltage of the PROBE TIP, a warning that the PROBE WIRE may not provide adequate protection if it comes into contact with a HAZARDOUS LIVE part;
- m) a warning that the applicable MEASUREMENT CATEGORY of a combination of a probe assembly and an accessory is the lower of the MEASUREMENT CATEGORIES of the probe assembly and of the accessory.

~~The RESPONSIBLE BODY shall be made aware that~~ There shall be a statement in the instructions that, if the PROBE ASSEMBLY is used in a manner not specified by the manufacturer, the protection provided by the probe assembly may be impaired.

Conformity is checked by inspection.

5.4.4 **MAINTENANCE Probe assembly maintenance and service**

~~Instructions for shall be provided to the RESPONSIBLE BODY concerning preventive maintenance and inspection necessary for safety shall be given~~ in sufficient detail to permit safe maintenance and inspection of the probe assembly, and to ensure continued safety of the probe assembly after the maintenance and inspection procedure.

The manufacturer shall specify any parts which are required to be examined or supplied only by the manufacturer or his agent.

The RATING and characteristics of fuses used shall be stated (see 5.1.3).

Instructions on the following subjects shall be provided for service personnel, as necessary to permit safe servicing and continued safety of the probe assembly after servicing if the probe assembly is suitable to be serviced:

- a) product-specific risks that may affect the service personnel;
- b) protective measures for these risks;
- c) verification of the safe state of the probe assembly after repair.

Instructions for service personnel do not need to be supplied to the RESPONSIBLE BODY, but should be made available to service personnel.

Conformity is checked by inspection.

6 Protection against electric shock

6.1 General

Protection against electric shock shall be maintained in NORMAL CONDITION and SINGLE FAULT CONDITION. ACCESSIBLE parts of probe assemblies shall not be HAZARDOUS LIVE (see 6.3).

6.1.1 EXCEPTIONS

If it is not feasible for operating reasons to prevent the following parts being both ACCESSIBLE and HAZARDOUS LIVE, they are permitted to be ACCESSIBLE to the OPERATOR during NORMAL USE while they are HAZARDOUS LIVE:

- a) parts intended to be replaced by the OPERATOR (for example, fuses) and which may be HAZARDOUS LIVE during replacement, but only if they have warning markings in accordance with 5.2;
- b) PROBE TIPS, provided that they meet the requirements of 6.4.3;
- c) unmated CONNECTORS as specified in 6.4.2 c).

Conformity is checked by the determination of 6.2 and the measurements of 6.3, followed by the tests of 6.4 to 6.7.

6.2 Determination of ACCESSIBLE parts

6.2.1 General

Unless obvious, determination of whether a part is ACCESSIBLE ~~shall be~~ is made as specified in 6.2.2 and 6.2.3. Test fingers (see Annex B) and pins ~~shall be~~ are applied without force ~~unless a force is specified~~. Parts are considered to be ACCESSIBLE if they can be touched with any part of a test finger or pin, or if they ~~can~~ could be touched in the absence of a covering which is not considered to provide suitable insulation (see 6.7.2).

If, in NORMAL USE, an OPERATOR is intended to perform any actions (with or without a TOOL) ~~which will that could~~ increase the accessibility of parts, such actions ~~shall be~~ are taken before performing the examinations of 6.2.2 and 6.2.3.

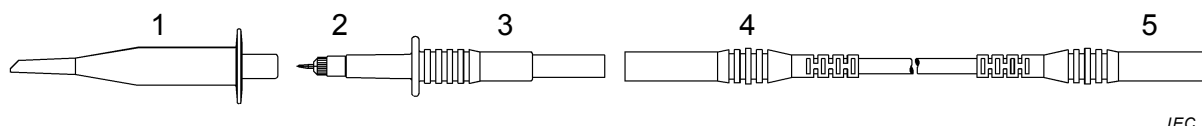
NOTE Examples of such actions include:

- a) removing covers;
- b) adjusting controls;
- c) replacing consumable materials;
- d) removing or installing parts and supplied accessories.

Figure 6 gives methods for determination of ACCESSIBLE parts of probe assemblies.

6.2.2 GENERAL Examination

The jointed test finger (see Figure B.2) is applied in every possible position without force. ~~If a force is specified, the rigid test finger (see figure B.1) is applied with the specified force. The force is exerted by the tip of the test finger so as to avoid wedge and lever action. The test is applied to all outer surfaces.~~

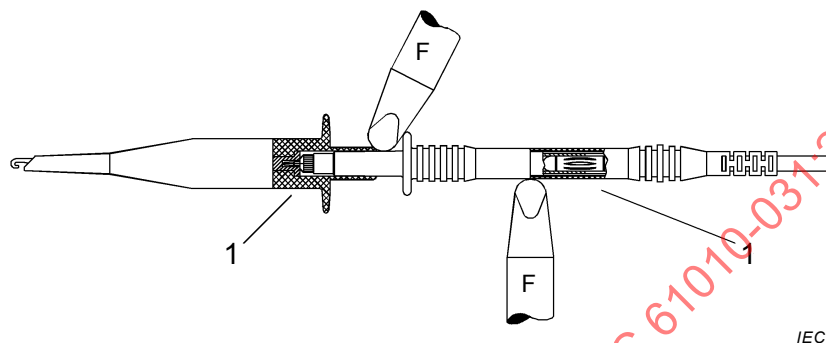


IEC

Key

- | | |
|-----------------------|--------------------------|
| 1 accessory PROBE TIP | 4 CONNECTOR |
| 2 PROBE TIP | 5 CONNECTOR to equipment |
| 3 probe body | |

Figure 3a 6a – Parts of a probe assembly

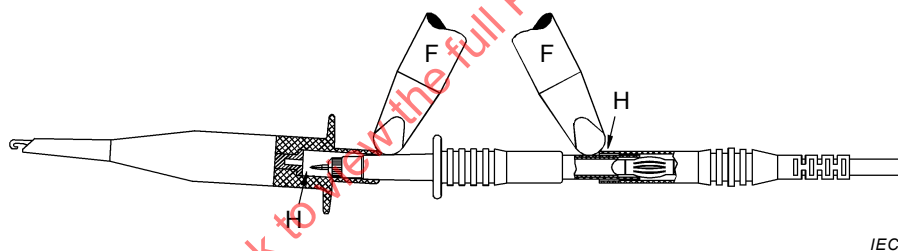


IEC

Key

- 1 CONNECTOR

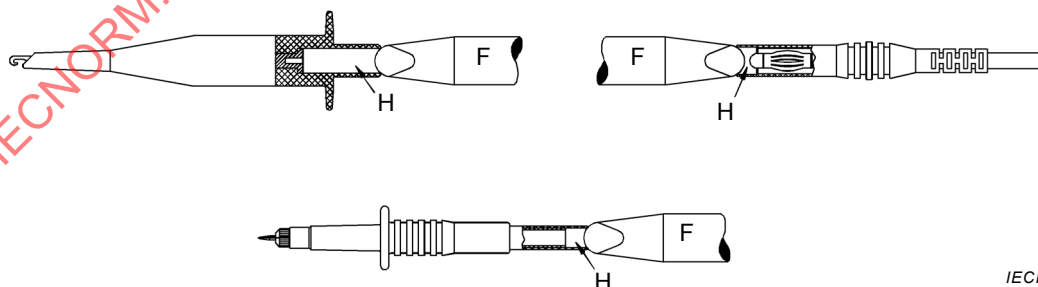
Figure 3b 6b – Fully-mated probe assembly (see 6.2 and 6.4.2 a)



IEC

Connecting parts are partially mated so as just to make electrical contact while allowing maximum access to the test finger.

Figure 3c 6c – Partially-mated probe assembly (see 6.2 and 6.4.2 b)



IECII

Key

- F rigid test finger (see Figure B.1)
H potentially HAZARDOUS LIVE part

Figure 3d 6d – Unmated parts of a probe assembly (see 6.2 and 6.4.2 c))

Figure 3 6 – Methods for determination of ACCESSIBLE parts (see 6.2) and for voltage tests of (see 6.4.2)

6.2.3 Openings for pre-set controls

A metal test pin 3 mm in diameter is inserted through holes intended to give access to pre-set controls which require the use of a screwdriver or other TOOL. The test pin is applied in every possible direction through the hole. Penetration shall not exceed three times the distance from the ENCLOSURE surface to the control shaft or 100 mm, whichever is smaller.

6.3 ~~Permissible limits~~ Limit values for ACCESSIBLE parts

6.3.1 General

~~To ensure that ACCESSIBLE parts are not HAZARDOUS LIVE Except as permitted in 6.1, the voltage or current between an ACCESSIBLE part and reference test earth, or between any two ACCESSIBLE parts on the same probe assembly, shall not exceed the values levels of 6.3.2 in NORMAL CONDITION or of 6.3.3 in SINGLE FAULT CONDITION.~~

~~Measurements on probe assemblies are carried out in accordance with figure 4. Foil is wrapped around~~

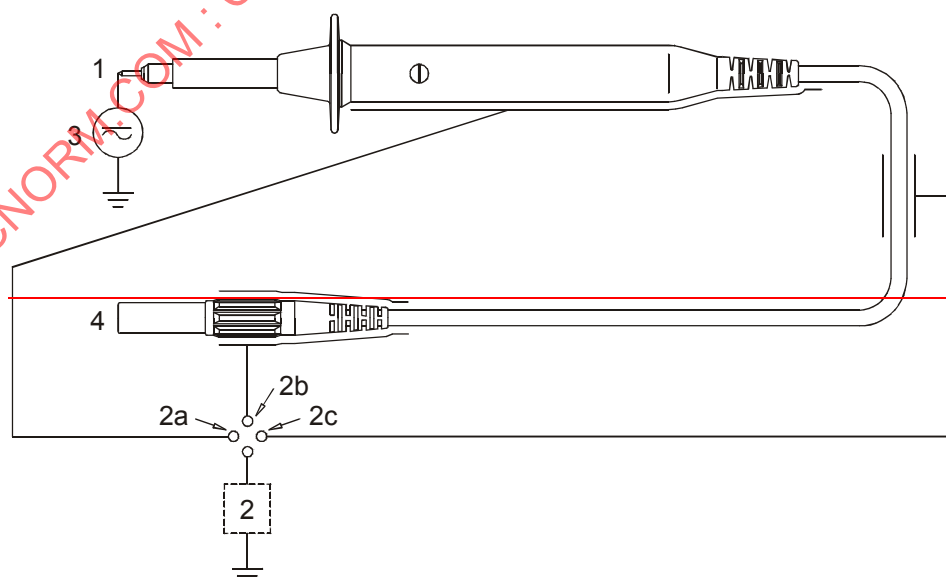
- ~~a) the probe body;~~
- ~~b) 150 mm ± 20 mm of the cable;~~
- ~~c) the connector.~~

~~The RATED voltage is applied to the PROBE TIP (1) and the ACCESSIBLE current is measured with the applicable measuring circuit of annex A, where the circuit (2) is connected in turn to the foil wrapped items (2a, 2b, 2c, etc.).~~

Outer conductors (shields) of probe assemblies, intended to be floating, are considered to be held at the same voltage as the PROBE TIP.

The ACCESSIBLE voltage shall be measured (see 6.3.4). If the voltage is below the limit levels of 6.3.2 a) or 6.3.3 a) as applicable, ACCESSIBLE the touch current and the capacitance need not be measured. If the voltage exceeds that value level, the touch current and the capacitance shall be measured. For high frequencies test probes, the alternative method of 6.3.4.3 can also be used.

Conformity is checked by inspection and as specified in 6.3.2 to 6.3.3.



Key

1 — PROBE TIP

2 — ACCESSIBLE current measuring circuit (see annex A)

- 2a — Connection to metal foil tightly wrapped around parts intended to be hand-held or hand-manipulated
- 2b — Connection to metal foil tightly wrapped around the connector
- 2c — Connection to metal foil tightly wrapped around the cable (see 6.4.3)
- 3 — Maximum RATED voltage
- 4 — Not connected to equipment

Figure 4 — Example of application of metal foil for ACCESSIBLE current measurement

6.3.2 VALUES Levels in NORMAL CONDITION

Values Voltages above the levels of ~~6.3.1.1, 6.3.1.2 and 6.3.1.3~~ in NORMAL CONDITION a) are deemed to be HAZARDOUS LIVE if any of the levels of b) or c) are exceeded at the same time.

6.3.1.1 VOLTAGE

- a) The a.c. voltage levels are ~~33~~ 30 V r.m.s. ~~and 46,7 or 42,4 V peak or 70 V d.c.~~, and the d.c. voltage level is 60 V. For probe assemblies ~~which are RATED for~~ intended for use in WET LOCATIONS, the a.c. voltage levels are 16 V r.m.s. ~~and or 22,6 V peak or 35 V d.c.~~, and the d.c. voltage level is 35 V.

6.3.1.2 CURRENT

- b) ~~If the voltage exceeds one of the values of 6.3.1.1,~~ The touch current levels are:
 - 1) 0,5 mA r.m.s. for sinusoidal waveforms, 0,7 mA peak for non-sinusoidal waveforms or mixed frequencies, or 2 mA d.c., when measured with the measuring circuit of Figure A.1. If the frequency does not exceed 100 Hz, the measuring circuit of Figure A.2 can be used. The measuring circuit of Figure A.5 is used for probe assemblies ~~which are RATED~~ intended for use in WET LOCATIONS;
 - 2) 70 mA r.m.s. when measured with measuring circuit of Figure A.3. This relates to possible burns at ~~higher~~ frequencies ~~above~~ 100 kHz.

6.3.1.3 CAPACITANCE

- c) ~~If the voltage exceeds one of the values of 6.3.1.1, the capacitance~~ The levels of capacitive charge or energy are:
 - 1) 45 µC charge for voltages up to 15 kV peak or d.c. Line A of Figure 7 shows the capacitance versus voltage for cases where the charge is 45 µC.
 - 2) 350 mJ stored energy for voltages above 15 kV peak or d.c.

6.3.3 VALUES Levels in SINGLE FAULT CONDITION

In SINGLE FAULT CONDITION, ~~values~~ voltages above the levels of ~~6.3.2.1, 6.3.2.2 and 6.3.2.3~~ a) are deemed to be HAZARDOUS LIVE if any of the levels of b) or c) are exceeded at the same time.

6.3.2.1 VOLTAGE

- a) The a.c. voltage levels are ~~55~~ 50 V r.m.s. ~~and 78 or 70,7 V peak or 140 V d.c.~~, and the d.c. voltage level is 120 V. For probe assemblies ~~which are RATED~~ intended for use in WET LOCATIONS, the a.c. voltage levels are 33 V r.m.s. ~~and or 46,7 V peak or 70 V d.c.~~, and the d.c. voltage level is 70 V.

6.3.2.2 CURRENT

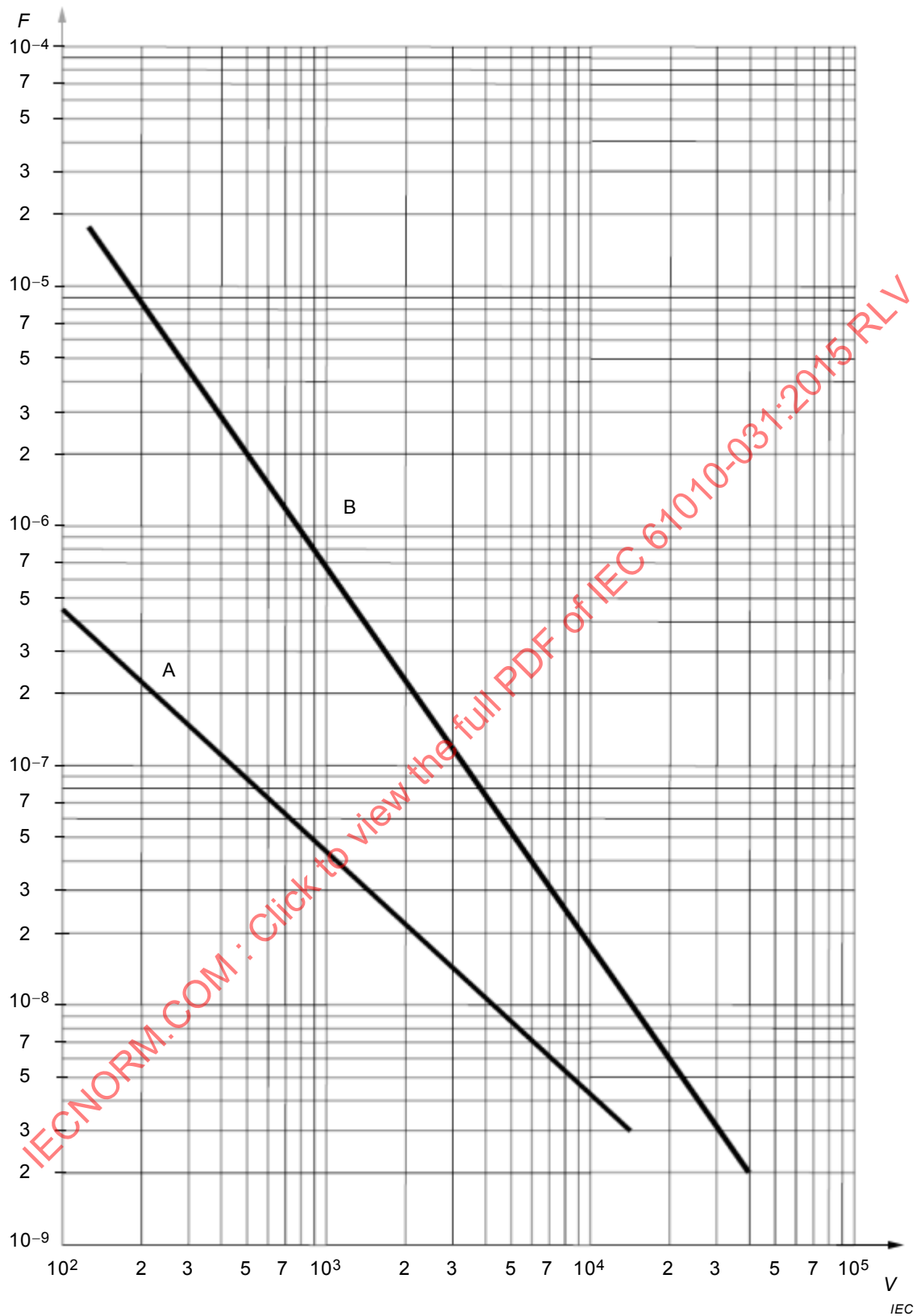
- b) ~~If the voltage exceeds one of the values of 6.3.2.1,~~ The touch current levels are:
 - 1) 3,5 mA r.m.s. for sinusoidal waveforms, 5 mA peak for non-sinusoidal waveforms or mixed frequencies, or 15 mA d.c., when measured with the measuring circuit of Figure A.1. If the frequency does not exceed 100 Hz, the measuring circuit of Figure A.2 can be used. The measuring circuit of Figure A.5 is used for probe assemblies ~~which are RATED~~ intended for use in WET LOCATIONS;

- 2) 500 mA r.m.s. when measured with the measuring circuit of Figure A.3. This relates to possible burns at ~~higher~~ frequencies ~~above~~ 100 kHz.

~~6.3.2.3~~ CAPACITANCE

- c) ~~If the voltage exceeds one of the values of 6.3.2.1,~~ The capacitance level is ~~that~~ line B of Figure 7.

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV



Key

A = NORMAL CONDITION

B = SINGLE FAULT CONDITION

Figure 5-7 – Charged Capacitance level versus voltage in NORMAL CONDITION and SINGLE-FAULT CONDITION (see 6.3.2.3 6.3.2 c) and 6.3.3 c))

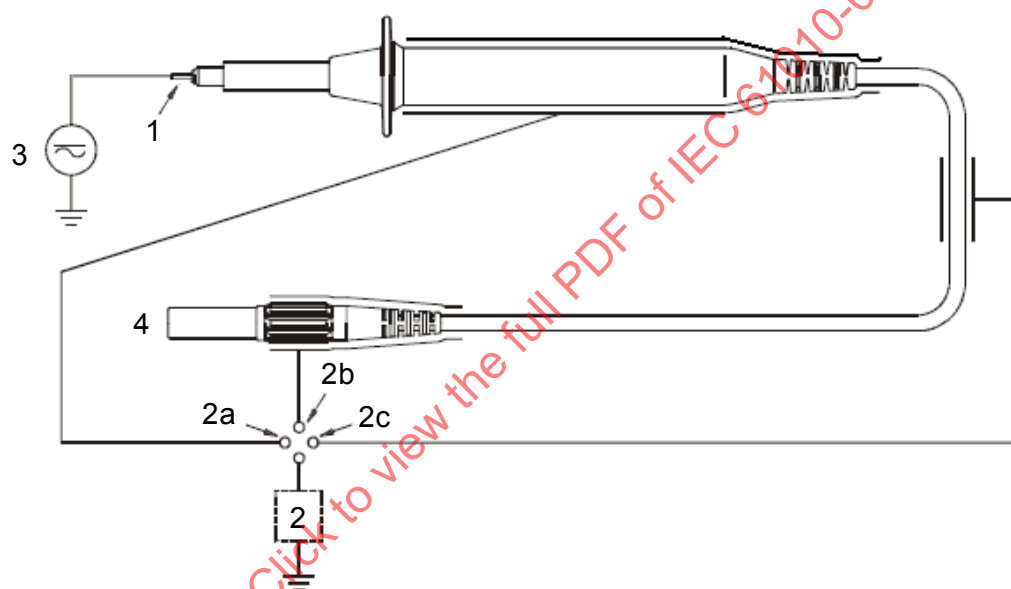
6.3.4 Measurement of voltage and touch current

6.3.4.1 General

Measurement of voltage and touch current on ACCESSIBLE parts of probe assemblies is carried out with metal foil wrapped around each of the following parts, individually:

- the probe body;
- 150 mm $\pm$ 20 mm of the PROBE WIRE or the maximum length of the cable whichever is shorter;
- hand-held or hand-manipulated parts of each CONNECTOR;
- other hand-held or hand-manipulated parts.

The RATED voltage to earth is applied between the PROBE TIP (1) and the earth. The voltage is measured between the foil and the earth. If necessary, the measurement circuit is connected in turn (2a – 2b – 2c) between each of the foil-wrapped items and the earth (see Figure 8 and Figure 9).

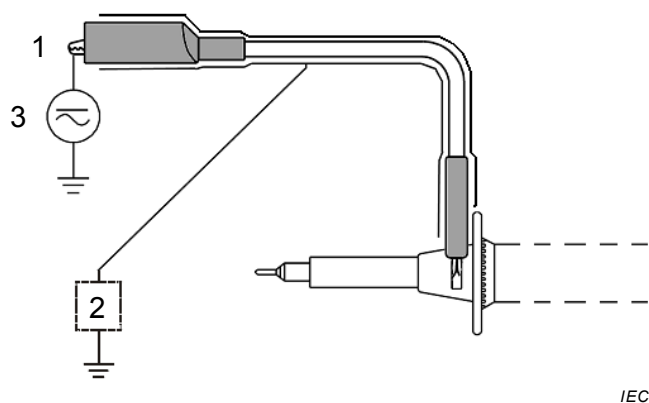


IEC

Key

- PROBE TIP
- Measurement of voltage or touch current (see annex A for applicable measuring circuits for touch current measurements)
 - Connection to metal foil tightly wrapped around parts intended to be hand-held or hand-manipulated
 - Connection to metal foil tightly wrapped around the CONNECTOR
 - Connection to metal foil tightly wrapped around the cable (see 12.3.2)
- Maximum RATED voltage with connection to internal conductor of the PROBE WIRE
- Not connected to test or measuring equipment

Figure 8 – Voltage and touch current measurement



Key

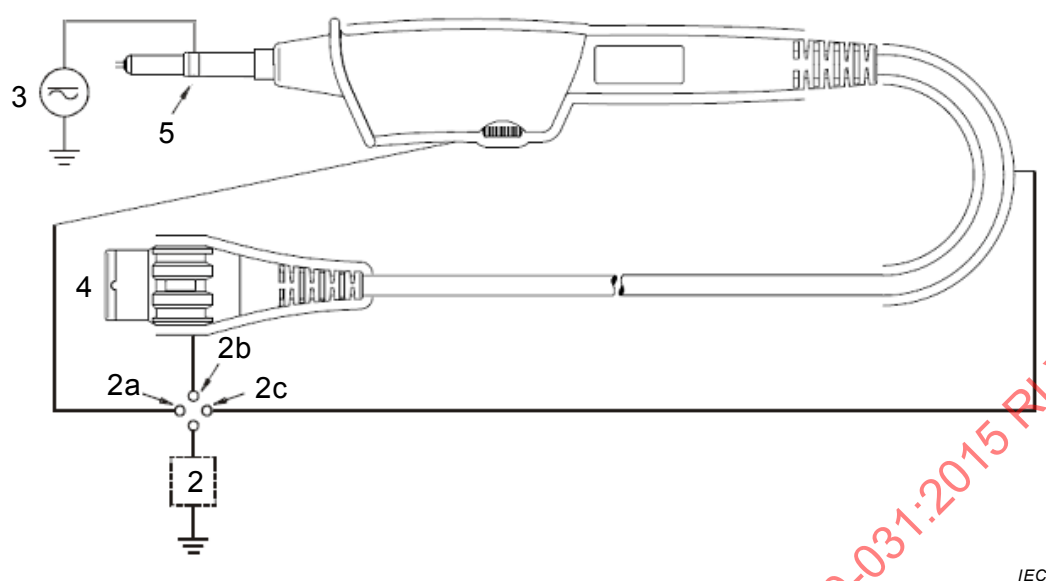
- 1 PROBE TIP of the reference CONNECTOR
- 2 Measurement of voltage or touch current (see annex A for applicable measuring circuits for touch current measurements)
- 3 Maximum RATED voltage for the reference CONNECTOR

Figure 9 – Voltage and touch current measurement for the reference CONNECTOR

6.3.4.2 Probe assemblies with floating outer conductors

For probe assemblies where the outer conductor (shield) connection may be intended to be floating, the test is also performed between the outer conductor PROBE TIP (5) and the earth (see Figure 10).

The touch current is determined by using the applicable measuring circuit of Annex A.

**Key**

- 2 Measurement of voltage or current (see Annex A for applicable measuring circuits for touch current measurements)
 - 2a Connection to metal foil tightly wrapped around parts intended to be hand-held or hand-manipulated
 - 2b Connection to metal foil tightly wrapped around the CONNECTOR
 - 2c Connection to metal foil tightly wrapped around the cable (see 12.3.2)
- 3 Maximum RATED voltage with connection to outer conductor PROBE TIP
- 4 Not connected to test or measuring equipment
- 5 A floating PROBE TIP connected to the shield or outer conductor of the PROBE WIRE

Figure 10 – Voltage and touch current measurement with shielded test probe

6.3.4.3 High frequency test probes

In case of test probes RATED for frequencies above 100 kHz, with floating outer conductor (shield), the maximum allowable voltage between the shield and ACCESSIBLE parts of the probe have to be determined to avoid electrical burns. The touch current shall be measured in the whole frequency range and at maximum voltage in each frequency range.

The measurements are made (see Figure 10):

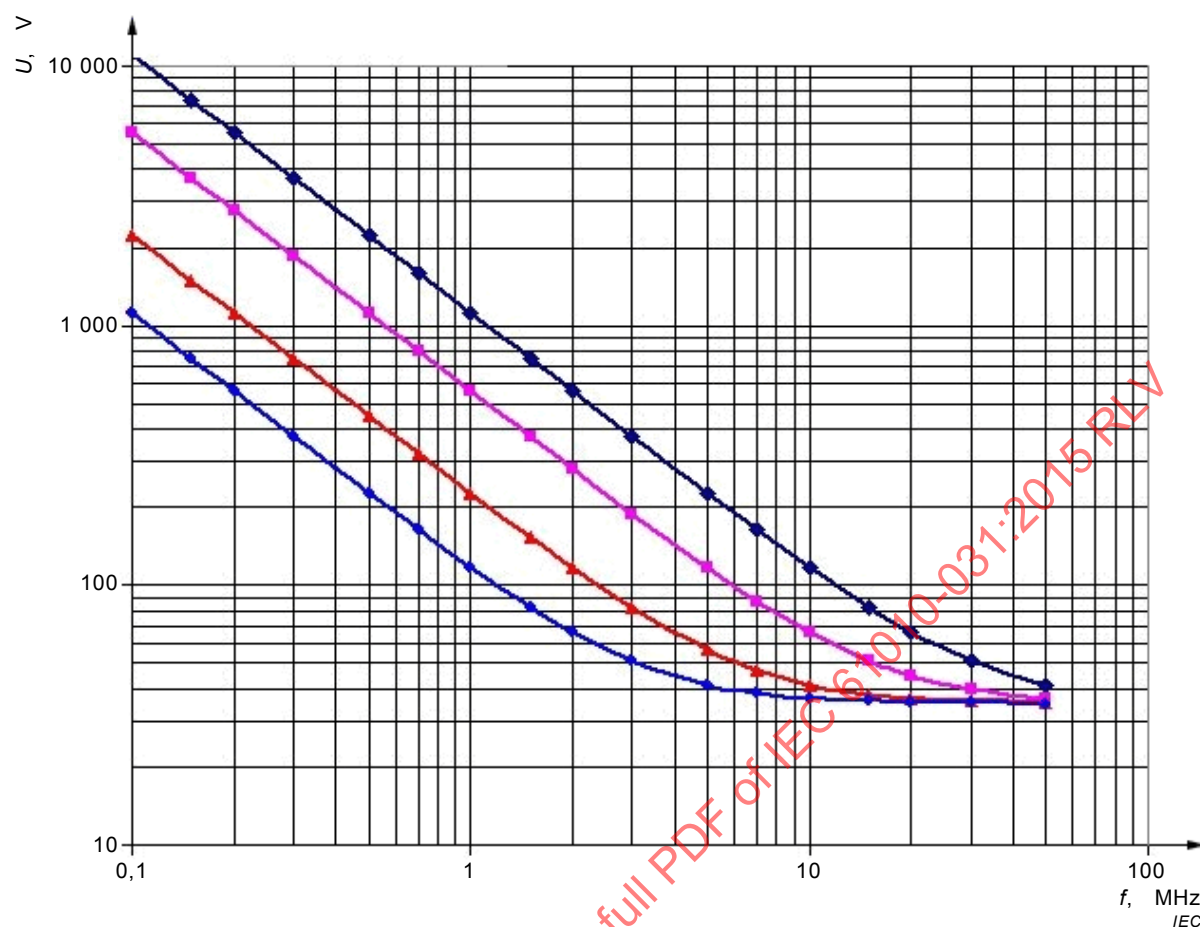
- a) between the shield and the foil around the probe body (2a), and
- b) between the shield and the foil around the coaxial CONNECTOR (2b), and
- c) between the shield and the foil around the PROBE WIRE (2c).

Alternative to the touch current measurement, the capacitance between the shield and the foil can be measured for the cases a) to c).

The capacitance C_s (measured capacitance between the shield and the foil) together with the circuit from A.3 creates the impedance shown in Figure A.4. The variable parameters of this impedance are the capacity C_s and the frequency (R_1 , C_1 and R_2 are fixed). With the means of these two parameters and with regard to electrical burns the maximum allowable voltage for the test probe can be calculated, for example for an allowable touch current of 70 mA (i.e. 35 V over R_2) as shown in Figure 11 for some values of the capacitance C_s .

The maximum voltage for each frequency can then be calculated.

NOTE In practice for the calculation with frequencies above 100 kHz, the values of R_1 and C_1 can be ignored.



Key

- ◆ 10 pF between probe (shield) and foil
- 20 pF between probe (shield) and foil
- ▲ 50 pF between probe (shield) and foil
- 100 pF between probe (shield) and foil

Figure 11 – Maximum test probe input voltage for 70 mA touch current

6.4 Insulation requirements for Means of protection against electric shock

6.4.1 General

CONNECTORS shall meet the requirements of 6.4.2.

PROBE TIPS shall meet the requirements of 6.4.3.

All other ACCESSIBLE parts of probe assemblies shall be prevented from becoming HAZARDOUS LIVE in both NORMAL CONDITION and SINGLE FAULT CONDITION by one or more of the following means:

- A) DOUBLE INSULATION ~~or REINFORCED INSULATION~~, consisting of BASIC INSULATION plus SUPPLEMENTARY INSULATION (see 6.4.6);
- B) BASIC INSULATION plus ENCLOSURES (see 6.7.3) or PROTECTIVE FINGERGUARDS;
- ~~C) ENCLOSURES or BARRIERS~~
- C) BASIC INSULATION plus impedance (see 6.4.4);
- D) REINFORCED INSULATION (see 6.4.6);
- E) PROTECTIVE IMPEDANCE (see 6.4.5).

~~CLEARANCES, CREEPAGE DISTANCES and insulation between ACCESSIBLE parts and HAZARDOUS LIVE parts shall meet the requirements of 6.5 and the applicable requirements of 6.4.1 to 6.4.4.~~

~~NOTE 1— CLEARANCES and CREEPAGE DISTANCES necessary for safety can be checked by measurement.~~

~~NOTE 2— Solid insulation necessary for safety can be checked by applying the test voltage of table 6 appropriate to the WORKING VOLTAGE. The thickness required for solid insulation can be determined from the test voltage it has to withstand. Partial discharge testing may also be appropriate (see IEC 60664-1 [4]).~~

~~NOTE 3— Under mechanical or thermal stress conditions, insulation may need to be increased to meet the requirements of clauses 7, 8 and 9.~~

~~Except for parts which are not intended to be hand-held or hand-manipulated by the OPERATOR during measurements or tests, insulation covers or sleeves which can be removed by the OPERATOR without the use of a TOOL are not considered to provide the required protection against electric shock (see note 4).~~

~~NOTE 4— For example, retractable insulation sleeves are not considered to provide adequate protection for hand-held parts. The only case in which they are acceptable is where they are needed for connection to equipment that is not provided with TERMINALS which accept fully insulated type connectors.~~

~~NOTE The PROBE WIRE is considered to be hand-held. Also see Clause 12 for requirements pertaining to the PROBE WIRE.~~

~~Conformity is checked by inspection and as specified in 6.4.2 to 6.4.6 and by the voltage tests of 6.6, as applicable.~~

6.4.2 CONNECTORS

Insulation, ACCESSIBLE parts, ~~CLEARANCES and CREEPAGE DISTANCES of~~ and SPACINGS for CONNECTORS ~~used on~~ of probe assemblies shall meet the applicable requirements of a) to c) below.

Annex E provides information regarding the recommended dimensions of 4 mm CONNECTORS.

a) CONNECTORS in fully-mated position.

- 1) ~~ACCESSIBLE parts of~~ CONNECTORS used only for connecting the probe assembly to the test or measurement equipment and which are not intended to be hand-held ~~after connection during the measurement operation shall be insulated from HAZARDOUS LIVE parts at least by BASIC INSULATION. This does not apply to connectors which can also be used to connect a probe and can become hand-held.~~
- 2) ~~ACCESSIBLE parts of~~ CONNECTORS which, ~~when fully mated,~~ are used for any other purpose or which are intended to be hand-held during the measurement ~~or test, and connectors which are interchangeable between the PROBE ASSEMBLY and the test or measurement equipment,~~ operation shall be insulated from HAZARDOUS LIVE parts by DOUBLE INSULATION or REINFORCED INSULATION.

~~Conformity is checked by inspection and measurement of CLEARANCES and CREEPAGE DISTANCES, by the voltage tests of 6.6, and by the determination of ACCESSIBLE parts as specified in 6.2 (see Figure 6 b)) and as specified in 6.4.6 for BASIC INSULATION and REINFORCED INSULATION.~~

b) Connectors in partially-mated position.

ACCESSIBLE parts of connectors in partially-mated condition shall be insulated from HAZARDOUS LIVE parts by BASIC INSULATION.

~~Conformity is checked by applying the voltage test of 6.6 for BASIC INSULATION, between the PROBE TIP and a test electrode of the same shape and size as the end of the standard test finger of figure B.1. This electrode is applied without force as near as possible to HAZARDOUS LIVE parts of the connector while it is mated just sufficiently to make electrical contact (see figure 3c)).~~

~~Conformity is checked by the determination of ACCESSIBLE parts as specified in 6.2 (see Figure 6 c)) and as specified in 6.4.6 for BASIC INSULATION.~~

c) Connectors in unmated position.

~~i) HAZARDOUS LIVE parts of unmated connectors shall not be ACCESSIBLE.~~

~~ii) The HAZARDOUS LIVE parts of an unmated integrated socket of a stackable connector shall be separated from ACCESSIBLE parts with CLEARANCE and CREEPAGE DISTANCES calculated for BASIC INSULATION.~~

~~The requirements of c) do not apply to locking or screw-held type connectors and to connectors of PROBE ASSEMBLIES where the ACCESSIBLE current is limited by PROTECTIVE IMPEDANCE, provided that all components used in the PROTECTIVE IMPEDANCE are HIGH INTEGRITY components.~~

~~Conformity is checked as follows:~~

~~i) ACCESSIBILITY for connectors carrying voltages up to 1 kV a.c. or 1,5 kV d.c. shall be determined as specified in 6.2, and for connectors carrying voltages above 1 kV a.c. or 1,5 kV d.c. by applying a test voltage between the PROBE TIP and an electrode of the same shape and size as the end of the standard test finger of figure B.1, placed as near as possible to ACCESSIBLE parts (see figure 3d)). The test voltage shall be 1,25 times the RATED voltage of the PROBE ASSEMBLY.~~

~~ii) By measurement of CLEARANCES and CREEPAGE DISTANCES, by the voltage tests of 6.6, and by the determination of ACCESSIBLE parts as specified in 6.2.~~

When the RATED voltages to earth are applied to other CONNECTORS or PROBE TIPS of the probe assembly,

- 1) conductive parts of locking-type or screw-held-type CONNECTORS including CONNECTORS which do not require the use of a TOOL for unlocking or unscrewing are permitted to be ACCESSIBLE while they are in unmated position
- 2) unmated integrated TERMINALS of STACKABLE CONNECTORS shall be protected by BASIC INSULATION,
- 3) conductive parts of other unmated CONNECTORS shall be prevented from becoming HAZARDOUS LIVE by PROTECTIVE IMPEDANCE (see 6.4.5) or shall have SPACINGS meeting the following requirements:
 - i) for unmated CONNECTORS with voltage RATING up to 1 000 V a.c. or 1 500 V d.c., the applicable SPACINGS of Table 2 from the closest approach of the test finger touching the external parts of the CONNECTOR in the least favorable position (see Figure 6 d), or
 - ii) for unmated CONNECTORS with voltage RATING exceeding 1 000 V a.c. or 1 500 V d.c., the SPACINGS shall not be less than 2.8 mm and shall withstand the voltage test of 6.6 with a test voltage equal to the RATED voltage of the CONNECTOR multiplied by 1,25.

Table 2 – SPACINGS for unmated CONNECTORS RATED up to 1 000 V a.c. or 1 500 V d.c. with HAZARDOUS LIVE conductive parts

Voltage on conductive parts of CONNECTOR	SPACING
V a.c. r.m.s. or V d.c.	mm
> 30 ≤ 300	0,8
> 300 ≤ 600	1,0
> 600 ≤ 1 000	2,6
> 1 000 ≤ 1 500 ^a	2,8
^a only for d.c. voltage	

Conformity is checked by inspection, by measuring the current or voltage to confirm that they do not exceed the applicable levels of 6.3, by the determination of ACCESSIBLE parts as specified in 6.2 (see Figure 6 c)) and measuring the applicable SPACINGS, and if applicable, the voltage test of 6.6.

Insulation covers or sleeves over CONNECTORS which are intended to be hand-held or hand-manipulated by the OPERATOR during measurement or test, and can be removed or displaced by the OPERATOR without the use of a TOOL, are not considered to provide the required protection against electric shock. For example, retractable insulation sleeves are not considered to provide adequate protection. The only case in which they are acceptable is where they are needed for connection to test or measurement equipment that is equipped with TERMINALS which cannot accept fully shrouded CONNECTORS.

Conformity is checked by inspection.

~~6.4.2 HAND-HELD PARTS OTHER THAN CONNECTORS~~

~~Parts of PROBE ASSEMBLIES that are hand-held or hand-manipulated by the OPERATOR during measurements or tests, shall be separated from parts which may become HAZARDOUS LIVE by DOUBLE insulation or REINFORCED INSULATION.~~

~~Conformity is checked by inspection and measurement of CLEARANCES and CREEPAGE DISTANCES, and by the voltage tests of 6.6 between each of a) and b) below on the one hand, and each of c), d), e) and f) below on the other hand.~~

- ~~a) Metal foil tightly wrapped around parts intended to be hand-held or hand-manipulated.~~
- ~~b) Metal foil tightly wrapped around a 150 mm ± 20 mm length of the cable (see figure 4).~~
- ~~c) The PROBE TIP. The test voltage is based on the RATED voltage of the PROBE ASSEMBLY.~~
- ~~d) (For type B only) the conductive parts enclosed by the hand-held area. The test voltage is based on the maximum WORKING VOLTAGE of the conductive parts in NORMAL USE, but is not less than 500 V.~~
- ~~e) (For type B only) the conductor of the REFERENCE CONNECTOR and the conductors of the connector for connecting the PROBE ASSEMBLY to the test or measurement equipment, joined together. The test voltage is based on the maximum RATED voltage of the PROBE ASSEMBLY divided by the divider ratio, but is not less than 500 V.~~
- ~~f) (For type C only) the conductor of the REFERENCE CONNECTOR if it is RATED above the voltage levels of 6.3.1.1. The test voltage is based on the maximum RATED voltage of the REFERENCE CONNECTOR.~~

~~NOTE The voltage tests of insulation which covers parts which are not HAZARDOUS LIVE (for example, the REFERENCE CONNECTOR) are to confirm the integrity of the insulation and not to impose additional requirements.~~

~~6.4.3 CABLES~~

~~Cables shall be RATED for the maximum voltage and current of NORMAL USE. Their conductors shall be separated from hand-held surfaces by DOUBLE INSULATION or REINFORCED INSULATION, based on the following values:~~

- ~~a) for type A PROBE ASSEMBLIES, 125 V or the maximum RATED voltage of the PROBE ASSEMBLY, whichever is greater;~~
- ~~b) for type B PROBE ASSEMBLIES, 500 V or the maximum RATED voltage of the PROBE ASSEMBLY divided by the divider ratio, whichever is greater;~~
- ~~c) for type C PROBE ASSEMBLIES, 125 V or the maximum RATED voltage of the PROBE ASSEMBLY divided by the divider ratio, whichever is greater.~~

~~Conformity is checked by inspection and measurement of CLEARANCES and CREEPAGE DISTANCES, and by the voltage tests of 6.6 (without humidity preconditioning), using metal foil tightly wrapped around a 150 mm ± 20 mm length of cable.~~

6.4.3 Probe tips

6.4.3.1 General

~~If, as permitted by 6.1.1, a PROBE TIP can become HAZARDOUS LIVE, a BARRIER shall be fitted to reduce the danger of touching the PROBE TIP, and to provide an indication of the limit beyond which it may be hazardous to touch the probe body during use.~~

~~CLEARANCE and CREEPAGE DISTANCE between the PROBE TIP and the hand-held side of the BARRIER shall be those specified for DOUBLE INSULATION or REINFORCED INSULATION. Figure 6a) gives examples of probe assemblies with BARRIERS and indicates applicable CLEARANCES and CREEPAGE DISTANCES.~~

PROBE TIPS that can become HAZARDOUS LIVE during NORMAL USE (see also 6.1 b)) shall meet the requirements of one of 6.4.3.2, 6.4.3.3, or 6.4.3.4 .

PROBE TIPS that can be used as CONNECTORS shall also meet the requirements of 6.4.3.5.

NOTE See Clause 13 for additional requirements for the exposed conductive parts of PROBE TIPS.

SPRING-LOADED CLIPS and similar probes that are intended to pierce the insulation of a wire to touch the conductor for measuring voltage purposes shall not have a voltage RATING above the levels of 6.3.2 a).

Conformity is checked by inspection and measurement.

6.4.3.2 Protection by a PROTECTIVE FINGERGUARD

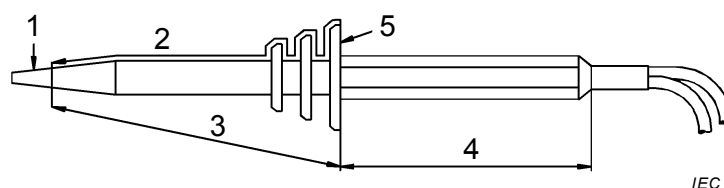
If a conductive part of a PROBE TIP can become HAZARDOUS LIVE, a PROTECTIVE FINGERGUARD shall be fitted to reduce the risk of touching an exposed conductive part of the PROBE TIP, and to provide an indication of the limit beyond which it may be hazardous to touch the probe body during use.

SPACINGS between the HAZARDOUS LIVE part of the PROBE TIP and the hand-held side of the PROTECTIVE FINGERGUARD shall be those specified for REINFORCED INSULATION.

The height of the PROTECTIVE FINGERGUARD from the side where the fingers are intended to be applied shall be at least 2 mm and the thickness shall be less than twice the height.

The PROTECTIVE FINGERGUARD of probe assemblies which have a voltage RATING above the levels of 6.3.2 a) shall extend across at least 80 % of the sides where the fingers are intended to be applied.

Figure 12 gives an example of a probe assembly with a PROTECTIVE FINGERGUARD and indicates applicable SPACINGS.

**Key**

- 1 PROBE TIP
- 2 CREEPAGE DISTANCE (along surface)
- 3 CLEARANCE (in air)
- 4 hand-held area of probe body
- 5 PROTECTIVE FINGERGUARD

Figure 12 – Protection by a PROTECTIVE FINGERGUARD

6.4.3.3 Protection by distance

~~SPRING-LOADED squeeze probes (see figure 6b)) are acceptable without a BARRIER CLIPS RATED for voltages to earth up to 1 kV are acceptable without a PROTECTIVE FINGERGUARD provided that~~

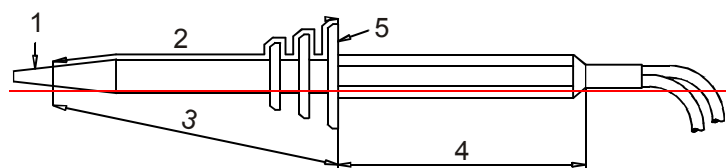
- a) actuation of the spring-loaded mechanism prevents the OPERATOR from touching a HAZARDOUS LIVE part; and
- b) ~~CLEARANCE and CREEPAGE DISTANCE~~ the SPACINGS between the PROBE TIP and the nearest surface which the OPERATOR needs to touch to actuate the mechanism ~~shall be~~ are increased by an additional protective distance of 45 mm.

~~Insulated crocodile and similar clips (see figure 6c)) which require finger pressure at about 90° to the axis of the clip are acceptable without a BARRIER, provided that there is a tactile indicator to indicate the limit of safe access for the OPERATOR. CLEARANCE and CREEPAGE DISTANCE between the BARRIER or tactile indicator and the tip of the clip shall be those specified for DOUBLE INSULATION or REINFORCED INSULATION.~~

~~The exposed conductive part of the PROBE TIP, except for parts of a crocodile clip where the outer jaws are insulated shall not be more than 19 mm long (see figure 6c) ii)).~~

~~NOTE A shorter length is recommended.~~

~~Conformity is checked by inspection and measurement.~~

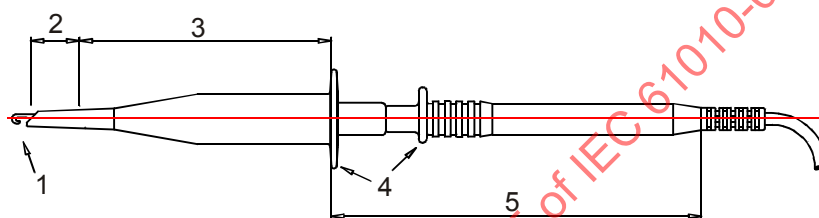


IEC 2605/01

Key

- 1— PROBE TIP
- 2— CREEPAGE-DISTANCE (along surface)
- 3— CLEARANCE (in air)
- 4— Hand-held-area of probe-body
- 5— BARRIER

Figure 6a – Protection by BARRIER

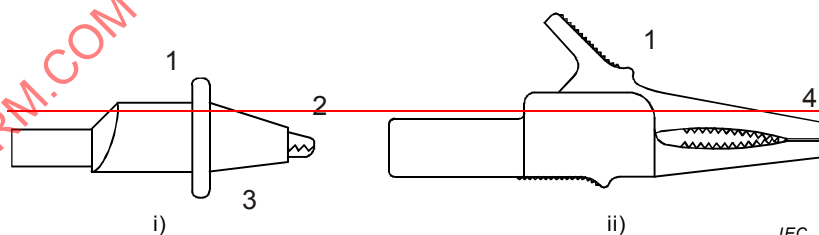


IEC 2606/01

Key

- 1— PROBE TIP
- 2— CLEARANCE and CREEPAGE-DISTANCE as specified in 6.5
- 3— Additional protective distance
- 4— Actuating parts
- 5— Hand-held area of spring-loaded squeeze PROBE-ASSEMBLY

Figure 6b – Protection by distance



IEC 2607/01

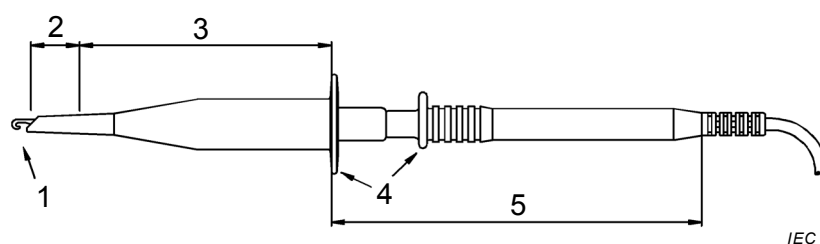
Key

- 1— Indication of limit of access (around or on both sides of clip)
- 2— Metal jaws
- 3— Insulation
- 4— Insulated metal jaws

Figure 6c – Examples of crocodile clips

Figure 6 – Protection against touching a PROBE TIP (see 6.4.4)

Figure 13 gives an example of a probe assembly protected by distance and indicates applicable SPACINGS.



Key

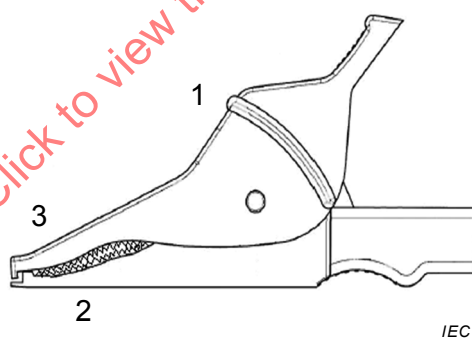
- 1 PROBE TIP
- 2 CLEARANCE and CREEPAGE DISTANCE as specified in 6.5
- 3 additional protective distance
- 4 actuating parts
- 5 hand-held area of the probe assembly

Figure 13 – Protection by distance

6.4.3.4 Protection by tactile indicator

SPRING-LOADED CLIPS RATED for MEASUREMENT CATEGORY II which require finger pressure at about 90° to the axis of the clip are acceptable without a PROTECTIVE FINGERGARD, provided that there is a tactile indicator to indicate the limit of safe access for the OPERATOR.

Figure 14 gives an example of a SPRING-LOADED CLIP with a tactile indicator.



Key

- 1 tactile indicator
- 2 metal jaws
- 3 insulated metal jaws

Figure 14 – Protection by tactile indicator

6.4.3.5 PROBE TIPS used as CONNECTORS

PROBE TIPS which can be used as CONNECTORS (for example, a PROBE TIP that is also intended to be connected to a SPRING-LOADED CLIP) shall also meet the requirements for CONNECTORS in fully-mated position and partially-mated position (see also 6.4.2 a) and b)).

6.4.4 Impedance

Impedance used as an additional means of protection in conjunction with BASIC INSULATION shall meet all the following requirements:

- a) it shall limit the current or voltage to not more than the applicable levels of 6.3.3;
- b) it shall be RATED for the WORKING VOLTAGE and for the amount of power that it will dissipate;
- c) SPACINGS between terminations of the impedance shall meet the applicable requirements of 6.5 for BASIC INSULATION.

Conformity is checked by inspection, by measuring the voltage or current to confirm that they do not exceed the levels of 6.3.3, and by measuring CLEARANCE and CREEPAGE DISTANCE as specified in 6.5.

~~6.4.5 Double insulation AND reinforced insulation~~

~~CLEARANCES and CREEPAGE DISTANCES forming part of DOUBLE INSULATION or REINFORCED INSULATION shall meet the applicable requirements of 6.5. ENCLOSURES shall meet the requirements of 6.7.2.~~

~~Solid insulation forming part of REINFORCED INSULATION shall pass the voltage test of 6.6 with the values for REINFORCED INSULATION.~~

~~Conformity is checked as specified in 6.5, 6.6 and 6.7.2. The parts of DOUBLE INSULATION are tested separately if this is possible; otherwise the tests for REINFORCED INSULATION are used. CLEARANCES and CREEPAGE DISTANCES necessary for safety can be checked by measurement.~~

6.4.5 PROTECTIVE IMPEDANCE

~~A PROTECTIVE IMPEDANCE which ensures that ACCESSIBLE conductive parts cannot become HAZARDOUS LIVE as a result of a SINGLE FAULT CONDITION shall be an appropriate HIGH-INTEGRITY single component (see 12.3).~~

~~Components, wires and connections shall be RATED for both NORMAL CONDITION and SINGLE FAULT CONDITION.~~

~~Conformity is checked by inspection and by the measurements of 6.3 in SINGLE FAULT CONDITION (see 4.4.2.1).~~

A PROTECTIVE IMPEDANCE shall limit the current or voltage to the levels of 6.3.2 in NORMAL CONDITION and 6.3.3 in SINGLE FAULT CONDITION (see also 4.4.2.2).

Insulation between the terminations of the PROTECTIVE IMPEDANCE shall meet the requirements of 6.4.6 for DOUBLE INSULATION or REINFORCED INSULATION.

A PROTECTIVE IMPEDANCE shall be one or more of the following:

- a) an appropriate single component which shall be constructed, selected and tested so that safety and reliability for protection against electric shock is assured. In particular, the component shall be:
 - 1) RATED for twice the WORKING VOLTAGE;
 - 2) if a resistor, RATED for twice the power dissipation for the WORKING VOLTAGE;
 - 3) if a capacitor, RATED for the maximum transient overvoltage;
- b) a combination of components.

When a combination of components is used, the SPACINGS shall take into account the WORKING VOLTAGE across each insulation.

A PROTECTIVE IMPEDANCE shall not be a single electronic device that employs electron conduction in a vacuum, gas or semiconductor.

Conformity is checked by inspection, by measuring the current or voltage to confirm that they do not exceed the applicable levels of 6.3 and by measuring SPACINGS as specified in 6.5. Conformity of a single component is checked by inspection of its RATING.

6.4.6 BASIC INSULATION, SUPPLEMENTARY INSULATION, DOUBLE INSULATION and REINFORCED INSULATION

SPACINGS and solid insulation forming BASIC INSULATION, SUPPLEMENTARY INSULATION or REINFORCED INSULATION between ACCESSIBLE parts and HAZARDOUS LIVE parts shall meet the applicable requirements of 6.5.

DOUBLE INSULATION is comprised of BASIC INSULATION and SUPPLEMENTARY INSULATION, each of which shall meet the applicable requirements of 6.5.

Conformity is checked as specified in 6.5.

~~6.5 CLEARANCES and CREEPAGE DISTANCES~~

~~CLEARANCES and CREEPAGE DISTANCES are specified in 6.5.1 to 6.5.4 so as to withstand the voltages that appear on the system for which the PROBE ASSEMBLY is intended. They also take account of RATED environmental conditions and of any protective devices fitted within the PROBE ASSEMBLY or required by the manufacturer's instructions.~~

~~There are no CLEARANCE or CREEPAGE DISTANCE requirements for the interior of void-free moulded parts, including the inner layers of multi-layer printed circuit boards.~~

~~Conformity is checked by inspection and measurement. When determining a CLEARANCE or CREEPAGE DISTANCE to ACCESSIBLE parts, the ACCESSIBLE surface of an insulating ENCLOSURE is considered to be conductive as if it was covered by metal foil wherever it can be touched with a standard test finger (see annex B). Conformity for homogeneous construction is checked as specified in 6.5.1.1.~~

6.5 Insulation requirements

6.5.1 The nature of insulation

6.5.1.1 General

Insulation between circuits and ACCESSIBLE parts (see 6.2) or between separate circuits consists of SPACINGS, solid insulation, or a combination of SPACINGS and solid insulation. SPACINGS comprise both CLEARANCES and CREEPAGE DISTANCES.

When used to provide protection against a HAZARD, the insulation needs to withstand the electric stresses that are caused by the voltages that may appear on parts of the probe assembly.

The requirements for insulation depend on:

- a) the required level of insulation (BASIC INSULATION, SUPPLEMENTARY INSULATION, or REINFORCED INSULATION);
- b) the maximum transient overvoltage that may appear on the circuit, either as a result of an external event (such as a lightning strike or a switching transient), or as the result of the operation of the probe assembly;
- c) the WORKING VOLTAGE;
- d) the POLLUTION DEGREE of the micro-environment.

6.5.1.2 SPACINGS

6.5.1.2.1 General requirements

SPACINGS are a combination of CLEARANCES and CREEPAGE DISTANCES, which are specified in 6.5.1.2.2 and 6.5.1.2.3 so as to withstand the voltages that appear on the system for which the probe assembly is intended. Also, they are selected to take account of the intended environmental conditions and any protective devices fitted within the probe assembly or required by the manufacturer's instructions.

6.5.1.2.2 CLEARANCES

CLEARANCES are specified to withstand the maximum transient overvoltage that can be present on the circuit to which the probe assembly can be connected in NORMAL USE, ~~either as a result of an external event (such as a lightning strike, or a switching transient), or as the result of the operation of the equipment to which the probe assembly is connected.~~ If transient overvoltages cannot occur, CLEARANCES are based on the ~~maximum~~ WORKING VOLTAGE.

~~The value for clearance depends on~~

- ~~— the type of insulation required (BASIC INSULATION, REINFORCED INSULATION, etc.);~~
- ~~— the POLLUTION degree of the micro-environment of the CLEARANCE.~~

The values for CLEARANCES given in Table 6 and Table 7 are based on absolute inhomogeneous field conditions. Reduced CLEARANCES may apply to ~~homogeneous~~ constructions which are shaped in a way to create a more homogeneous condition, because the dielectric strength of an air gap is dependent on the shape of the electric field within the gap, as well as on the width of the gap. ~~In homogeneous construction, conductive parts are shaped and arranged so that homogeneous or near homogeneous electric field conditions exist between them. As a result, reduced CLEARANCES can be accepted between such conductive parts.~~

No particular value can be specified for a reduced CLEARANCE for ~~these more~~ homogeneous constructions, but it can be tested by a ~~dielectric strength~~ voltage test (see 6.6). ~~The test is a d.c. or a.c. peak test, using the voltage specified in table 6 for the peak impulse test for the CLEARANCE which would apply for inhomogeneous construction. For test site altitude corrections, see table 7.~~ CLEARANCES which meet the values of Table 6 and Table 7 will meet the requirements for any construction and need not be tested by a voltage test, but can be checked by measurement alone.

If the ~~equipment~~ probe assembly is RATED to operate at an altitude greater than 2 000 m, the values for CLEARANCES are multiplied by the applicable factor ~~derived from~~ Table 3. ~~The factors are not applied to CREEPAGE DISTANCE, but CREEPAGE DISTANCE shall always be at least as large as the value specified for CLEARANCE.~~

Table 2 3 – Multiplication factors for CLEARANCES of probe assembly RATED for operation at altitudes up to 5 000 m

RATED operating altitude m	Multiplication factor
Up to 2 000	1,00
2 001 to 3 000	1,14
3 001 to 4 000	1,29
4 001 to 5 000	1,48

In all cases, the minimum CLEARANCE value for POLLUTION DEGREE 2 is 0,2 mm and for POLLUTION DEGREE 3 is 0,8 mm.

See Annex C for details of how to measure CLEARANCES.

Conformity is checked by inspection, measurement, and in the case of more homogeneous construction by the voltage test of 6.6.

6.5.1.2.3 CREEPAGE DISTANCES-values

~~For CREEPAGE DISTANCES between two circuits, the actual WORKING VOLTAGE which stresses the insulation between the circuits shall be used (see table 5). CREEPAGE DISTANCES shall be based on the actual WORKING VOLTAGE which stresses the insulation (see Table 9). Linear interpolation of CREEPAGE DISTANCE is permissible. CREEPAGE DISTANCE shall always be at least as large as the value specified for CLEARANCE. If the calculated CREEPAGE DISTANCE is smaller than the CLEARANCE, the CREEPAGE DISTANCE shall be increased to the value of the CLEARANCE.~~

~~For coated printed wiring boards whose coatings meet the requirements for type A coatings given in IEC 60664-3, the values for POLLUTION DEGREE 1 apply. Coatings that meet the requirements of Annex H of IEC 61010-1:2010 when applied to the outer surfaces of printed wiring boards reduce the POLLUTION DEGREE of the coated area to POLLUTION DEGREE 1.~~

For REINFORCED INSULATION, the value of the CREEPAGE DISTANCE ~~shall be~~ is twice the value specified for BASIC INSULATION.

CREEPAGE DISTANCES ~~are~~ protect against tracking on the surface of an insulation, which is a long-term phenomenon. Therefore, they cannot be confirmed by voltage testing, but have to be measured as specified in Annex C.

Conformity is checked by inspection and measurement.

6.5.1.2.4 SOLID INSULATION

6.5.1.2.4.1 General

Solid insulation shall withstand the electric and mechanical stresses that may occur in NORMAL USE, in all RATED environmental conditions (see 1.4).

The manufacturer should take the expected life of the probe assembly into account when selecting insulating materials.

Conformity is checked by inspection, and by the a.c. voltage test of 6.6.5.1, or for probe assemblies stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4:

Table 4 – Test voltages for testing solid insulation

Nominal a.c. r.m.s. or d.c. RATED voltage to earth V	Test voltage			
	1 min a.c. test V r.m.s.		1 min d.c. test V d.c.	
	BASIC INSULATION and SUPPLEMENTARY INSULATION	REINFORCED INSULATION	BASIC INSULATION and SUPPLEMENTARY INSULATION	REINFORCED INSULATION
≤ 150	1 350	2 700	1 900	3 800
> 150 ≤ 300	1 500	3 000	2 100	4 200
> 300 ≤ 600	1 800	3 600	2 550	5 100
> 600 ≤ 1000	2 200	4 400	3 100	6 200
> 1 000 ≤ 63 000	1,5 times the RATED voltage to earth or 2 200 V, whichever is larger	Twice the RATED voltage to earth or 4 400 V, whichever is larger	1,5 times the RATED voltage to earth or 3 100 V, whichever is larger	Twice the RATED voltage to earth or 6 200 V, whichever is larger

Solid insulation shall also meet the following requirements, as applicable:

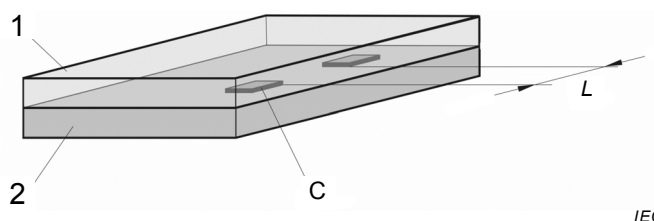
- for solid insulation used as an ENCLOSURE or PROTECTIVE FINGERGUARD, the requirements of Clause 8;
- for moulded and potted parts, the requirements of 6.5.1.2.4.2;
- for inner layers of printed wiring boards, the requirements of 6.5.1.2.4.3;
- for thin-film insulation, the requirements of 6.5.1.2.4.4.

Conformity is checked as specified in 6.5.1.2.4.2 to 6.5.1.2.4.4, and in Clause 8, as applicable.

6.5.1.2.4.2 Moulded and potted parts

For BASIC INSULATION, SUPPLEMENTARY INSULATION, and REINFORCED INSULATION, conductors located on an interface between the same two layers moulded together (see Figure 15, item L) shall be separated by at least the applicable minimum distance of Table 5 after the moulding is completed.

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.



Key

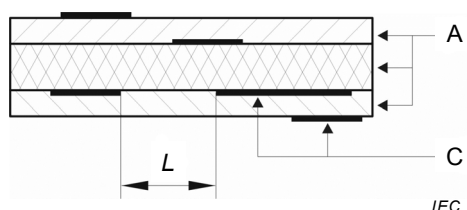
- 1 Layer 1
- 2 Layer 2
- C Conductor
- L Distance between conductors

Figure 15 – Distance between conductors on an interface between two layers

6.5.1.2.4.3 Insulating layers of printed wiring boards

For BASIC INSULATION, SUPPLEMENTARY INSULATION and REINFORCED INSULATION, conductors located between the same two layers (see Figure 16, item L) shall be separated by at least the applicable minimum distance of Table 5.

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.



Key

- L Distance between conductors on the same surface
 A Layers
 C Conductors

Figure 16 – Distance between adjacent conductors along an interface of two layers

Table 5 – Minimum values for distance or thickness

WORKING VOLTAGE V	Minimum thickness mm	Minimum distance L (see Figure 16) ^a mm
≤ 300	0,4	0,4
> 300 ≤ 600	0,6	0,6
> 600 ≤ 1 000 ^b	1,0	1,0
^a These values apply for BASIC INSULATION, SUPPLEMENTARY INSULATION and REINFORCED INSULATION.		
^b For voltage above 1 000 V, a partial discharge test should be used (test procedure under consideration)		

REINFORCED INSULATION of insulating layers of printed wiring boards (see Figure 16, item A) shall also have adequate electric strength through the respective layers. One of the following methods shall be used.

- a) The thickness of the insulation is at least the value of Table 5;

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.

- b) The insulation is assembled from at least two separate layers of printed wiring board materials, each of which is RATED by the manufacturer of the material for an electric strength of at least the value of the test voltage of the Table 4 for BASIC INSULATION.

Conformity is checked by inspection of the manufacturer's specifications.

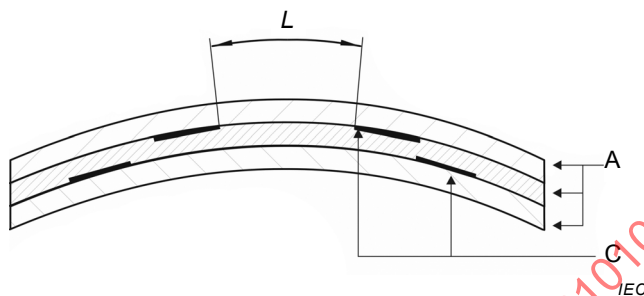
- c) The insulation is assembled from at least two separate layers of printed wiring board materials, and the combination of layers is RATED by the manufacturer of the material for an electric strength of at least the value of the test voltage of the Table 4 for REINFORCED INSULATION.

Conformity is checked by inspection of the manufacturer's specifications.

6.5.1.2.4.4 Thin-film insulation

For BASIC INSULATION, SUPPLEMENTARY INSULATION, and REINFORCED INSULATION, conductors located between the same two layers (see Figure 17, item L).shall be separated by at least the applicable SPACINGS.

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.



Key

L distance between adjacent conductors

A layers of thin-film material such as tape and polyester film

C conductors

NOTE There might be air present between the layers.

Figure 17 – Distance between adjacent conductors located between the same two layers

REINFORCED INSULATION through the layers of thin-film insulation shall also have adequate electric strength. One of the following methods shall be used.

- The thickness through the insulation is at least the value of Table 5.

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.

- The insulation consists of at least two separate layers of thin-film materials, each of which is RATED by the manufacturer of the material for an electric strength of at least the value of the test voltage of the Table 4 for BASIC INSULATION.

Conformity is checked by inspection of the manufacturer's specifications.

- The insulation consists of at least three separate layers of thin-film materials, any two of which have been tested to exhibit adequate electric strength.

Conformity is checked by the a.c. voltage test of 6.6.5.1, or for probe assemblies stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min applied to two of the three layers using the applicable test voltage of Table 4 for REINFORCED INSULATION.

NOTE For the purposes of this test, a special sample can be assembled with only two layers of the material.

6.5.2 Measuring circuits Insulation requirements for probe assemblies

6.5.2.1 GENERAL

Measuring circuits are subjected to WORKING VOLTAGES and transient stresses from the circuit to which they are connected during measurement or test. When the measuring circuit is used to measure mains supplies or circuits directly connected to them, the transient stresses can be estimated by the location within the installation at which the measurement is performed. When the measuring circuit is used to measure any other electrical signal, the transient

stresses ~~must~~ should be considered by the ~~user to check~~ OPERATOR to ensure that they do not exceed the capabilities of the ~~measuring equipment probe assembly~~. In this standard, ~~PROBE ASSEMBLY~~ circuits are divided into the following measurement categories.

~~Measurement category IV is for measurements performed at the source of the low voltage installation.~~

NOTE 1 ~~Examples are electricity meters and measurements on primary overcurrent protection devices and ripple control units.~~

~~Measurement category III is for measurements performed in the building installation.~~

NOTE 2 ~~Examples are measurements on distribution boards, circuit-breakers, wiring, including cables, bus-bars, junction boxes, switches, socket outlets in the fixed installation, and equipment for industrial use and some other equipment, for example, stationary motors with permanent connection to the fixed installation.~~

~~Measurement category II is for measurements performed on circuits directly connected to the low voltage installation.~~

NOTE 3 ~~Examples are measurements on household appliances, portable tools and similar equipment.~~

~~Measurement category I is for measurements performed on circuits not directly connected to a mains supply.~~

NOTE 4 ~~Examples are measurements on circuits not derived from a mains supply and specially protected (internal) circuits derived from a mains supply. In the latter case, transient stresses are variable; for that reason 5.4.3 g) requires that the transient withstand capability of the equipment is made known to the user.~~

6.5.2.2 CLEARANCES ~~VALUES~~ for probe assemblies of MEASUREMENT CATEGORIES II, III and IV

CLEARANCES for ~~probe assemblies of~~ MEASUREMENT CATEGORIES II, III and IV are specified in Table 6.

Table 3 6 – CLEARANCES for ~~probe assemblies of~~ MEASUREMENT CATEGORIES II, III and IV

Highest Nominal a.c. ~~or d.c.~~ r.m.s. line-to-neutral ~~or~~ d.c. voltage of mains ~~supply~~ to which the probe assembly is designed to be connected V	CLEARANCE mm					
	BASIC INSULATION ~~or and~~ SUPPLEMENTARY INSULATION			DOUBLE ~~or~~ REINFORCED INSULATION		
	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV
≤ 50	0,04	0,1	0,5	0,1	0,3	1,5
> 50 ≤ 100	0,1	0,5	1,5	0,3	1,5	3,0
> 100 ≤ 150	0,5	1,5	3,0	1,5	3,0	6,0
> 150 ≤ 300	1,5	3,0	5,5	3,0	5,9	10,5
> 300 ≤ 600	3,0	5,5	8	5,9	10,5	14,3
> 600 ≤ 1 000	5,5	8	14	10,5	14,3	24,3
> 1 000 ≤ 1 500 ^a	8	11	18	14,3	19,4	31,4

^a only for d.c. voltage

Conformity is checked by inspection and measurement or by the a.c. voltage test of 6.6.5.1 with a duration of at least 5 s or the impulse voltage test of 6.6.5.3, or for probe assemblies stressed only by d.c., the 1 min d.c. voltage test of 6.6.5.2 or the impulse voltage test of 6.6.5.3, using the test voltage of Table 10 for the required clearance.

6.5.2.3 CLEARANCES ~~VALUES for probe assemblies which are not RATED for MEASUREMENT CATEGORIES I, II, III, or IV~~

6.5.2.3.1 General

CLEARANCES for probe assemblies which are not RATED for MEASUREMENT CATEGORIES II, III, or IV are calculated according to 6.5.2.3.2.

If they have either of the following characteristics, CLEARANCES are also determined according to 6.5.2.3.3, and the larger of the two CLEARANCE values is the required clearance:

- a) the WORKING VOLTAGE includes a recurring peak voltage that may include a periodic non-sinusoidal waveform or a non-periodic waveform that occurs with some regularity;
- b) the WORKING VOLTAGE has a frequency above 30 kHz.

6.5.2.3.2 CLEARANCE calculation

CLEARANCES for BASIC INSULATION and SUPPLEMENTARY INSULATION are determined from the following formula:

$$\text{CLEARANCE} = D_1 + F \times (D_2 - D_1)$$

where

F is a factor, determined from one of the equations:

$$F = (1,25 \times U_w/U_m) - 0,25 \quad \text{if } 0,2 < U_w/U_m \leq 1 \quad U_w/U_m > 0,2$$

$$F = 0 \quad \text{if } U_w/U_m \leq 0,2$$

where

$$U_m = U_w + U_t;$$

U_w = the maximum peak value of the WORKING VOLTAGE;

U_t = the maximum additional transient overvoltage

D_1 and D_2 are values taken from Table 7 for U_m .

where

D_1 represents the CLEARANCE that would be applicable to ~~the maximum voltage U_m if it consisted only~~ a transient overvoltage with the shape of a $1,2 \times 50 \mu\text{s}$ impulse

D_2 represents the CLEARANCE that would be applicable to ~~the maximum voltage U_m if it consisted only~~ of the peak WORKING VOLTAGE without any transient overvoltage

~~The maximum voltage (U_m) is the maximum peak WORKING VOLTAGE U_w plus the maximum transient overvoltage U_t ;~~

CLEARANCES for REINFORCED INSULATION are ~~calculated using the same formula, but values of D_1 and D_2 are those specified in table 4 for a voltage 1,6 times the actual WORKING VOLTAGE twice the values for BASIC INSULATION.~~

Conformity is checked by inspection and measurement or by the a.c. voltage test of 6.6.5.1 with a duration of at least 5 s, or the impulse voltage test of 6.6.5.3, using the applicable voltage from Table 10 for the required CLEARANCE.

Table 4 7 – CLEARANCE values for the calculation of 6.5.2.3.2

$\hat{U}_m$ Maximum voltage U_m	CLEARANCE		$\hat{U}_m$ Maximum voltage U_m	CLEARANCE	
	D_1	D_2		D_1	D_2
V	mm	mm	V	mm	mm
14,1 to 266	0,010	0,010	4 000	2,93	6,05
283	0,010	0,013	4 530	3,53	7,29
330	0,010	0,020	5 660	4,92	10,1
354	0,013	0,025	6 000	5,37	10,8
453	0,027	0,052	7 070	6,86	13,1
500	0,036	0,071	8 000	8,25	15,2
566	0,052	0,10	8 910	9,69	17,2
707	0,081	0,20	11 300	12,9	22,8
800	0,099	0,29	14 100	16,7	29,5
891	0,12	0,41	17 700	21,8	38,5
1 130	0,19	0,83	22 600	29,0	51,2
1 410	0,38	1,27	28 300	37,8	66,7
1 500	0,45	1,40	35 400	49,1	86,7
1 770	0,75	1,79	45 300	65,5	116
2 260	1,25	2,58	56 600	85,0	150
2 500	1,45	3,00	70 700	110	195
2 830	1,74	3,61	89 100	145	255
3 540	2,44	5,04	100 000	165	290

NOTE 1 Linear Interpolation of CLEARANCES is allowed.

NOTE 2 Minimum CLEARANCE for POLLUTION degree 2 is 0,2 mm, for POLLUTION degree 3 is 0,8 mm.

NOTE The following is an example calculation:

CLEARANCE for REINFORCED INSULATION for a ~~peak~~ WORKING VOLTAGE with peak value of 3 500 V and ~~a maximum~~ an additional transient overvoltage of 4 500 V (this can be expected within an electronic switching-circuit):

Maximum voltage $U_M = U_W + U_t = (3\,500 + 4\,500) \text{ V} = 8\,000 \text{ V}$

$$U_W / U_M = 3\,500 / 8\,000 = 0,44 > 0,2$$

$$\text{thus } F = (1,25 \times U_W / U_M) - 0,25 = (1,25 \times 3\,500 / 8\,000) - 0,25 = 0,347 \text{ } 0,297$$

Values derived from Table 7 at 8 000 V:

$D_1 = 16,7 \text{ mm}$; $D_2 = 29,5 \text{ mm}$ (values for $8\,000 \times 1,6 = 12\,800 \text{ V}$) $8,25 \text{ mm}$, $D_2 = 15,2 \text{ mm}$

$$\text{CLEARANCE} = D_1 + F(D_2 - D_1) = 16,7 + 0,347(29,5 - 16,7) = 17,7 + 4,4 = 21,1 \text{ mm}$$

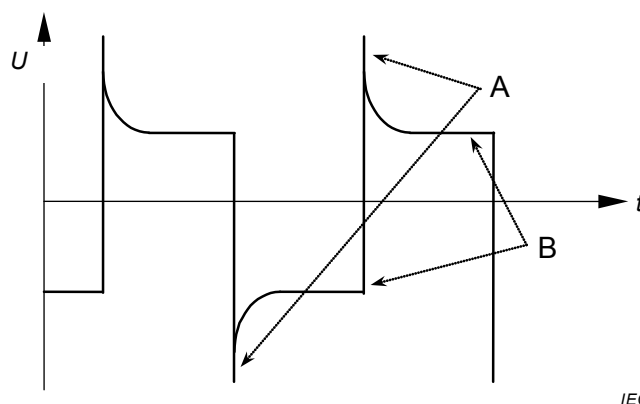
$$8,25 + 0,297 \times (15,2 - 8,25) = 8,25 + 2,06 = 10,3 \text{ mm}$$

For REINFORCED INSULATION the value is doubled. CLEARANCE = 20,6 mm.

6.5.2.3.3 CLEARANCES for probe assemblies subjected to recurring peak voltages, or WORKING VOLTAGES with frequencies above 30 kHz, or both

CLEARANCES for BASIC INSULATION and SUPPLEMENTARY INSULATION for probe assemblies subjected to recurring peak voltages with frequencies not exceeding 30 kHz shall meet the values of the second column of Table 8, using the recurring peak voltage as the index (see Figure 18 for an example of a recurring peak voltage).

NOTE In most practical recurring waveforms, the fundamental frequency has a substantially higher amplitude than the harmonics. Therefore, the fundamental frequency is to be used for determining whether the frequency of the waveform exceeds 30 kHz. However, the peak amplitude of the waveform, and not the peak amplitude of the fundamental component of the waveform, is to be used for determining SPACINGS. For more information, see E.2 of IEC 60664-4:2005.



Key

A peak value of recurring voltage

B WORKING VOLTAGE value

Figure 18 – Example of recurring peak voltage

CLEARANCES for BASIC INSULATION and SUPPLEMENTARY INSULATION for probe assemblies that are subjected to WORKING VOLTAGES with frequencies above 30 kHz shall meet the values of the third column of Table 8, using the peak value of the WORKING VOLTAGE as the index.

CLEARANCES for BASIC INSULATION and SUPPLEMENTARY INSULATION for probe assemblies that may be subjected to both recurring peak voltages and WORKING VOLTAGES with frequencies above 30 kHz shall meet the higher of these requirements.

CLEARANCES for REINFORCED INSULATION are twice the values for BASIC INSULATION.

Conformity is checked by inspection and measurement.

Table 8 – CLEARANCES for BASIC INSULATION in probe assemblies subjected to recurring peak voltages or WORKING VOLTAGES with frequencies above 30 kHz

Voltage peak value	CLEARANCE	
	Frequencies up to 30 kHz	Frequencies above 30 kHz
V	mm	mm
0 to 330	0,01	0,02
400	0,02	0,04
500	0,04	0,07
600	0,06	0,11
800	0,13	0,26
1 000	0,26	0,48
1 200	0,42	0,76
1 500	0,76	1,1
2 000	1,27	1,8
2 500	1,8	2,6
3 000	2,4	3,5
4 000	3,8	5,7
5 000	5,7	8
6 000	7,9	10
8 000	11	15
10 000	15,2	20
12 000	19	25
15 000	25	32
20 000	34	44
25 000	44	58
30 000	55	72
40 000	77	100
50 000*	100	
Linear interpolation is allowed.		

6.5.3 6.5.2.4 Creepage distances ~~VALUES~~

Table 5 gives ~~CREEPAGE DISTANCE values based on the WORKING VOLTAGE.~~

CREEPAGE DISTANCES for BASIC INSULATION or SUPPLEMENTARY INSULATION for probe assemblies shall meet the applicable values of Table 9, based on the WORKING VOLTAGE which stresses the insulation. Values for REINFORCED INSULATION are twice the values for BASIC INSULATION.

Conformity is checked by inspection and measurement.

Table 5 9 – CREEPAGE DISTANCES for BASIC INSULATION or SUPPLEMENTARY INSULATION

WORKING VOLTAGE a.c. r.m.s. or d.c.	BASIC INSULATION or SUPPLEMENTARY INSULATION CREEPAGE DISTANCES				
	Printed wiring board material		Other circuits insulating material		
	POLLUTION DEGREE		POLLUTION DEGREE		
	1	2	1	2	3
V	mm	mm	mm	mm	mm
10	0,025	0,04	0,08	0,40	1,00
12,5	0,025	0,04	0,09	0,42	1,05
16	0,025	0,04	0,10	0,45	1,10
20	0,025	0,04	0,11	0,48	1,20
25	0,025	0,04	0,125	0,50	1,25
32	0,025	0,04	0,14	0,53	1,3
40	0,025	0,04	0,16	0,56	1,4
50	0,025	0,04	0,18	0,60	1,5
63	0,040	0,063	0,20	0,63	1,6
80	0,063	0,10	0,22	0,67	1,7
100	0,10	0,16	0,25	0,71	1,8
125	0,16	0,25	0,28	0,75	1,9
160	0,25	0,40	0,32	0,80	2,0
200	0,40	0,63	0,42	1,00	2,5
250	0,56	1,0	0,56	1,25	3,2
320	0,75	1,6	0,75	1,60	4,0
400	1,0	2,0	1,0	2,0	5,0
500	1,3	2,5	1,3	2,5	6,3
630	1,8	3,2	1,8	3,2	8,0
800	2,4	4,0	2,4	4,0	10,0
1 000	3,2	5,0	3,2	5,0	12,5
1 250	4,2	6,3	4,2	6,3	16
1 600	5,6	8,0	5,6	8,0	20
2 000	7,5	10,0	7,5	10,0	25
2 500	10,0	12,5	10,0	12,5	32
3 200	12,5	16	12,5	16	40
4 000	16	20	16	20	50
5 000	20	25	20	25	63
6 300	25	32	25	32	80
8 000	32	40	32	40	100
10 000	40	50	40	50	125
12 500	50	63	50	63	156
16 000	63	80	63	80	200
20 000	80	100	80	100	250
25 000	100	125	100	125	315
32 000	125	160	125	160	400
40 000	160	200	160	200	500
50 000	200	250	200	250	625
63 000	250	320	250	320	790

Linear interpolation is allowed.

6.6 ~~Dielectric strength tests~~ Procedure for voltage tests

6.6.1 ~~REFERENCE TEST EARTH~~ General

~~The reference test earth is the reference point for voltage tests. It is one or more of the following, bonded together if more than one.~~

The following test procedures apply to type testing, and deterioration of the test specimen may occur. Further use of the test specimen may not be appropriate.

Test equipment for the voltage tests is specified in IEC 61180-1 and IEC 61180-2.

The reference point for the voltage tests is one or more of the following, bonded together if more than one.

a) Any ACCESSIBLE conductive part, except for any live parts permitted to be ACCESSIBLE because they do not exceed the values of 6.3.2 and any ACCESSIBLE conductive parts which are allowed to be HAZARDOUS LIVE by the exceptions of 6.1.

b) Any ACCESSIBLE insulating part of the ENCLOSURE, covered with metal foil everywhere except around ~~TERMINALS CONNECTORS~~. For test voltages up to 10 kV a.c. peak or d.c., the distance from foil to ~~TERMINAL CONNECTOR~~ is not more than 20 mm. For higher voltages the distance is the minimum to prevent flashover.

c) ACCESSIBLE parts of controls with parts made of insulating material being wrapped in metal foil or having soft conductive material pressed against them.

6.6.2 Humidity preconditioning

To ensure that the probe assembly does not become hazardous in the humidity conditions of 1.4, it is subjected to humidity preconditioning before the voltage tests ~~of 6.6.4~~. The probe assembly is not operated during preconditioning.

If wrapping in foil is required by 6.6.1, the foil is ~~not~~ applied ~~until~~ after humidity preconditioning and recovery.

Electrical components, covers, and other parts which can be removed by hand are removed and subjected to the humidity preconditioning together with the main part.

Preconditioning is carried out in a humidity chamber containing air with a humidity of ~~92,5 % r.h. ± 2,5 % r.h.~~ $93 \% RH \pm 3 \% RH$. The temperature of the air in the chamber is maintained at $40\text{ °C} \pm 2\text{ °C}$.

Before applying humidity, the probe assembly is brought to a temperature of $42\text{ °C} \pm 2\text{ °C}$, normally by keeping it at this temperature for at least 4 h before the humidity preconditioning.

The air in the chamber is stirred and the chamber is designed so that condensation will not precipitate on the probe assembly.

The probe assembly remains in the chamber for 48 h, after which it is removed and allowed a recovery period of 2 h under the environmental conditions of 4.3.1, ~~with any covers of non-ventilated PROBE ASSEMBLIES removed~~ after which parts removed (see above) are re-installed.

6.6.3 Conduct of tests

The tests ~~specified in 6.6.4~~ are performed and completed within 1 h of the end of the recovery period after humidity preconditioning. The probe assembly is not operated during the tests.

Voltage tests are not made between two circuits, or between a circuit and an ACCESSIBLE conductive part, if they are connected to each other or not separated from each other.

PROTECTIVE IMPEDANCE in parallel with the insulation to be tested is disconnected.

If two or more protective means are used in combination (see 6.4), *it is likely that* the voltages specified for DOUBLE INSULATION and REINFORCED INSULATION ~~could~~ *would* be applied to parts of circuits which are not required to withstand these voltages. To avoid this, such parts may be disconnected during the tests, or the parts of circuits where DOUBLE INSULATION or REINFORCED INSULATION is required may be tested separately.

6.6.4 ~~VOLTAGE TESTS~~ Test voltages

~~Voltage tests are applied, using the values specified in table 6. No breakdown or repeated flashover shall occur. Corona effects and similar phenomena are disregarded.~~

~~For solid insulation, the a.c. and d.c. tests are alternative test methods. It is sufficient that the insulation passes either of the two. The tests are conducted with the voltage raised gradually over a period of 5 s or less to the specified value so that no appreciable transients occur, then maintained for 5 s. For simplicity a.c. may be chosen, or d.c. to avoid capacitive currents.~~

~~Voltage tests for solid insulation are applied using the values specified in Table 4.~~

~~Voltage tests for CLEARANCES are applied using the values specified in Table 10.~~

~~The CLEARANCE in case of homogeneous construction (see ~~6.5.1.1~~ 6.5.1.2.2), is tested with an a.c., d.c. or peak impulse voltage with the peak value specified in Table 10 for the value of CLEARANCE specified for inhomogeneous construction.~~

~~Impulse tests are the 1,2/50 μ s test specified in IEC 60060, conducted for a minimum of three pulses of each polarity at 1 s minimum intervals. If a.c. or d.c. tests are chosen, they shall be conducted for a minimum of three cycles in the case of a.c., or three times with a duration of 10 μ s in each polarity in the case of d.c.~~

~~The values for testing DOUBLE INSULATION or REINFORCED INSULATION are 1,6 times the values from table 6 for BASIC INSULATION.~~

~~NOTE 1—When testing circuits, it may not be possible to separate tests of CLEARANCE from tests of solid insulation.~~

~~NOTE 2—The maximum test current of test equipment is usually limited to avoid HAZARDS arising from the test and damage to equipment which fails the test.~~

~~NOTE 3—It may be useful to make partial discharges within the insulation material perceptible (see IEC 60270 [3]).~~

~~NOTE 4—Care should be taken to discharge stored energy after test.~~

~~The values of Table 10 apply to test sites located at 2 000 m altitude. For other test site altitudes, the correction factors of Table 11 are applied to the values of Table 10 when testing CLEARANCE but not when testing solid insulation.~~

~~NOTE The electric testing of CLEARANCES will also stress the associated solid insulation.~~

Table 6 10 – Test voltages for BASIC INSULATION based on CLEARANCES

Required CLEARANCE	Peak voltage for impulse testing Impulse 1,2/50 µs	Voltage a.c. r.m.s. 50/60 Hz	Voltage a.c. peak 50/60 Hz or d.c.	Required CLEARANCE	Peak voltage for impulse testing Impulse 1,2/50 µs	Voltage a.c. r.m.s. 50/60 Hz	Voltage a.c. peak 50/60 Hz or d.c.
mm	V peak	V	V	mm	V peak	V	V
0,010	330	230	330	16,5	14 000	7 600	10 700
0,025	440	310	440	17,0	14 300	7 800	11 000
0,040	520	370	520	17,5	14 700	8 000	11 300
0,063	600	420	600	18,0	15 000	8 200	11 600
0,1	806	500	700	19	15 800	8 600	12 100
0,2	1 140	620	880	20	16 400	9 000	12 700
0,3	1 310	710	1 010	25	19 900	10 800	15 300
0,5	1 550	840	1 200	30	23 300	12 600	17 900
1,0	1 950	1 060	1 500	35	26 500	14 400	20 400
1,4	2 440	1 330	1 880	40	29 700	16 200	22 900
2,0	3 100	1 690	2 400	45	32 900	17 900	25 300
2,5	3 600	1 960	2 770	50	36 000	19 600	27 700
3,0	4 070	2 210	3 130	55	39 000	21 200	30 000
3,5	4 510	2 450	3 470	60	42 000	22 900	32 300
4,0	4 930	2 680	3 790	65	45 000	24 500	34 600
4,5	5 330	2 900	4 100	70	47 900	26 100	36 900
5,0	5 720	3 110	4 400	75	50 900	27 700	39 100
5,5	6 100	3 320	4 690	80	53 700	29 200	41 300
6,0	6 500	3 520	4 970	85	56 610	30 800	43 500
6,5	6 800	3 710	5 250	90	59 400	32 300	45 700
7,0	7 200	3 900	5 510	95	62 200	33 800	47 900
7,5	7 500	4 080	5 780	100	65 000	35 400	50 000
8,0	7 800	4 300	6 030	110	70 500	38 400	54 200
8,5	8 200	4 400	6 300	120	76 000	41 300	58 400
9,0	8 500	4 600	6 500	130	81 300	44 200	62 600
9,5	8 800	4 800	6 800	140	86 600	47 100	66 700
10,0	9 100	4 950	7 000	150	91 900	50 000	70 700
10,5	9 500	5 200	7 300	160	97 100	52 800	74 700
11,0	9 900	5 400	7 600	170	102 300	55 600	78 700
11,5	10 300	5 600	7 900	180	107 400	58 400	82 600
12,0	10 600	5 800	8 200	190	112 500	61 200	86 500
12,5	11 000	6 000	8 500	200	117 500	63 900	90 400
13,0	11 400	6 200	8 800	210	122 500	66 600	94 200
13,5	11 800	6 400	9 000	220	127 500	69 300	98 000
14,0	12 100	6 600	9 300	230	132 500	72 000	102 000
14,5	12 500	6 800	9 600	240	137 300	74 700	106 000
15,0	12 900	7 000	9 900	250	142 200	77 300	109 400
15,5	13 200	7 200	10 200	264	149 000	81 100	115 000
16,0	13 600	7 400	10 500				

NOTE Linear interpolation of test voltages is allowed.

**Table 7 11 – Correction factors according to test site altitude
for test voltages for CLEARANCES**

	Altitude Correction factors for ranges of test voltages			
Test voltage peak	$\geq 327 \text{ V} < 600 \text{ V}$	$\geq 600 \text{ V} < 3\,500 \text{ V}$	$\geq 3\,500 \text{ V} < 25 \text{ kV}$	$\geq 25 \text{ kV}$
Test voltage r.m.s.	$\geq 231 \text{ V} < 424 \text{ V}$	$\geq 424 \text{ V} < 2\,475 \text{ V}$	$\geq 2\,475 \text{ V} < 17,7 \text{ kV}$	$\geq 17,7 \text{ kV}$
Test site altitude m	$327 \text{ V}_{\text{peak}} \leq U_{\text{test}}$ $< 600 \text{ V}_{\text{peak}}$ $231 \text{ V}_{\text{r.m.s.}} \leq U_{\text{test}}$ $< 424 \text{ V}_{\text{r.m.s.}}$	$600 \text{ V}_{\text{peak}} \leq U_{\text{test}}$ $< 3\,500 \text{ V}_{\text{peak}}$ $424 \text{ V}_{\text{r.m.s.}} \leq U_{\text{test}}$ $< 2\,475 \text{ V}_{\text{r.m.s.}}$	$3\,500 \text{ V}_{\text{peak}} \leq U_{\text{test}}$ $< 25 \text{ kV}_{\text{peak}}$ $2\,475 \text{ V}_{\text{r.m.s.}} \leq U_{\text{test}}$ $< 17,7 \text{ kV}_{\text{r.m.s.}}$	$25 \text{ kV}_{\text{peak}} \leq U_{\text{test}}$ $17,7 \text{ kV}_{\text{r.m.s.}} \leq U_{\text{test}}$
Sea-level 0	1,08	1,16	1,22	1,24
500	1,06	1,12	1,16	1,17
1 000	1,04	1,08	1,11	1,12
2 000	1,00	1,00	1,00	1,00
3 000	0,96	0,92	0,89	0,88
4 000	0,92	0,85	0,80	0,79
5 000	0,88	0,78	0,71	0,70

Linear interpolation is allowed.

6.6.5 Test procedures

6.6.5.1 The a.c. voltage test

The voltage test equipment shall have a regulated output capable of maintaining the test voltage throughout the test. The waveform of the power frequency test voltage shall be substantially sinusoidal. This requirement is fulfilled if the ratio between the peak value and the r.m.s. value is $\sqrt{2} \pm 3 \%$.

The test voltage is raised uniformly from 0 V to the specified value within 5 s and held at that value for at least the specified time.

No flashover of CLEARANCES or breakdown of solid insulation shall occur during the test.

6.6.5.2 The 1 min d.c. voltage test

The voltage test equipment shall have a regulated output capable of maintaining the test voltage throughout the test. The d.c. test voltage shall be substantially free of ripple. This requirement is fulfilled if the ratio between the peak value of the voltage and the average value is $1,0 \pm 3 \%$.

The d.c. test voltage is raised uniformly from 0 V to the specified value within 5 s and held at that value for at least 1 min.

No flashover of CLEARANCES or breakdown of solid insulation shall occur during the test.

6.6.5.3 The impulse voltage test

The test shall be conducted for five impulses of each polarity with an interval of at least 1 s between impulses. The impulse voltage test is carried out with a 1,2/50 μs waveform (see Figure 1 of IEC 61180-1:1992). The wave shape of each impulse shall be observed.

When verifying CLEARANCES within probe assembly by an impulse voltage test, it is necessary to ensure that the specified impulse voltage appears at the CLEARANCE.

No flashover of CLEARANCES or breakdown of solid insulation shall occur during the test, but partial discharges are allowed.

6.7 Constructional requirements for protection against electric shock

6.7.1 General

If a failure could cause a HAZARD,

- a) the security of wiring connections subject to mechanical stresses shall not depend on soldering;
- b) screws securing removable covers shall be captive if their length determines a ~~CLEARANCE~~ ~~OF CREEPAGE DISTANCE~~ ~~SPACING~~ between ACCESSIBLE conductive parts and HAZARDOUS LIVE parts;
- c) accidental loosening or freeing of the wiring, screws, etc., shall not cause ACCESSIBLE parts to become HAZARDOUS LIVE.

NOTE Screws or nuts with lock washers are not regarded as likely to become loose, nor are wires which are mechanically secured by more than soldering alone.

Conformity is checked by inspection and by measurement of SPACINGS.

6.7.2 Insulating materials

The following shall not be used as insulation for safety purposes:

- a) materials which can easily be damaged (for example, lacquer, enamel, oxides, anodic films);
- b) non-impregnated ~~hydroscopic~~ ~~hygroscopic~~ materials (for example, paper, fibres, fibrous materials).

Conformity is checked by inspection.

6.7.3 ENCLOSURES of probe assemblies with DOUBLE INSULATION or REINFORCED INSULATION

A probe assembly which relies on DOUBLE INSULATION or REINFORCED INSULATION throughout for protection against electric shock shall have an ENCLOSURE which surrounds all metal parts. This requirement does not apply to small metal parts such as nameplates, screws or rivets, if they are separated from parts which are HAZARDOUS LIVE by REINFORCED INSULATION or its equivalent.

ENCLOSURES or parts of ENCLOSURES made of insulating material shall meet the requirements for DOUBLE INSULATION or REINFORCED INSULATION.

Protection for ENCLOSURES or parts of ENCLOSURES made of metal shall be provided by one of the following means, except for parts where PROTECTIVE IMPEDANCE is used:

- a) an insulating coating or a barrier on the inside of the ENCLOSURE which shall surround all metal parts and all places where loosening of a part which is HAZARDOUS LIVE might cause it to touch a metal part of the ENCLOSURE;
- b) ~~CLEARANCES and CREEPAGE DISTANCES~~ ~~SPACINGS~~ between the ENCLOSURE and parts which are HAZARDOUS LIVE that cannot be reduced below the values specified in 6.5 by loosening of parts or wires.

NOTE Screws or nuts with lock washers are not regarded as liable to become loose, nor are wires which are mechanically secured by more than soldering alone.

Conformity is checked by inspection and measurement and as specified in 6.5.

6.7.3 CORONA AND PARTIAL DISCHARGE

~~The construction of a PROBE ASSEMBLY shall be such that, while operating at maximum RATED voltage, there is no corona or partial discharge.
Conformity is under consideration.~~

6.7.4 CABLE PROBE WIRE attachment

6.7.4.1 General

The attachment of the ~~cable~~ PROBE WIRE to the probe body and to the equipment (or to the CONNECTORS if the attachment is not fixed) shall withstand forces likely to be encountered in NORMAL USE without damage which could cause a HAZARD. Solder alone, without mechanical gripping, shall not be used for strain relief. The insulation of the ~~cable~~ PROBE WIRE shall be mechanically secured to avoid retraction.

Conformity is checked by inspection and by applying the tests of 6.7.4.2 to 6.7.4.4. After the tests,

- a) ~~the cable~~ PROBE WIRE shall not have been damaged;
- b) the insulation of the ~~cable~~ PROBE WIRE shall not have been cut or torn, and shall not have moved more than 2 mm in the bushing;
- c) ~~CLEARANCES and CREEPAGE DISTANCES SPACINGS~~ shall not have been reduced below the applicable value of 6.5;
- d) ~~the cable~~ PROBE WIRE shall pass the a.c. voltage test or the d.c. voltage test of 6.6 using the applicable test voltage and duration of Table 4 (without humidity preconditioning).

NOTE For test purposes, it ~~may~~ could be useful to prepare a special sample of the probe, manufactured in all respects like the probe being investigated but in which no solder has been applied.

6.7.4.2 Pull test

With the probe body or equipment or CONNECTOR clamped so that it cannot move and any soldered connection severed, the ~~cable~~ PROBE WIRE is subjected for 1 min to a steady axial pull at the values shown below:

- a) for probe bodies and for locking CONNECTORS, ~~twice~~ the pull force value from Table 12;
- b) for non-locking CONNECTORS, ~~twice~~ the pull force value from Table 12 or four times the axial pull force required to disconnect the CONNECTOR, whichever is less.

6.7.4.3 Flexing/pull test

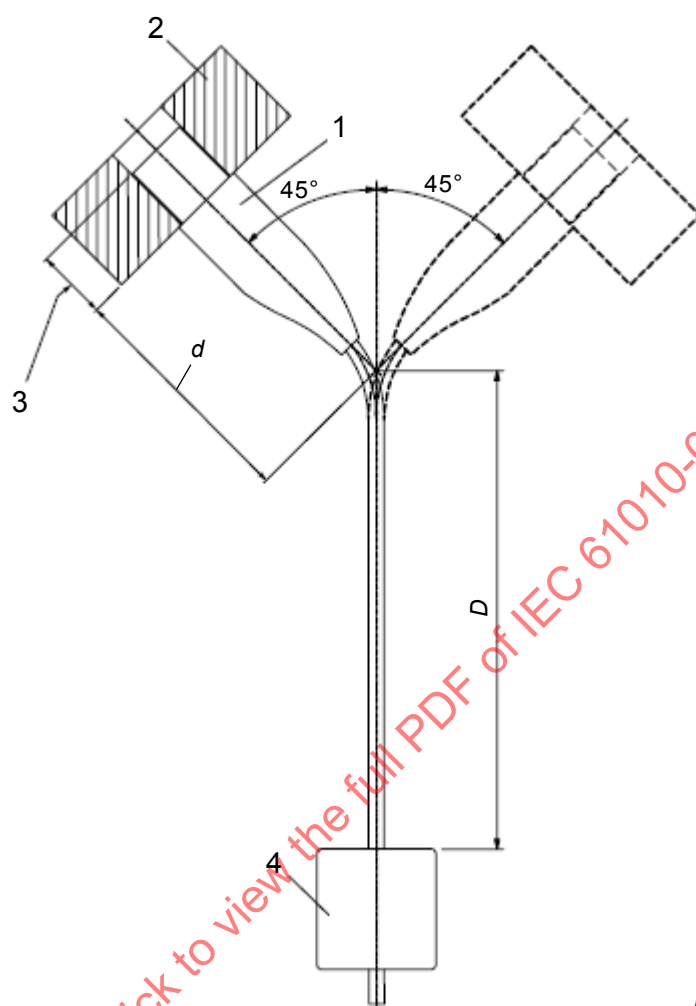
~~The test is shown in figure 7. With the probe body or equipment or connector clamped so that it cannot move and any soldered connection severed, the mass provides a force of 10 N for conductors with a cross-sectional area of 0,3 mm² to 0,75 mm² and 20 N for conductors with a cross-sectional area above 0,75 mm². For cables with multiple conductors, the cross-sectional area is calculated as the sum of the cross-sectional areas of the individual conductors.~~

~~The end being tested is made to oscillate 45° on each side of the axis of oscillation with minimum movement of the hanging mass. Samples with flat flexible cords are mounted so that the major axis of the section is parallel to the axis of oscillation. Halfway through the test, cords with circular section are turned 90° about the centre line. Ten thousand flexings (single movements through 90° either backwards or forwards) are made at a rate of 60 per minute.~~

~~CONNECTORS shall be subjected to a flexing test in an apparatus similar to that shown in Figure 19.~~

~~The CONNECTOR is fixed to the oscillating member of the apparatus so that, when this is at the midpoint of its travel, the axis of the flexible PROBE WIRE, where it enters the CONNECTOR, is vertical and passes through the axis of oscillation.~~

The oscillating member is, by variation of distance d shown in Figure 19, so positioned that the flexible PROBE WIRE makes a minimum lateral movement when the oscillating member of the test apparatus is moved over its full travel.



IEC

Key $D > 300 \text{ mm}$

1 CONNECTOR

2 Part of oscillating member for fixing the CONNECTOR

3 Depth specified for the shroud of corresponding equipment TERMINAL

4 Weight

Figure 7 19 – Flexing test

The PROBE WIRE is loaded with a weight such that the force from Table 12 is applied.

The oscillating member is moved to each side of vertical through a total angle of 90° (45° on each side of vertical). The total number of flexings is 5 000. The rate of flexing is 60 per minute. A complete cycle is two flexings.

CONNECTORS with PROBE WIRE of nominally circular cross-sectional area are rotated approximately 90° around the vertical axis within the oscillating member after 2 500 flexings; CONNECTORS with flat flexible PROBE WIRE are not so rotated, and are only flexed in a direction perpendicular to the thinner dimension of the cross-section.

If a HAZARD can result from the breaking of a conductor or a short-circuit between conductors, a current equal to the RATED current of the probe assembly is passed through each conductor, the voltage between them being the RATED voltage. During the test, there shall be no interruption of the test current and no short-circuit between the conductors.

Table-8 12 – Pull forces for ~~cable~~ PROBE WIRE attachment tests

Cross-section sectional area of the conductor (a) mm ²	Pull force N
~~a < 2,5~~	~~36~~
~~2,5 < a < 4~~	~~50~~
~~4 < a < 6~~	~~60~~
~~6 < a < 10~~	~~80~~
~~10 < a < 16~~	~~90~~
0,25	2,5
0,50	5
1,0	10
2,5	18
4	25
6	30
10	40
16	45

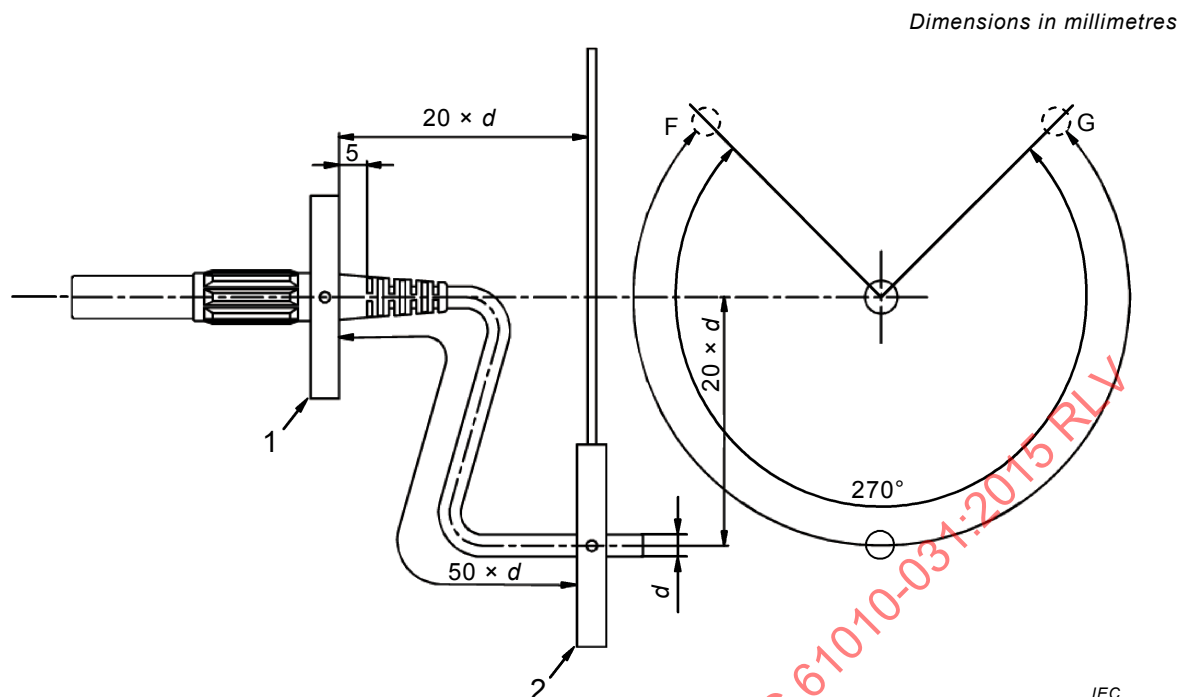
NOTE Linear interpolation is allowed.

For ~~cables~~ PROBE WIRES with multiple conductors, the cross-sectional area (a) is calculated as the sum of the cross-sectional areas of the individual conductors.

For the purpose of this calculation, the cross-sectional area of any shield is ignored.

6.7.4.4 Rotational flexing test

The ~~lead~~ probe assembly is mounted in the test fixture as shown in Figure 20, so that the fixed clamp holds the probe body, CONNECTOR, or equipment with at least 5 mm of the solid portion protruding through the clamp. The rotating clamp is attached to the probe lead at a point 50 times the diameter of the ~~cable~~ PROBE WIRE, measured along the surface of the lead from the fixed clamp. The rotating clamp rotates in a plane at a distance equal to 20 times the diameter of the ~~cable~~ PROBE WIRE from the fixed clamp. The rotating clamp is rotated from point F to G and back to point F (one complete oscillation) at a rate of 20 oscillations per minute for a total of 250 swings. The ~~plug~~ probe body or CONNECTOR is turned 90° about its axis and the test continued for a further 250 oscillations.

**Key** d diameter of PROBE WIRE

F start point, end point

G middle point ($F + 270^\circ$)

1 fixed clamp

2 rotating clamp

Figure 8 20 – Rotational flexing test for cable used in PROBE ASSEMBLIES (see 6.7.4)**7 Protection against mechanical HAZARDS**

Handling of a probe assembly or an accessory during NORMAL USE shall not lead to a HAZARD.

NOTE Easily touched edges, projections, etc. should be smooth and rounded so as not to cause injury during NORMAL USE (This does not apply to PROBE TIPS, plug pins, etc.).

Conformity is checked by inspection.

8 Mechanical Resistance to shock and impact Resistance to mechanical stresses**8.1 General**

Probe assemblies shall not cause a HAZARD when subjected to shock and impact mechanical stresses likely to occur in NORMAL USE. To achieve this requirement, probe assemblies shall have adequate mechanical strength, components shall be reliably secured and electrical connections shall be secure.

Conformity is checked by performing the tests of 8.2 to 8.4. The probe assembly is not operated during the tests.

After completion of the tests, the probe assembly shall pass the **a.c. voltage test or the d.c. voltage test** of 6.6 **using the applicable test voltage and duration of Table 4** (without humidity preconditioning) and is inspected to check that:

- a) parts which are **HAZARDOUS LIVE** have not become **ACCESSIBLE**;
- b) **ENCLOSURES** show no cracks which could cause a **HAZARD**;
- c) **CLEARANCES SPACINGS** are not less than their permitted values and the insulation of internal wiring remains undamaged;
- d) **BARRIERS PROTECTIVE FINGERGUARDS** have not been damaged or loosened;
- e) there has been no damage which could cause spread of fire.

Damage to the finish, small dents which do not reduce ~~CREEPAGE DISTANCES OR CLEARANCES SPACINGS~~ below the values specified in 6.5, and small chips which do not adversely affect the protection against electric shock or moisture, are ignored.

8.2 Rigidity test

The **non-operative treatment of 10.2** is performed. Within 2 min of the end of the **non-operative treatment**, the probe assembly is held firmly against a rigid support and subjected to a force of 20 N applied by the hemispherical end of a hard rod of 12 mm diameter. The rod is applied three times to any part of the probe assembly which is **ACCESSIBLE** when the probe assembly is ready for use, and which could cause a **HAZARD** if distorted.

8.3 Drop test

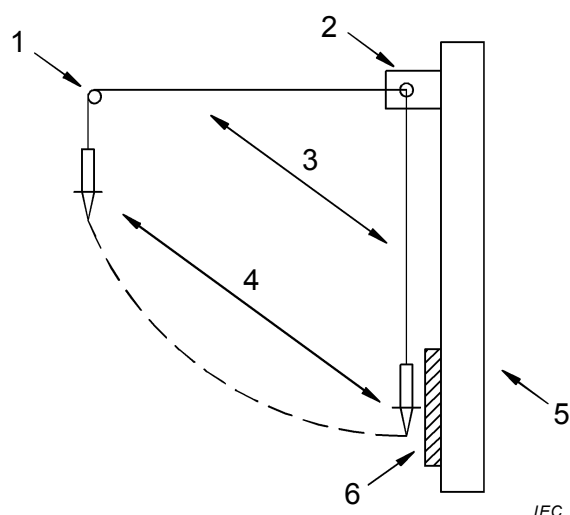
Three samples of the probe assembly are each dropped three times through a distance of 1 m onto a 50 mm thick hardwood board having a density of more than 700 kg/m³, lying flat on a rigid base such as ~~a concrete block~~. For each sample, the three tests are carried out so as to apply the impact to different points on the probe body.

Non-metallic ENCLOSURES of probe assembly with a minimum **RATED** ambient temperature below 2 °C are cooled to the minimum **RATED** ambient temperature, then tested within 2 min.

8.4 Impact swing test

The probe body is subjected to **one** impact against a **5 mm thick** hardwood board **having a density of more than 700 kg/m³** fixed to a solid wall, when swinging as a pendulum by its ~~cable~~ **PROBE WIRE** (see Figure 21). The height of the drop is 2 m, or the ~~PROBE cable WIRE~~ length if shorter. ~~The hardwood board has a thickness of 50 mm and a density of more than 700 kg/m³.~~

Non-metallic probe bodies with a minimum **RATED** ambient temperature below 2 °C are cooled to the minimum **RATED** ambient temperature, then tested within 2 min.

**Key**

- 1 start point
- 2 suspension point
- 3 ~~cable~~ PROBE WIRE
- 4 probe
- 5 wall
- 6 hardwood board

Figure 9 21 – Impact swing test**9 Temperature limits and protection against the spread of fire****9.1 General**

Any heating shall not cause a HAZARD in NORMAL CONDITION or in SINGLE FAULT CONDITION, nor shall it cause spread of fire outside the probe assembly.

Easily touched surfaces shall not exceed the following temperatures in NORMAL CONDITION, nor 105 °C in SINGLE FAULT CONDITION, at an ambient temperature of 40 °C, or the maximum RATED ambient temperature if higher.

Metal: 55 °C

Non-metallic materials: 70 °C

~~Wire and cable~~ PROBE WIRES: 75 °C

If easily touched heated surfaces are necessary for functional reasons, they are permitted to exceed these values, but shall be recognizable as such by appearance or function, or shall be marked with Symbol 6 of Table 1 (see 5.2).

If protection against fire depends on separation of circuits, they shall be separated at least by BASIC INSULATION.

The maximum temperature of a part is determined by measuring the temperature rise of the part under the conditions of 9.2 and adding it to the maximum ambient temperature (40 °C or the maximum RATED ambient temperature if higher, see 1.4).

Conformity is checked by inspection, by the tests of 9.2 and by tests in the SINGLE FAULT CONDITIONS of 4.4. Alternatively, if protection is assured by separation of circuits, conformity is checked by measurement of ~~CLEARANCES and CREEPAGE DISTANCES SPACINGS~~, and by making the voltage tests of 6.6.5 (without humidity preconditioning) *using the applicable test voltage of Table 10.*

9.2 Temperature tests

A PROBE ASSEMBLY is tested under reference test conditions and in the position of NORMAL USE (see 4.3.2). *The tests of 6.7.4.2 to 6.7.4.4 are performed before performing these temperature tests.* Temperatures are measured when steady state has been attained.

NOTE 1—~~The maximum temperature of a part is in most cases determined by measuring the temperature rise of the part under the conditions of 9.2 and adding it to the maximum ambient temperature (40 °C or the maximum RATED ambient temperature if higher, see 1.4).~~

NOTE 2—~~NORMAL USE includes following the manufacturers instructions for ventilation and any specified limits for intermittent operation given in the documentation.~~

10 Resistance to heat

10.1 Integrity of ~~CLEARANCES and CREEPAGE DISTANCES SPACINGS~~

~~CLEARANCES and CREEPAGE DISTANCES SPACINGS~~ shall meet the requirements of 6.5 when the probe assembly is operated at an ambient temperature of 40 °C or the maximum RATED ambient temperature if higher (see 1.4).

Conformity in cases of doubt, if the probe assembly produces an appreciable amount of heat, is checked by operating the probe assembly under the reference test conditions of 4.3, except that the ambient temperature is 40 °C or the maximum RATED ambient temperature, if higher. After this test, ~~CLEARANCES and CREEPAGE DISTANCES SPACINGS~~ shall not have been reduced below the requirements of 6.5.

If the ~~PROBE ASSEMBLY has an ENCLOSURE which~~ ENCLOSURE is non-metallic, the temperature of parts of the ENCLOSURE is measured *during the above test* for the purpose of 10.2.

10.2 Resistance to heat

~~PROBE ASSEMBLIES ENCLOSURES~~ of non-metallic material shall be resistant to elevated temperatures.

Conformity is checked by ~~one of the following treatments~~ the test of 8.2, applied after the following ~~non-operative conditioning~~ :

a) ~~a non-operative treatment, in which~~ The probe assembly, not energized, is stored for 7 h at a temperature of 70 °C. However, if during the test of 10.1, a higher temperature is measured, the storage temperature is to be 10 °C above that measured temperature. If the probe assembly contains components which might be damaged by this treatment, an empty ~~probe assembly~~ ENCLOSURE may be treated, followed by assembly *of the probe* at the end of the treatment.

b) ~~an operative treatment, in which the probe assembly is operated under the reference test conditions of 4.3 and in an ambient temperature of 60 °C or 20 °C above the maximum rated ambient temperature, if higher.~~

~~After the treatment, the PROBE ASSEMBLY shall cause no HAZARD and shall pass the tests of 6.6, 8.1, 8.2 and 8.3. CLEARANCE and CREEPAGE DISTANCES shall not have been reduced below the requirements of 6.5.~~

11 Protection against HAZARDS from fluids

11.1 General

Probe assemblies containing fluids, or to be used in measurements of processes on fluids, shall be designed to give protection to the OPERATOR and surrounding area against HAZARDS from fluids encountered in NORMAL USE.

NOTE Fluids likely to be encountered fall into three categories:

- a) having continuous contact, for example, in vessels intended to contain them;
- b) having occasional contact, for example, cleaning fluids;
- c) having accidental (unexpected) contact. The manufacturer cannot safeguard against such cases.

Conformity is checked by the treatment and tests of 11.2.

11.2 Cleaning

If a cleaning or decontamination ~~process method~~ is specified by the manufacturer, this shall not cause a direct safety HAZARD, an electric shock HAZARD, or a HAZARD resulting from corrosion or other weakening of structural parts associated with safety. The cleaning method and any decontamination method shall be described in the documentation (see 5.4.3).

Conformity is checked by cleaning the probe assembly three times according to the manufacturer's instructions. If, immediately after this treatment, there are any signs of wetting of parts likely to cause a HAZARD, the probe assembly shall pass the a.c. voltage test or the d.c. voltage test of 6.6 using the applicable test voltage and duration of Table 4 (without humidity preconditioning) and ACCESSIBLE parts shall not exceed the ~~limits levels~~ of 6.3.2. If a decontamination method is specified, this method is applied once.

11.3 Specially protected probe assemblies

If the probe assembly is ~~RATED or~~ marked by the manufacturer as having a protected ENCLOSURE, ~~it shall comply with the relevant requirements according to the stated degrees of protection of IEC 60529, it shall adequately resist the ingress of solid foreign objects and water which could lead to a HAZARD.~~

Conformity is checked by inspection and by subjecting the probe assembly to the appropriate treatment of IEC 60529, after which the probe assembly shall pass the a.c. voltage test or the d.c. voltage test of 6.6 using the applicable test voltage and duration of Table 4 (without humidity preconditioning) and ACCESSIBLE parts shall not exceed the ~~limits levels~~ of 6.3.2.

12 Components

12.1 General

If safety is involved, components shall be used in accordance with their specified RATING unless a specific exception is made. They shall conform to one of the following.

- a) All applicable safety requirements of relevant IEC standards. Conformity with other requirements of the component standard is not required. If necessary for the application, they shall be subjected to the tests of this standard, except that it is not necessary to carry out identical or equivalent tests already performed to check conformity with the component standard.
- b) The requirements of this standard and, where necessary for the application, any additional applicable safety requirements of the relevant IEC component standard.
- c) If there is no relevant IEC standard, the requirements of this standard.

- d) Applicable safety requirements of a non-IEC standard which are at least as high as those of the relevant IEC standard, provided that the component has been approved to the non-IEC standard by a recognized testing authority.

Tests performed by a recognized testing authority which confirm conformity with all applicable safety requirements need not be repeated, even if the tests were performed using a non-IEC standard.

~~Components approved by a recognized testing authority for conformity with all applicable safety requirements need not be retested.~~

Conformity is checked by inspection, and if necessary, by test.

12.2 Fuses

Fuses in probe assemblies may be used to provide protection to the user against arc explosions or burns, or they may be used to protect the equipment to which the probes are connected.

If a fuse is installed in a probe assembly, it shall have a voltage RATING at least as high as the highest RATED voltage of the probe assembly, and an appropriate breaking capacity and current RATING for the intended application of the probe assembly (see also 5.1.3). If the probe assembly is RATED for both a.c. and d.c., the a.c. and d.c. breaking capacities shall be individually determined, and the fuse shall meet the RATED voltage and breaking capacity for each case.

Conformity is checked by inspection.

~~NOTE The minimum breaking capacity will normally need to be the current produced by dividing the maximum RATED voltage by the impedance of the probe assembly, or pair of PROBE ASSEMBLIES, as appropriate.~~

12.3 ~~HIGH-INTegrity components~~

~~HIGH-INTegrity components shall be used in positions (for example, PROTECTIVE IMPEDANCE) where, if short-circuiting or disconnection occurred, an infringement of the requirements in SINGLE FAULT CONDITION would be caused. HIGH-INTegrity components shall be constructed, dimensioned and tested to IEC publications (if applicable) so that safety and reliability for the expected application is assured. They may be regarded as fault-free in relation to the safety requirements of this standard.~~

~~NOTE 1 Examples for such requirements and tests are:~~

- ~~a) dielectric strength tests appropriate for DOUBLE INSULATION or REINFORCED INSULATION;~~
- ~~b) dimensioning for at least twice the dissipation (resistor);~~
- ~~c) climatic tests and endurance tests to ensure reliability for the expected life of the PROBE ASSEMBLY;~~
- ~~d) surge tests for resistors (see IEC 60065 [2]).~~

~~A single electronic device which employs electron conduction in a vacuum, gas or semiconductor is not regarded as a HIGH-INTegrity component.~~

~~*Conformity is checked by performing the relevant tests.*~~

~~NOTE 2 Requirements and test methods are under consideration for evaluating whether a single component can be considered to be a HIGH-INTegrity component.~~

12.3.1 RESISTORS USED IN PROTECTIVE IMPEDANCE

Any resistor or resistor assembly forming part of a PROTECTIVE IMPEDANCE used in a PROBE ASSEMBLY (see 6.4) shall be a HIGH INTEGRITY resistor or assembly meeting the following requirements:

- a) the resistor or assembly shall withstand twice the dissipation occurring at the maximum RATED voltage of the PROBE ASSEMBLY;
- b) the resistor or assembly shall withstand twice the maximum RATED voltage of the PROBE ASSEMBLY for at least 1 s;
- c) the distance across the resistor or assembly shall be at least the value of CLEARANCE for DOUBLE INSULATION at the maximum RATED voltage of the PROBE ASSEMBLY. If heating occurs at maximum RATED voltage, then the CLEARANCE shall be the value applicable to the RATED maximum WORKING VOLTAGE multiplied by T_2/T_1 , where T_1 is the maximum RATED ambient temperature of the PROBE ASSEMBLY and T_2 is the maximum temperature around the resistor at maximum RATED voltage with the maximum ambient temperature applied (both in kelvins).

Conformity is checked by measurement and test.

12.3 PROBE WIRE

12.3.1 General

PROBE WIRE shall be suitable for its intended use in NORMAL CONDITION and SINGLE FAULT CONDITION.

Conformity is checked as specified in 12.3.2 to 12.3.6.

12.3.2 RATING OF PROBE WIRE

PROBE WIRES shall be RATED for the maximum voltage and current of NORMAL USE and shall withstand the voltage test for the highest RATED voltage to earth. Conductors shall be separated from ACCESSIBLE SURFACES by DOUBLE INSULATION or REINFORCED INSULATION, based on the following values:

- a) for type A probe assemblies, 125 V or the highest RATED voltage to earth of the probe assembly, whichever is greater;
- b) for type B probe assemblies, 500 V or the highest RATED voltage to earth of the probe assembly divided by the divider ratio, whichever is greater;
- c) for type C probe assemblies, 125 V or the highest RATED voltage to earth of the probe assembly, whichever is greater;
- d) for type D probe assemblies, 125 V.

For type B probe assemblies, Symbol 7 shall be marked on the probe assembly and a warning shall be provided in the documentation that the PROBE WIRE may not provide adequate protection if it comes into contact with the circuit under test.

Insulation of PROBE WIRES which have a wear indicator shall meet the requirements for BASIC INSULATION when the wear indicator has become visible.

A wear indicator is highly recommended (see also 5.4.3 j)).

Conformity is checked by inspection, and by the a.c. voltage test of 6.6.5.1, or for PROBE WIRES stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4 for REINFORCED INSULATION. If the insulation includes a wear indicator, then the voltage test is repeated with the test voltage value for BASIC INSULATION after sufficient insulation has been removed from the cable to make the wear indicator just visible.

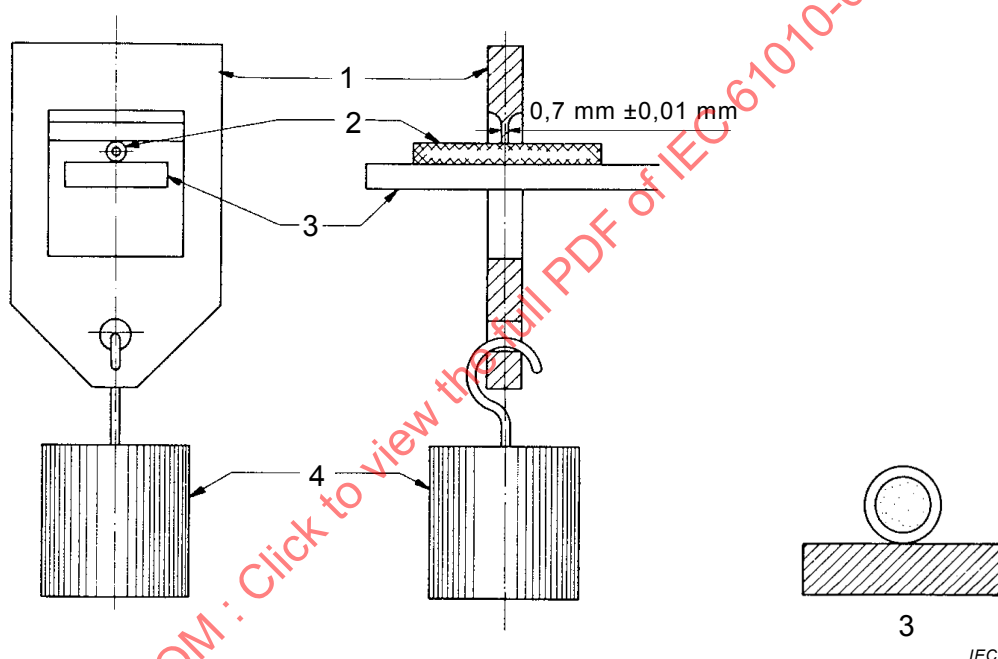
NOTE For the purposes of this test, the wear indicator can be made visible by slicing thin layers from the insulation, by abrasion, or by manufacturing special samples of the cable without the outer insulating layer.

12.3.3 Pressure test at high temperature for insulations

For each *PROBE WIRE* to be tested, three adjacent samples are taken from a *PROBE WIRE* having a length of 150 mm to 300 mm. The length of each sample is 50 mm to 100 mm. The conductors of flat *PROBE WIRES* without sheaths are not separated.

If the samples have a covering or semiconducting layer over the insulation, it is mechanically removed.

The indentation device is shown in Figure 22, and consists of a rectangular blade with an edge $0,70 \text{ mm} \pm 0,01 \text{ mm}$ wide, which can be pressed against the sample. Each sample is placed in the position shown in Figure 22. A flat cord without a sheath is laid on its flat side. Samples are fixed on the support in such a manner that they do not curve under the pressure of the blade. The force is applied in a direction perpendicular to the axis of the sample; the blade is also perpendicular to the axis of the sample.



Key

- 1 Testing frame
- 2 Sample
- 3 Supports
- 4 Weight

Figure 22 – Indentation device

The compressing force F which is exerted by the blade upon the sample is given by the formula:

$$F = 0,6 \times \sqrt{(2 \times d \times e - e^2)}$$

Where:

F is in newtons

e is the mean value of the thickness of the insulation of the sample

d is the mean value of the outer diameter of the sample

e and d are both expressed in millimetres, to one decimal place, and measured on a thin slice cut from the end of the test piece.

The test is carried out in air (i.e. in an air oven). The temperature of the air is maintained continuously at a temperature of $100\text{ °C} \pm 3\text{ °C}$. The loaded samples are kept in the test position for 4 h. Following this, the samples are rapidly cooled which may be carried out by spraying the sample with cold water on the spot where the blade is pressing. The sample is removed from the apparatus when it has cooled to a temperature where recovery of the insulation no longer occurs. The sample is then cooled further by immersion in cold water.

Conformity is checked by the a.c. voltage test of 6.6.5.1, or for PROBE WIRES stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4 for REINFORCED INSULATION (without humidity preconditioning).

12.3.4 Tests for resistance of insulation to cracking

Four samples of suitable length are cut from two sections of the PROBE WIRE separated by at least 1 m. External coverings, if any, are removed from the insulation.

Each sample is tautly wound and fixed, at ambient temperature, on a mandrel to form a close helix. The diameter of the mandrel and the number of turns are given in Table 13.

Table 13 – Diameter of mandrel and numbers of turns

Outer diameter of the PROBE WIRE (d) mm	Mandrel diameter mm	Number of turns
$d \leq 2,5$	5	6
$2,5 < d \leq 4,5$	9	6
$4,5 < d \leq 6,5$	13	6
$6,5 < d \leq 9,5$	19	4
$9,5 < d \leq 12,5$	40	2

Two samples, on their mandrels, are placed in an air oven pre-heated to a temperature $100\text{ °C} \pm 3\text{ °C}$. The samples are maintained at the specified temperature for 1 h. After the samples have been allowed to return to approximately ambient temperature, they are examined while still on the mandrel.

The other two samples are conditioned in a cold chamber for 4 h at $-10\text{ °C} \pm 2\text{ °C}$. The test is to be performed in the cold chamber where space and mounting means are available in the chamber. Where this is not practical, it is appropriate to remove a sample and a mandrel from the test chamber and perform the test outside the chamber. In either case, the winding is to be completed within 30 s of the time that the cold chamber is opened. The winding is to be done at a rate of about 3 s per turn ($18\text{ s} \pm 3\text{ s}$ for six turns), and successive turns are to be in contact with one another.

Flat PROBE WIRES are to be wrapped in a U-bend in which the sample is in contact with a mandrel having a diameter of twice the minor axis diameter of the sample for minimum 180° .

Insulated conductors as well as the finished PROBE WIRE are to be tested separately.

Circumferential depressions in the outer surface indicate cracks on the inside surface of the insulation or jacket of most materials. Circumferential depressions in a fluoropolymer surface are yield marks (locally stronger points) rather than indicators of cracking.

After this conditioning, the samples shall show no cracks when examined with normal or corrected vision without magnification, and shall meet the requirements for solid insulation.

Conformity is checked by inspection and by the a.c. voltage test of 6.6.5.1, or for PROBE WIRES stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4 for REINFORCED INSULATION without humidity preconditioning.

12.3.5 Voltage test

Six lengths of insulated PROBE WIRE or insulated conductors removed from a jacketed wire are to be tested for each specimen of wire to be evaluated. Each sample is 600 mm in length. Three of the samples are to be tested in an unaged condition. The other three samples are to be tested after air oven conditioning.

The three straight samples intended for oven ageing are to be conditioned in a circulating air oven pre-heated to a temperature $100\text{ }^{\circ}\text{C} \pm 3\text{ }^{\circ}\text{C}$. The test piece shall be maintained at the specified temperature for 1 h.

After air oven conditioning, the three specimens are to be cooled to room temperature in still air for a period of 16 h to 96 h before testing. After the cooling period, both the unaged and oven-conditioned samples are to be tested. The centre 300 mm of each sample is to be wrapped with metal foil.

Except for flat PROBE WIRES, the foil-wrapped centre section of each sample is to then be wrapped closely for six complete turns around a metal mandrel having a diameter of two times the outside diameter of the specimen or 5 mm, whichever is larger. The end of each resulting helix is to be twisted loosely together or fastened together with tape to prevent unwinding. Specimens of flat wires are to be wrapped in a U-bend in which the specimen is in contact with a mandrel having a diameter of twice the minor axis diameter of the specimen for 180° minimum.

The test voltage is applied between the conductor of the test specimen and the metal mandrel. The a.c. voltage test of 6.6.5.1, or for PROBE WIRES stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4 for REINFORCED INSULATION is then performed without humidity preconditioning. After 1 min at the specified test voltage, the test voltage is increased at a rate not exceeding 500 V/s until dielectric breakdown occurs. The dielectric breakdown voltage values are recorded separately for unaged specimens and oven-aged specimens. The average of the dielectric breakdown voltage values is calculated and recorded separately for unaged specimens and oven-aged specimens.

Samples of both unaged and oven-aged specimens shall comply with the following:

- a) unaged and oven-aged samples shall withstand the test voltage without breakdown for 1 min and
- b) the average dielectric breakdown value of oven-aged samples shall not be less than 50 % of the average breakdown value of unaged samples.

Conformity is checked by inspection and test.

12.3.6 Tensile test

12.3.6.1 General

These tests are to determine the tensile strength and elongation at break of the insulating material (exclusive of any semi-conducting layers) of the PROBE WIRE in the condition as manufactured (i.e. without any ageing treatment) and after an accelerated ageing treatment.

For the unaged samples, the median value of the tensile strengths shall be at least 7 N/mm² and the samples shall exhibit a median value of elongation of at least 100 % before they break. For the aged samples, the median value of the tensile strengths shall be at least 70 % of the result for unaged samples, and the samples shall exhibit a median value of elongation of at least 45 % of the result of the unaged samples before they break.

After the test conditioning and procedure of 12.3.6.2 to 12.3.6.6, conformity is checked by calculation of the tensile strength and the elongation at break respectively and determination of the median value of the result.

12.3.6.2 Sampling

The samples selected for the ageing treatment are from positions adjacent to the samples used for the test without ageing and the tensile tests on the aged and unaged test pieces are made in immediate succession.

One section of each core to be tested is taken of sufficient size to provide a minimum of ten samples, five each for the tensile tests without ageing and for the tensile tests after the ageing treatment, bearing in mind that a 100 mm length is needed for the preparation of each sample. The cores of flat cords are not separated. Any sample that shows signs of mechanical damage is not used for the test.

12.3.6.3 Preparation and conditioning of samples

The section of core is cut into ten samples, each approximately 100 mm long and the conductor and any outer coverings are removed, care being taken not to damage the insulation. The samples are marked to identify the section from which they were prepared and their relative positions in the section.

The centre 20 mm shall be marked immediately before the tensile test.

12.3.6.4 Determination of cross-sectional area

At the middle of the section being used to prepare the samples, a piece is taken to determine the cross-sectional area A by the following method (for samples with a round shape).

$$A = \pi \times (d - e) \times e$$

Where:

e is the mean value of the thickness of the insulation,

d is the mean value of the outer diameter of the test piece.

For samples which are to be aged, the cross-sectional area is determined before ageing treatment.

12.3.6.5 Ageing treatment

The five samples intended for oven ageing are to be conditioned in a circulating air oven pre-heated to a temperature $100\text{ °C} \pm 3\text{ °C}$. The test piece is maintained at the specified temperature for 1 h, and then allowed to cool to the temperature of 12.3.6.6.

12.3.6.6 Tensile testing procedure

The test is carried out at a temperature of $23\text{ °C} \pm 5\text{ °C}$.

The grips of the tensile testing machine may be either of a self-tightening type or not. The distance between the grips is:

- a) 50 mm for tubes, if tested with self-tightening grips;
- b) 85 mm for tubes, if tested with non-self-tightening grips.

The rate of separation shall be 250 mm/min $\pm$ 50 mm/min and, in case of doubt, 25 mm/min $\pm$ 5 mm/min.

For each sample, the maximum tensile force during the test is measured and recorded, and the distance between the two reference marks at the breaking point is measured and recorded.

The breaking of a sample due to damage in the grips, or breaking outside the reference marks is an unsatisfactory result, which is ignored. In this event, at least four valid results are required in order to calculate the tensile strength and elongation at break; otherwise the entire test procedure is repeated.

13 Prevention of HAZARD from arc flash and short-circuits

13.1 General

When a PROBE TIP or SPRING-LOADED CLIP temporarily bridges two high-energy conductors at different potentials, it could cause a high current to flow through the PROBE TIP or SPRING-LOADED CLIP which could become hot and melt. This could cause burns to an OPERATOR or a bystander.

If the bridge is opened (by OPERATOR action, melting, or other event) while the high current is flowing through the PROBE TIP or SPRING-LOADED CLIP, arcing could occur. The arcing will ionize the air, permitting continued current flow in the vicinity of the PROBE TIP or SPRING-LOADED CLIP. If there is sufficient available energy, then the ionization of the air will continue to spread and the flow of current through the air will continue to increase. The result is an arc flash, which is similar to an explosion, and can cause injury or death to an OPERATOR or a bystander.

PROBE TIPS and SPRING-LOADED CLIPS shall be constructed to reduce the risk of short-circuits and arc flashes.

Conformity is checked as specified in 13.2.

13.2 Exposed conductive parts

The exposed conductive part of a PROBE TIP shall be constructed as follows:

- a) For SPRING-LOADED CLIPS RATED for MEASUREMENT CATEGORY III or IV:
 - 1) in closed position, the exposed ACCESSIBLE conductive parts shall not exceed 4 mm (in all directions);
 - 2) in open position,
 - i) the length of the exposed ACCESSIBLE conductive parts of SPRING-LOADED CLIPS with one hook shall not exceed 10 mm,
 - ii) the outer surfaces of SPRING-LOADED CLIPS with more than one hook or jaw shall not be conductive.
- b) Except for SPRING-LOADED CLIPS RATED for MEASUREMENT CATEGORY III or IV:
 - 1) for probe assemblies RATED for MEASUREMENT CATEGORY III or IV, the exposed conductive part of a PROBE TIP shall not exceed 4 mm;
 - 2) for probe assemblies not RATED for MEASUREMENT CATEGORY II, III or IV, and for use in special applications where the energy levels will not support arc flash or fire, the exposed conductive part of a PROBE TIP shall not exceed 80 mm;

- 3) for probe assemblies RATED for MEASUREMENT CATEGORY II, and for other probe assemblies not covered by items 1) and 2), above, the exposed conductive part of a PROBE TIP shall not exceed 19 mm.

Conformity is checked by inspection and measurement of the exposed conductive parts of the PROBE TIP or jaws as follows:

- 1) *spring-loaded parts covering the conductive part of a PROBE TIP are retracted before the measurements are made;*
- 2) *moving parts other than spring-loaded parts which change the RATING and the markings of the probe assembly are evaluated in each position;*
- 3) *removable parts which change the RATING and the markings of the probe assembly are removed.*

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

Annex A (normative)

Measuring circuits for ~~ACCESSIBLE touch~~ current (see 6.3)

NOTE Annex A is based on IEC 60990, which specifies procedures for measuring touch-current, and also specifies the characteristics for test voltmeters.

A.1 Measuring circuits for a.c. with frequencies up to 1 MHz and for d.c.

The current ~~shall be~~ is measured with the circuit of Figure A.1. The current ~~shall be~~ is calculated from:

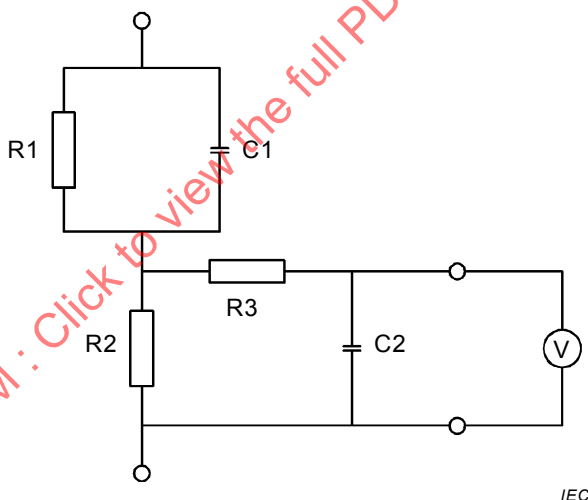
$$I = \frac{U}{500}$$

where

I is the current, in amperes;

U is the voltage, in volts, indicated by the voltmeter.

This circuit represents the impedance of the body and compensates for the change of physiological response of the body with frequency.



$R1 = 1\,500\ \Omega \pm 5\%$

$R2 = 500\ \Omega \pm 5\%$

$R3 = 10\ \text{k}\Omega \pm 5\%$

$C1 = 0,22\ \mu\text{F} \pm 10\%$

$C2 = 0,022\ \mu\text{F} \pm 10\%$

V — Voltmeter

Figure A.1 – Measuring circuit for a.c. with frequencies up to 1 MHz and for d.c.

A.2 Measuring circuits for a.c. with sinusoidal frequencies up to 100 Hz and for d.c.

If the frequency does not exceed 100 Hz, the current may be measured with the alternative circuit of Figure A.2. When using the voltmeter, the current shall be calculated from:

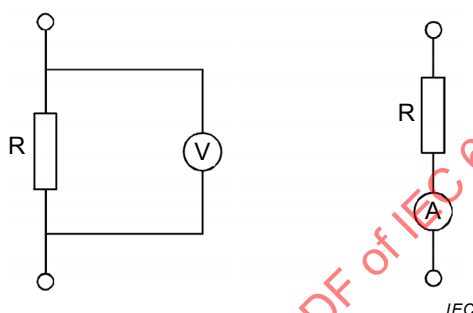
$$I = \frac{U}{2\,000}$$

where

I is the current, in amperes;

U is the voltage, in volts, indicated by the voltmeter.

The circuit represents the impedance of the body for frequencies not exceeding 100 Hz.



$$R = 2\,000\ \Omega \pm 5\%$$

V — Voltmeter

NOTE The value 2 000 Ω includes the impedance of the measuring instrument.

Figure A.2 – Measuring circuits for a.c. with sinusoidal frequencies up to 100 Hz and for d.c.

A.3 Current measuring circuit for electrical burns at ~~high~~ frequencies above 100 kHz

The current ~~shall be~~ is measured with the circuit of Figure A.3 or Figure A.4 as specified in 6.3.2, 6.3.3, or 6.3.4.3. The current ~~shall be~~ is calculated from:

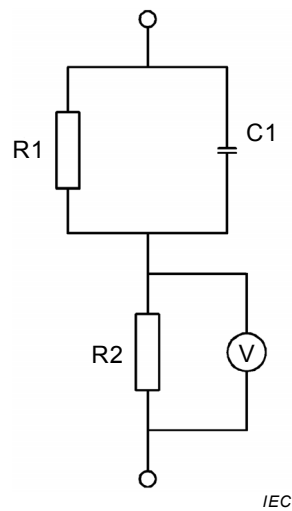
$$I = \frac{U}{500}$$

where

I is the current, in amperes;

U is the voltage, in volts, indicated by the voltmeter.

These circuits compensate for the ~~change of~~ physiological response of the body to high frequencies.



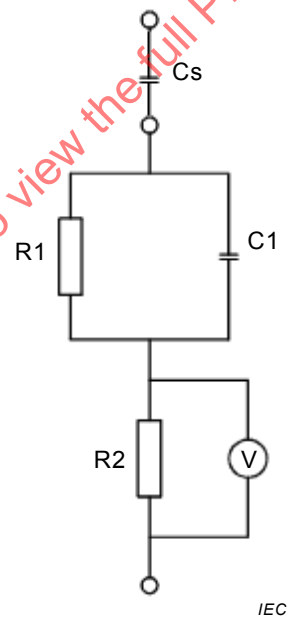
$R1 = 1\,500\ \Omega \pm 5\%$

$R2 = 500\ \Omega \pm 5\%$

$C1 = 0,22\ \mu\text{F} \pm 10\%$

V — Voltmeter

Figure A.3 – Current measuring circuit for electrical burns



$R1 = 1\,500\ \Omega \pm 5\%$

$R2 = 500\ \Omega \pm 5\%$

$C1 = 0,22\ \mu\text{F} \pm 10\%$

Cs = Capacitance between the shield and the foil (see Figure 10)

Figure A.4 – Current measuring circuit for high frequency test probes

A.4 **Current measuring circuit for WET-contact LOCATIONS**

For WET-contact LOCATIONS the current is measured using the circuit of Figure A.5 ~~shall be used~~. The current is calculated from:

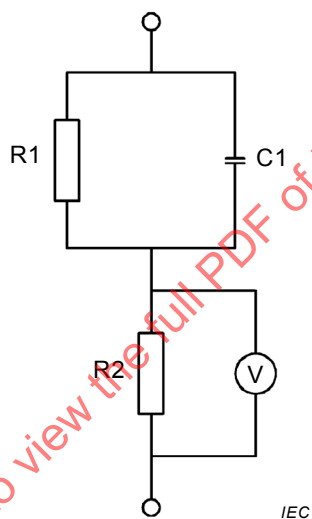
$$I = \frac{U}{500}$$

where

I is the current, in amperes;

U is the voltage, in volts, indicated by the voltmeter.

~~This circuit represents the impedance of the body when there is no skin contact resistance.~~



$R1 = 375 \, \Omega \pm 5 \, \%$

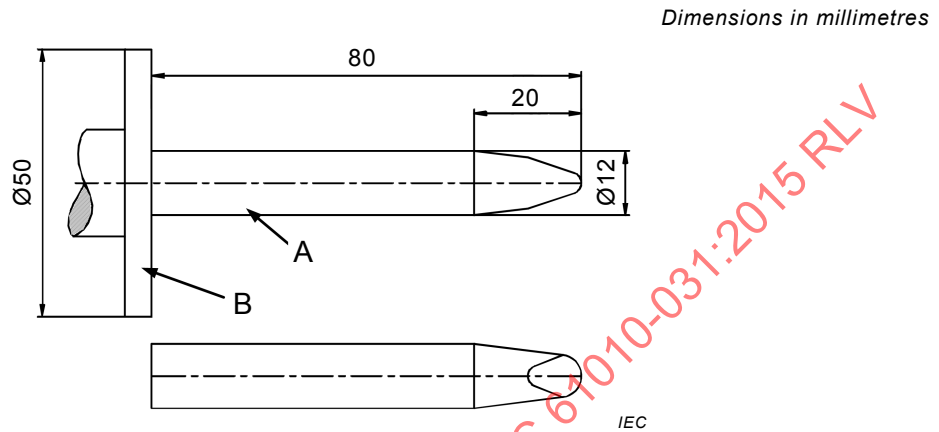
$R2 = 500 \, \Omega \pm 5 \, \%$

$C1 = 0,22 \, \mu\text{F} \pm 10 \, \%$

Figure A.4 A.5 – Current measuring circuit for WET-contact LOCATIONS

Annex B (normative)

Standard test fingers (see 6.2)



Key

A Metal

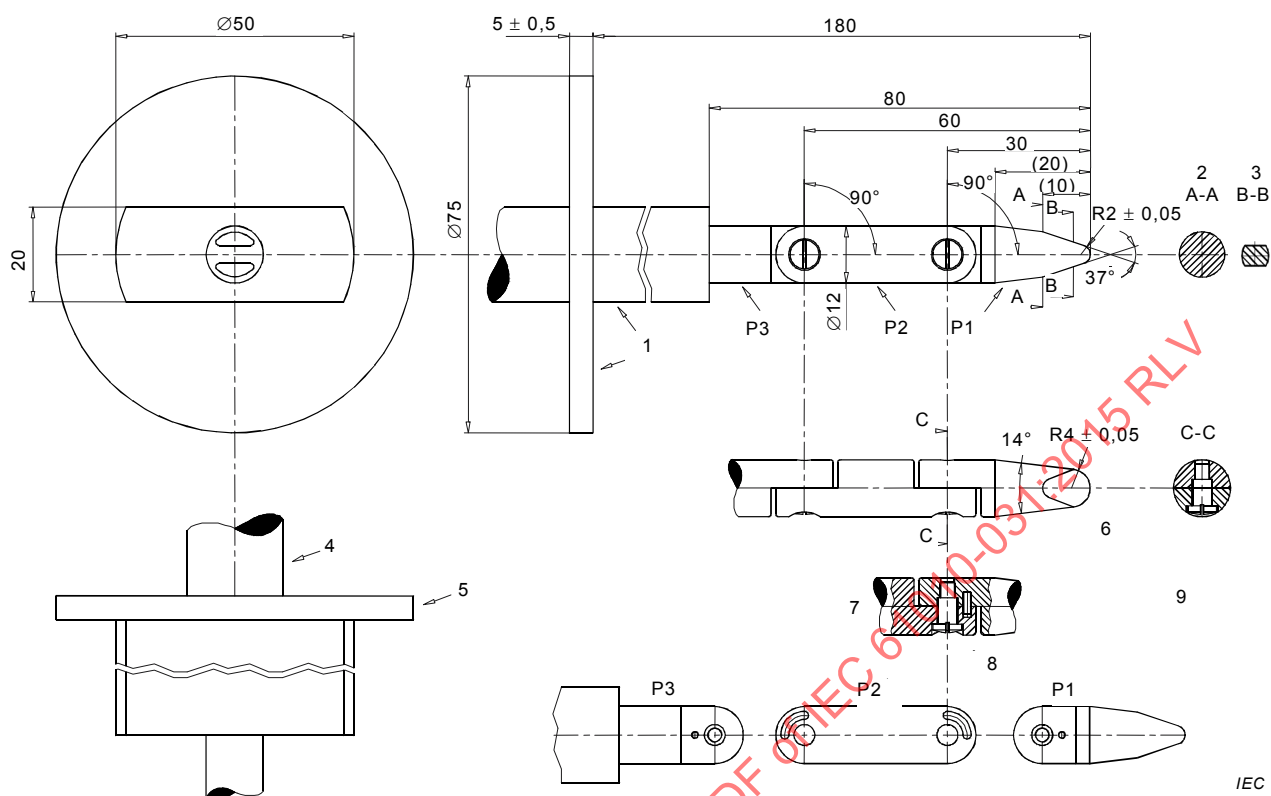
B Insulating material

For tolerances and dimensions of the fingertip, see Figure B.2.

NOTE This test finger is identical to test probe 11 from IEC 61032.

Figure B.1 – Rigid test finger

Dimensions in millimetres

**Key**

- | | |
|-----------------------|----------------------|
| 1 insulating material | 6 spherical |
| 2 section AA | 7 detail × (example) |
| 3 section BB | 8 side view |
| 4 handle | 9 chamfer all edges |
| 5 stop plate | |

Figure B.2 – Jointed test finger

Tolerances on dimensions without specific tolerance:

on angles: $\begin{matrix} 0 \\ -10' \end{matrix}$

on linear dimensions:

up to 25 mm: $\begin{matrix} 0 \\ -0.05 \end{matrix}$ mm

over 25 mm: ± 0.2 mm

Material of finger: heat-treated steel, etc.

Both joints of this finger may be bent through an angle of $(90^{+10}_0)^\circ$ but in one and the same direction only.

Using the pin and groove solution is only one of the possible approaches in order to limit the bending angle to 90° . For this reason, dimensions and tolerances of these details are not given in the drawing. The actual design shall ensure a $(90^{+10}_0)^\circ$ bending angle.

NOTE This test finger is identical to test probe B from [Figure 2](#) of IEC 61032:1997.

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

Annex C (normative)

Measurement of CLEARANCES and CREEPAGE DISTANCES

The methods of measuring CLEARANCES and CREEPAGE DISTANCES are indicated in Examples 1 to ~~11~~ 7. These cases do not differentiate between gaps and grooves or between types of insulation.

~~The width X of grooves specified in Examples 1 to 11 apply to all examples as a function of the POLLUTION degrees given in Table C.1.~~

In the following examples dimension X has the value given in Table C.1 depending on the POLLUTION DEGREE.

Table C.1 – ~~Relation between POLLUTION degrees and width of grooves~~ Dimension of X

POLLUTION DEGREE	~~Width X of grooves, minimum values~~ Dimension X mm
1	0,25
2	1,0
3	1,5

If the associated CLEARANCE is less than 3 mm, the ~~minimum groove width shall~~ dimension X in Table C.1 may be reduced to one-third of this CLEARANCE.

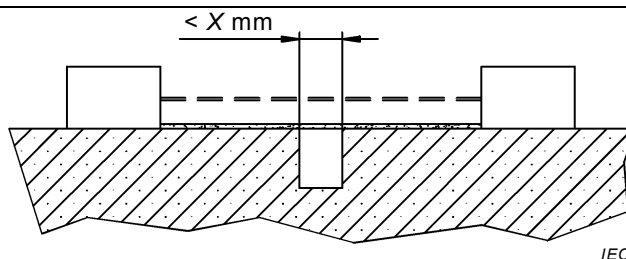
~~The following assumptions are made:~~

- ~~a) if the distance across a groove is equal to, or larger than, the specified width X, the CREEPAGE DISTANCE is measured along the contours of the groove (see example 2);~~
- ~~b) any recess is assumed to be bridged with an insulating link having a length equal to the specified width X and being placed in the most unfavourable position (see example 3);~~
- ~~d) CREEPAGE DISTANCES and CLEARANCES measured between parts which can assume different positions in relation to each other, are measured when these parts are in their most unfavourable position.~~

Example 1:

The path includes a parallel- or converging-sided groove of any depth with a width less than X mm.

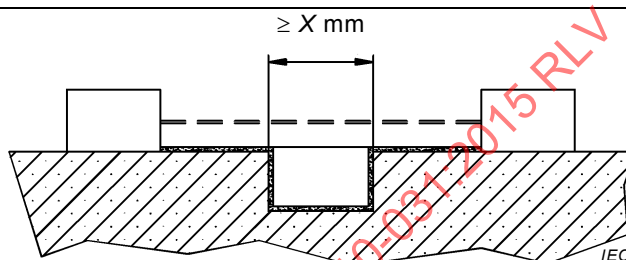
The CLEARANCE and CREEPAGE DISTANCE are measured directly across the groove as shown.



Example 2:

The path includes a parallel-sided groove of any depth and equal to, or ~~more~~ greater than, X mm.

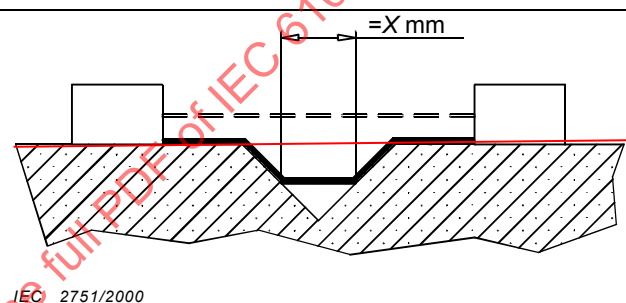
CLEARANCE is the "line-of-sight" distance. The CREEPAGE DISTANCE follows the contour of the groove.



Example 3:

~~The path includes a V-shaped groove with a width greater than X .~~

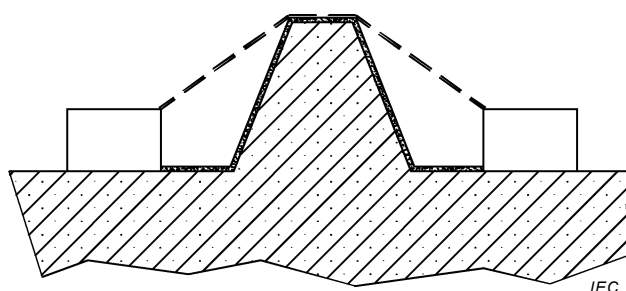
~~The CLEARANCE is the "line-of-sight" distance. The CREEPAGE DISTANCE follows the contour of the groove but "short-circuits" the bottom of the groove by X link.~~



Example 3:

The path includes a rib.

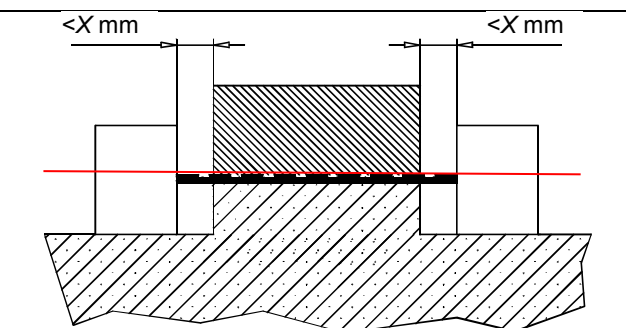
The CLEARANCE is the shortest direct air path over the top of the rib. The CREEPAGE DISTANCE follows the contour of the rib.



Example 5:

~~The path includes an uncemented joint with grooves less than X wide on each side.~~

~~The CLEARANCE and the CREEPAGE DISTANCE path is the "line-of-sight" distance shown.~~

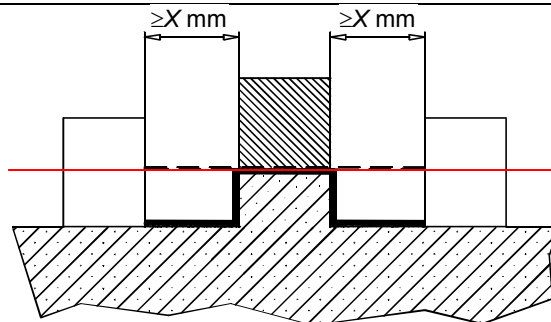


Example 6:

The path includes an uncemented joint with grooves equal to, or more than, X.

The CLEARANCE is the "line-of-sight" distance.

The CREEPAGE DISTANCE follows the contour of the grooves.

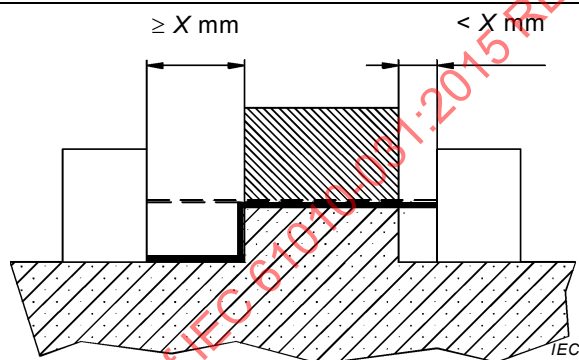


IEC 2754/2000

Example 4:

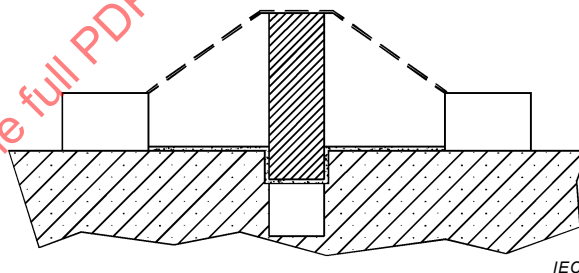
The path includes an uncemented joint with a groove on each one side less than X wide and the groove on the other side equal to, or greater than, X wide.

The CLEARANCE and the CREEPAGE DISTANCE is the "line-of-sight" distance are as shown.

**Example 5:**

The CLEARANCE is the shortest direct air path over the top of the barrier.

The CREEPAGE DISTANCE through the uncemented joint is less than the CREEPAGE DISTANCE over the barrier.

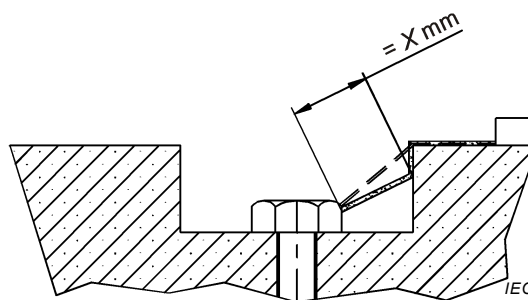


IEC

Example 6:

The gap between the head of the screw and the wall of the recess is too narrow to be taken into account.

Measurement of the CREEPAGE DISTANCE is from screw to wall when the distance is equal to X.

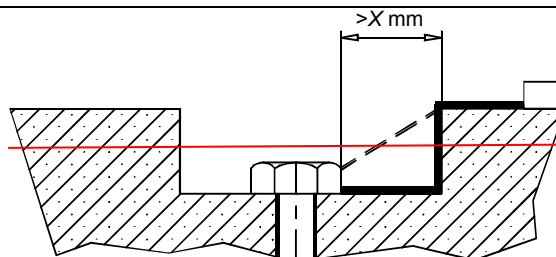


IEC

Example 10:

The gap between the head of the screw and the wall of the recess wide enough to be taken into account.

Measurement of the CREEPAGE DISTANCE is from screw to wall when the distance is equal to X.



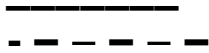
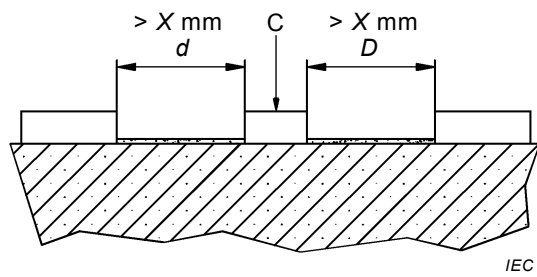
IEC 2758/2000

Example 7:

C is a floating part.

The CLEARANCE is the distance $d + D$.

The CREEPAGE DISTANCE is also $d + D$



CREEPAGE DISTANCE

CLEARANCE

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

Annex D (normative)

Routine spark tests on PROBE WIRE

D.1 General

The spark test shall be performed by the manufacturer as a ROUTINE TEST on 100 % of the PROBE WIRE in accordance with the following spark test procedure and routine spark test method for PROBE WIRE.

D.2 Spark test procedure

A d.c. or a.c. spark tester shall include a voltage source, an electrode, a voltmeter, a system for detecting and counting signalling faults, and the appropriate electrical connections.

The voltage source of a d.c. or a.c. spark tester shall maintain the following test voltage under all NORMAL CONDITIONS of leakage current:

- a) a sinusoidal or nearly sinusoidal r.m.s. voltage specified for an a.c. test of the wire type;
- b) the voltage specified for a d.c. test of the wire type. The d.c. power supply output current capability shall not exceed 5 mA. Any ripple shall not exceed 1 %. After a fault, the d.c. test voltage shall recover to the specified level within 5 ms unless 610 mm or less of the product travels through the electrode in the time it takes for the full voltage recovery.

One TERMINAL of the d.c. power supply, the core of a transformer, and one end of the secondary winding in an a.c. power supply shall be solidly connected to earth. A voltage source shall not be connected to more than one electrode.

The electrode of a d.c. or a.c. spark tester shall be of the link- or bead-chain type or shall be of another evaluated and approved type. A link- or bead-chain electrode shall make intimate contact throughout its entire length with the surface of the insulated conductor being tested.

The bottom of a metal link- or bead-chain electrode enclosure shall be U- or V-shaped, the chains shall have a length appreciably greater than the depth of the enclosure, and the width of the trough shall be greater (typically 40 mm) than the diameter of the largest PROBE WIRE being tested.

For a bead-chain electrode, the longitudinal and transverse spacings of the chains and the diameter of each bead shall comply with Table D.1 (see also Figure D.1). The vertical spacing between beads in each chain shall not exceed the diameter of a bead.

Table D.1 – Maximum centre-to-centre spacings of bead chains

Diameter of a bead ^a	Longitudinal spacing within each row ^a	Transverse spacing between rows ^a	
		Chains staggered	Chains unstaggered
mm	mm	mm	mm
5,0	13	13	10
2,5	b	b	b

^a Other diameters and spacings are also acceptable if investigation shows that the chains contact an equal or greater area of the outer surface of the insulated conductor or initial assembly of conductors.

^b The chains shall be staggered and shall touch one another in the longitudinal and transverse directions.

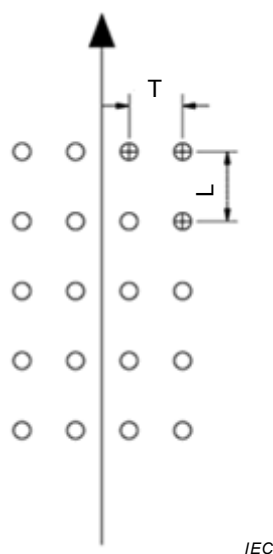


Figure D.1a – Chains unstaggered

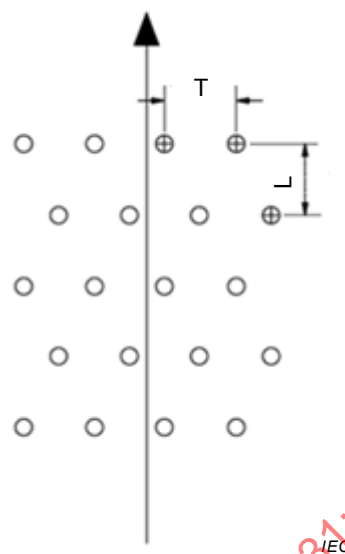


Figure D.1b – Chains staggered

Key

A Wire centre

T Transverse spacing

L Longitudinal spacing

Figure D.1 – Bead Chain Configuration (if applicable)

The electrode shall have an earthed metal screen or an equivalent guard that protects operating personnel against electric shock from the electrode and associated live parts.

The voltmeter shall be connected in the circuit to indicate the actual test potential at all times.

The test equipment shall include a fault detector, fault counter, and a means of signalling each fault that occurs. When a fault is detected, the signal shall be maintained until the indicator is reset manually.

The fault detector shall detect a voltage breakdown of the insulation. A breakdown is characterized by arcing between the electrode and the earthed conductor(s) under test. A breakdown is defined as a decrease of 25 % or more from the test voltage applied between the electrode and the earthed conductor(s). The output current of the test equipment shall not exceed 5 mA.

The fault detector shall consist of a trigger circuit that converts an input pulse of short time duration to an output pulse of a magnitude and duration that reliably operates the fault-indicating circuit.

The fault counter shall accumulate the faults as a numerically increasing sequence and shall display the accumulated total. The response time of the fault counter shall result in the counter registering faults spaced no farther than 610 mm apart for any combination of product speed and counter response time. This distance is to be calculated as follows:

$$D = S \times t$$

Where:

D = distance between faults

S = product speed as $0,656 \times \text{m/min}$

t = counter response time in seconds

For a d.c. test using a link- or bead-chain electrode, the surface of the insulated conductor(s) shall be in intimate contact with the link or bead chains for a distance of $125 \text{ mm} \pm 25 \text{ mm}$.

The length of a link- or bead-chain electrode is not specified for an a.c. test; however, the rate of speed at which the insulated conductor travels through the electrode shall keep any point on the product in contact with the electrode for not less than a total of 18 positive and negative crests of the a.c. supply voltage (the equivalent of a full 9 cycles of the a-c supply voltage). The maximum speed V of the product is to be determined for an a.c. test by means of the following formula:

$$V = (F \times L) / 150$$

Where:

V = speed in m/min

F = frequency in Hz

L = electrode length in mm

For convenience, Table D.2 shows the formulas for seven frequencies.

Table D.2 – Formula for maximum speed of wire in terms of electrode length L of link- or bead-chain electrode

Nominal supply frequency F (Hz)	Speed V (m/min) with electrode length L (mm)
50	$0,333 \cdot L$
60	$0,400 \cdot L$
100	$0,667 \cdot L$
400	$2,67 \cdot L$
1 000	$6,67 \cdot L$
3 000	$20,9 \cdot L$
4 000	$26,7 \cdot L$

The conductor being tested shall be earthed during the spark test. Where the conductor coming from the pay-off reel is bare, the conductor shall be earthed at the pay-off reel or at another point at which continuous contact with the bare conductor, prior to the insulating process, is maintained and the conductor is not required to be tested for continuity or earthed at the take-up reel. Where the conductor coming from a pay-off reel is insulated, an earth connection shall be made at each pay-off reel and at the take-up reel. The earth connection shall be bonded to the protective earth TERMINAL in the spark tester.

D.3 Routine spark test method for PROBE WIRE

For single-conductor wires with other than extruded insulation, the potential shall be 1 500 V if the wire is RATED for 300 V and shall be 2 000 V if the wire is RATED for 600 V.

For all other wires and insulations, the potential shall be 10 times the voltage RATING of the wire, up to 1 000 V, with a minimum potential of 1 500 V. If the RATED voltage is not specified, the potential shall be 3 000 V. For wire RATED more than 1 000 V, the potential shall be two times the RATED voltage with a minimum potential of 10 000 V. Insulated conductors or the insulated conductors of a jacketed wire shall be tested. In the case of a jacketed wire, the insulated conductors shall be tested prior to the application of the overall jacket or covering.

The spark test shall be performed at some point prior to the wire being cut to its final length or before being cut into shipping lengths.

Any faults shall be cut out or repaired. The insulation at points of repair shall be retested.

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

Annex E (informative)

4 mm CONNECTORS

E.1 General

HAZARDS may arise from an OPERATOR's reliance on values displayed by the equipment when CONNECTORS appear to be in mated position but conductive parts are not in contact.

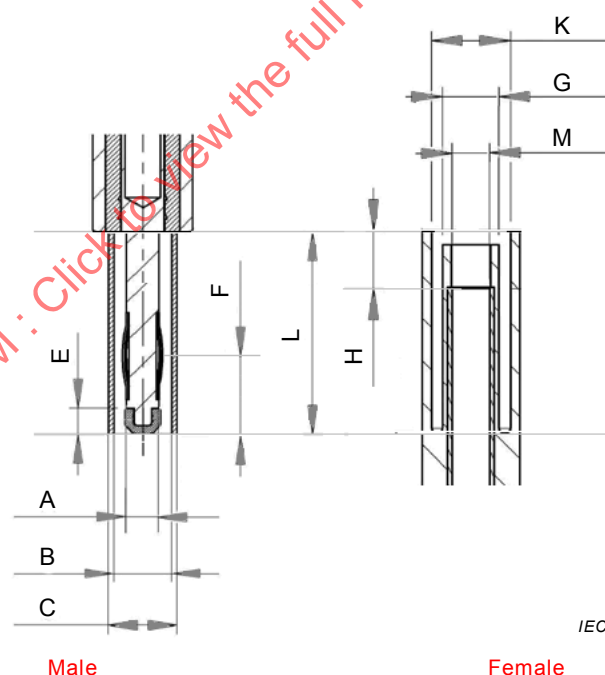
Annex E gives the recommended dimensions for safety purposes of 4 mm CONNECTORS when used on probe assemblies and equipment to which probe assemblies can be connected. These 4 mm CONNECTORS are often called “banana connectors” or “banana plugs”.

E.2 Dimensions

The dimensions of Figure E.1 are compatible with 4 mm CONNECTORS RATED for MEASUREMENT CATEGORIES II, III or IV up to 1 000 V.

These dimensions ensure that SPACINGS of 6.4.2 are met when the CONNECTORS are mated, unmated or partially mated, and conductive parts of mated CONNECTORS are in contact.

NOTE Extraction or insertion forces and contact resistance values have not been considered.



Key:

A = 3,90 mm $\pm$ 0,05 mm (compressed)

 $B \geq 6.6 \text{ mm}$
$$C \leq 7,9 \text{ mm}$$
$$2,6 \text{ mm} \leq E \leq 6 \text{ mm}$$
$$F \leq 12 \text{ mm}$$
$$M = 4,00 \text{ mm} + 0,05 \text{ mm}$$

$G \leq 6.4 \text{ mm}$

 $K \geq 8,1 \text{ mm}$
$$4 \text{ mm} \leq H \leq 6 \text{ mm}$$
 $L \geq 20 \text{ mm}$

Figure E.1 – Recommended dimensions of 4 mm CONNECTORS

Tolerances on dimensions without specific tolerances: $\pm 0,1$ mm

- F is the point where the best contact occurs
- A is the maximum diameter where the contact occurs
- Minimum value of E and H depends of the presence of plastic parts. SPACINGS shall be at least 2,6 mm

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

Annex F (normative)

Measurement Categories

F.1 General

For the purposes of this standard, the following MEASUREMENT CATEGORIES are used. These MEASUREMENT CATEGORIES are not the same as the OVERVOLTAGE CATEGORIES according to Annex K of IEC 61010-1:2010 and IEC 60664-1, or the impulse withstand categories (overvoltage categories) according to IEC 60364-4-44.

NOTE 1 IEC 60664-1 and IEC 60364-4-44 categories are created to achieve an insulation coordination of the components and equipment used within the low-voltage MAINS supply system.

NOTE 2 MEASUREMENT CATEGORIES are based on locations on the MAINS supply system where measurements can be made.

F.2 MEASUREMENT CATEGORIES

F.2.1 MEASUREMENT CATEGORY II

MEASUREMENT CATEGORY II is applicable to test and measuring circuits connected directly to utilization points (socket outlets and similar points) of the low-voltage mains installation (see Table F.1 and Figure F.1).

EXAMPLE Measurements on MAINS CIRCUITS of household appliances, portable tools and similar equipment, and on the consumer side only of socket-outlets in the fixed installation.

F.2.2 MEASUREMENT CATEGORY III

MEASUREMENT CATEGORY III is applicable to test and measuring circuits connected to the distribution part of the building's low-voltage mains installation (see Table F.1 and Figure F.1).

To avoid risks caused by the HAZARDS arising from these higher short-circuit currents, additional insulation and other provisions are required.

EXAMPLE Measurements on distribution boards (including secondary meters), photovoltaic panels, circuit-breakers, wiring, including cables, bus-bars, junction boxes, switches, socket-outlets in the fixed installation, and equipment for industrial use and some other equipment such as stationary motors with permanent connection to the fixed installation.

NOTE For equipment that is part of a fixed installation, the fuse or circuit breaker of the installation can be considered to provide adequate protection against short-circuit currents.

F.2.3 MEASUREMENT CATEGORY IV

MEASUREMENT CATEGORY IV is applicable to test and measuring circuits connected at the source of the building's low-voltage mains installation (see Table F.1 and Figure F.1).

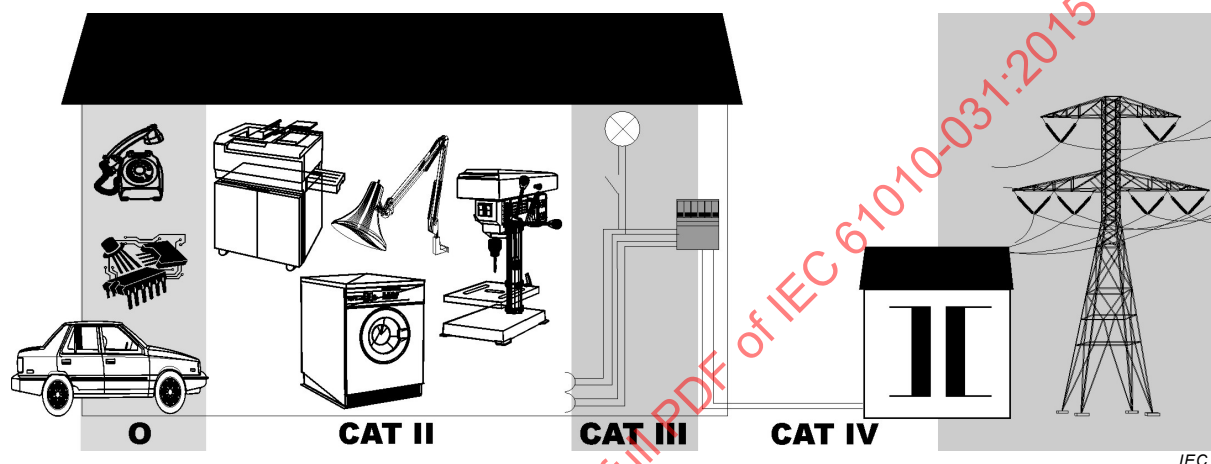
Due to these high short-circuit currents which can be followed by a high energy level, measurements made within these locations are extremely dangerous. Great precautions shall be made to avoid any chance of a short circuit.

EXAMPLE Measurements on devices installed before the main fuse or circuit breaker in the building installation.

F.2.4 Probe assemblies without a MEASUREMENT CATEGORY RATING

Many types of test and measuring circuits are not intended to be directly connected to the mains supply. Some of these measuring circuits are intended for very low energy applications, but others of these measuring circuits may experience very high amounts of available energy because of high short-circuit currents or high open-circuit voltages. There are no standard transient levels defined for these circuits. An analysis of the WORKING VOLTAGES, loop impedances, temporary overvoltages, and transient overvoltages in these circuits is necessary to determine the insulation requirements and short-circuit current requirements.

EXAMPLE Thermocouple measuring circuits, high-frequency measuring circuits, automotive testers, and testers used to characterize the mains installation before the installation is connected to the mains supply.



Key

- O Other circuits that are not directly connected to mains
- CAT II MEASUREMENT CATEGORY II
- CAT III MEASUREMENT CATEGORY III
- CAT IV MEASUREMENT CATEGORY IV

Figure F.1 – Example to identify the locations of MEASUREMENT CATEGORIES

Table F.1 – Characteristics of MEASUREMENT CATEGORIES

MEASUREMENT CATEGORY	Short-circuit current ^a (typical) kA	Location in the building installation
II	< 10	Circuits connected to mains socket outlets and similar points in the mains installation
III	< 50	Mains distribution parts of the building
IV	> 50	Source of the mains installation in the building

^a The values of loop impedances (installation impedances) do not take into account the resistance of the test leads and impedances internal to the measuring equipment. These short-circuit currents vary, depending on the characteristics of the installation.

Annex G

Index of defined terms

Term	Definition
ACCESSIBLE (of a part)	3.4.1
~~BARRIER~~	~~3.1.3~~
BASIC INSULATION	3.5.1
~~CONNECTOR~~	~~3.1.5~~
CLEARANCE	3.5.10
CREEPAGE DISTANCE	3.5.11
DOUBLE INSULATION	3.5.3
ENCLOSURE	3.1.2
HAZARD	3.4.3
HAZARDOUS LIVE	3.4.2
~~HIGH INTEGRITY~~	~~3.4.3~~
~~MEASUREMENT CATEGORY~~	~~3.4.11~~
NORMAL CONDITION	3.4.6
NORMAL USE	3.4.5
OPERATOR	3.4.8
POLLUTION	3.5.5
POLLUTION DEGREE	3.5.6
POLLUTION DEGREE 1	3.5.7
POLLUTION DEGREE 2	3.5.8
POLLUTION DEGREE 3	3.5.9
~~PROBE ASSEMBLY~~	~~3.1.4~~
PROBE TIP	3.1.4
~~PROBE WIRE~~	~~3.1.7~~
~~PROTECTIVE FINGERGUARD~~	~~3.1.3~~
PROTECTIVE IMPEDANCE	3.4.4
RATED (value)	3.2.1
RATING	3.2.2
~~REFERENCE CONNECTOR~~	~~3.1.6~~
~~REASONABLY FORESEEABLE MISUSE~~	~~3.4.12~~
REINFORCED INSULATION	3.5.4
RESPONSIBLE BODY	3.4.9
~~ROUTINE TEST~~	~~3.3.2~~
SINGLE FAULT CONDITION	3.4.7
~~SPACING~~	~~3.5.12~~
~~SPRING-LOADED CLIP~~	~~3.1.8~~
~~STACKABLE CONNECTOR~~	~~3.1.9~~
SUPPLEMENTARY INSULATION	3.5.2
TERMINAL	3.1.1

TOOL	3.1.6
TYPE TEST	3.3.1
WET LOCATION	3.4.10
WORKING VOLTAGE.....	3.2.3

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

Bibliography

IEC 60050-151:2001, *International Electrotechnical Vocabulary – Part 151: Electrical and magnetic devices*

IEC 60050-195:1998, *International Electrotechnical Vocabulary – Part 195: Earthing and protection against electric shock*

IEC 60065, *Audio, video and similar electronic apparatus – Safety requirements*

IEC 60270, *High-voltage test techniques – Partial discharge measurements*

IEC 60364-4-44, *Low-voltage electrical installations – Part 4-44: Protection for safety – Protection against voltage disturbances and electromagnetic disturbances*

IEC 60417, *Graphical symbols for use on equipment* (available at: <http://www.graphical-symbols.info/equipment>)

IEC 60664-1, *Insulation coordination for equipment within low-voltage systems – Part 1: Principles, requirements and tests*

~~IEC 61032, *Protection of persons and equipment by enclosures – Probes for verification*~~

IEC 60664-3:2003, *Insulation coordination for equipment within low-voltage systems – Part 3: Use of coating, potting or moulding for protection against pollution*
IEC 60664-3:2003/AMD1:2010

IEC 60664-4:2005, *Insulation coordination for equipment within low-voltage systems – Part 4: Consideration of high-frequency voltage stress*

IEC 60990, *Methods of measurement of touch current and protective conductor current*

IEC 61010 (all parts), *Safety requirements for electrical equipment for measurement, control and laboratory use*

IEC 61032:1997, *Protection of persons and equipment by enclosures – Probes for verification*

ISO 7000, *Graphical symbols for use on equipment* (available at: <http://www.iso.org/obp>)

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

INTERNATIONAL STANDARD

NORME INTERNATIONALE



GROUP SAFETY PUBLICATION
PUBLICATION GROUPEE DE SÉCURITÉ

Safety requirements for electrical equipment for measurement, control and laboratory use –

Part 031: Safety requirements for hand-held probe assemblies for electrical measurement and test

Règles de sécurité pour appareils électriques de mesure, de régulation et de laboratoire –

Partie 031: Exigences de sécurité pour sondes équipées tenues à la main pour mesurage et essais électriques

CONTENTS

FOREWORD.....	7
1 Scope and object.....	10
1.1 Scope	10
1.1.1 Probe assemblies included in scope	10
1.1.2 Probe assemblies excluded from scope	13
1.2 Object.....	13
1.2.1 Aspects included in scope	13
1.2.2 Aspects excluded from scope	13
1.3 Verification.....	13
1.4 Environmental conditions	13
1.4.1 Normal environmental conditions	13
1.4.2 Extended environmental conditions	13
2 Normative references	14
3 Terms and definitions	14
3.1 Parts and accessories.....	14
3.2 Quantities	15
3.3 Tests	16
3.4 Safety terms	16
3.5 Insulation	17
4 Tests	18
4.1 General.....	18
4.2 Sequence of tests	19
4.3 Reference test conditions.....	19
4.3.1 Environmental conditions.....	19
4.3.2 State of probe assemblies.....	19
4.3.3 Position of the probe assembly	19
4.3.4 Accessories.....	20
4.3.5 Covers and removable parts	20
4.3.6 Input and output voltages	20
4.3.7 Controls.....	20
4.3.8 Connections	20
4.3.9 Duty cycle.....	20
4.4 Testing in SINGLE FAULT CONDITION.....	20
4.4.1 General	20
4.4.2 Application of fault conditions	20
4.4.3 Duration of tests	21
4.4.4 Conformity after application of fault conditions.....	21
4.5 Tests in REASONABLY FORESEEABLE MISUSE	22
4.5.1 General	22
4.5.2 Fuses	22
5 Marking and documentation.....	22
5.1 Marking.....	22
5.1.1 General	22
5.1.2 Identification	22
5.1.3 Fuses	23
5.1.4 CONNECTORS and operating devices.....	24

5.1.5	RATING	24
5.2	Warning markings	24
5.3	Durability of markings	24
5.4	Documentation	25
5.4.1	General	25
5.4.2	Probe assembly RATING	25
5.4.3	Probe assembly operation	25
5.4.4	Probe assembly maintenance and service	26
6	Protection against electric shock	26
6.1	General	26
6.2	Determination of ACCESSIBLE parts	27
6.2.1	General	27
6.2.2	Examination	27
6.2.3	Openings for pre-set controls	28
6.3	Limit values for ACCESSIBLE parts	28
6.3.1	General	28
6.3.2	Levels in NORMAL CONDITION	29
6.3.3	Levels in SINGLE FAULT CONDITION	29
6.3.4	Measurement of voltage and touch current	31
6.4	Means of protection against electric shock	34
6.4.1	General	34
6.4.2	CONNECTORS	35
6.4.3	PROBE TIPS	36
6.4.4	Impedance	38
6.4.5	PROTECTIVE IMPEDANCE	38
6.4.6	BASIC INSULATION, SUPPLEMENTARY INSULATION, DOUBLE INSULATION and REINFORCED INSULATION	39
6.5	Insulation requirements	39
6.5.1	The nature of insulation	39
6.5.2	Insulation requirements for probe assemblies	44
6.6	Procedure for voltage tests	50
6.6.1	General	50
6.6.2	Humidity preconditioning	50
6.6.3	Conduct of tests	50
6.6.4	Test voltages	51
6.6.5	Test procedures	53
6.7	Constructional requirements for protection against electric shock	54
6.7.1	General	54
6.7.2	Insulating materials	54
6.7.3	ENCLOSURES of probe assemblies with DOUBLE INSULATION or REINFORCED INSULATION	54
6.7.4	PROBE WIRE attachment	54
7	Protection against mechanical HAZARDS	58
8	Resistance to mechanical stresses	58
8.1	General	58
8.2	Rigidity test	59
8.3	Drop test	59
8.4	Impact swing test	59
9	Temperature limits and protection against the spread of fire	60

9.1	General.....	60
9.2	Temperature tests.....	61
10	Resistance to heat.....	61
10.1	Integrity of SPACINGS	61
10.2	Resistance to heat.....	61
11	Protection against HAZARDS from fluids	61
11.1	General.....	61
11.2	Cleaning	61
11.3	Specially protected probe assemblies	62
12	Components	62
12.1	General.....	62
12.2	Fuses.....	62
12.3	PROBE WIRE.....	63
12.3.1	General	63
12.3.2	RATING of PROBE WIRE	63
12.3.3	Pressure test at high temperature for insulations	63
12.3.4	Tests for resistance of insulation to cracking	65
12.3.5	Voltage test	65
12.3.6	Tensile test.....	66
13	Prevention of HAZARD from arc flash and short-circuits.....	68
13.1	General.....	68
13.2	Exposed conductive parts	68
Annex A	(normative) Measuring circuits for touch current (see 6.3).....	69
A.1	Measuring circuits for a.c. with frequencies up to 1 MHz and for d.c.	69
A.2	Measuring circuits for a.c. with sinusoidal frequencies up to 100 Hz and for d.c.	69
A.3	Current measuring circuit for electrical burns at frequencies above 100 kHz	70
A.4	Current measuring circuit for WET LOCATIONS	71
Annex B	(normative) Standard test fingers	73
Annex C	(normative) Measurement of CLEARANCES and CREEPAGE DISTANCES.....	76
Annex D	(normative) Routine spark tests on PROBE WIRE.....	78
D.1	General.....	78
D.2	Spark test procedure.....	78
D.3	Routine spark test method for PROBE WIRE	80
Annex E	(informative) 4 mm CONNECTORS	82
E.1	General.....	82
E.2	Dimensions	82
Annex F	(normative) MEASUREMENT CATEGORIES	84
F.1	General.....	84
F.2	MEASUREMENT CATEGORIES	84
F.2.1	MEASUREMENT CATEGORY II.....	84
F.2.2	MEASUREMENT CATEGORY III.....	84
F.2.3	MEASUREMENT CATEGORY IV	84
F.2.4	Probe assemblies without a MEASUREMENT CATEGORY RATING.....	85
Annex G	Index of defined terms	86
Bibliography		87

Figure 1 – Examples of type A probe assemblies	11
Figure 2 – Examples of type B probe assemblies	11
Figure 3 – Examples of type C probe assemblies	12
Figure 4 – Examples of type D probe assemblies	12
Figure 5 – Example of a STACKABLE CONNECTOR with a male CONNECTOR and a female TERMINAL	15
Figure 6 – Methods for determination of ACCESSIBLE parts (see 6.2) and for voltage tests of (see 6.4.2)	28
Figure 7 – Capacitance level versus voltage in NORMAL CONDITION and SINGLE-FAULT CONDITION (see 6.3.2 c) and 6.3.3 c))	30
Figure 8 – Voltage and touch current measurement	31
Figure 9 – Voltage and touch current measurement for the reference CONNECTOR	32
Figure 10 – Voltage and touch current measurement with shielded test probe	33
Figure 11 – Maximum test probe input voltage for 70 mA touch current	34
Figure 12 – Protection by a PROTECTIVE FINGERGUARD	37
Figure 13 – Protection by distance	37
Figure 14 – Protection by tactile indicator	38
Figure 15 – Distance between conductors on an interface between two layers	42
Figure 16 – Distance between adjacent conductors along an interface of two layers	42
Figure 17 – Distance between adjacent conductors located between the same two layers	44
Figure 18 – Example of recurring peak voltage	47
Figure 19 – Flexing test	56
Figure 20 – Rotational flexing test	58
Figure 21 – Impact swing test	60
Figure 22 – Indentation device	64
Figure A.1 – Measuring circuit for a.c. with frequencies up to 1 MHz and for d.c.	69
Figure A.2 – Measuring circuits for a.c. with sinusoidal frequencies up to 100 Hz and for d.c.	70
Figure A.3 – Current measuring circuit for electrical burns	71
Figure A.4 – Current measuring circuit for high frequency test probes	71
Figure A.5 – Current measuring circuit for WET LOCATIONS	72
Figure B.1 – Rigid test finger	73
Figure B.2 – Jointed test finger	74
Figure D.1 – Bead Chain Configuration (if applicable)	79
Figure E.1 – Recommended dimensions of 4 mm CONNECTORS	82
Figure F.1 – Example to identify the locations of MEASUREMENT CATEGORIES	85
Table 1 – Symbols	23
Table 2 – SPACINGS for unmated CONNECTORS RATED up to 1 000 V a.c. or 1 500 V d.c. with HAZARDOUS LIVE conductive parts	36
Table 3 – Multiplication factors for CLEARANCES of probe assembly RATED for operation at altitudes up to 5 000 m	40
Table 4 – Test voltages for testing solid insulation	41
Table 5 – Minimum values for distance or thickness	43

Table 6 – CLEARANCES for probe assemblies of MEASUREMENT CATEGORIES II, III and IV	44
Table 7 – CLEARANCE values for the calculation of 6.5.2.3.2.....	46
Table 8 – CLEARANCES for BASIC INSULATION in probe assemblies subjected to recurring peak voltages or WORKING VOLTAGES with frequencies above 30 kHz.....	48
Table 9 – CREEPAGE DISTANCES for BASIC INSULATION or SUPPLEMENTARY INSULATION	49
Table 10 – Test voltages based on CLEARANCES.....	52
Table 11 – Correction factors according to test site altitude for test voltages for CLEARANCES	53
Table 12 – Pull forces for PROBE WIRE attachment tests.....	57
Table 13 – Diameter of mandrel and numbers of turns	65
Table C.1 – Dimension of X	76
Table D.1 – Maximum centre-to-centre spacings of bead chains	78
Table D.2 – Formula for maximum speed of wire in terms of electrode length L of link- or bead-chain electrode	80
Table F.1 – Characteristics of MEASUREMENT CATEGORIES.....	85

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT
FOR MEASUREMENT, CONTROL AND LABORATORY USE –****Part 031: Safety requirements for hand-held
probe assemblies for electrical measurement and test**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 61010-031 has been prepared by IEC technical committee 66: Safety of measuring, control and laboratory equipment.

It has the status of a group safety publication in accordance with IEC GUIDE 104.

IEC 61010-031 is a stand-alone standard. This second edition cancels and replaces the first edition published in 2002 and Amendment 1:2008. This edition constitutes a technical revision.

This edition includes the following significant changes from the first edition, as well as numerous other changes:

- a) Voltages above the levels of 30 V r.m.s., 42,4 V peak, or 60 V d.c. are deemed to be HAZARDOUS LIVE instead of 33 V r.m.s., 46,7 V peak, or 70 V d.c.

- b) Servicing is now included within the scope.
- c) Extended environmental conditions are included within the scope.
- d) New terms have been defined.
- e) Tests for REASONABLY FORESEEABLE MISUSE have been added, in particular for fuses.
- f) Additional instruction requirements for probe assembly operation have been specified.
- g) Limit values for ACCESSIBLE parts and for measurement of voltage and touch current have been modified.
- h) SPACINGS requirements for mating of CONNECTORS have been modified.
- i) PROBE TIPS and SPRING-LOADED CLIPS requirements have been modified. The PROTECTIVE FINGERGUARD replace the BARRIER with new requirements.
- j) Insulation requirements (6.5) and test procedures (6.6.5) have been rewritten and aligned when relevant with Part 1. Specific requirements have been added for solid insulation and thin-film insulation.
- k) The terminology for MEASUREMENT CATEGORY I has been replaced with the designation “not RATED for measurements within MEASUREMENT CATEGORIES II, III, or IV”.
- l) The flexing/pull test (6.7.4.3) has been partially rewritten.
- m) Surface temperature limits (Clause 10) have been modified to conform to the limits of IEC Guide 117.
- n) Requirements for resistance of PROBE WIRES to mechanical stresses have been added in Clause 12 and a new Annex D.
- o) Requirements have been added regarding the prevention of HAZARD from arc flash and short-circuits for SPRING-LOADED CLIPS.
- p) A new informative Annex E defines the dimension of the 4 mm banana CONNECTORS.

The text of this standard is based on the following documents:

FDIS	Report on voting
66/569/FDIS	66/571/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 61010 series, under the general title, *Safety requirements for electrical equipment for measurement, control, and laboratory use*, may be found on the IEC website.

In this standard, the following print types are used:

- requirements and definitions: in roman type;
- NOTES and EXAMPLES: in smaller roman type;
- *conformity and tests: in italic type;*
- terms used throughout this standard which have been defined in Clause 3: SMALL ROMAN CAPITALS.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 REV

SAFETY REQUIREMENTS FOR ELECTRICAL EQUIPMENT FOR MEASUREMENT, CONTROL AND LABORATORY USE –

Part 031: Safety requirements for hand-held probe assemblies for electrical measurement and test

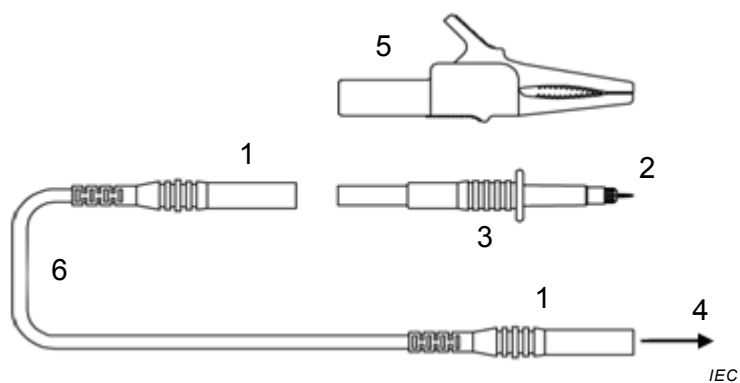
1 Scope and object

1.1 Scope

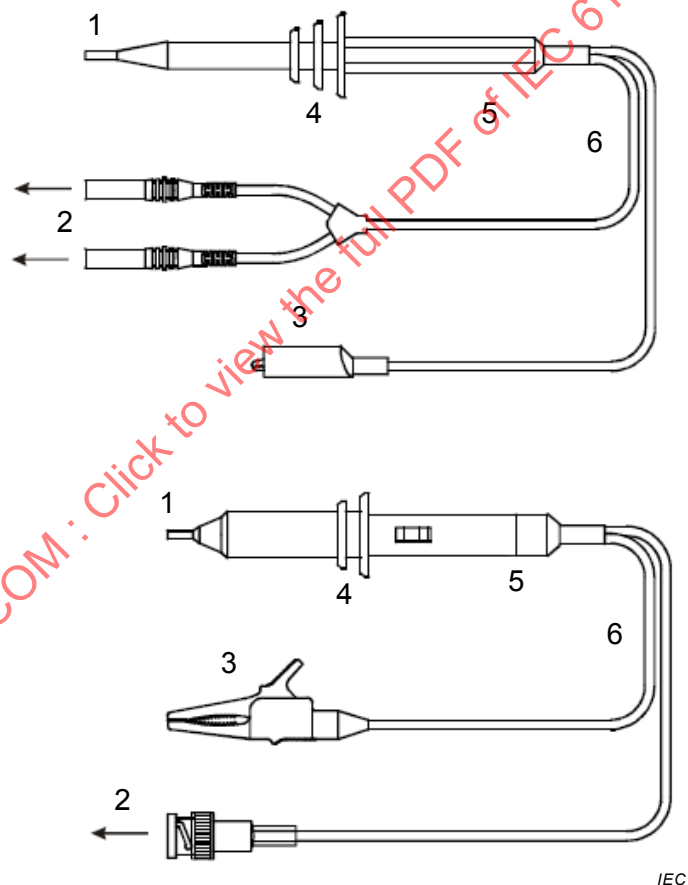
1.1.1 Probe assemblies included in scope

This part of IEC 61010 specifies safety requirements for hand-held and hand-manipulated probe assemblies of the types described below, and their related accessories. These probe assemblies are for direct electrical connection between a part and electrical test and measurement equipment. They may be fixed to the equipment or be detachable accessories for the equipment.

- a) Type A: low-voltage and high-voltage, non-attenuating probe assemblies. Non-attenuating probe assemblies that are RATED for direct connection to voltages exceeding 30 V r.m.s., 42,4 V peak, or 60 V d.c., but not exceeding 63 kV. They do not incorporate components which are intended to provide a voltage divider function or a signal conditioning function, but they may contain non-attenuating components such as fuses (see Figure 1.)
- b) Type B: high-voltage attenuating or divider probe assemblies. Attenuating or divider probe assemblies that are RATED for direct connection to secondary voltages exceeding 1 kV r.m.s. or 1,5 kV d.c. but not exceeding 63 kV r.m.s. or d.c. The divider function may be carried out wholly within the probe assembly, or partly within the test or measurement equipment to be used with the probe assembly (see Figure 2).
- c) Type C: low-voltage attenuating or divider probe assemblies. Attenuating or divider probe assemblies for direct connection to voltages not exceeding 1 kV r.m.s. or 1,5 kV d.c. The signal conditioning function may be carried out wholly within the probe assembly, or partly within the test or measurement equipment intended to be used with the probe assembly (see Figure 3).
- d) Type D: low-voltage attenuating, non-attenuating or other signal conditioning probe assemblies, that are RATED for direct connection only to voltages not exceeding 30 V r.m.s., or 42,4 V peak, or 60 V d.c., and are suitable for currents exceeding 8 A (see Figure 4).

**Key**

- | | |
|----------------------|----------------------|
| 1 typical CONNECTORS | 4 to equipment |
| 2 PROBE TIP | 5 SPRING-LOADED CLIP |
| 3 probe body | 6 PROBE WIRE |

Figure 1 – Examples of type A probe assemblies**Key**

- | | |
|-----------------------|--------------------------------|
| 1 PROBE TIP | 4 PROTECTIVE FINGERGUARD |
| 2 to equipment | 5 hand-held area of probe body |
| 3 reference CONNECTOR | 6 PROBE WIRE |

Figure 2 – Examples of type B probe assemblies

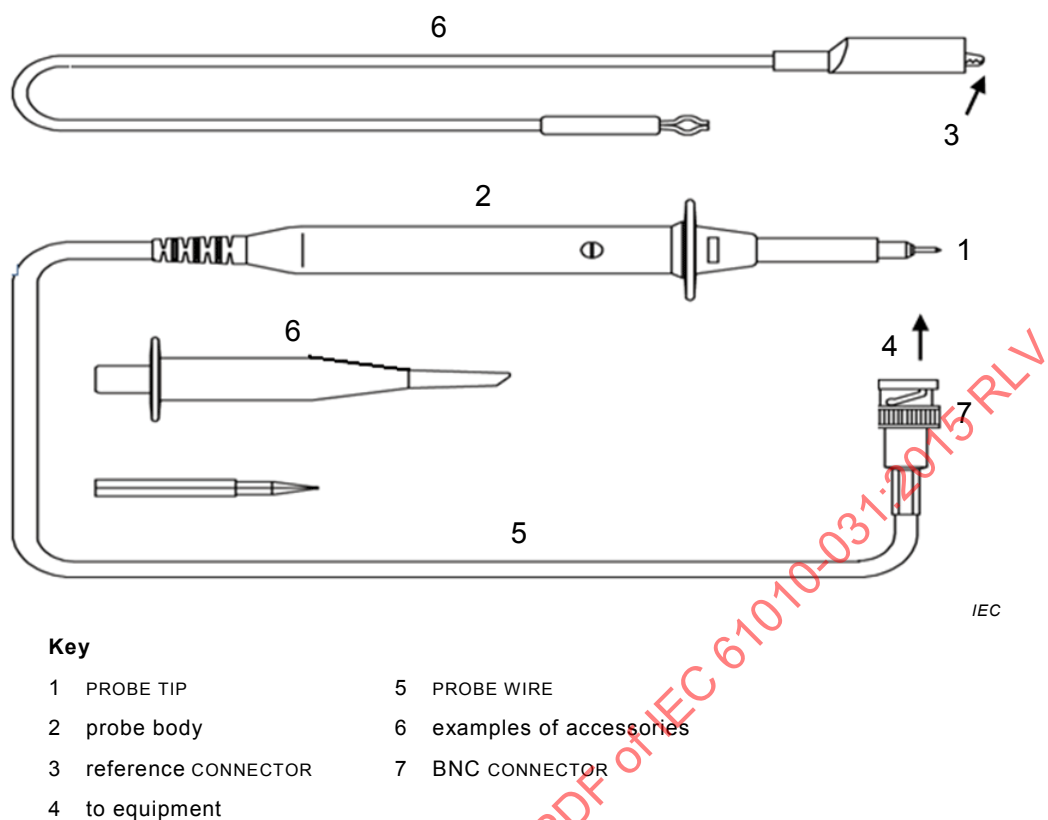


Figure 3 – Examples of type C probe assemblies

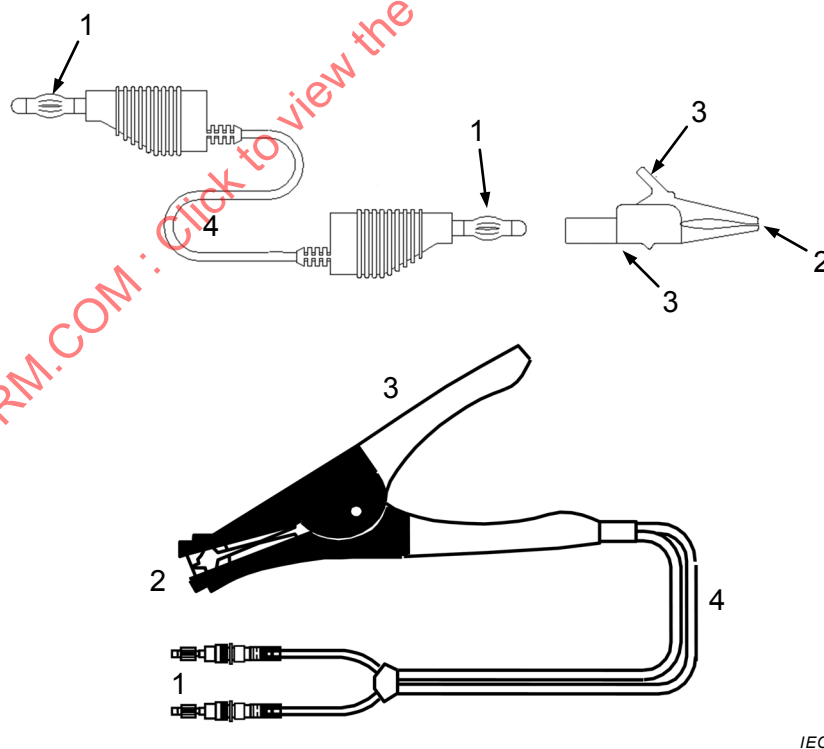


Figure 4 – Examples of type D probe assemblies

1.1.2 Probe assemblies excluded from scope

This standard does not apply to current sensors within the scope of IEC 61010-2-032 (Hand-held and hand-manipulated current sensors), but may apply to their input measuring circuit leads and accessories.

1.2 Object

1.2.1 Aspects included in scope

The purpose of the requirements of this standard is to ensure that HAZARDS to the OPERATOR and the surrounding area are reduced to a tolerable level.

Requirements for protection against particular types of HAZARDS are given in Clauses 6 to 13, as follows:

- a) electric shock or burn (see Clauses 6, 10 and 11);
- b) mechanical HAZARDS (see Clauses 7, 8 and 11);
- c) excessive temperature (see Clause 9);
- d) spread of fire from the probe assembly (see Clause 9);
- e) arc flash (see Clause 13).

Additional requirements for probe assemblies which are designed to be powered from a low-voltage mains supply, or include other features not specifically addressed in this standard are in other parts of IEC 61010.

NOTE Attention is drawn to the possible existence of additional requirements regarding the health and safety of labour forces.

1.2.2 Aspects excluded from scope

This standard does not cover:

- a) reliable function, performance, or other properties of the probe assembly;
- b) effectiveness of transport packaging.

1.3 Verification

This standard also specifies methods of verifying that the probe assembly meets the requirements of this standard, through inspection, TYPE TESTS, and ROUTINE TESTS.

1.4 Environmental conditions

1.4.1 Normal environmental conditions

This standard applies to probe assemblies designed to be safe at least under the following conditions:

- a) altitude up to 2 000 m;
- b) ambient temperature of 5 °C to 40 °C;
- c) maximum relative humidity of 80 % for temperatures up to 31 °C decreasing linearly to 50 % relative humidity at 40 °C;
- d) applicable POLLUTION DEGREE of the intended environment.

1.4.2 Extended environmental conditions

This standard applies to probe assemblies designed to be safe not only in the environmental conditions specified in 1.4.1, but also in any of the following conditions as RATED by the manufacturer of the probe assemblies:

- a) outdoor use;
- b) altitudes above 2 000 m;
- c) ambient temperatures below 5 °C or above 40 °C;
- d) relative humidities above the levels specified in 1.4.1;
- e) WET LOCATIONS.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letters symbols to be used in electrical technology*

IEC 60529, *Degrees of protection provided by enclosures (IP Code)*

IEC 61010-1:2010, *Safety requirements for electrical equipment for measurement, control, and laboratory use – Part 1: General requirements*

IEC 61180-1:1992, *High-voltage test techniques for low-voltage equipment – Part 1: Definitions, test and procedure requirements*

IEC 61180-2, *High-voltage test techniques for low-voltage equipment – Part 2: Test equipment*

IEC GUIDE 104, *The preparation of safety publications and the use of basic safety publications and group safety publications*

ISO/IEC GUIDE 51, *Safety aspects – Guidelines for their inclusion in standards*

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

3.1 Parts and accessories

3.1.1

TERMINAL

component provided for the connection of a device (equipment) to external conductors

Note 1 to entry: TERMINALS can contain one or several contacts and the term includes sockets, pins, connectors, etc.

3.1.2

ENCLOSURE

part providing protection of a probe assembly against certain external influences and, in any direction, protection against direct contact

3.1.3

PROTECTIVE FINGERGUARD

part of the ENCLOSURE that indicates the limit of safe access and that reduces the risk of the OPERATOR touching HAZARDOUS LIVE parts

3.1.4**PROBE TIP**

part of a probe assembly or accessory which makes a connection to the point being measured or tested

Note 1 to entry: The term "PROBE TIP" includes the conductive parts of the jaws or hooks of SPRING-LOADED CLIPS.

3.1.5**CONNECTOR**

component which is attached to the PROBE WIRE, to connect to a TERMINAL of the equipment or to a CONNECTOR of another probe assembly

3.1.6**TOOL**

external device, including a key or coin, used to aid a person performing a mechanical function

3.1.7**PROBE WIRE**

flexible wire or cable used as part of the probe assembly or its accessories, consisting of one or more conductors and associated insulation

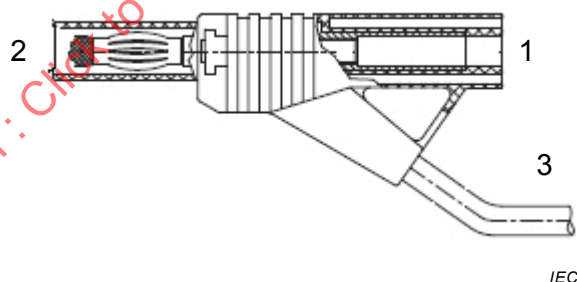
3.1.8**SPRING-LOADED CLIP**

probe or probe accessory with one or more hooks or jaws forced by a spring to grip the part being measured or tested

3.1.9**STACKABLE CONNECTOR**

CONNECTOR assembly which contains an additional TERMINAL

EXAMPLE: Figure 5 is an example of a STACKABLE CONNECTOR with a male CONNECTOR and a female TERMINAL.

**Key**

- 1 TERMINAL for additional CONNECTOR
- 2 CONNECTOR
- 3 PROBE WIRE

Figure 5 – Example of a STACKABLE CONNECTOR with a male CONNECTOR and a female TERMINAL

3.2 Quantities**3.2.1****RATED** (condition or value)

condition or quantity value assigned, generally by a manufacturer, for a specified operating condition of a component, device, or probe assembly

3.2.2

RATING

set of RATED values and operating conditions

[SOURCE: IEC 60050-151:2001, 151-16-11]

3.2.3

WORKING VOLTAGE

highest r.m.s. value of the a.c. or d.c. voltage across any particular insulation which can continuously appear during NORMAL USE

Note 1 to entry: Transients and voltage fluctuations are not considered to be part of the WORKING VOLTAGE

3.3 Tests

3.3.1

TYPE TEST

test of one or more samples of a probe assembly (or parts of a probe assembly) made to a particular design, to show that the design and construction meet the requirements of this standard

Note 1 to entry: This is an amplification of the IEC 60050-151:2001, 151-16-16 definition to cover design as well as construction.

3.3.2

ROUTINE TEST

conformity test made on each individual item during or after manufacture

[SOURCE: IEC 60050-151:2001, 151-16-17]

3.4 Safety terms

3.4.1

ACCESSIBLE

able to be touched with a standard test finger or test pin, when used as specified in 6.2

3.4.2

HAZARDOUS LIVE

capable of rendering an electric shock or electric burn

3.4.3

HAZARD

potential source of harm

3.4.4

PROTECTIVE IMPEDANCE

component or assembly of components whose impedance, construction and reliability are suitable to provide protection against electric shock

3.4.5

NORMAL USE

operation, including stand-by, according to the instructions for use or for the obvious intended purpose

3.4.6

NORMAL CONDITION

condition in which all means for protection against HAZARDS are intact

3.4.7**SINGLE FAULT CONDITION**

condition in which one means for protection against a HAZARD is defective or one fault is present which could cause a HAZARD

3.4.8**OPERATOR**

person operating the probe assembly for its intended purpose

3.4.9**RESPONSIBLE BODY**

individual or group responsible for the safe use and maintenance of probe assemblies

3.4.10**WET LOCATION**

location where water or another conductive liquid may be present and is likely to cause reduced human body impedance due to wetting of the contact between the human body and the probe assembly, or wetting of the contact between the human body and the environment

3.4.11**MEASUREMENT CATEGORY**

classification of testing and measuring circuits according to the types of mains circuits to which they are intended to be connected

3.4.12**REASONABLY FORESEEABLE MISUSE**

use of a product in a way not intended by the supplier, but which may result from readily predictable human behaviour

3.5 Insulation**3.5.1****BASIC INSULATION**

insulation of HAZARDOUS LIVE parts which provides basic protection

[SOURCE: IEC 60050-195:1998, 195-06-06]

3.5.2**SUPPLEMENTARY INSULATION**

independent insulation applied in addition to BASIC INSULATION in order to provide protection against electric shock in the event of a failure of BASIC INSULATION

3.5.3**DOUBLE INSULATION**

insulation comprising both BASIC INSULATION and SUPPLEMENTARY INSULATION

[SOURCE: IEC 60050-195:1998, 195-06-08]

3.5.4**REINFORCED INSULATION**

insulation which provides a degree of protection against electric shock not less than that provided by DOUBLE INSULATION

3.5.5**POLLUTION**

addition of foreign matter, solid, liquid or gaseous (ionized gases), that may produce a reduction of dielectric strength or surface resistivity

3.5.6

POLLUTION DEGREE

numeral indicating the level of POLLUTION that may be present in the environment

3.5.7

POLLUTION DEGREE 1

no POLLUTION or only dry, non-conductive POLLUTION occurs, which has no influence

3.5.8

POLLUTION DEGREE 2

only non-conductive POLLUTION occurs except that occasionally a temporary conductivity caused by condensation is expected

3.5.9

POLLUTION DEGREE 3

conductive POLLUTION occurs, or dry, non-conductive POLLUTION occurs which becomes conductive due to condensation which is expected

3.5.10

CLEARANCE

shortest distance in air between two conductive parts

3.5.11

CREEPAGE DISTANCE

shortest distance along the surface of a solid insulating material between two conductive parts

[SOURCE: IEC 60050-151:2001, 151-15-50]

3.5.12

SPACING

any combination of CLEARANCES and CREEPAGE DISTANCES

4 Tests

4.1 General

Tests in this standard are TYPE TESTS to be carried out on samples of probe assemblies or their parts. Their only purpose is to check that the design and construction ensure conformity with this standard. In addition, the ROUTINE TESTS of Annex D shall be performed on the PROBE WIRE.

The probe assembly shall at least meet the requirements of this standard. It is permissible to exceed the requirements. If, in this standard, a lower limit is specified for a conformity value, then the probe assembly may demonstrate a larger value. If an upper limit is specified for a conformity value, the probe assembly may demonstrate a lower value. Manufacturing variations and tolerances shall be taken into account.

Tests on components or parts of the probe assembly meeting the requirements of the relevant standards specified in this standard, and used in accordance with them, need not be repeated during TYPE TESTS of the whole probe assembly.

If a probe assembly is of more than one probe type (see 1.1.1), each type shall be tested according to its applicable requirements.

Conformity with the requirements of this standard is checked by carrying out all applicable tests, except that a test may be omitted if examination of the probe assembly and design

documentation demonstrates conclusively that it would pass the test. Tests are carried out both under reference test conditions (see 4.3) and fault conditions (see 4.4).

Where conformity statements in this standard require inspection, this may include examination of the probe assembly by measurement, examination of the markings on the probe assembly, examination of the instructions supplied with the probe assembly, examination of the data sheets of the materials or components from which the probe assembly is manufactured, etc. In each case, the inspection will either demonstrate that the probe assembly meets the applicable requirements, or will indicate that further testing is required.

If, when carrying out a conformity test, there is any uncertainty about the exact value of an applied or measured quantity (for example voltage) due to the tolerance:

- a) manufacturers should ensure that at least the specified test value is applied;*
- b) test houses should ensure that no more than the specified test value is applied.*

If the RATED range of environmental conditions for probe assemblies is wider than that stated in 1.4.1, the manufacturer should make sure (for example, by suitable alteration of test requirements or additional tests) that the safety requirements of this standard are still fulfilled.

Probe assemblies which have been type tested may no longer be suitable for their intended function because of the residual effect of stresses resulting from tests. A probe assembly which has undergone TYPE TESTS shall not then be put into use.

4.2 Sequence of tests

The sequence of tests is optional unless otherwise specified. The probe assemblies under test shall be carefully inspected after each test. If the result of a test causes doubt whether any earlier tests would have passed if the sequence had been reversed, these earlier tests shall be repeated.

4.3 Reference test conditions

4.3.1 Environmental conditions

Unless otherwise specified in this standard, the following environmental conditions (but not conflicting with those of 1.4.1, shall exist in the test location:

- a) a temperature of 15 °C to 35 °C;
- b) a relative humidity of not more than 75 %;
- c) an air pressure of 75 kPa to 106 kPa;
- d) no hoarfrost, dew, percolating water, rain, solar irradiation, etc.

4.3.2 State of probe assemblies

Unless otherwise specified, tests shall be carried out on the probe assemblies assembled for NORMAL USE and under the least favourable combination of the conditions given in 4.3.3 to 4.3.9.

In case of doubt, tests shall be performed in more than one combination of conditions.

If dimensions or mass make it unsuitable to carry out particular tests on a complete probe assembly, tests on sub-assemblies are allowed, provided it is verified that the assembled probe assembly will meet the requirements of this standard.

4.3.3 Position of the probe assembly

All possible orientations of the probe assembly are considered to be positions of NORMAL USE.

4.3.4 Accessories

Accessories and OPERATOR-interchangeable parts available from, or recommended by, the manufacturer for use with the probe assembly under test shall be either connected or not connected.

4.3.5 Covers and removable parts

Covers or parts which can be removed without using a TOOL shall be removed or not removed whichever is the worst condition.

4.3.6 Input and output voltages

Input and output voltages, including floating voltages shall be set to any voltage within the RATED voltage range.

4.3.7 Controls

Controls which the OPERATOR can adjust without the use of a TOOL shall be set to any position except for combinations of settings prohibited by the manufacturer's marking on the probe assembly.

4.3.8 Connections

The probe assembly shall be connected for NORMAL USE or not connected whichever is the worst condition.

4.3.9 Duty cycle

Probe assemblies for short-term or intermittent operation shall be operated for the longest RATED period and shall have the shortest RATED recovery period consistent with the manufacturer's instructions.

4.4 Testing in SINGLE FAULT CONDITION

4.4.1 General

The following requirements apply.

- a) Examination of the probe assembly and its circuit diagram will generally show the fault conditions which are liable to result in HAZARDS and which, therefore, shall be applied.
- b) Fault tests shall be made as specified for checking conformity, unless it can be demonstrated that no HAZARD could arise from a particular fault condition.
- c) The probe assembly shall be operated under the least favourable combination of reference test conditions (see 4.3). These combinations may be different for different faults and they shall be recorded for each test.

4.4.2 Application of fault conditions

4.4.2.1 General

Fault conditions shall include those specified in 4.4.2.2 to 4.4.2.5. They shall be applied only one at a time and shall be applied in turn in the most convenient order. Multiple simultaneous faults shall not be applied unless they are a consequence of an applied fault.

After each application of a fault condition, the probe assembly or part shall pass the applicable tests of 4.4.4.

4.4.2.2 PROTECTIVE IMPEDANCE

The following requirements apply.

- a) If a PROTECTIVE IMPEDANCE is formed by a combination of components, each component shall be short-circuited or disconnected, whichever is less favourable.
- b) If a PROTECTIVE IMPEDANCE is formed with a single component that meets the requirements of 6.4.5, it need not be short-circuited or disconnected.

4.4.2.3 Probe assemblies or parts for short-term or intermittent operation

These shall be operated continuously if continuous operation could occur in a SINGLE FAULT CONDITION.

4.4.2.4 Outputs

Outputs of Type B and Type C probe assemblies shall be short-circuited.

4.4.2.5 Insulation between circuits and parts

Insulation between circuits and parts which is below the level specified for BASIC INSULATION shall be bridged to check against the spread of fire if the method of 9.1 is used.

4.4.3 Duration of tests

The probe assembly shall be operated until further change as a result of the applied fault is unlikely. Each test is normally limited to 1 h since a secondary fault arising from a SINGLE FAULT CONDITION will usually manifest itself within that time. If there is an indication that a HAZARD of electric shock, spread of fire or injury to persons may eventually occur, the test shall be continued for a maximum period of 4 h.

4.4.4 Conformity after application of fault conditions

4.4.4.1 Electric shock

Conformity with requirements for protection against electric shock after the application of single faults is checked as follows:

- a) *by making the measurements of 6.3.3 to check that no ACCESSIBLE conductive parts have become HAZARDOUS LIVE, except as permitted by 6.1;*
- b) *by performing a voltage test on DOUBLE INSULATION or REINFORCED INSULATION to check that the protection is still at least at the level of BASIC INSULATION. The voltage tests are made as specified in 6.6 (without humidity preconditioning) with the test voltage for BASIC INSULATION.*

4.4.4.2 Temperature

Conformity with requirements for temperature protection is checked by determining the temperature of the outer surface of the probe assembly (see Clause 9).

This temperature is determined by measuring the temperature rise of the surface or part and adding it to the maximum RATED ambient temperature.

4.4.4.3 Spread of fire

Conformity with requirements for protection against the spread of fire is checked by placing the probe assembly on white tissue-paper covering a softwood surface and covering the probe assembly with cheesecloth. No molten metal, burning insulation, flaming particles, etc. shall fall on the surface on which the probe assembly stands and there shall be no charring, glowing, or flaming of the tissue paper or cheesecloth. Melting of insulation material shall be ignored if no HAZARD could arise.

4.4.4.4 Other HAZARDS

Conformity with the requirements for protection against other HAZARDS is checked as specified in Clauses 7 to 13.

4.5 Tests in REASONABLY FORESEEABLE MISUSE

4.5.1 General

Tests needed to support a risk assessment pertaining to REASONABLY FORESEEABLE MISUSE are carried out in the combinations of conditions and operations determined during the risk assessment.

4.5.2 Fuses

Fused probe assemblies are used where insufficient protection may be provided by the equipment to which the hand manipulated probe assemblies are connected in particular under the REASONABLY FORESEEABLE MISUSE conditions associated with the equipment that could lead to fire or arc explosion.

For the purposes of this test, it is assumed that the equipment to which the probe assemblies are connected represents a short circuit condition. It is further assumed that the fused probe assembly may be connected to any voltage source within the RATING of the probe assembly. This leads to a test condition where any current level up to the maximum prospective short circuit current may be applied. With respect to prospective short circuit currents associated with MAINS installations, the fuse shall be RATED according to 12.2 and no additional testing related to the interrupt current RATING is necessary. However, testing is necessary at current levels near the RATING of fuse which could potentially lead to excessive temperature rise on hand held parts as well as damage to insulating parts, ENCLOSURES, and barriers.

It shall be demonstrated that the maximum fuse temperature under any current load condition up to 5 times the fuse RATING through the fused probe assembly does not lead to a HAZARD.

Conformity is checked by inspection and measurement.

5 Marking and documentation

5.1 Marking

5.1.1 General

Probe assemblies shall bear markings in accordance with 5.1.2 to 5.2. Markings applying to a probe assembly as a whole shall not be put on parts which can be removed by an OPERATOR without the use of a TOOL.

Letter symbols for quantities and units shall be in accordance with IEC 60027. Graphic symbols shall be in accordance with Table 1 if applicable. There are no requirements for size or colour. If there is no applicable symbol in Table 1, any other graphic symbol may be used on a probe assembly provided the symbol is explained in the accompanying documentation (see 5.4.1).

If it is not possible to put all of the required markings on the part, the necessary information shall be included in the documentation. Symbol 7 of Table 1 may also be used.

Conformity is checked by inspection.

5.1.2 Identification

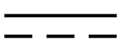
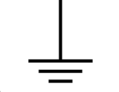
Each probe assembly and, when possible, its accessories shall be marked with:

- a) the name or registered trade mark of the manufacturer or supplier;
- b) in addition for Type B and Type C only, the model number or name or other means of identifying the probe assembly or part.

If a probe assembly is designed for use only with a specific model of equipment, this shall be made clear, and the specific equipment or model shall be identified, either by marking on the probe assembly or in the accompanying documentation.

Conformity is checked by inspection.

Table 1 – Symbols

Number	Symbol	Reference	Description
1		IEC 60417-5031 (2002-10)	Direct current
2		IEC 60417-5032 (2002-10)	Alternating current
3		IEC 60417-5033 (2002-10)	Both direct and alternating current
4		IEC 60417-5017 (2006-08)	Earth (ground) TERMINAL
5		IEC 60417-6042 (2010-11)	Caution, possibility of electric shock
6		IEC 60417-5041 (2002-10)	Caution, hot surface
7		ISO 7000-0434 (2004-01)	Caution ^a
^a See 5.4.1 which requires manufacturers to state that documentation must be consulted in all cases where this symbol is marked.			

5.1.3 Fuses

Probe assemblies which contain fuses intended to be replaced by an OPERATOR shall be marked with all the details necessary for the OPERATOR to obtain the correct fuse. These shall include the voltage RATING and the breaking capacity (the maximum current that the fuse can safely interrupt at the highest RATED voltage). If there is not sufficient room, Symbol 7 of Table 1 shall be marked on the probe assembly and the necessary information shall be included in the documentation.

Conformity is checked by inspection.

5.1.4 CONNECTORS and operating devices

If necessary for safety, an indication shall be given of the purpose of CONNECTORS, TERMINALS, and controls, including any sequence of operations.

Conformity is checked by inspection.

5.1.5 RATING

The RATING of probe assemblies shall be marked as follows.

- a) Probe assemblies which do not have a RATING for MEASUREMENT CATEGORIES II, III, or IV (see 6.5.2) shall be marked with the RATED voltage to earth and with Symbol 7 of Table 1 (see also 5.4.3 f) and g)).
- b) Probe assemblies for measurements within MEASUREMENT CATEGORIES II, III and IV (see 6.5.2) shall be marked with the RATED voltages to earth and the relevant MEASUREMENT CATEGORIES. The MEASUREMENT CATEGORY markings shall be "CAT II", "CAT III" or "CAT IV" as applicable.

Marking on a probe assembly shall preferably be on the probe body. The nature of the voltage (a.c., d.c., etc.) shall also be marked, unless the voltage marking applies to both a.c. r.m.s. and d.c. If a reference CONNECTOR is intended for connection to points at a voltage level exceeding the values of 6.3.2, the RATED voltage shall be marked on the CONNECTOR or as close to the CONNECTOR as is practicable.

For Type A and Type D probe assemblies only, the RATED current of the probe assembly shall be marked together with the RATED voltage to earth. The RATED current does not need to be marked on probe assemblies which are specified for use only in conjunction with equipment which has high-impedance inputs or limited-current outputs.

Conformity is checked by inspection.

5.2 Warning markings

Warning markings shall be legible when the probe assembly is ready for NORMAL USE.

If it is necessary for the OPERATOR to refer to the instruction manual to preserve the protection afforded by the probe assembly, the probe assembly shall be marked with the Symbol 7 of Table 1. If a warning applies to a particular part of the probe assembly, the marking shall be placed on or near this part.

If the instructions for use state that an OPERATOR is permitted to gain access, using a TOOL, to any part which in NORMAL USE may be HAZARDOUS LIVE, there shall be a warning marking which states that the probe assembly must be isolated or disconnected from the HAZARDOUS LIVE voltage before access, or Symbol 7 of Table 1 may be used provided that the information is included in the instructions for use.

Unless their heated state is self-evident or is obvious from the function of the probe assembly, parts which are easily touched and are also permitted by 9.1 to exceed the temperature limits of 9.1 shall be marked with Symbol 6 of Table 1.

Conformity is checked by inspection.

5.3 Durability of markings

Required markings shall remain clear and legible under conditions of NORMAL USE and shall resist the effects of cleaning agents specified by the manufacturer.

Conformity is checked by performing the following test for durability of markings on the outside of the probe assembly. The markings are rubbed by hand, without undue pressure, for 30 s with a cloth soaked with each specified cleaning agent, one at a time, or, if not specified, with a solution containing a minimum of 70 % isopropyl alcohol in water.

After the above treatment the markings shall be clearly legible and adhesive labels shall not have worked loose or become curled at the edges.

5.4 Documentation

5.4.1 General

Probe assemblies shall be accompanied by documentation when necessary for safety purposes. Such documentation shall include as a minimum:

- a) technical specification;
- b) instructions for use;
- c) name and address of manufacturer or supplier from whom technical assistance may be obtained;
- d) the information specified in 5.4.2 to 5.4.4.

If applicable, warning statements and a clear explanation of warning symbols marked on the probe assembly shall be provided in the documentation or shall be durably and legibly marked on the probe assembly. In particular, there shall be a statement that documentation needs to be consulted in all cases where Symbol 7 of Table 1 is used, in order to find out the nature of the potential HAZARD and any actions which have to be taken.

Conformity is checked by inspection.

5.4.2 Probe assembly RATING

Documentation shall include the voltage and current RATING (as appropriate), and the MEASUREMENT CATEGORY as well as a statement of the range of environmental conditions for which the probe assembly is designed (see 1.4).

Conformity is checked by inspection.

5.4.3 Probe assembly operation

Instructions for use shall include, if applicable:

- a) identification of operating controls and their use in all operating modes;
- b) for probe assemblies designed for use only with a specific model of equipment, a clear identification of the equipment;
- c) an explanation of symbols related to safety which are used on the probe assembly;
- d) a definition of the relevant MEASUREMENT CATEGORY if marking is required on the probe assembly (see 5.1.5);
- e) a specification of limits for intermittent operation, if applicable;
- f) instructions for interconnection to accessories and other equipment, including indication of suitable accessories, detachable parts and any special materials;
- g) instructions for cleaning;
- h) instructions for replacement of consumable materials;
- i) for probe assemblies which do not have PROBE WIRE with a wear indicator, instructions to periodically inspect the PROBE WIRE;

- j) for probe assemblies which do have PROBE WIRE with a wear indicator, a warning not to use the probe assembly if the wear indicator has become visible (see 12.3.2);
- k) for probe assemblies which do not have a RATING for MEASUREMENT CATEGORIES II, III, or IV, a warning not to use the probe assemblies for measurements on mains circuits;
- l) for Type B probe assemblies, if the RATED voltage of the PROBE WIRE is lower than the RATED voltage of the PROBE TIP, a warning that the PROBE WIRE may not provide adequate protection if it comes into contact with a HAZARDOUS LIVE part;
- m) a warning that the applicable MEASUREMENT CATEGORY of a combination of a probe assembly and an accessory is the lower of the MEASUREMENT CATEGORIES of the probe assembly and of the accessory.

There shall be a statement in the instructions that, if the probe assembly is used in a manner not specified by the manufacturer, the protection provided by the probe assembly may be impaired.

Conformity is checked by inspection.

5.4.4 Probe assembly maintenance and service

Instructions shall be provided to the RESPONSIBLE BODY in sufficient detail to permit safe maintenance and inspection of the probe assembly, and to ensure continued safety of the probe assembly after the maintenance and inspection procedure.

The manufacturer shall specify any parts which are required to be examined or supplied only by the manufacturer or his agent.

The RATING and characteristics of fuses used shall be stated (see 5.1.3).

Instructions on the following subjects shall be provided for service personnel, as necessary to permit safe servicing and continued safety of the probe assembly after servicing if the probe assembly is suitable to be serviced:

- a) product-specific risks that may affect the service personnel;
- b) protective measures for these risks;
- c) verification of the safe state of the probe assembly after repair.

Instructions for service personnel do not need to be supplied to the RESPONSIBLE BODY, but should be made available to service personnel.

Conformity is checked by inspection.

6 Protection against electric shock

6.1 General

Protection against electric shock shall be maintained in NORMAL CONDITION and SINGLE FAULT CONDITION. ACCESSIBLE parts of probe assemblies shall not be HAZARDOUS LIVE (see 6.3).

If it is not feasible for operating reasons to prevent the following parts being both ACCESSIBLE and HAZARDOUS LIVE, they are permitted to be ACCESSIBLE to the OPERATOR during NORMAL USE while they are HAZARDOUS LIVE:

- a) parts intended to be replaced by the OPERATOR (for example, fuses) and which may be HAZARDOUS LIVE during replacement, but only if they have warning markings in accordance with 5.2;
- b) PROBE TIPS, provided that they meet the requirements of 6.4.3;

c) unmated CONNECTORS as specified in 6.4.2 c).

Conformity is checked by the determination of 6.2 and the measurements of 6.3, followed by the tests of 6.4 to 6.7.

6.2 Determination of ACCESSIBLE parts

6.2.1 General

Unless obvious, determination of whether a part is ACCESSIBLE is made as specified in 6.2.2 and 6.2.3. Test fingers (see Annex B) and pins are applied without force. Parts are considered to be ACCESSIBLE if they can be touched with any part of a test finger or pin, or if they could be touched in the absence of a covering which is not considered to provide suitable insulation (see 6.7.2).

If, in NORMAL USE, an OPERATOR is intended to perform any actions (with or without a TOOL) that could increase the accessibility of parts, such actions are taken before performing the examinations of 6.2.2 and 6.2.3.

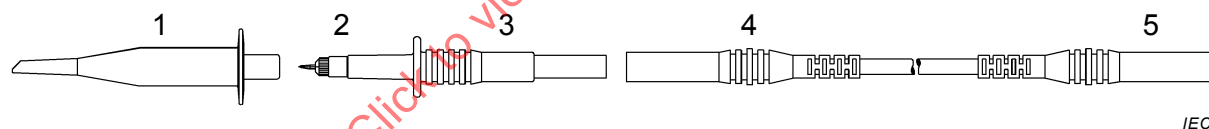
NOTE Examples of such actions include:

- a) removing covers;
- b) adjusting controls;
- c) replacing consumable materials;
- d) removing or installing parts and supplied accessories.

Figure 6 gives methods for determination of ACCESSIBLE parts of probe assemblies.

6.2.2 Examination

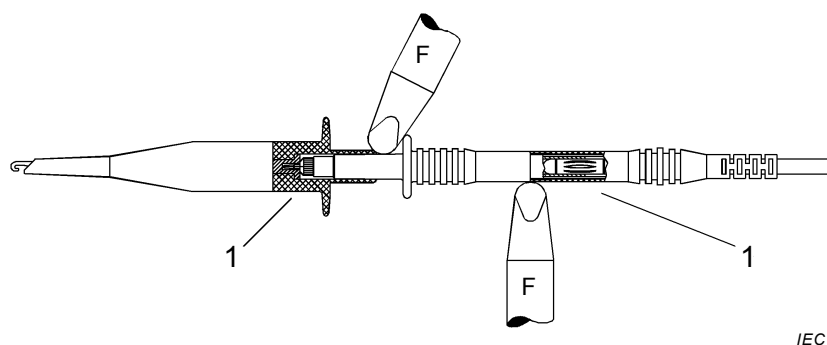
The jointed test finger (see Figure B.2) is applied in every possible position without force. The test is applied to all outer surfaces.



Key

- | | |
|-----------------------|--------------------------|
| 1 accessory PROBE TIP | 4 CONNECTOR |
| 2 PROBE TIP | 5 CONNECTOR to equipment |
| 3 probe body | |

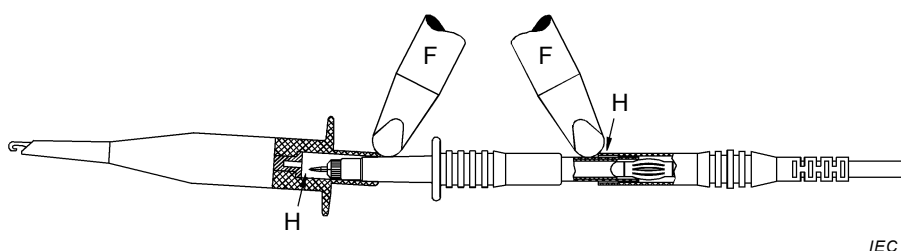
Figure 6a – Parts of a probe assembly



Key

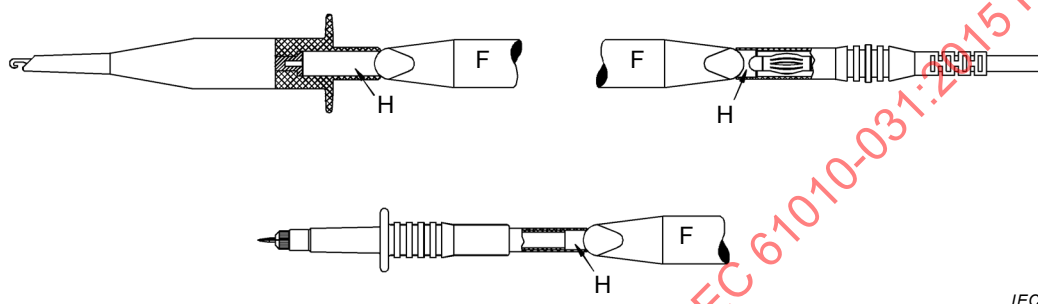
- 1 CONNECTOR

Figure 6b – Fully-mated probe assembly (see 6.2 and 6.4.2 a)



Connecting parts are partially mated so as just to make electrical contact while allowing maximum access to the test finger.

Figure 6c – Partially-mated probe assembly (see 6.2 and 6.4.2 b)



Key

F rigid test finger (see Figure B.1)

H potentially HAZARDOUS LIVE part

Figure 6d – Unmated parts of a probe assembly (see 6.2 and 6.4.2 c))

Figure 6 – Methods for determination of ACCESSIBLE parts (see 6.2) and for voltage tests of (see 6.4.2)

6.2.3 Openings for pre-set controls

A metal test pin 3 mm in diameter is inserted through holes intended to give access to pre-set controls which require the use of a screwdriver or other TOOL. The test pin is applied in every possible direction through the hole. Penetration shall not exceed three times the distance from the ENCLOSURE surface to the control shaft or 100 mm, whichever is smaller.

6.3 Limit values for ACCESSIBLE parts

6.3.1 General

Except as permitted in 6.1, the voltage between an ACCESSIBLE part and earth, or between any two ACCESSIBLE parts on the same probe assembly, shall not exceed the levels of 6.3.2 in NORMAL CONDITION or of 6.3.3 in SINGLE FAULT CONDITION.

Outer conductors (shields) of probe assemblies, intended to be floating, are considered to be held at the same voltage as the PROBE TIP.

The ACCESSIBLE voltage shall be measured (see 6.3.4). If the voltage is below the levels of 6.3.2 a) or 6.3.3 a) as applicable, the touch current and the capacitance need not be measured. If the voltage exceeds that level, the touch current and the capacitance shall be measured. For high frequencies test probes, the alternative method of 6.3.4.3 can also be used.

Conformity is checked by inspection and as specified in 6.3.2 to 6.3.3.

6.3.2 Levels in NORMAL CONDITION

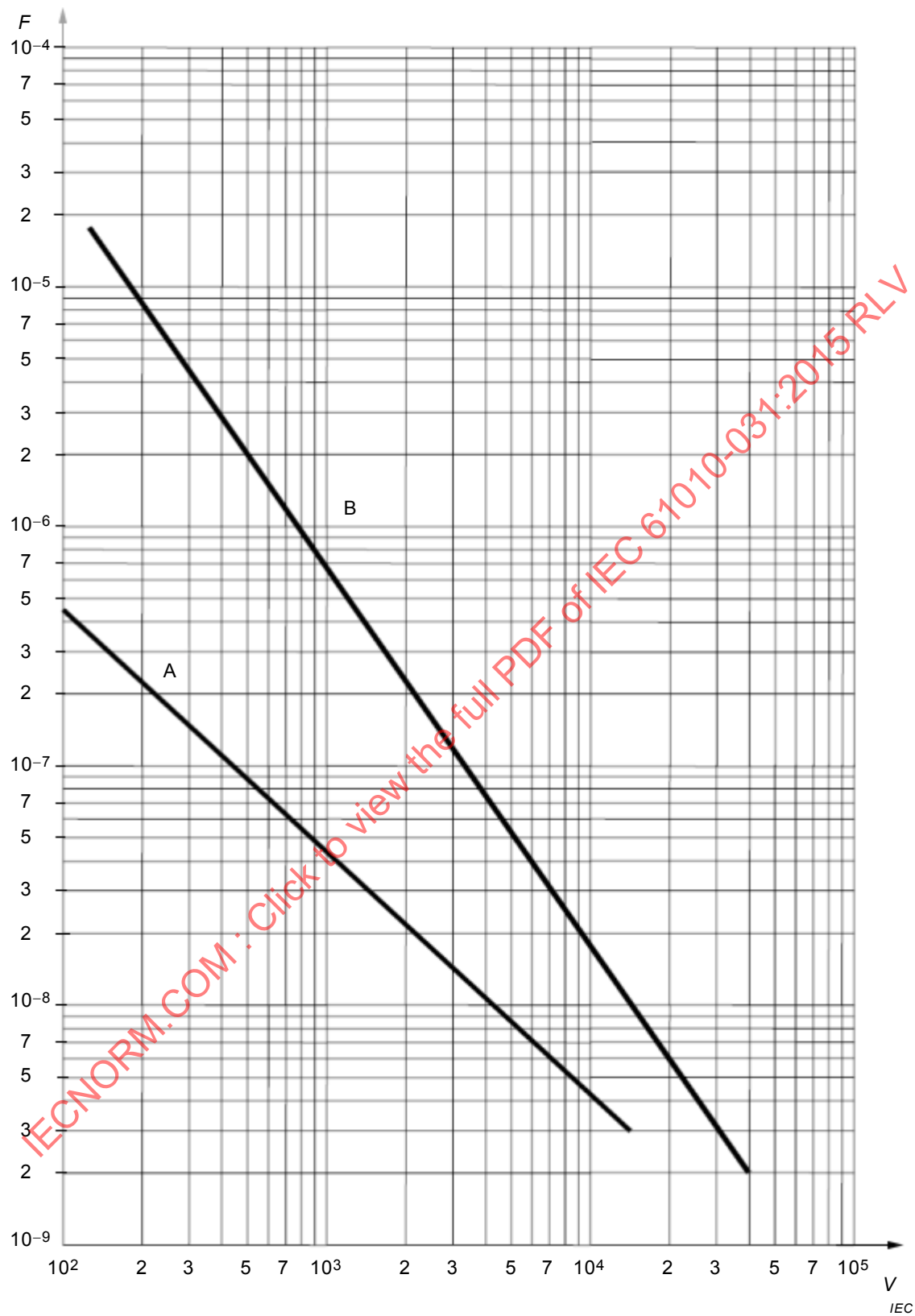
Voltages above the levels of a) are deemed to be HAZARDOUS LIVE if any of the levels of b) or c) are exceeded at the same time.

- a) The a.c. voltage levels are 30 V r.m.s. or 42,4 V peak, and the d.c. voltage level is 60 V. For probe assemblies intended for use in WET LOCATIONS, the a.c. voltage levels are 16 V r.m.s. or 22,6 V peak, and the d.c. voltage level is 35 V.
- b) The touch current levels are:
 - 1) 0,5 mA r.m.s. for sinusoidal waveforms, 0,7 mA peak for non-sinusoidal waveforms or mixed frequencies, or 2 mA d.c., when measured with the measuring circuit of Figure A.1. If the frequency does not exceed 100 Hz, the measuring circuit of Figure A.2 can be used. The measuring circuit of Figure A.5 is used for probe assemblies intended for use in WET LOCATIONS.
 - 2) 70 mA r.m.s. when measured with measuring circuit of Figure A.3. This relates to possible burns at frequencies above 100 kHz.
- c) The levels of capacitive charge or energy are:
 - 1) 45 μ C charge for voltages up to 15 kV peak or d.c. Line A of Figure 7 shows the capacitance versus voltage for cases where the charge is 45 μ C.
 - 2) 350 mJ stored energy for voltages above 15 kV peak or d.c.

6.3.3 Levels in SINGLE FAULT CONDITION

In SINGLE FAULT CONDITION, voltages above the levels of a) are deemed to be HAZARDOUS LIVE if any of the levels of b) or c) are exceeded at the same time.

- a) The a.c. voltage levels are 50 V r.m.s. or 70,7 V peak, and the d.c. voltage level is 120 V. For probe assemblies intended for use in WET LOCATIONS, the a.c. voltage levels are 33 V r.m.s. or 46,7 V peak, and the d.c. voltage level is 70 V.
- b) The touch current levels are:
 - 1) 3,5 mA r.m.s. for sinusoidal waveforms, 5 mA peak for non-sinusoidal waveforms or mixed frequencies, or 15 mA d.c., when measured with the measuring circuit of Figure A.1. If the frequency does not exceed 100 Hz; the measuring circuit of Figure A.2 can be used. The measuring circuit of Figure A.5 is used for probe assemblies intended for use in WET LOCATIONS.
 - 2) 500 mA r.m.s. when measured with the measuring circuit of Figure A.3. This relates to possible burns at frequencies above 100 kHz.
- c) The capacitance level is line B of Figure 7.



Key

A = NORMAL CONDITION

B = SINGLE FAULT CONDITION

Figure 7 – Capacitance level versus voltage in NORMAL CONDITION and SINGLE-FAULT CONDITION (see 6.3.2 c) and 6.3.3 c))

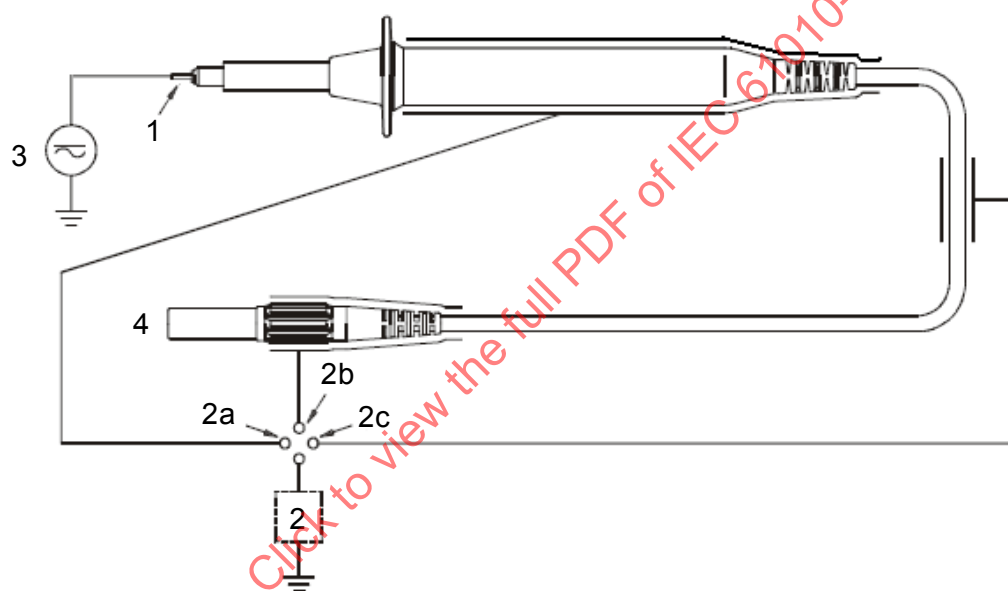
6.3.4 Measurement of voltage and touch current

6.3.4.1 General

Measurement of voltage and touch current on ACCESSIBLE parts of probe assemblies is carried out with metal foil wrapped around each of the following parts, individually:

- a) the probe body;
- b) 150 mm $\pm$ 20 mm of the PROBE WIRE or the maximum length of the cable whichever is shorter;
- c) hand-held or hand-manipulated parts of each CONNECTOR;
- d) other hand-held or hand-manipulated parts.

The RATED voltage to earth is applied between the PROBE TIP (1) and the earth. The voltage is measured between the foil and the earth. If necessary, the measurement circuit is connected in turn (2a – 2b – 2c) between each of the foil-wrapped items and the earth (see Figure 8 and Figure 9).

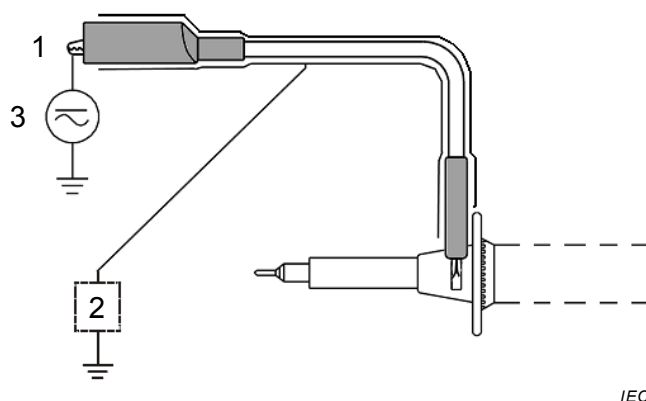


IEC

Key

- 1 PROBE TIP
- 2 Measurement of voltage or touch current (see annex A for applicable measuring circuits for touch current measurements)
 - 2a Connection to metal foil tightly wrapped around parts intended to be hand-held or hand-manipulated
 - 2b Connection to metal foil tightly wrapped around the CONNECTOR
 - 2c Connection to metal foil tightly wrapped around the cable (see 12.3.2)
- 3 Maximum RATED voltage with connection to internal conductor of the PROBE WIRE
- 4 Not connected to test or measuring equipment

Figure 8 – Voltage and touch current measurement



Key

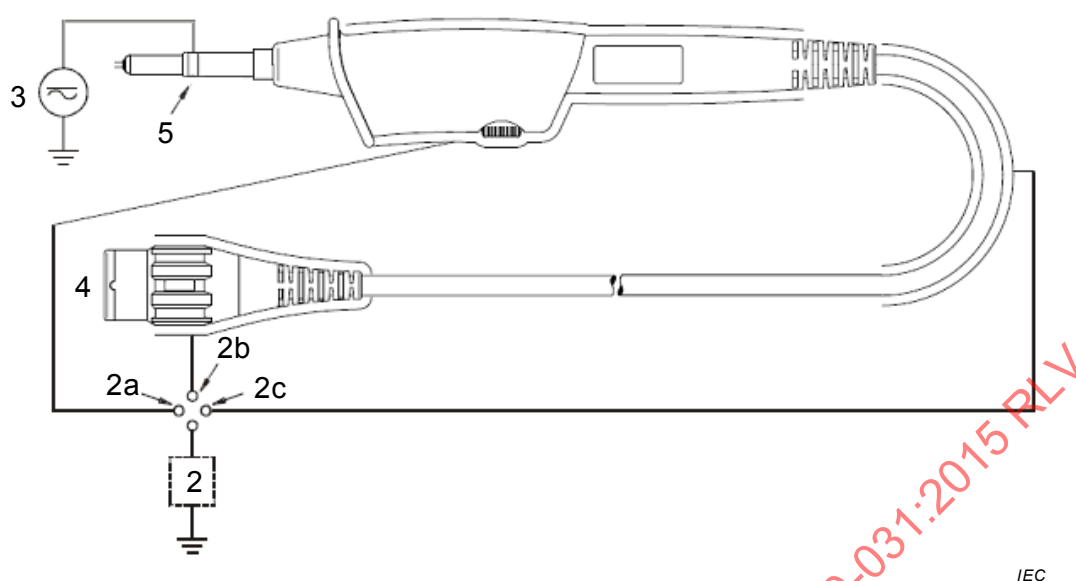
- 1 PROBE TIP of the reference CONNECTOR
- 2 Measurement of voltage or touch current (see annex A for applicable measuring circuits for touch current measurements)
- 3 Maximum RATED voltage for the reference CONNECTOR

Figure 9 – Voltage and touch current measurement for the reference CONNECTOR

6.3.4.2 Probe assemblies with floating outer conductors

For probe assemblies where the outer conductor (shield) connection may be intended to be floating, the test is also performed between the outer conductor PROBE TIP (5) and the earth (see Figure 10).

The touch current is determined by using the applicable measuring circuit of Annex A.

**Key**

- 2 Measurement of voltage or current (see Annex A for applicable measuring circuits for touch current measurements)
 - 2a Connection to metal foil tightly wrapped around parts intended to be hand-held or hand-manipulated
 - 2b Connection to metal foil tightly wrapped around the CONNECTOR
 - 2c Connection to metal foil tightly wrapped around the cable (see 12.3.2)
- 3 Maximum RATED voltage with connection to outer conductor PROBE TIP
- 4 Not connected to test or measuring equipment
- 5 A floating PROBE TIP connected to the shield or outer conductor of the PROBE WIRE

Figure 10 – Voltage and touch current measurement with shielded test probe

6.3.4.3 High frequency test probes

In case of test probes RATED for frequencies above 100 kHz, with floating outer conductor (shield), the maximum allowable voltage between the shield and ACCESSIBLE parts of the probe have to be determined to avoid electrical burns. The touch current shall be measured in the whole frequency range and at maximum voltage in each frequency range.

The measurements are made (see Figure 10):

- a) *between the shield and the foil around the probe body (2a), and*
- b) *between the shield and the foil around the coaxial CONNECTOR (2b), and*
- c) *between the shield and the foil around the PROBE WIRE (2c).*

Alternative to the touch current measurement, the capacitance between the shield and the foil can be measured for the cases a) to c).

The capacitance C_s (measured capacitance between the shield and the foil) together with the circuit from A.3 creates the impedance shown in Figure A.4. The variable parameters of this impedance are the capacity C_s and the frequency (R_1 , C_1 and R_2 are fixed). With the means of these two parameters and with regard to electrical burns the maximum allowable voltage for the test probe can be calculated, for example for an allowable touch current of 70 mA (i.e. 35 V over R_2) as shown in Figure 11 for some values of the capacitance C_s .

The maximum voltage for each frequency can then be calculated.

NOTE *In practice for the calculation with frequencies above 100 kHz, the values of R_1 and C_1 can be ignored.*

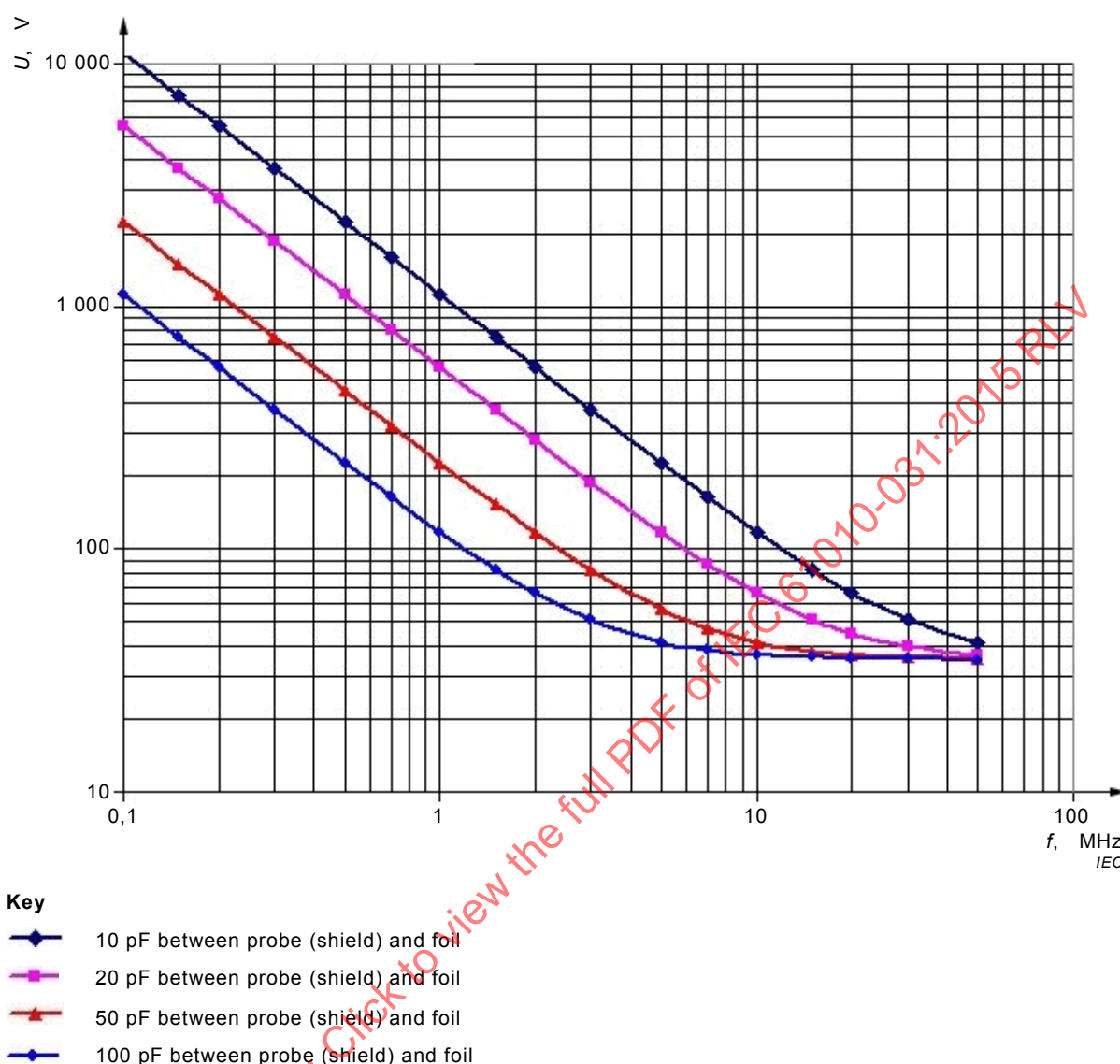


Figure 11 – Maximum test probe input voltage for 70 mA touch current

6.4 Means of protection against electric shock

6.4.1 General

CONNECTORS shall meet the requirements of 6.4.2.

PROBE TIPS shall meet the requirements of 6.4.3.

All other ACCESSIBLE parts of probe assemblies shall be prevented from becoming HAZARDOUS LIVE in both NORMAL CONDITION and SINGLE FAULT CONDITION by one or more of the following means:

- a) DOUBLE INSULATION, consisting of BASIC INSULATION plus SUPPLEMENTARY INSULATION (see 6.4.6);
- b) BASIC INSULATION plus ENCLOSURES (see 6.7.3) or PROTECTIVE FINGERGUARDS;
- c) BASIC INSULATION plus impedance (see 6.4.4);
- d) REINFORCED INSULATION (see 6.4.6);
- e) PROTECTIVE IMPEDANCE (see 6.4.5).

NOTE The PROBE WIRE is considered to be hand-held. Also see Clause 12 for requirements pertaining to the PROBE WIRE.

Conformity is checked by inspection and as specified in 6.4.2 to 6.4.6, as applicable.

6.4.2 CONNECTORS

Insulation, ACCESSIBLE parts and SPACINGS for CONNECTORS of probe assemblies shall meet the applicable requirements of a) to c) below.

Annex E provides information regarding the recommended dimensions of 4 mm CONNECTORS.

a) CONNECTORS in fully-mated position.

- 1) ACCESSIBLE parts of CONNECTORS used only for connecting the probe assembly to the test or measurement equipment and which are not intended to be hand-held during the measurement operation shall be insulated from HAZARDOUS LIVE parts by BASIC INSULATION.
- 2) ACCESSIBLE parts of CONNECTORS which are used for any other purpose or which are intended to be hand-held during the measurement operation shall be insulated from HAZARDOUS LIVE parts by DOUBLE INSULATION or REINFORCED INSULATION.

Conformity is checked by the determination of ACCESSIBLE parts as specified in 6.2 (see Figure 6 b)) and as specified in 6.4.6 for BASIC INSULATION and REINFORCED INSULATION.

b) CONNECTORS in partially-mated position.

ACCESSIBLE parts of CONNECTORS in partially-mated condition shall be insulated from HAZARDOUS LIVE parts by BASIC INSULATION.

Conformity is checked by the determination of ACCESSIBLE parts as specified in 6.2 (see Figure 6 c)) and as specified in 6.4.6 for BASIC INSULATION.

c) CONNECTORS in unmated position.

When the RATED voltages to earth are applied to other CONNECTORS or PROBE TIPS of the probe assembly,

- 1) conductive parts of locking-type or screw-held-type CONNECTORS including CONNECTORS which do not require the use of a TOOL for unlocking or unscrewing are permitted to be ACCESSIBLE while they are in unmated position,
- 2) unmated integrated TERMINALS of STACKABLE CONNECTORS shall be protected by BASIC INSULATION,
- 3) conductive parts of other unmated CONNECTORS shall be prevented from becoming HAZARDOUS LIVE by PROTECTIVE IMPEDANCE (see 6.4.5) or shall have SPACINGS meeting the following requirements:
 - i) for unmated CONNECTORS with voltage RATING up to 1 000 V a.c. or 1 500 V d.c., the applicable SPACINGS of Table 2 from the closest approach of the test finger touching the external parts of the CONNECTOR in the least favorable position (see Figure 6 d), or
 - ii) for unmated CONNECTORS with voltage RATING exceeding 1 000 V a.c. or 1 500 V d.c., the SPACINGS shall not be less than 2.8 mm and shall withstand the voltage test of 6.6 with a test voltage equal to the RATED voltage of the CONNECTOR multiplied by 1,25.

Table 2 – SPACINGS for unmated CONNECTORS RATED up to 1 000 V a.c. or 1 500 V d.c. with HAZARDOUS LIVE conductive parts

Voltage on conductive parts of CONNECTOR	SPACING
V a.c. r.m.s. or V d.c.	mm
> 30 ≤ 300	0,8
> 300 ≤ 600	1,0
> 600 ≤ 1 000	2,6
> 1 000 ≤ 1 500 ^a	2,8
^a only for d.c. voltage	

Conformity is checked by inspection, by measuring the current or voltage to confirm that they do not exceed the applicable levels of 6.3, by the determination of ACCESSIBLE parts as specified in 6.2 (see Figure 6 c)) and measuring the applicable SPACINGS, and if applicable, the voltage test of 6.6.

Insulation covers or sleeves over CONNECTORS which are intended to be hand-held or hand-manipulated by the OPERATOR during measurement or test, and can be removed or displaced by the OPERATOR without the use of a TOOL, are not considered to provide the required protection against electric shock. For example, retractable insulation sleeves are not considered to provide adequate protection. The only case in which they are acceptable is where they are needed for connection to test or measurement equipment that is equipped with TERMINALS which cannot accept fully shrouded CONNECTORS.

Conformity is checked by inspection.

6.4.3 PROBE TIPS

6.4.3.1 General

PROBE TIPS that can become HAZARDOUS LIVE during NORMAL USE (see also 6.1 b)) shall meet the requirements of one of 6.4.3.2, 6.4.3.3, or 6.4.3.4 .

PROBE TIPS that can be used as CONNECTORS shall also meet the requirements of 6.4.3.5.

NOTE See Clause 13 for additional requirements for the exposed conductive parts of PROBE TIPS.

SPRING-LOADED CLIPS and similar probes that are intended to pierce the insulation of a wire to touch the conductor for measuring voltage purposes shall not have a voltage RATING above the levels of 6.3.2 a).

Conformity is checked by inspection and measurement.

6.4.3.2 Protection by a PROTECTIVE FINGERGUARD

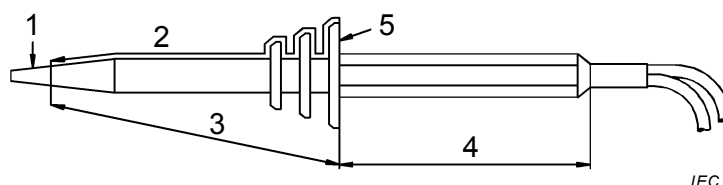
If a conductive part of a PROBE TIP can become HAZARDOUS LIVE, a PROTECTIVE FINGERGUARD shall be fitted to reduce the risk of touching an exposed conductive part of the PROBE TIP, and to provide an indication of the limit beyond which it may be hazardous to touch the probe body during use.

SPACINGS between the HAZARDOUS LIVE part of the PROBE TIP and the hand-held side of the PROTECTIVE FINGERGUARD shall be those specified for REINFORCED INSULATION.

The height of the PROTECTIVE FINGERGUARD from the side where the fingers are intended to be applied shall be at least 2 mm and the thickness shall be less than twice the height.

The PROTECTIVE FINGERGUARD of probe assemblies which have a voltage RATING above the levels of 6.3.2 a) shall extend across at least 80 % of the sides where the fingers are intended to be applied.

Figure 12 gives an example of a probe assembly with a PROTECTIVE FINGERGUARD and indicates applicable SPACINGS.



Key

- 1 PROBE TIP
- 2 CREEPAGE DISTANCE (along surface)
- 3 CLEARANCE (in air)
- 4 hand-held area of probe body
- 5 PROTECTIVE FINGERGUARD

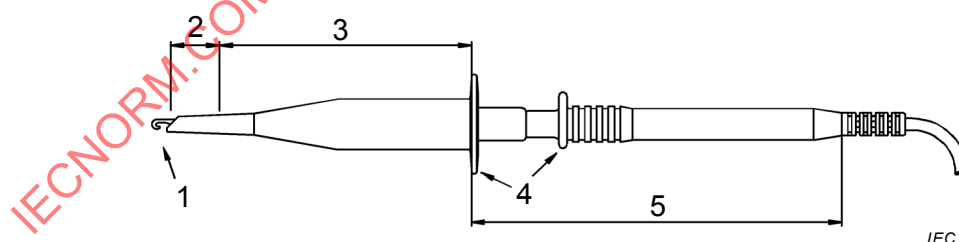
Figure 12 – Protection by a PROTECTIVE FINGERGUARD

6.4.3.3 Protection by distance

SPRING-LOADED CLIPS RATED for voltages to earth up to 1 kV are acceptable without a PROTECTIVE FINGERGUARD provided that:

- a) actuation of the spring-loaded mechanism prevents the OPERATOR from touching a HAZARDOUS LIVE part; and
- b) the SPACINGS between the PROBE TIP and the nearest surface which the OPERATOR needs to touch to actuate the mechanism are increased by an additional protective distance of 45 mm.

Figure 13 gives an example of a probe assembly protected by distance and indicates applicable SPACINGS.



Key

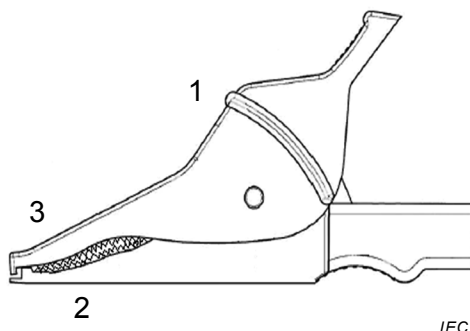
- 1 PROBE TIP
- 2 CLEARANCE and CREEPAGE DISTANCE as specified in 6.5
- 3 additional protective distance
- 4 actuating parts
- 5 hand-held area of the probe assembly

Figure 13 – Protection by distance

6.4.3.4 Protection by tactile indicator

SPRING-LOADED CLIPS RATED for MEASUREMENT CATEGORY II which require finger pressure at about 90° to the axis of the clip are acceptable without a PROTECTIVE FINGERGUARD, provided that there is a tactile indicator to indicate the limit of safe access for the OPERATOR.

Figure 14 gives an example of a SPRING-LOADED CLIP with a tactile indicator.



Key

- 1 tactile indicator
- 2 metal jaws
- 3 insulated metal jaws

Figure 14 – Protection by tactile indicator

6.4.3.5 PROBE TIPS used as CONNECTORS

PROBE TIPS which can be used as CONNECTORS (for example, a PROBE TIP that is also intended to be connected to a SPRING-LOADED CLIP) shall also meet the requirements for CONNECTORS in fully-mated position and partially-mated position (see also 6.4.2 a) and b)).

6.4.4 Impedance

Impedance used as an additional means of protection in conjunction with BASIC INSULATION shall meet all the following requirements:

- a) it shall limit the current or voltage to not more than the applicable levels of 6.3.3;
- b) it shall be RATED for the WORKING VOLTAGE and for the amount of power that it will dissipate;
- c) SPACINGS between terminations of the impedance shall meet the applicable requirements of 6.5 for BASIC INSULATION.

Conformity is checked by inspection, by measuring the voltage or current to confirm that they do not exceed the levels of 6.3.3, and by measuring CLEARANCE and CREEPAGE DISTANCE as specified in 6.5.

6.4.5 PROTECTIVE IMPEDANCE

A PROTECTIVE IMPEDANCE shall limit the current or voltage to the levels of 6.3.2 in NORMAL CONDITION and 6.3.3 in SINGLE FAULT CONDITION (see also 4.4.2.2).

Insulation between the terminations of the PROTECTIVE IMPEDANCE shall meet the requirements of 6.4.6 for DOUBLE INSULATION or REINFORCED INSULATION.

A PROTECTIVE IMPEDANCE shall be one or more of the following:

- a) an appropriate single component which shall be constructed, selected and tested so that safety and reliability for protection against electric shock is assured. In particular, the component shall be:
 - 1) RATED for twice the WORKING VOLTAGE;
 - 2) if a resistor, RATED for twice the power dissipation for the WORKING VOLTAGE;
 - 3) if a capacitor, RATED for the maximum transient overvoltage;
- b) a combination of components.

When a combination of components is used, the SPACINGS shall take into account the WORKING VOLTAGE across each insulation.

A PROTECTIVE IMPEDANCE shall not be a single electronic device that employs electron conduction in a vacuum, gas or semiconductor.

Conformity is checked by inspection, by measuring the current or voltage to confirm that they do not exceed the applicable levels of 6.3 and by measuring SPACINGS as specified in 6.5. Conformity of a single component is checked by inspection of its RATING.

6.4.6 BASIC INSULATION, SUPPLEMENTARY INSULATION, DOUBLE INSULATION and REINFORCED INSULATION

SPACINGS and solid insulation forming BASIC INSULATION, SUPPLEMENTARY INSULATION or REINFORCED INSULATION between ACCESSIBLE parts and HAZARDOUS LIVE parts shall meet the applicable requirements of 6.5.

DOUBLE INSULATION is comprised of BASIC INSULATION and SUPPLEMENTARY INSULATION, each of which shall meet the applicable requirements of 6.5.

Conformity is checked as specified in 6.5.

6.5 Insulation requirements

6.5.1 The nature of insulation

6.5.1.1 General

Insulation between circuits and ACCESSIBLE parts (see 6.2) or between separate circuits consists of SPACINGS, solid insulation, or a combination of SPACINGS and solid insulation. SPACINGS comprise both CLEARANCES and CREEPAGE DISTANCES.

When used to provide protection against a HAZARD, the insulation needs to withstand the electric stresses that are caused by the voltages that may appear on parts of the probe assembly.

The requirements for insulation depend on:

- a) the required level of insulation (BASIC INSULATION, SUPPLEMENTARY INSULATION, or REINFORCED INSULATION);
- b) the maximum transient overvoltage that may appear on the circuit, either as a result of an external event (such as a lightning strike or a switching transient), or as the result of the operation of the probe assembly;
- c) the WORKING VOLTAGE;
- d) the POLLUTION DEGREE of the micro-environment.

6.5.1.2 SPACINGS

6.5.1.2.1 General

SPACINGS are a combination of CLEARANCES and CREEPAGE DISTANCES, which are specified in 6.5.1.2.2 and 6.5.1.2.3 so as to withstand the voltages that appear on the system for which the probe assembly is intended. Also, they are selected to take account of the intended environmental conditions and any protective devices fitted within the probe assembly or required by the manufacturer's instructions.

6.5.1.2.2 CLEARANCES

CLEARANCES are specified to withstand the maximum transient overvoltage that can be present on the circuit to which the probe assembly can be connected in NORMAL USE. If transient overvoltages cannot occur, CLEARANCES are based on the WORKING VOLTAGE.

The values for CLEARANCES given in Table 6 and Table 7 are based on absolute inhomogeneous field conditions. Reduced CLEARANCES may apply to constructions which are shaped in a way to create a more homogeneous condition, because the dielectric strength of an air gap is dependent on the shape of the electric field within the gap, as well as on the width of the gap.

No particular value can be specified for a reduced CLEARANCE for these more homogeneous constructions, but it can be tested by a voltage test (see 6.6). CLEARANCES which meet the values of Table 6 and Table 7 will meet the requirements for any construction and need not be tested by a voltage test, but can be checked by measurement alone.

If the probe assembly is RATED to operate at an altitude greater than 2 000 m, the values for CLEARANCES are multiplied by the applicable factor of Table 3.

Table 3 – Multiplication factors for CLEARANCES of probe assembly RATED for operation at altitudes up to 5 000 m

RATED operating altitude m	Multiplication factor
Up to 2 000	1,00
2 001 to 3 000	1,14
3 001 to 4 000	1,29
4 001 to 5 000	1,48

In all cases, the minimum CLEARANCE value for POLLUTION DEGREE 2 is 0,2 mm and for POLLUTION DEGREE 3 is 0,8 mm.

See Annex C for details of how to measure CLEARANCES.

Conformity is checked by inspection, measurement, and in the case of more homogeneous construction by the voltage test of 6.6.

6.5.1.2.3 CREEPAGE DISTANCES

CREEPAGE DISTANCES shall be based on the actual WORKING VOLTAGE which stresses the insulation (see Table 9). Linear interpolation of CREEPAGE DISTANCE is permissible.

Coatings that meet the requirements of Annex H of IEC 61010-1:2010 when applied to the outer surfaces of printed wiring boards reduce the POLLUTION DEGREE of the coated area to POLLUTION DEGREE 1.

For REINFORCED INSULATION, the value of the CREEPAGE DISTANCE is twice the value specified for BASIC INSULATION.

CREEPAGE DISTANCES protect against tracking on the surface of an insulation, which is a long-term phenomenon. Therefore, they cannot be confirmed by voltage testing, but have to be measured as specified in Annex C.

Conformity is checked by inspection and measurement.

6.5.1.2.4 SOLID INSULATION

6.5.1.2.4.1 General

Solid insulation shall withstand the electric and mechanical stresses that may occur in NORMAL USE, in all RATED environmental conditions (see 1.4).

The manufacturer should take the expected life of the probe assembly into account when selecting insulating materials.

Conformity is checked by inspection, and by the a.c. voltage test of 6.6.5.1, or for probe assemblies stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4.:

Table 4 – Test voltages for testing solid insulation

Nominal a.c. r.m.s. or d.c. RATED voltage to earth V	Test voltage			
	1 min a.c. test V r.m.s.		1 min d.c. test V d.c.	
	BASIC INSULATION and SUPPLEMENTARY INSULATION	REINFORCED INSULATION	BASIC INSULATION and SUPPLEMENTARY INSULATION	REINFORCED INSULATION
≤ 150	1 350	2 700	1 900	3 800
> 150 ≤ 300	1 500	3 000	2 100	4 200
> 300 ≤ 600	1 800	3 600	2 550	5 100
> 600 ≤ 1000	2 200	4 400	3 100	6 200
> 1 000 ≤ 63 000	1,5 times the RATED voltage to earth or 2 200 V, whichever is larger	Twice the RATED voltage to earth or 4 400 V, whichever is larger	1,5 times the RATED voltage to earth or 3 100 V, whichever is larger	Twice the RATED voltage to earth or 6 200 V, whichever is larger

Solid insulation shall also meet the following requirements, as applicable:

- for solid insulation used as an ENCLOSURE or PROTECTIVE FINGERGUARD, the requirements of Clause 8;
- for moulded and potted parts, the requirements of 6.5.1.2.4.2;
- for inner layers of printed wiring boards, the requirements of 6.5.1.2.4.3;
- for thin-film insulation, the requirements of 6.5.1.2.4.4.

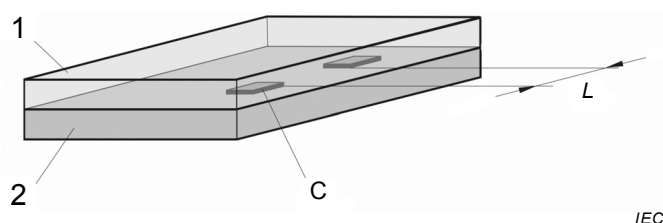
Conformity is checked as specified in 6.5.1.2.4.2 to 6.5.1.2.4.4, and in Clause 8, as applicable.

6.5.1.2.4.2 Moulded and potted parts

For BASIC INSULATION, SUPPLEMENTARY INSULATION, and REINFORCED INSULATION, conductors located on an interface between the same two layers moulded together (see Figure 15,

item L) shall be separated by at least the applicable minimum distance of Table 5 after the moulding is completed.

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.



Key

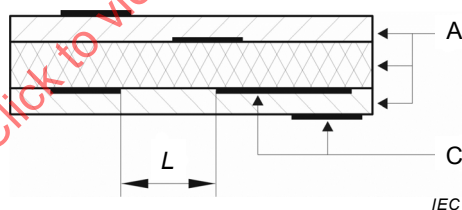
- 1 Layer 1
- 2 Layer 2
- C Conductor
- L Distance between conductors

Figure 15 – Distance between conductors on an interface between two layers

6.5.1.2.4.3 Insulating layers of printed wiring boards

For BASIC INSULATION, SUPPLEMENTARY INSULATION and REINFORCED INSULATION, conductors located between the same two layers (see Figure 16, item L) shall be separated by at least the applicable minimum distance of Table 5.

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.



Key

- L Distance between conductors on the same surface
- A Layers
- C Conductors

Figure 16 – Distance between adjacent conductors along an interface of two layers

Table 5 – Minimum values for distance or thickness

WORKING VOLTAGE V	Minimum thickness mm	Minimum distance <i>L</i> (see Figure 16) ^a mm
≤ 300	0,4	0,4
> 300 ≤ 600	0,6	0,6
> 600 ≤ 1 000 ^b	1,0	1,0

^a These values apply for BASIC INSULATION, SUPPLEMENTARY INSULATION and REINFORCED INSULATION.

^b For voltage above 1 000 V, a partial discharge test should be used (test procedure under consideration)

REINFORCED INSULATION of insulating layers of printed wiring boards (see Figure 16, item A) shall also have adequate electric strength through the respective layers. One of the following methods shall be used.

- a) The thickness of the insulation is at least the value of Table 5;

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.

- b) The insulation is assembled from at least two separate layers of printed wiring board materials, each of which is RATED by the manufacturer of the material for an electric strength of at least the value of the test voltage of the Table 4 for BASIC INSULATION.

Conformity is checked by inspection of the manufacturer's specifications.

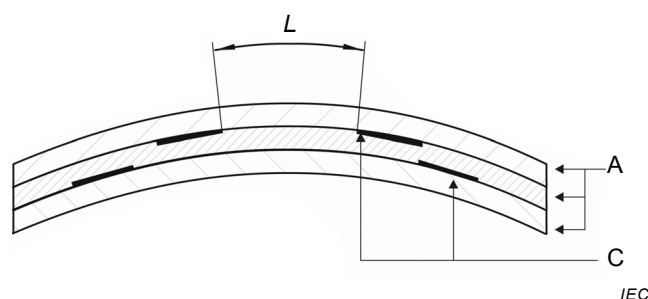
- c) The insulation is assembled from at least two separate layers of printed wiring board materials, and the combination of layers is RATED by the manufacturer of the material for an electric strength of at least the value of the test voltage of the Table 4 for REINFORCED INSULATION.

Conformity is checked by inspection of the manufacturer's specifications.

6.5.1.2.4.4 Thin-film insulation

For BASIC INSULATION, SUPPLEMENTARY INSULATION, and REINFORCED INSULATION, conductors located between the same two layers (see Figure 17, item L).shall be separated by at least the applicable SPACINGS.

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.



Key

L distance between adjacent conductors

A layers of thin-film material such as tape and polyester film

C conductors

NOTE There might be air present between the layers.

Figure 17 – Distance between adjacent conductors located between the same two layers

REINFORCED INSULATION through the layers of thin-film insulation shall also have adequate electric strength. One of the following methods shall be used.

- a) The thickness through the insulation is at least the value of Table 5.

Conformity is checked by inspection and either by measurement of the separation or by inspection of the manufacturer's specifications.

- b) The insulation consists of at least two separate layers of thin-film materials, each of which is RATED by the manufacturer of the material for an electric strength of at least the value of the test voltage of the Table 4 for BASIC INSULATION.

Conformity is checked by inspection of the manufacturer's specifications.

- c) The insulation consists of at least three separate layers of thin-film materials, any two of which have been tested to exhibit adequate electric strength.

Conformity is checked by the a.c. voltage test of 6.6.5.1, or for probe assemblies stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min applied to two of the three layers using the applicable test voltage of Table 4 for REINFORCED INSULATION.

NOTE For the purposes of this test, a special sample can be assembled with only two layers of the material.

6.5.2 Insulation requirements for probe assemblies

6.5.2.1 GENERAL

Measuring circuits are subjected to WORKING VOLTAGES and transient stresses from the circuit to which they are connected during measurement or test. When the measuring circuit is used to measure mains supplies or circuits directly connected to them, the transient stresses can be estimated by the location within the installation at which the measurement is performed. When the measuring circuit is used to measure any other electrical signal, the transient stresses should be considered by the OPERATOR to ensure that they do not exceed the capabilities of the probe assembly.

6.5.2.2 CLEARANCES for probe assemblies of MEASUREMENT CATEGORIES II, III and IV

CLEARANCES for probe assemblies of MEASUREMENT CATEGORIES II, III and IV are specified in Table 6.

Table 6 – CLEARANCES for probe assemblies of MEASUREMENT CATEGORIES II, III and IV

Nominal a.c. r.m.s. line-to-neutral or d.c. voltage of mains to which the probe assembly is designed to be connected V	CLEARANCE mm					
	BASIC INSULATION and SUPPLEMENTARY INSULATION			REINFORCED INSULATION		
	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV	MEASUREMENT CATEGORY II	MEASUREMENT CATEGORY III	MEASUREMENT CATEGORY IV
≤ 50	0,04	0,1	0,5	0,1	0,3	1,5
> 50 ≤ 100	0,1	0,5	1,5	0,3	1,5	3,0
> 100 ≤ 150	0,5	1,5	3,0	1,5	3,0	6,0
> 150 ≤ 300	1,5	3,0	5,5	3,0	5,9	10,5
> 300 ≤ 600	3,0	5,5	8	5,9	10,5	14,3
> 600 ≤ 1 000	5,5	8	14	10,5	14,3	24,3
> 1 000 ≤ 1 500 ^a	8	11	18	14,3	19,4	31,4

^a only for d.c. voltage

Conformity is checked by inspection and measurement or by the a.c. voltage test of 6.6.5.1 with a duration of at least 5 s or the impulse voltage test of 6.6.5.3, or for probe assemblies stressed only by d.c., the 1 min d.c. voltage test of 6.6.5.2 or the impulse voltage test of 6.6.5.3, using the test voltage of Table 10 for the required clearance.

6.5.2.3 CLEARANCES for probe assemblies which are not RATED for MEASUREMENT CATEGORIES II, III, or IV

6.5.2.3.1 General

CLEARANCES for probe assemblies which are not RATED for MEASUREMENT CATEGORIES II, III, or IV are calculated according to 6.5.2.3.2.

If they have either of the following characteristics, CLEARANCES are also determined according to 6.5.2.3.3, and the larger of the two CLEARANCE values is the required clearance:

- a) the WORKING VOLTAGE includes a recurring peak voltage that may include a periodic non-sinusoidal waveform or a non-periodic waveform that occurs with some regularity;
- b) the WORKING VOLTAGE has a frequency above 30 kHz.

6.5.2.3.2 CLEARANCE calculation

CLEARANCES for BASIC INSULATION and SUPPLEMENTARY INSULATION are determined from the following formula:

$$\text{CLEARANCE} = D_1 + F \times (D_2 - D_1)$$

where

F is a factor, determined from one of the equations:

$$F = (1,25 \times U_w/U_m) - 0,25 \quad \text{if } U_w/U_m > 0,2$$

$$F = 0 \quad \text{if } U_w/U_m \leq 0,2$$

where

$$U_m = U_w + U_t;$$

U_w = the maximum peak value of the WORKING VOLTAGE;

U_t = the maximum additional transient overvoltage

D_1 and D_2 are values taken from Table 7 for U_m .

where

D_1 represents the CLEARANCE that would be applicable to a transient overvoltage with the shape of a $1,2 \times 50 \mu\text{s}$ impulse

D_2 represents the CLEARANCE that would be applicable to the peak WORKING VOLTAGE without any transient overvoltage

CLEARANCES for REINFORCED INSULATION are twice the values for BASIC INSULATION.

Conformity is checked by inspection and measurement or by the a.c. voltage test of 6.6.5.1 with a duration of at least 5 s, or the impulse voltage test of 6.6.5.3, using the applicable voltage from Table 10 for the required CLEARANCE.

Table 7 – CLEARANCE values for the calculation of 6.5.2.3.2

Maximum voltage U_m	CLEARANCE		Maximum voltage U_m	CLEARANCE	
	D_1	D_2		D_1	D_2
V	mm	mm	V	mm	mm
14,1 to 266	0,010	0,010	4 000	2,93	6,05
283	0,010	0,013	4 530	3,53	7,29
330	0,010	0,020	5 660	4,92	10,1
354	0,013	0,025	6 000	5,37	10,8
453	0,027	0,052	7 070	6,86	13,1
500	0,036	0,071	8 000	8,25	15,2
566	0,052	0,10	8 910	9,69	17,2
707	0,081	0,20	11 300	12,9	22,8
800	0,099	0,29	14 100	16,7	29,5
891	0,12	0,41	17 700	21,8	38,5
1 130	0,19	0,83	22 600	29,0	51,2
1 410	0,38	1,27	28 300	37,8	66,7
1 500	0,45	1,40	35 400	49,1	86,7
1 770	0,75	1,79	45 300	65,5	116
2 260	1,25	2,58	56 600	85,0	150
2 500	1,45	3,00	70 700	110	195
2 830	1,74	3,61	89 100	145	255
3 540	2,44	5,04	100 000	165	290
Linear interpolation is allowed.					

NOTE The following is an example calculation:

CLEARANCE for REINFORCED INSULATION for a WORKING VOLTAGE with peak value of 3 500 V and an additional transient voltage of 4 500 V (this can be expected within an electronic switching-circuit):

Maximum voltage $U_m = U_w + U_t = (3\,500 + 4\,500) \text{ V} = 8\,000 \text{ V}$

$$U_w / U_m = 3\,500 / 8\,000 = 0,44 > 0,2$$

$$\text{thus } F = (1,25 \times U_w / U_m) - 0,25 = (1,25 \times 3\,500 / 8\,000) - 0,25 = 0,297$$

Values derived from Table 7 at 8 000 V:

$$D_1 = 8,25 \text{ mm}, D_2 = 15,2 \text{ mm}$$

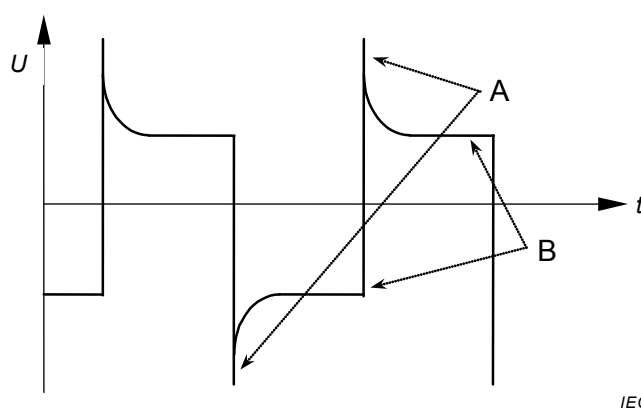
$$\text{CLEARANCE} = D_1 + F \times (D_2 - D_1) = 8,25 + 0,297 \times (15,2 - 8,25) = 8,25 + 2,06 = 10,3 \text{ mm}$$

For REINFORCED INSULATION the value is doubled. CLEARANCE = 20,6 mm.

6.5.2.3.3 CLEARANCES for probe assemblies subjected to recurring peak voltages, or WORKING VOLTAGES with frequencies above 30 kHz, or both

CLEARANCES for BASIC INSULATION and SUPPLEMENTARY INSULATION for probe assemblies subjected to recurring peak voltages with frequencies not exceeding 30 kHz shall meet the values of the second column of Table 8, using the recurring peak voltage as the index (see Figure 18 for an example of a recurring peak voltage).

NOTE In most practical recurring waveforms, the fundamental frequency has a substantially higher amplitude than the harmonics. Therefore, the fundamental frequency is to be used for determining whether the frequency of the waveform exceeds 30 kHz. However, the peak amplitude of the waveform, and not the peak amplitude of the fundamental component of the waveform, is to be used for determining SPACINGS. For more information, see E.2 of IEC 60664-4:2005.

**Key**

A peak value of recurring voltage

B WORKING VOLTAGE value

Figure 18 – Example of recurring peak voltage

CLEARANCES for BASIC INSULATION and SUPPLEMENTARY INSULATION for probe assemblies that are subjected to WORKING VOLTAGES with frequencies above 30 kHz shall meet the values of the third column of Table 8, using the peak value of the WORKING VOLTAGE as the index.

CLEARANCES for BASIC INSULATION and SUPPLEMENTARY INSULATION for probe assemblies that may be subjected to both recurring peak voltages and WORKING VOLTAGES with frequencies above 30 kHz shall meet the higher of these requirements.

CLEARANCES for REINFORCED INSULATION are twice the values for BASIC INSULATION.

Conformity is checked by inspection and measurement.

Table 8 – CLEARANCES for BASIC INSULATION in probe assemblies subjected to recurring peak voltages or WORKING VOLTAGES with frequencies above 30 kHz

Voltage peak value	CLEARANCE	
	Frequencies up to 30 kHz	Frequencies above 30 kHz
V	mm	mm
0 to 330	0,01	0,02
400	0,02	0,04
500	0,04	0,07
600	0,06	0,11
800	0,13	0,26
1 000	0,26	0,48
1 200	0,42	0,76
1 500	0,76	1,1
2 000	1,27	1,8
2 500	1,8	2,6
3 000	2,4	3,5
4 000	3,8	5,7
5 000	5,7	8
6 000	7,9	10
8 000	11	15
10 000	15,2	20
12 000	19	25
15 000	25	32
20 000	34	44
25 000	44	58
30 000	55	72
40 000	77	100
50 000	100	
Linear interpolation is allowed.		

6.5.2.4 CREEPAGE DISTANCES

CREEPAGE DISTANCES for BASIC INSULATION or SUPPLEMENTARY INSULATION for probe assemblies shall meet the applicable values of Table 9, based on the WORKING VOLTAGE which stresses the insulation. Values for REINFORCED INSULATION are twice the values for BASIC INSULATION.

Conformity is checked by inspection and measurement.

Table 9 – CREEPAGE DISTANCES for BASIC INSULATION or SUPPLEMENTARY INSULATION

WORKING VOLTAGE a.c. r.m.s. or d.c.	CREEPAGE DISTANCES				
	Printed wiring board material		Other insulating material		
	POLLUTION DEGREE		POLLUTION DEGREE		
	1	2	1	2	3
V	mm	mm	mm	mm	mm
10	0,025	0,04	0,08	0,40	1,00
12,5	0,025	0,04	0,09	0,42	1,05
16	0,025	0,04	0,10	0,45	1,10
20	0,025	0,04	0,11	0,48	1,20
25	0,025	0,04	0,125	0,50	1,25
32	0,025	0,04	0,14	0,53	1,3
40	0,025	0,04	0,16	0,56	1,4
50	0,025	0,04	0,18	0,60	1,5
63	0,040	0,063	0,20	0,63	1,6
80	0,063	0,10	0,22	0,67	1,7
100	0,10	0,16	0,25	0,71	1,8
125	0,16	0,25	0,28	0,75	1,9
160	0,25	0,40	0,32	0,80	2,0
200	0,40	0,63	0,42	1,00	2,5
250	0,56	1,0	0,56	1,25	3,2
320	0,75	1,6	0,75	1,60	4,0
400	1,0	2,0	1,0	2,0	5,0
500	1,3	2,5	1,3	2,5	6,3
630	1,8	3,2	1,8	3,2	8,0
800	2,4	4,0	2,4	4,0	10,0
1 000	3,2	5,0	3,2	5,0	12,5
1 250	4,2	6,3	4,2	6,3	16
1 600	5,6	8,0	5,6	8,0	20
2 000	7,5	10,0	7,5	10,0	25
2 500	10,0	12,5	10,0	12,5	32
3 200	12,5	16	12,5	16	40
4 000	16	20	16	20	50
5 000	20	25	20	25	63
6 300	25	32	25	32	80
8 000	32	40	32	40	100
10 000	40	50	40	50	125
12 500	50	63	50	63	156
16 000	63	80	63	80	200
20 000	80	100	80	100	250
25 000	100	125	100	125	315
32 000	125	160	125	160	400
40 000	160	200	160	200	500
50 000	200	250	200	250	625
63 000	250	320	250	320	790

Linear interpolation is allowed.

6.6 Procedure for voltage tests

6.6.1 General

The following test procedures apply to type testing, and deterioration of the test specimen may occur. Further use of the test specimen may not be appropriate.

Test equipment for the voltage tests is specified in IEC 61180-1 and IEC 61180-2.

The reference point for the voltage tests is one or more of the following, bonded together if more than one.

- a) *Any ACCESSIBLE conductive part, except for any live parts permitted to be ACCESSIBLE because they do not exceed the values of 6.3.2 and any ACCESSIBLE conductive parts which are allowed to be HAZARDOUS LIVE by the exceptions of 6.1.*
- b) *Any ACCESSIBLE insulating part of the ENCLOSURE, covered with metal foil everywhere except around CONNECTORS. For test voltages up to 10 kV a.c. peak or d.c., the distance from foil to CONNECTOR is not more than 20 mm. For higher voltages the distance is the minimum to prevent flashover.*
- c) *ACCESSIBLE parts of controls with parts made of insulating material being wrapped in metal foil or having soft conductive material pressed against them.*

6.6.2 Humidity preconditioning

To ensure that the probe assembly does not become hazardous in the humidity conditions of 1.4, it is subjected to humidity preconditioning before the voltage tests. The probe assembly is not operated during preconditioning.

If wrapping in foil is required by 6.6.1, the foil is applied after humidity preconditioning and recovery.

Electrical components, covers, and other parts which can be removed by hand are removed and subjected to the humidity preconditioning together with the main part.

Preconditioning is carried out in a humidity chamber containing air with a humidity of 93 % RH $\pm$ 3 % RH. The temperature of the air in the chamber is maintained at 40 °C $\pm$ 2 °C.

Before applying humidity, the probe assembly is brought to a temperature of 42 °C $\pm$ 2 °C, normally by keeping it at this temperature for at least 4 h before the humidity preconditioning.

The air in the chamber is stirred and the chamber is designed so that condensation will not precipitate on the probe assembly.

The probe assembly remains in the chamber for 48 h, after which it is removed and allowed a recovery period of 2 h under the environmental conditions of 4.3.1, after which parts removed (see above) are re-installed.

6.6.3 Conduct of tests

The tests are performed and completed within 1 h of the end of the recovery period after humidity preconditioning. The probe assembly is not operated during the tests.

Voltage tests are not made between two circuits, or between a circuit and an ACCESSIBLE conductive part, if they are connected to each other or not separated from each other.

PROTECTIVE IMPEDANCE in parallel with the insulation to be tested is disconnected.

If two or more protective means are used in combination (see 6.4), it is likely that the voltages specified for DOUBLE INSULATION and REINFORCED INSULATION would be applied to parts of circuits which are not required to withstand these voltages. To avoid this, such parts may be disconnected during the tests, or the parts of circuits where DOUBLE INSULATION or REINFORCED INSULATION is required may be tested separately.

6.6.4 Test voltages

Voltage tests for solid insulation are applied using the values specified in Table 4.

Voltage tests for CLEARANCES are applied using the values specified in Table 10.

The CLEARANCE in case of homogeneous construction (see 6.5.1.2.2), is tested with an a.c., d.c., or peak impulse voltage with the peak value specified in Table 10 for the value of CLEARANCE specified for inhomogeneous construction.

The values of Table 10 apply to test sites located at 2 000 m altitude. For other test site altitudes, the correction factors of Table 11 are applied to the values of Table 10 when testing CLEARANCE but not when testing solid insulation.

NOTE *The electric testing of CLEARANCES will also stress the associated solid insulation.*

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 PLV

Table 10 – Test voltages based on CLEARANCES

Required CLEARANCE	Impulse 1,2/50 µs	a.c. r.m.s. 50/60 Hz	a.c. peak 50/60 Hz or d.c.	Required CLEARANCE	Impulse 1,2/50 µs	a.c. r.m.s. 50/60 Hz	a.c. peak 50/60 Hz or d.c.
mm	V peak	V	V	mm	V peak	V	V
0,010	330	230	330	16,5	14 000	7 600	10 700
0,025	440	310	440	17,0	14 300	7 800	11 000
0,040	520	370	520	17,5	14 700	8 000	11 300
0,063	600	420	600	18,0	15 000	8 200	11 600
0,1	806	500	700	19	15 800	8 600	12 100
0,2	1 140	620	880	20	16 400	9 000	12 700
0,3	1 310	710	1 010	25	19 900	10 800	15 300
0,5	1 550	840	1 200	30	23 300	12 600	17 900
1,0	1 950	1 060	1 500	35	26 500	14 400	20 400
1,4	2 440	1 330	1 880	40	29 700	16 200	22 900
2,0	3 100	1 690	2 400	45	32 900	17 900	25 300
2,5	3 600	1 960	2 770	50	36 000	19 600	27 700
3,0	4 070	2 210	3 130	55	39 000	21 200	30 000
3,5	4 510	2 450	3 470	60	42 000	22 900	32 300
4,0	4 930	2 680	3 790	65	45 000	24 500	34 600
4,5	5 330	2 900	4 100	70	47 900	26 100	36 900
5,0	5 720	3 110	4 400	75	50 900	27 700	39 100
5,5	6 100	3 320	4 690	80	53 700	29 200	41 300
6,0	6 500	3 520	4 970	85	56 610	30 800	43 500
6,5	6 800	3 710	5 250	90	59 400	32 300	45 700
7,0	7 200	3 900	5 510	95	62 200	33 800	47 900
7,5	7 500	4 080	5 780	100	65 000	35 400	50 000
8,0	7 800	4 300	6 030	110	70 500	38 400	54 200
8,5	8 200	4 400	6 300	120	76 000	41 300	58 400
9,0	8 500	4 600	6 500	130	81 300	44 200	62 600
9,5	8 800	4 800	6 800	140	86 600	47 100	66 700
10,0	9 100	4 950	7 000	150	91 900	50 000	70 700
10,5	9 500	5 200	7 300	160	97 100	52 800	74 700
11,0	9 900	5 400	7 600	170	102 300	55 600	78 700
11,5	10 300	5 600	7 900	180	107 400	58 400	82 600
12,0	10 600	5 800	8 200	190	112 500	61 200	86 500
12,5	11 000	6 000	8 500	200	117 500	63 900	90 400
13,0	11 400	6 200	8 800	210	122 500	66 600	94 200
13,5	11 800	6 400	9 000	220	127 500	69 300	98 000
14,0	12 100	6 600	9 300	230	132 500	72 000	102 000
14,5	12 500	6 800	9 600	240	137 300	74 700	106 000
15,0	12 900	7 000	9 900	250	142 200	77 300	109 400
15,5	13 200	7 200	10 200	264	149 000	81 100	115 000
16,0	13 600	7 400	10 500				

Linear interpolation is allowed.

**Table 11 – Correction factors according to test site altitude
for test voltages for CLEARANCES**

	Correction factors			
Test voltage peak	$\geq 327 \text{ V} < 600 \text{ V}$	$\geq 600 \text{ V} < 3\,500 \text{ V}$	$\geq 3\,500 \text{ V} < 25 \text{ kV}$	$\geq 25 \text{ kV}$
Test voltage r.m.s.	$\geq 231 \text{ V} < 424 \text{ V}$	$\geq 424 \text{ V} < 2\,475 \text{ V}$	$\geq 2\,475 \text{ V} < 17,7 \text{ kV}$	$\geq 17,7 \text{ kV}$
Test site altitude m				
0	1,08	1,16	1,22	1,24
500	1,06	1,12	1,16	1,17
1 000	1,04	1,08	1,11	1,12
2 000	1,00	1,00	1,00	1,00
3 000	0,96	0,92	0,89	0,88
4 000	0,92	0,85	0,80	0,79
5 000	0,88	0,78	0,71	0,70
Linear interpolation is allowed.				

6.6.5 Test procedures

6.6.5.1 The a.c. voltage test

The voltage test equipment shall have a regulated output capable of maintaining the test voltage throughout the test. The waveform of the power frequency test voltage shall be substantially sinusoidal. This requirement is fulfilled if the ratio between the peak value and the r.m.s. value is $\sqrt{2} \pm 3 \%$.

The test voltage is raised uniformly from 0 V to the specified value within 5 s and held at that value for at least the specified time.

No flashover of CLEARANCES or breakdown of solid insulation shall occur during the test.

6.6.5.2 The 1 min d.c. voltage test

The voltage test equipment shall have a regulated output capable of maintaining the test voltage throughout the test. The d.c. test voltage shall be substantially free of ripple. This requirement is fulfilled if the ratio between the peak value of the voltage and the average value is $1,0 \pm 3 \%$.

The d.c. test voltage is raised uniformly from 0 V to the specified value within 5 s and held at that value for at least 1 min.

No flashover of CLEARANCES or breakdown of solid insulation shall occur during the test.

6.6.5.3 The impulse voltage test

The test shall be conducted for five impulses of each polarity with an interval of at least 1 s between impulses. The impulse voltage test is carried out with a 1,2/50 μs waveform (see Figure 1 of IEC 61180-1:1992). The wave shape of each impulse shall be observed.

When verifying CLEARANCES within probe assembly by an impulse voltage test, it is necessary to ensure that the specified impulse voltage appears at the CLEARANCE.

No flashover of CLEARANCES or breakdown of solid insulation shall occur during the test, but partial discharges are allowed.

6.7 Constructional requirements for protection against electric shock

6.7.1 General

If a failure could cause a HAZARD,

- a) the security of wiring connections subject to mechanical stresses shall not depend on soldering;
- b) screws securing removable covers shall be captive if their length determines a SPACING between ACCESSIBLE conductive parts and HAZARDOUS LIVE parts;
- c) accidental loosening or freeing of the wiring, screws, etc., shall not cause ACCESSIBLE parts to become HAZARDOUS LIVE.

NOTE Screws or nuts with lock washers are not regarded as likely to become loose, nor are wires which are mechanically secured by more than soldering alone.

Conformity is checked by inspection and by measurement of SPACINGS.

6.7.2 Insulating materials

The following shall not be used as insulation for safety purposes:

- a) materials which can easily be damaged (for example, lacquer, enamel, oxides, anodic films);
- b) non-impregnated hygroscopic materials (for example, paper, fibres, fibrous materials).

Conformity is checked by inspection.

6.7.3 ENCLOSURES of probe assemblies with DOUBLE INSULATION or REINFORCED INSULATION

A probe assembly which relies on DOUBLE INSULATION or REINFORCED INSULATION throughout for protection against electric shock shall have an ENCLOSURE which surrounds all metal parts. This requirement does not apply to small metal parts such as nameplates, screws or rivets, if they are separated from parts which are HAZARDOUS LIVE by REINFORCED INSULATION or its equivalent.

ENCLOSURES or parts of ENCLOSURES made of insulating material shall meet the requirements for DOUBLE INSULATION or REINFORCED INSULATION.

Protection for ENCLOSURES or parts of ENCLOSURES made of metal shall be provided by one of the following means, except for parts where PROTECTIVE IMPEDANCE is used:

- a) an insulating coating or a barrier on the inside of the ENCLOSURE which shall surround all metal parts and all places where loosening of a part which is HAZARDOUS LIVE might cause it to touch a metal part of the ENCLOSURE;
- b) SPACINGS between the ENCLOSURE and parts which are HAZARDOUS LIVE that cannot be reduced below the values specified in 6.5 by loosening of parts or wires.

Conformity is checked by inspection and measurement and as specified in 6.5.

6.7.4 PROBE WIRE attachment

6.7.4.1 General

The attachment of the PROBE WIRE to the probe body and to the equipment (or to the CONNECTORS if the attachment is not fixed) shall withstand forces likely to be encountered in

NORMAL USE without damage which could cause a HAZARD. Solder alone, without mechanical gripping, shall not be used for strain relief. The insulation of the PROBE WIRE shall be mechanically secured to avoid retraction.

Conformity is checked by inspection and by applying the tests of 6.7.4.2 to 6.7.4.4. After the tests,

- a) the PROBE WIRE shall not have been damaged;*
- b) the insulation of the PROBE WIRE shall not have been cut or torn, and shall not have moved more than 2 mm in the bushing;*
- c) SPACINGS shall not have been reduced below the applicable value of 6.5;*
- d) the PROBE WIRE shall pass the a.c. voltage test or the d.c. voltage test of 6.6 using the applicable test voltage and duration of Table 4 (without humidity preconditioning).*

NOTE For test purposes, it could be useful to prepare a special sample of the probe, manufactured in all respects like the probe being investigated but in which no solder has been applied.

6.7.4.2 Pull test

With the probe body or equipment or CONNECTOR clamped so that it cannot move and any soldered connection severed, the PROBE WIRE is subjected for 1 min to a steady axial pull at the values shown below:

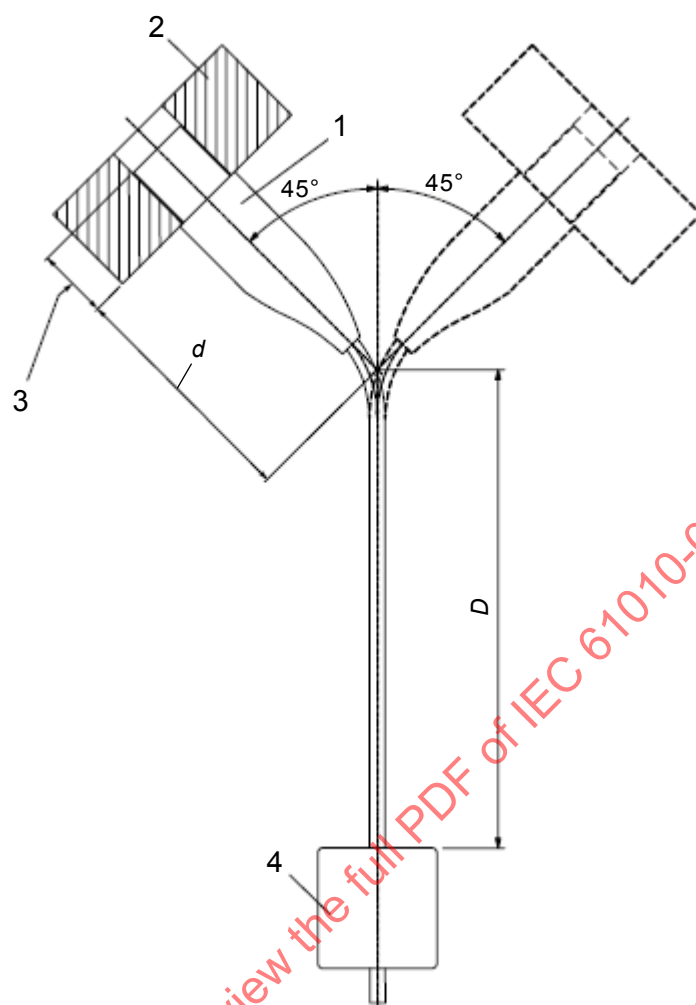
- a) for probe bodies and for locking CONNECTORS, twice the pull force value from Table 12;*
- b) for non-locking CONNECTORS, twice the pull force value from Table 12 or four times the axial pull force required to disconnect the CONNECTOR, whichever is less.*

6.7.4.3 Flexing/pull test

CONNECTORS shall be subjected to a flexing test in an apparatus similar to that shown in Figure 19.

The CONNECTOR is fixed to the oscillating member of the apparatus so that, when this is at the midpoint of its travel, the axis of the flexible PROBE WIRE, where it enters the CONNECTOR, is vertical and passes through the axis of oscillation.

The oscillating member is, by variation of distance d shown in Figure 19, so positioned that the flexible PROBE WIRE makes a minimum lateral movement when the oscillating member of the test apparatus is moved over its full travel.



Key

D > 300 mm

1 CONNECTOR

2 Part of oscillating member for fixing the CONNECTOR

3 Depth specified for the shroud of corresponding equipment TERMINAL

4 Weight

Figure 19 – Flexing test

The PROBE WIRE is loaded with a weight such that the force from Table 12 is applied.

The oscillating member is moved to each side of vertical through a total angle of 90° (45° on each side of vertical). The total number of flexings is 5 000. The rate of flexing is 60 per minute. A complete cycle is two flexings.

CONNECTORS with PROBE WIRE of nominally circular cross-sectional area are rotated approximately 90° around the vertical axis within the oscillating member after 2 500 flexings; CONNECTORS with flat flexible PROBE WIRE are not so rotated, and are only flexed in a direction perpendicular to the thinner dimension of the cross-section.

If a HAZARD can result from the breaking of a conductor or a short-circuit between conductors, a current equal to the RATED current of the probe assembly is passed through each conductor, the voltage between them being the RATED voltage. During the test, there shall be no interruption of the test current and no short-circuit between the conductors.

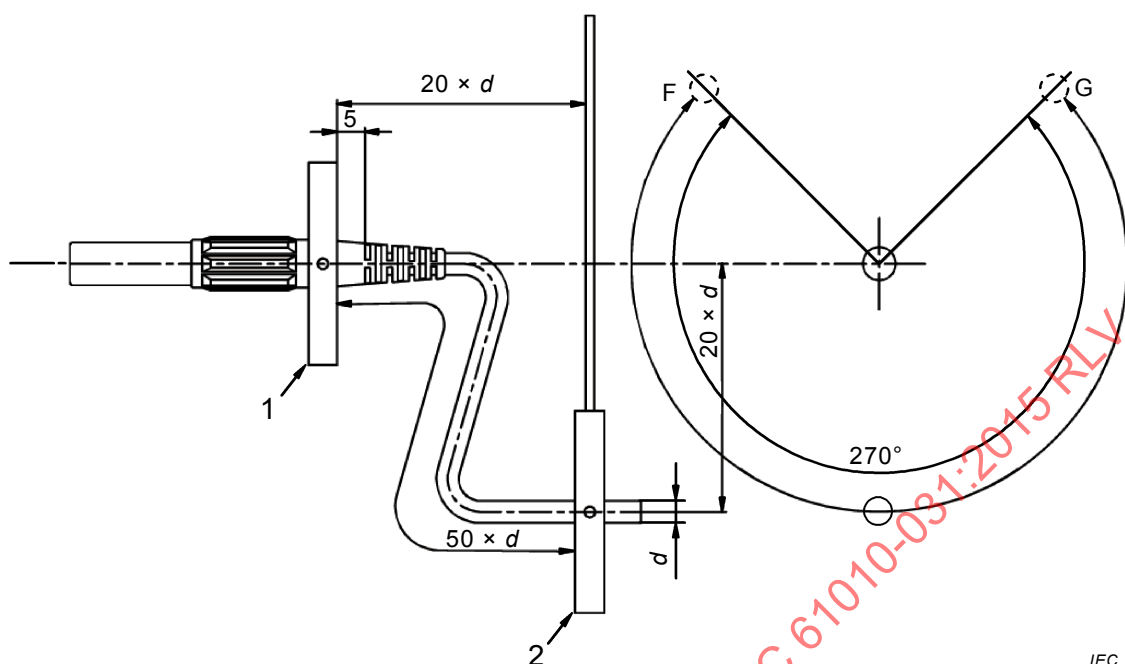
Table 12 – Pull forces for PROBE WIRE attachment tests

Cross sectional area of the conductor (a) mm ²	Pull force N
0,25	2,5
0,50	5
1,0	10
2,5	18
4	25
6	30
10	40
16	45
Linear interpolation is allowed. For PROBE WIRES with multiple conductors, the cross-sectional area (a) is calculated as the sum of the cross-sectional areas of the individual conductors. For the purpose of this calculation, the cross-sectional area of any shield is ignored.	

6.7.4.4 Rotational flexing test

The probe assembly is mounted in the test fixture as shown in Figure 20, so that the fixed clamp holds the probe body, CONNECTOR, or equipment with at least 5 mm of the solid portion protruding through the clamp. The rotating clamp is attached to the probe lead at a point 50 times the diameter of the PROBE WIRE, measured along the surface of the lead from the fixed clamp. The rotating clamp rotates in a plane at a distance equal to 20 times the diameter of the PROBE WIRE from the fixed clamp. The rotating clamp is rotated from point F to G and back to point F (one complete oscillation) at a rate of 20 oscillations per minute for a total of 250 swings. The probe body or CONNECTOR is turned 90° about its axis and the test continued for a further 250 oscillations.

Dimensions in millimetres



Key

- d diameter of PROBE WIRE
- F start point, end point
- G middle point ($F + 270^\circ$)
- 1 fixed clamp
- 2 rotating clamp

Figure 20 – Rotational flexing test

7 Protection against mechanical HAZARDS

Handling of a probe assembly or an accessory during NORMAL USE shall not lead to a HAZARD.

Easily touched edges, projections, etc. should be smooth and rounded so as not to cause injury. This does not apply to PROBE TIPS.

Conformity is checked by inspection.

8 Resistance to mechanical stresses

8.1 General

Probe assemblies shall not cause a HAZARD when subjected to mechanical stresses likely to occur in NORMAL USE. To achieve this requirement, probe assemblies shall have adequate mechanical strength, components shall be reliably secured and electrical connections shall be secure.

Conformity is checked by performing the tests of 8.2 to 8.4. The probe assembly is not operated during the tests.

After completion of the tests, the probe assembly shall pass the a.c. voltage test or the d.c. voltage test of 6.6 using the applicable test voltage and duration of Table 4 (without humidity preconditioning) and is inspected to check that:

- a) *parts which are HAZARDOUS LIVE have not become ACCESSIBLE;*
- b) *ENCLOSURES show no cracks which could cause a HAZARD;*
- c) *SPACINGS are not less than their permitted values and the insulation of internal wiring remains undamaged;*
- d) *PROTECTIVE FINGERGUARDS have not been damaged or loosened;*
- e) *there has been no damage which could cause spread of fire.*

Damage to the finish, small dents which do not reduce SPACINGS below the values specified in 6.5, and small chips which do not adversely affect the protection against electric shock or moisture, are ignored.

8.2 Rigidity test

The non-operative treatment of 10.2 is performed. Within 2 min of the end of the non-operative treatment, the probe assembly is held firmly against a rigid support and subjected to a force of 20 N applied by the hemispherical end of a hard rod of 12 mm diameter. The rod is applied three times to any part of the probe assembly which is ACCESSIBLE when the probe assembly is ready for use, and which could cause a HAZARD if distorted.

8.3 Drop test

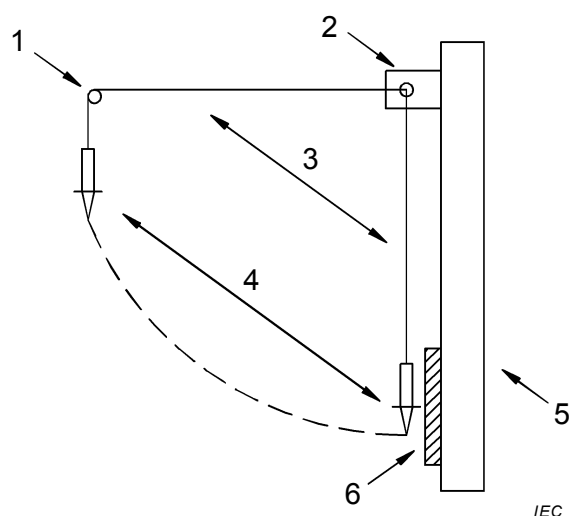
Three samples of the probe assembly are each dropped three times through a distance of 1 m onto a 50 mm thick hardwood board having a density of more than 700 kg/m³, lying flat on a rigid base such as concrete. For each sample, the three tests are carried out so as to apply the impact to different points on the probe body.

Non-metallic ENCLOSURES of probe assembly with a minimum RATED ambient temperature below 2 °C are cooled to the minimum RATED ambient temperature, then tested within 2 min.

8.4 Impact swing test

The probe body is subjected to one impact against a 5 mm thick hardwood board having a density of more than 70 kg/m³ fixed to a solid wall, when swinging as a pendulum by its PROBE WIRE (see Figure 21). The height of the drop is 2 m, or the PROBE WIRE length if shorter.

Non-metallic probe bodies with a minimum RATED ambient temperature below 2 °C are cooled to the minimum RATED ambient temperature, then tested within 2 min.



Key

- 1 start point
- 2 suspension point
- 3 PROBE WIRE
- 4 probe
- 5 wall
- 6 hardwood board

Figure 21 – Impact swing test

9 Temperature limits and protection against the spread of fire

9.1 General

Any heating shall not cause a HAZARD in NORMAL CONDITION or in SINGLE FAULT CONDITION, nor shall it cause spread of fire outside the probe assembly.

Easily touched surfaces shall not exceed the following temperatures in NORMAL CONDITION, nor 105 °C in SINGLE FAULT CONDITION, at an ambient temperature of 40 °C, or the maximum RATED ambient temperature if higher.

Metal:	55 °C
Non-metallic materials:	70 °C
PROBE WIRES:	75 °C

If easily touched heated surfaces are necessary for functional reasons, they are permitted to exceed these values, but shall be recognizable as such by appearance or function, or shall be marked with Symbol 6 of Table 1 (see 5.2).

If protection against fire depends on separation of circuits, they shall be separated at least by BASIC INSULATION.

The maximum temperature of a part is determined by measuring the temperature rise of the part under the conditions of 9.2 and adding it to the maximum ambient temperature (40 °C or the maximum RATED ambient temperature if higher, see 1.4).

Conformity is checked by inspection, by the tests of 9.2 and by tests in the SINGLE FAULT CONDITIONS of 4.4. Alternatively, if protection is assured by separation of circuits, conformity is

checked by measurement of SPACINGS, and by making the voltage tests of 6.6.5 (without humidity preconditioning) using the applicable test voltage of Table 10.

9.2 Temperature tests

A probe assembly is tested under reference test conditions and in the position of NORMAL USE (see 4.3.2). The tests of 6.7.4.2 to 6.7.4.4 are performed before performing these temperature tests. Temperatures are measured when steady state has been attained.

10 Resistance to heat

10.1 Integrity of SPACINGS

SPACINGS shall meet the requirements of 6.5 when the probe assembly is operated at an ambient temperature of 40 °C or the maximum RATED ambient temperature if higher (see 1.4).

Conformity in cases of doubt, if the probe assembly produces an appreciable amount of heat, is checked by operating the probe assembly under the reference test conditions of 4.3, except that the ambient temperature is 40 °C or the maximum RATED ambient temperature, if higher. After this test, SPACINGS shall not have been reduced below the requirements of 6.5.

If the ENCLOSURE is non-metallic, the temperature of parts of the ENCLOSURE is measured during the above test for the purpose of 10.2.

10.2 Resistance to heat

ENCLOSURES of non-metallic material shall be resistant to elevated temperatures.

Conformity is checked by the test of 8.2, applied after the following non-operative conditioning:

The probe assembly, not energized, is stored for 7 h at a temperature of 70 °C. However, if during the test of 10.1, a higher temperature is measured, the storage temperature is to be 10 °C above that measured temperature. If the probe assembly contains components which might be damaged by this treatment, an empty ENCLOSURE may be treated, followed by assembly of the probe at the end of the treatment.

11 Protection against HAZARDS from fluids

11.1 General

Probe assemblies containing fluids, or to be used in measurements of processes on fluids, shall be designed to give protection to the OPERATOR and surrounding area against HAZARDS from fluids encountered in NORMAL USE.

NOTE Fluids likely to be encountered fall into three categories:

- a) having continuous contact, for example, in vessels intended to contain them;
- b) having occasional contact, for example, cleaning fluids;
- c) having accidental (unexpected) contact. The manufacturer cannot safeguard against such cases.

Conformity is checked by the treatment and tests of 11.2.

11.2 Cleaning

If a cleaning or decontamination method is specified by the manufacturer, this shall not cause a direct safety HAZARD, an electric shock HAZARD, or a HAZARD resulting from corrosion or

other weakening of structural parts associated with safety. The cleaning method and any decontamination method shall be described in the documentation (see 5.4.3).

Conformity is checked by cleaning the probe assembly three times according to the manufacturer's instructions. If, immediately after this treatment, there are any signs of wetting of parts likely to cause a HAZARD, the probe assembly shall pass the a.c. voltage test or the d.c. voltage test of 6.6 using the applicable test voltage and duration of Table 4 (without humidity preconditioning) and ACCESSIBLE parts shall not exceed the levels of 6.3.2. If a decontamination method is specified, this method is applied once.

11.3 Specially protected probe assemblies

If the probe assembly is RATED and marked by the manufacturer as having a protected ENCLOSURE according to the stated degrees of protection of IEC 60529, it shall adequately resist the ingress of solid foreign objects and water which could lead to a HAZARD.

Conformity is checked by inspection and by subjecting the probe assembly to the appropriate treatment of IEC 60529, after which the probe assembly shall pass the a.c. voltage test or the d.c. voltage test of 6.6 using the applicable test voltage and duration of Table 4 (without humidity preconditioning) and ACCESSIBLE parts shall not exceed the levels of 6.3.2.

12 Components

12.1 General

If safety is involved, components shall be used in accordance with their specified RATING unless a specific exception is made. They shall conform to one of the following.

- a) All applicable safety requirements of relevant IEC standards. Conformity with other requirements of the component standard is not required. If necessary for the application, they shall be subjected to the tests of this standard, except that it is not necessary to carry out identical or equivalent tests already performed to check conformity with the component standard.
- b) The requirements of this standard and, where necessary for the application, any additional applicable safety requirements of the relevant IEC component standard.
- c) If there is no relevant IEC standard, the requirements of this standard.
- d) Applicable safety requirements of a non-IEC standard which are at least as high as those of the relevant IEC standard, provided that the component has been approved to the non-IEC standard by a recognized testing authority.

Tests performed by a recognized testing authority which confirm conformity with all applicable safety requirements need not be repeated, even if the tests were performed using a non-IEC standard.

Conformity is checked by inspection, and if necessary, by test.

12.2 Fuses

Fuses in probe assemblies may be used to provide protection to the user against arc explosions or burns, or they may be used to protect the equipment to which the probes are connected.

If a fuse is installed in a probe assembly, it shall have a voltage RATING at least as high as the highest RATED voltage of the probe assembly, and an appropriate breaking capacity and current RATING for the intended application of the probe assembly (see also 5.1.3). If the probe assembly is RATED for both a.c. and d.c., the a.c. and d.c. breaking capacities shall be individually determined, and the fuse shall meet the RATED voltage and breaking capacity for each case.

Conformity is checked by inspection.

12.3 PROBE WIRE

12.3.1 General

PROBE WIRE shall be suitable for its intended use in NORMAL CONDITION and SINGLE FAULT CONDITION.

Conformity is checked as specified in 12.3.2 to 12.3.6.

12.3.2 RATING of PROBE WIRE

PROBE WIRES shall be RATED for the maximum voltage and current of NORMAL USE and shall withstand the voltage test for the highest RATED voltage to earth. Conductors shall be separated from ACCESSIBLE surfaces by DOUBLE INSULATION or REINFORCED INSULATION, based on the following values:

- a) for type A probe assemblies, 125 V or the highest RATED voltage to earth of the probe assembly, whichever is greater;
- b) for type B probe assemblies, 500 V or the highest RATED voltage to earth of the probe assembly divided by the divider ratio, whichever is greater;
- c) for type C probe assemblies, 125 V or the highest RATED voltage to earth of the probe assembly, whichever is greater;
- d) for type D probe assemblies, 125 V.

For type B probe assemblies, Symbol 7 shall be marked on the probe assembly and a warning shall be provided in the documentation that the PROBE WIRE may not provide adequate protection if it comes into contact with the circuit under test.

Insulation of PROBE WIRES which have a wear indicator shall meet the requirements for BASIC INSULATION when the wear indicator has become visible.

A wear indicator is highly recommended (see also 5.4.3 j)).

Conformity is checked by inspection, and by the a.c. voltage test of 6.6.5.1, or for PROBE WIRES stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4 for REINFORCED INSULATION. If the insulation includes a wear indicator, then the voltage test is repeated with the test voltage value for BASIC INSULATION after sufficient insulation has been removed from the cable to make the wear indicator just visible.

NOTE For the purposes of this test, the wear indicator can be made visible by slicing thin layers from the insulation, by abrasion, or by manufacturing special samples of the cable without the outer insulating layer.

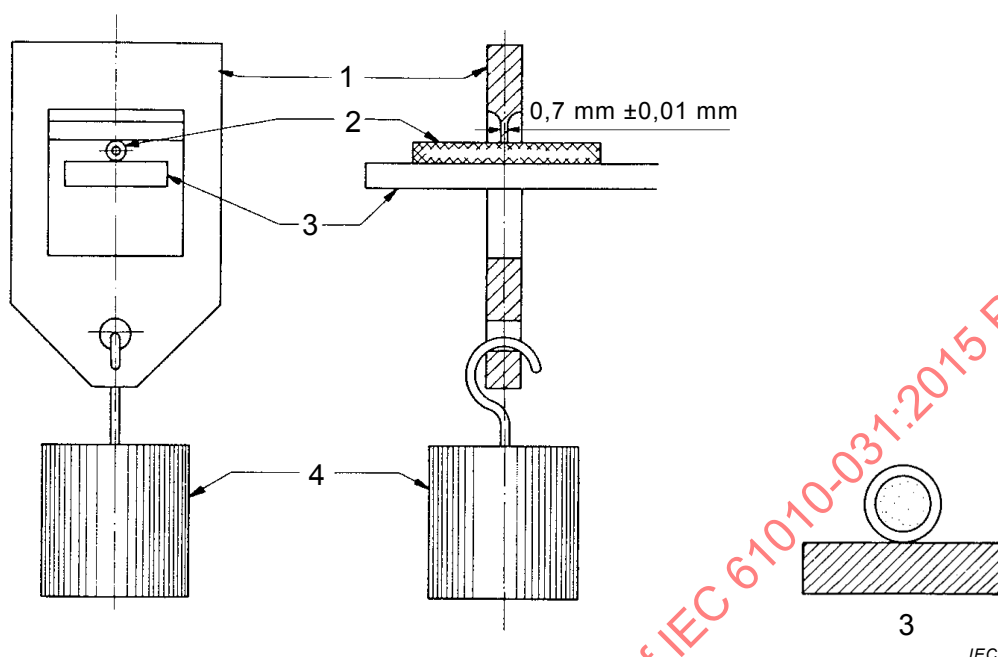
12.3.3 Pressure test at high temperature for insulations

For each PROBE WIRE to be tested, three adjacent samples are taken from a PROBE WIRE having a length of 150 mm to 300 mm. The length of each sample is 50 mm to 100 mm. The conductors of flat PROBE WIRES without sheaths are not separated.

If the samples have a covering or semiconducting layer over the insulation, it is mechanically removed.

The indentation device is shown in Figure 22, and consists of a rectangular blade with an edge $0,70 \text{ mm} \pm 0,01 \text{ mm}$ wide, which can be pressed against the sample. Each sample is placed in the position shown in Figure 22. A flat cord without a sheath is laid on its flat side. Samples are fixed on the support in such a manner that they do not curve under the pressure

of the blade. The force is applied in a direction perpendicular to the axis of the sample; the blade is also perpendicular to the axis of the sample.



Key

- 1 Testing frame
- 2 Sample
- 3 Supports
- 4 Weight

Figure 22 – Indentation device

The compressing force F which is exerted by the blade upon the sample is given by the formula:

$$F = 0,6 \times \sqrt{(2 \times d \times e - e^2)}$$

Where:

F is in newtons

e is the mean value of the thickness of the insulation of the sample

d is the mean value of the outer diameter of the sample

e and d are both expressed in millimetres, to one decimal place, and measured on a thin slice cut from the end of the test piece.

The test is carried out in air (i.e. in an air oven). The temperature of the air is maintained continuously at a temperature of $100\text{ °C} \pm 3\text{ °C}$. The loaded samples are kept in the test position for 4 h. Following this, the samples are rapidly cooled which may be carried out by spraying the sample with cold water on the spot where the blade is pressing. The sample is removed from the apparatus when it has cooled to a temperature where recovery of the insulation no longer occurs. The sample is then cooled further by immersion in cold water.

Conformity is checked by the a.c. voltage test of 6.6.5.1, or for PROBE WIRES stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4 for REINFORCED INSULATION (without humidity preconditioning).

12.3.4 Tests for resistance of insulation to cracking

Four samples of suitable length are cut from two sections of the PROBE WIRE separated by at least 1 m. External coverings, if any, are removed from the insulation.

Each sample is tautly wound and fixed, at ambient temperature, on a mandrel to form a close helix. The diameter of the mandrel and the number of turns are given in Table 13.

Table 13 – Diameter of mandrel and numbers of turns

Outer diameter of the PROBE WIRE (d) mm	Mandrel diameter mm	Number of turns
$d \leq 2,5$	5	6
$2,5 < d \leq 4,5$	9	6
$4,5 < d \leq 6,5$	13	6
$6,5 < d \leq 9,5$	19	4
$9,5 < d \leq 12,5$	40	2

Two samples, on their mandrels, are placed in an air oven pre-heated to a temperature $100\text{ }^{\circ}\text{C} \pm 3\text{ }^{\circ}\text{C}$. The samples are maintained at the specified temperature for 1 h. After the samples have been allowed to return to approximately ambient temperature, they are examined while still on the mandrel.

The other two samples are conditioned in a cold chamber for 4 h at $-10\text{ }^{\circ}\text{C} \pm 2\text{ }^{\circ}\text{C}$. The test is to be performed in the cold chamber where space and mounting means are available in the chamber. Where this is not practical, it is appropriate to remove a sample and a mandrel from the test chamber and perform the test outside the chamber. In either case, the winding is to be completed within 30 s of the time that the cold chamber is opened. The winding is to be done at a rate of about 3 s per turn ($18\text{ s} \pm 3\text{ s}$ for six turns), and successive turns are to be in contact with one another.

Flat PROBE WIRES are to be wrapped in a U-bend in which the sample is in contact with a mandrel having a diameter of twice the minor axis diameter of the sample for minimum 180° .

Insulated conductors as well as the finished PROBE WIRE are to be tested separately.

Circumferential depressions in the outer surface indicate cracks on the inside surface of the insulation or jacket of most materials. Circumferential depressions in a fluoropolymer surface are yield marks (locally stronger points) rather than indicators of cracking.

After this conditioning, the samples shall show no cracks when examined with normal or corrected vision without magnification, and shall meet the requirements for solid insulation.

Conformity is checked by inspection and by the a.c. voltage test of 6.6.5.1, or for PROBE WIRES stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4 for REINFORCED INSULATION without humidity preconditioning.

12.3.5 Voltage test

Six lengths of insulated PROBE WIRE or insulated conductors removed from a jacketed wire are to be tested for each specimen of wire to be evaluated. Each sample is 600 mm in length. Three of the samples are to be tested in an unaged condition. The other three samples are to be tested after air oven conditioning.

The three straight samples intended for oven ageing are to be conditioned in a circulating air oven pre-heated to a temperature $100\text{ }^{\circ}\text{C} \pm 3\text{ }^{\circ}\text{C}$. The test piece shall be maintained at the specified temperature for 1 h.

After air oven conditioning, the three specimens are to be cooled to room temperature in still air for a period of 16 h to 96 h before testing. After the cooling period, both the unaged and oven-conditioned samples are to be tested. The centre 300 mm of each sample is to be wrapped with metal foil.

Except for flat PROBE WIRES, the foil-wrapped centre section of each sample is to then be wrapped closely for six complete turns around a metal mandrel having a diameter of two times the outside diameter of the specimen or 5 mm, whichever is larger. The end of each resulting helix is to be twisted loosely together or fastened together with tape to prevent unwinding. Specimens of flat wires are to be wrapped in a U-bend in which the specimen is in contact with a mandrel having a diameter of twice the minor axis diameter of the specimen for 180° minimum.

The test voltage is applied between the conductor of the test specimen and the metal mandrel. The a.c. voltage test of 6.6.5.1, or for PROBE WIRES stressed only by d.c., the d.c. voltage test of 6.6.5.2, with a duration of at least 1 min using the applicable test voltage of Table 4 for REINFORCED INSULATION is then performed without humidity preconditioning. After 1 min at the specified test voltage, the test voltage is increased at a rate not exceeding 500 V/s until dielectric breakdown occurs. The dielectric breakdown voltage values are recorded separately for unaged specimens and oven-aged specimens. The average of the dielectric breakdown voltage values is calculated and recorded separately for unaged specimens and oven-aged specimens.

Samples of both unaged and oven-aged specimens shall comply with the following:

- a) unaged and oven-aged samples shall withstand the test voltage without breakdown for 1 min and
- b) the average dielectric breakdown value of oven-aged samples shall not be less than 50 % of the average breakdown value of unaged samples.

Conformity is checked by inspection and test.

12.3.6 Tensile test

12.3.6.1 General

These tests are to determine the tensile strength and elongation at break of the insulating material (exclusive of any semi-conducting layers) of the PROBE WIRE in the condition as manufactured (i.e. without any ageing treatment) and after an accelerated ageing treatment.

For the unaged samples, the median value of the tensile strengths shall be at least 7 N/mm² and the samples shall exhibit a median value of elongation of at least 100 % before they break. For the aged samples, the median value of the tensile strengths shall be at least 70 % of the result for unaged samples, and the samples shall exhibit a median value of elongation of at least 45 % of the result of the unaged samples before they break.

After the test conditioning and procedure of 12.3.6.2 to 12.3.6.6, conformity is checked by calculation of the tensile strength and the elongation at break respectively and determination of the median value of the result.

12.3.6.2 Sampling

The samples selected for the ageing treatment are from positions adjacent to the samples used for the test without ageing and the tensile tests on the aged and unaged test pieces are made in immediate succession.

One section of each core to be tested is taken of sufficient size to provide a minimum of ten samples, five each for the tensile tests without ageing and for the tensile tests after the ageing treatment, bearing in mind that a 100 mm length is needed for the preparation of each sample. The cores of flat cords are not separated. Any sample that shows signs of mechanical damage is not used for the test.

12.3.6.3 Preparation and conditioning of samples

The section of core is cut into ten samples, each approximately 100 mm long and the conductor and any outer coverings are removed, care being taken not to damage the insulation. The samples are marked to identify the section from which they were prepared and their relative positions in the section.

The centre 20 mm shall be marked immediately before the tensile test.

12.3.6.4 Determination of cross-sectional area

At the middle of the section being used to prepare the samples, a piece is taken to determine the cross-sectional area A by the following method (for samples with a round shape).

$$A = \pi \times (d - e) \times e$$

Where:

e is the mean value of the thickness of the insulation,

d is the mean value of the outer diameter of the test piece.

For samples which are to be aged, the cross-sectional area is determined before ageing treatment.

12.3.6.5 Ageing treatment

The five samples intended for oven ageing are to be conditioned in a circulating air oven pre-heated to a temperature $100\text{ °C} \pm 3\text{ °C}$. The test piece is maintained at the specified temperature for 1 h, and then allowed to cool to the temperature of 12.3.6.6.

12.3.6.6 Tensile testing procedure

The test is carried out at a temperature of $23\text{ °C} \pm 5\text{ °C}$.

The grips of the tensile testing machine may be either of a self-tightening type or not. The distance between the grips is:

- a) 50 mm for tubes, if tested with self-tightening grips;
- b) 85 mm for tubes, if tested with non-self-tightening grips.

The rate of separation shall be $250\text{ mm/min} \pm 50\text{ mm/min}$ and, in case of doubt, $25\text{ mm/min} \pm 5\text{ mm/min}$.

For each sample, the maximum tensile force during the test is measured and recorded, and the distance between the two reference marks at the breaking point is measured and recorded.

The breaking of a sample due to damage in the grips, or breaking outside the reference marks is an unsatisfactory result, which is ignored. In this event, at least four valid results are required in order to calculate the tensile strength and elongation at break; otherwise the entire test procedure is repeated.

13 Prevention of HAZARD from arc flash and short-circuits

13.1 General

When a PROBE TIP or SPRING-LOADED CLIP temporarily bridges two high-energy conductors at different potentials, it could cause a high current to flow through the PROBE TIP or SPRING-LOADED CLIP which could become hot and melt. This could cause burns to an OPERATOR or a bystander.

If the bridge is opened (by OPERATOR action, melting, or other event) while the high current is flowing through the PROBE TIP or SPRING-LOADED CLIP, arcing could occur. The arcing will ionize the air, permitting continued current flow in the vicinity of the PROBE TIP or SPRING-LOADED CLIP. If there is sufficient available energy, then the ionization of the air will continue to spread and the flow of current through the air will continue to increase. The result is an arc flash, which is similar to an explosion, and can cause injury or death to an OPERATOR or a bystander.

PROBE TIPS and SPRING-LOADED CLIPS shall be constructed to reduce the risk of short-circuits and arc flashes.

Conformity is checked as specified in 13.2.

13.2 Exposed conductive parts

The exposed conductive part of a PROBE TIP shall be constructed as follows:

- a) For SPRING-LOADED CLIPS RATED for MEASUREMENT CATEGORY III or IV:
 - 1) in closed position, the exposed ACCESSIBLE conductive parts shall not exceed 4 mm (in all directions);
 - 2) in open position,
 - i) the length of the exposed ACCESSIBLE conductive parts of SPRING-LOADED CLIPS with one hook shall not exceed 10 mm,
 - ii) the outer surfaces of SPRING-LOADED CLIPS with more than one hook or jaw shall not be conductive
- b) Except for SPRING-LOADED CLIPS RATED for MEASUREMENT CATEGORY III or IV:
 - 1) for probe assemblies RATED for MEASUREMENT CATEGORY III or IV, the exposed conductive part of a PROBE TIP shall not exceed 4 mm;
 - 2) for probe assemblies not RATED for MEASUREMENT CATEGORY II, III or IV, and for use in special applications where the energy levels will not support arc flash or fire, the exposed conductive part of a PROBE TIP shall not exceed 80 mm;
 - 3) for probe assemblies RATED for MEASUREMENT CATEGORY II, and for other probe assemblies not covered by items 1) and 2), above, the exposed conductive part of a PROBE TIP shall not exceed 19 mm.

Conformity is checked by inspection and measurement of the exposed conductive parts of the PROBE TIP or jaws as follows:

- 1) *spring-loaded parts covering the conductive part of a PROBE TIP are retracted before the measurements are made;*
- 2) *moving parts other than spring-loaded parts which change the RATING and the markings of the probe assembly are evaluated in each position;*
- 3) *removable parts which change the RATING and the markings of the probe assembly are removed.*

Annex A (normative)

Measuring circuits for touch current (see 6.3)

NOTE Annex A is based on IEC 60990, which specifies procedures for measuring touch-current, and also specifies the characteristics for test voltmeters.

A.1 Measuring circuits for a.c. with frequencies up to 1 MHz and for d.c.

The current is measured with the circuit of Figure A.1. The current is calculated from:

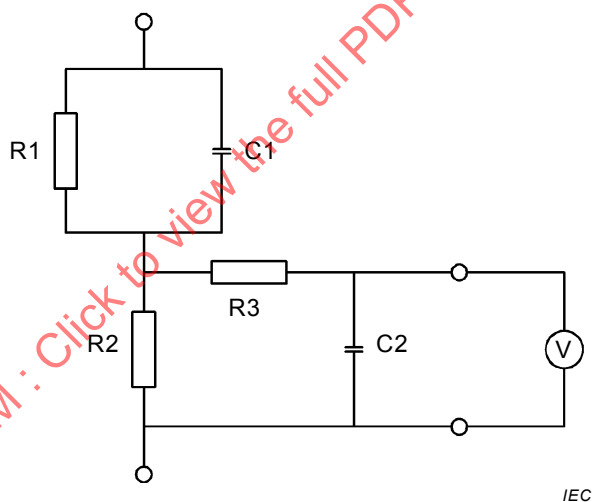
$$I = \frac{U}{500}$$

where

I is the current, in amperes;

U is the voltage, in volts, indicated by the voltmeter.

This circuit represents the impedance of the body and compensates for the change of physiological response of the body with frequency.



$$R1 = 1\,500\,\Omega \pm 5\%$$

$$R2 = 500\,\Omega \pm 5\%$$

$$R3 = 10\,\text{k}\Omega \pm 5\%$$

$$C1 = 0,22\,\mu\text{F} \pm 10\%$$

$$C2 = 0,022\,\mu\text{F} \pm 10\%$$

Figure A.1 – Measuring circuit for a.c. with frequencies up to 1 MHz and for d.c.

A.2 Measuring circuits for a.c. with sinusoidal frequencies up to 100 Hz and for d.c.

If the frequency does not exceed 100 Hz, the current may be measured with the alternative circuit of Figure A.2. When using the voltmeter, the current shall be calculated from:

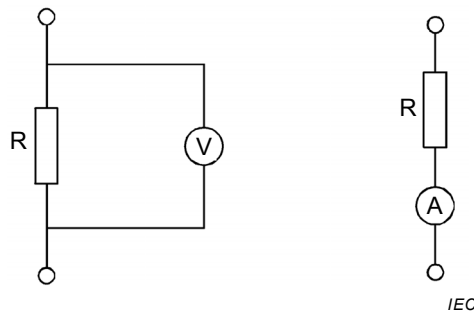
$$I = \frac{U}{2\,000}$$

where

I is the current, in amperes;

U is the voltage, in volts, indicated by the voltmeter.

The circuit represents the impedance of the body for frequencies not exceeding 100 Hz.



$$R = 2\,000\ \Omega \pm 5\%$$

NOTE The value 2 000 Ω includes the impedance of the measuring instrument.

Figure A.2 – Measuring circuits for a.c. with sinusoidal frequencies up to 100 Hz and for d.c.

A.3 Current measuring circuit for electrical burns at frequencies above 100 kHz

The current is measured with the circuit of Figure A.3 or Figure A.4 as specified in 6.3.2, 6.3.3, or 6.3.4.3. The current is calculated from:

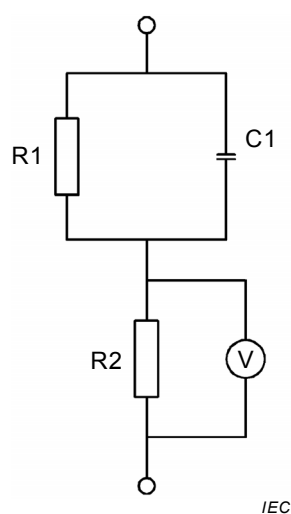
$$I = \frac{U}{500}$$

where

I is the current, in amperes;

U is the voltage, in volts, indicated by the voltmeter.

These circuits compensate for the physiological response of the body to high frequencies.

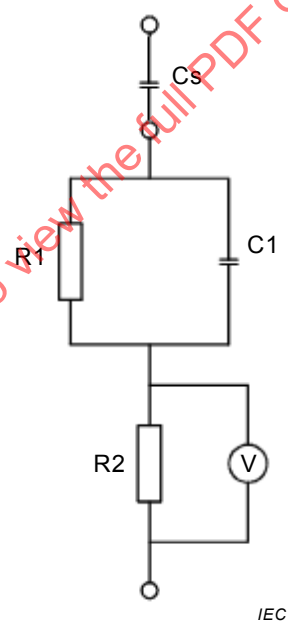


$R1 = 1\,500\ \Omega \pm 5\%$

$R2 = 500\ \Omega \pm 5\%$

$C1 = 0,22\ \mu\text{F} \pm 10\%$

Figure A.3 – Current measuring circuit for electrical burns



$R1 = 1\,500\ \Omega \pm 5\%$

$R2 = 500\ \Omega \pm 5\%$

$C1 = 0,22\ \mu\text{F} \pm 10\%$

Cs = Capacitance between the shield and the foil (see Figure 10)

Figure A.4 – Current measuring circuit for high frequency test probes

A.4 Current measuring circuit for WET LOCATIONS

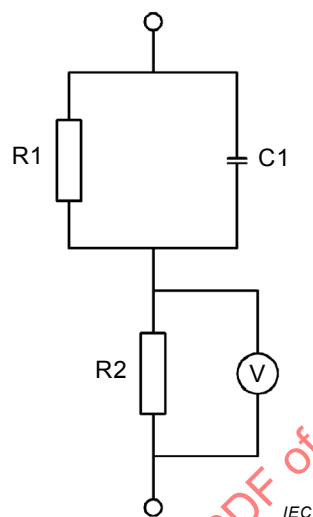
For WET LOCATIONS the current is measured using the circuit of Figure A.5. The current is calculated from:

$$I = \frac{U}{500}$$

where

I is the current, in amperes;

U is the voltage, in volts, indicated by the voltmeter.



$R1 = 375 \, \Omega \pm 5 \, \%$

$R2 = 500 \, \Omega \pm 5 \, \%$

$C1 = 0,22 \, \mu\text{F} \pm 10 \, \%$

Figure A.5 – Current measuring circuit for WET LOCATIONS

Annex B (normative)

Standard test fingers

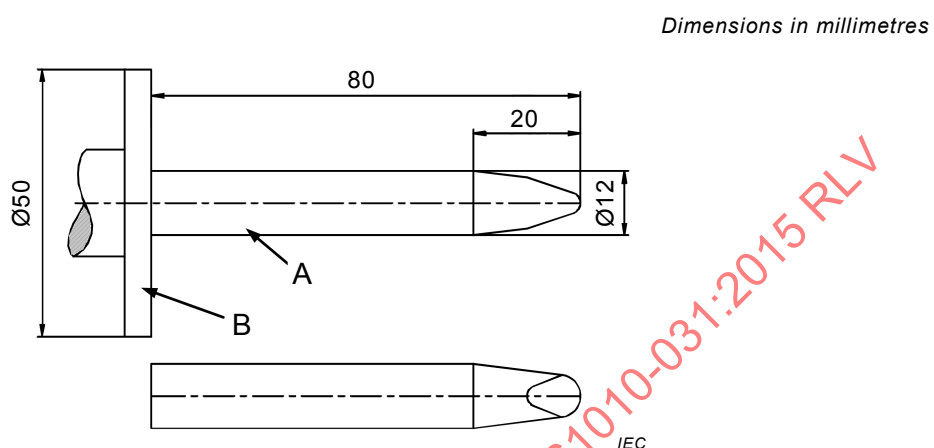
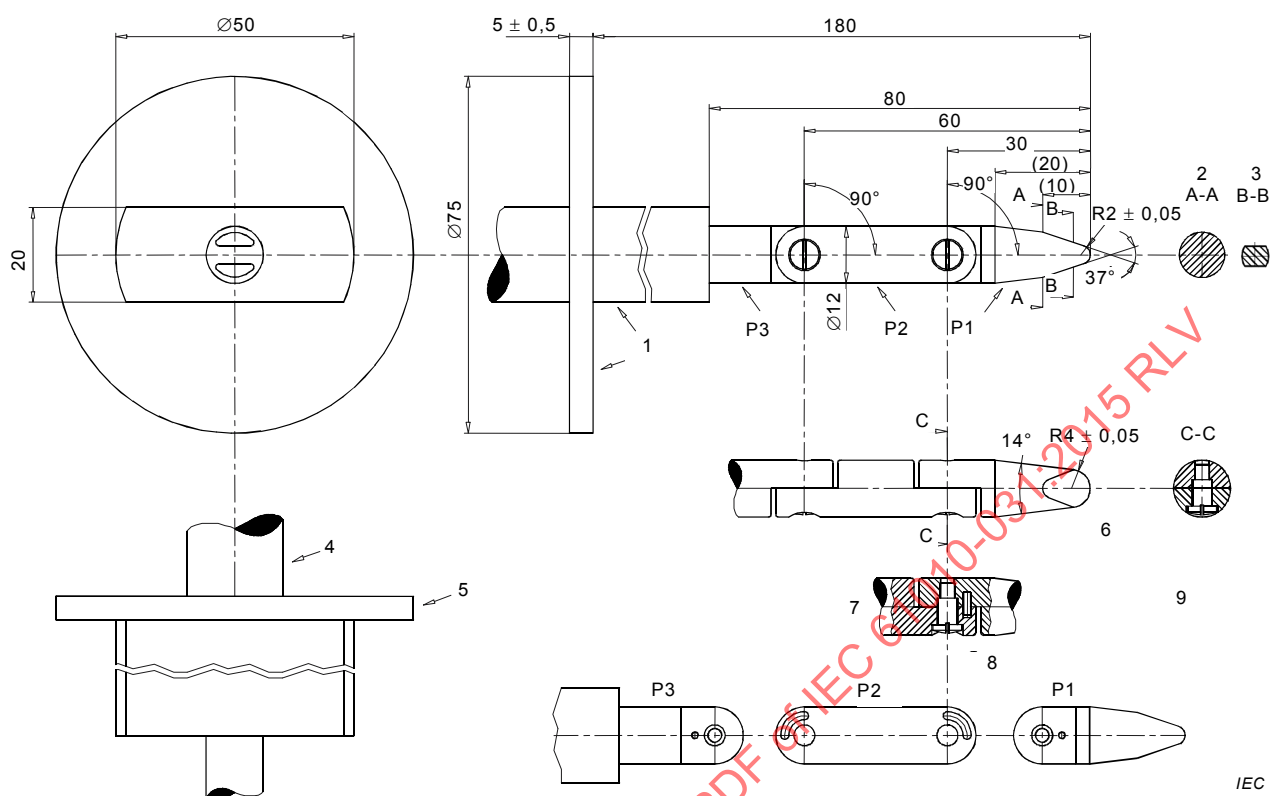


Figure B.1 – Rigid test finger

Dimensions in millimetres



Key

- | | |
|-----------------------|----------------------|
| 1 insulating material | 6 spherical |
| 2 section AA | 7 detail x (example) |
| 3 section BB | 8 side view |
| 4 handle | 9 chamfer all edges |
| 5 stop plate | |

Figure B.2 – Jointed test finger

Tolerances on dimensions without specific tolerance:

on angles: $\begin{matrix} 0 \\ -10' \end{matrix}$

on linear dimensions:

up to 25 mm: $\begin{matrix} 0 \\ -0,05 \end{matrix}$ mm

over 25 mm: $\pm 0,2$ mm

Material of finger: heat-treated steel, etc.

Both joints of this finger may be bent through an angle of $(90^{+10}_0)^{\circ}$ but in one and the same direction only.

Using the pin and groove solution is only one of the possible approaches in order to limit the bending angle to 90° . For this reason, dimensions and tolerances of these details are not given in the drawing. The actual design shall ensure a $(90^{+10}_0)^\circ$ bending angle.

NOTE This test finger is identical to test probe B from Figure 2 of IEC 61032:1997.

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

Annex C (normative)

Measurement of CLEARANCES and CREEPAGE DISTANCES

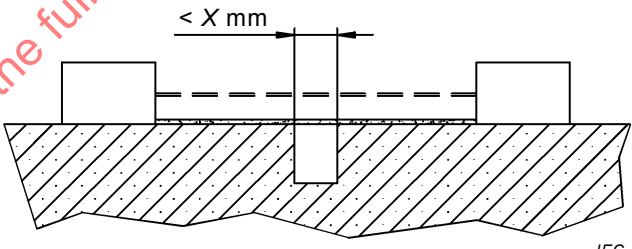
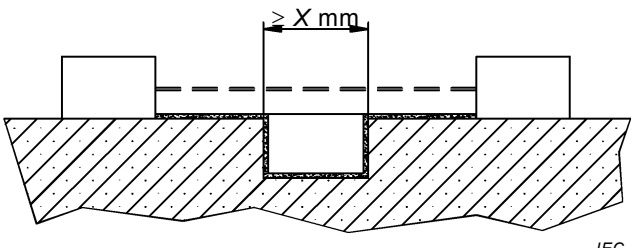
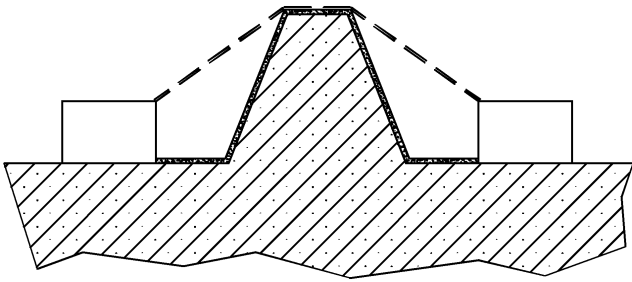
The methods of measuring CLEARANCES and CREEPAGE DISTANCES are indicated in Examples 1 to 7. These cases do not differentiate between gaps and grooves or between types of insulation.

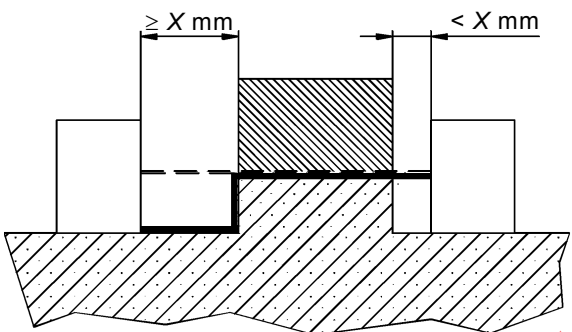
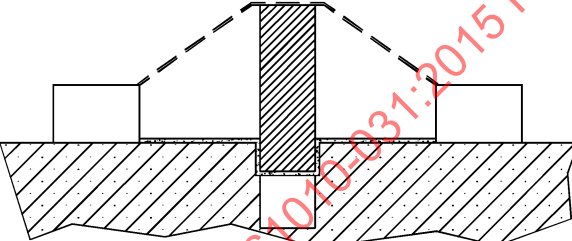
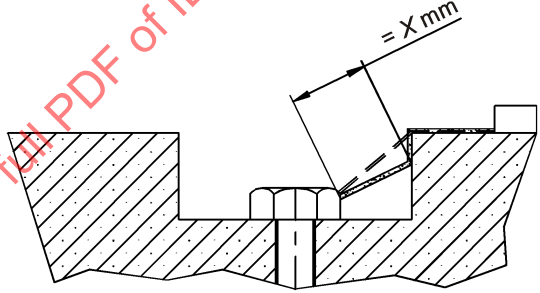
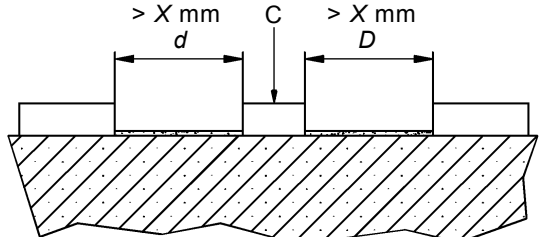
In the following examples dimension X has the value given in Table C.1 depending on the POLLUTION DEGREE.

Table C.1 – Dimension of X

POLLUTION DEGREE	Dimension X mm
1	0,25
2	1,0
3	1,5

If the associated CLEARANCE is less than 3 mm, the dimension X in Table C.1 may be reduced to one-third of this CLEARANCE.

Example 1: The path includes a parallel- or converging-sided groove of any depth with a width less than X mm. The CLEARANCE and CREEPAGE DISTANCE are measured directly across the groove as shown.	 IEC
Example 2: The path includes a parallel-sided groove of any depth and equal to, or greater than, X mm. CLEARANCE is the "line-of-sight" distance. The CREEPAGE DISTANCE follows the contour of the groove.	 IEC
Example 3: The path includes a rib. The CLEARANCE is the shortest direct air path over the top of the rib. The CREEPAGE DISTANCE follows the contour of the rib.	 IEC

Example 4: The path includes an uncemented joint with a groove on one side less than X wide and the groove on the other side equal to, or greater than, X wide. The CLEARANCE and the CREEPAGE DISTANCE are as shown.	 IEC
Example 5: The CLEARANCE is the shortest direct air path over the top of the barrier. The CREEPAGE DISTANCE through uncemented joint is less than the CREEPAGE DISTANCE over the barrier.	 IEC
Example 6: The gap between the head of screw and the wall of the recess is too narrow to be taken into account. Measurement of the CREEPAGE DISTANCE is from screw to wall when the distance is equal to X.	 IEC
Example 7: C is a floating part. The CLEARANCE is the distance $d + D$. The CREEPAGE DISTANCE is also $d + D$	 IEC

 CREEPAGE DISTANCE
 CLEARANCE

Annex D (normative)

Routine spark tests on PROBE WIRE

D.1 General

The spark test shall be performed by the manufacturer as a ROUTINE TEST on 100 % of the PROBE WIRE in accordance with the following spark test procedure and routine spark test method for PROBE WIRE.

D.2 Spark test procedure

A d.c. or a.c. spark tester shall include a voltage source, an electrode, a voltmeter, a system for detecting and counting signalling faults, and the appropriate electrical connections.

The voltage source of a d.c. or a.c. spark tester shall maintain the following test voltage under all NORMAL CONDITIONS of leakage current:

- a) a sinusoidal or nearly sinusoidal r.m.s. voltage specified for an a.c. test of the wire type;
- b) the voltage specified for a d.c. test of the wire type. The d.c. power supply output current capability shall not exceed 5 mA. Any ripple shall not exceed 1 %. After a fault, the d.c. test voltage shall recover to the specified level within 5 ms unless 610 mm or less of the product travels through the electrode in the time it takes for the full voltage recovery.

One TERMINAL of the d.c. power supply, the core of a transformer, and one end of the secondary winding in an a.c. power supply shall be solidly connected to earth. A voltage source shall not be connected to more than one electrode.

The electrode of a d.c. or a.c. spark tester shall be of the link- or bead-chain type or shall be of another evaluated and approved type. A link- or bead-chain electrode shall make intimate contact throughout its entire length with the surface of the insulated conductor being tested.

The bottom of a metal link- or bead-chain electrode enclosure shall be U- or V-shaped, the chains shall have a length appreciably greater than the depth of the enclosure, and the width of the trough shall be greater (typically 40 mm) than the diameter of the largest PROBE WIRE being tested.

For a bead-chain electrode, the longitudinal and transverse spacings of the chains and the diameter of each bead shall comply with Table D.1 (see also Figure D.1). The vertical spacing between beads in each chain shall not exceed the diameter of a bead.

Table D.1 – Maximum centre-to-centre spacings of bead chains

Diameter of a bead ^a	Longitudinal spacing within each row ^a	Transverse spacing between rows ^a	
		Chains staggered	Chains unstaggered
mm	mm	mm	mm
5,0	13	13	10
2,5	^b	^b	^b

^a Other diameters and spacings are also acceptable if investigation shows that the chains contact an equal or greater area of the outer surface of the insulated conductor or initial assembly of conductors.

^b The chains shall be staggered and shall touch one another in the longitudinal and transverse directions.

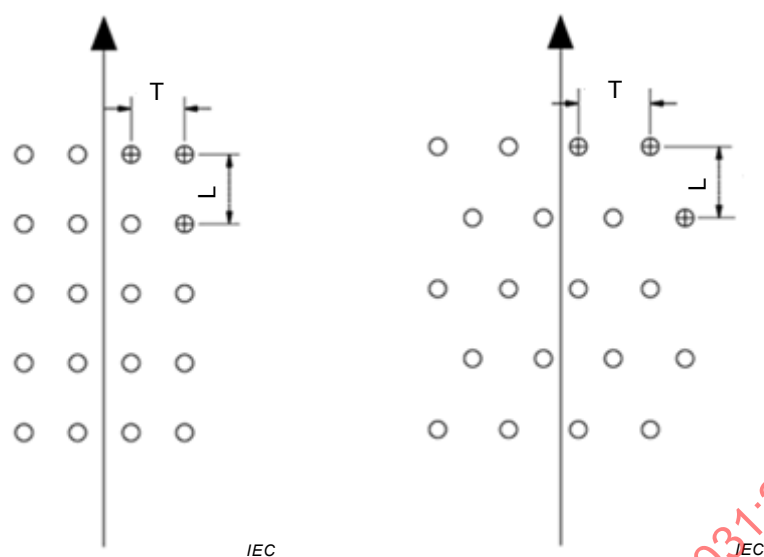


Figure D.1a – Chains unstaggered

Figure D.1b – Chains staggered

Key

- A Wire centre
- T Transverse spacing
- L Longitudinal spacing

Figure D.1 – Bead Chain Configuration (if applicable)

The electrode shall have an earthed metal screen or an equivalent guard that protects operating personnel against electric shock from the electrode and associated live parts.

The voltmeter shall be connected in the circuit to indicate the actual test potential at all times.

The test equipment shall include a fault detector, fault counter, and a means of signalling each fault that occurs. When a fault is detected, the signal shall be maintained until the indicator is reset manually.

The fault detector shall detect a voltage breakdown of the insulation. A breakdown is characterized by arcing between the electrode and the earthed conductor(s) under test. A breakdown is defined as a decrease of 25 % or more from the test voltage applied between the electrode and the earthed conductor(s). The output current of the test equipment shall not exceed 5 mA.

The fault detector shall consist of a trigger circuit that converts an input pulse of short time duration to an output pulse of a magnitude and duration that reliably operates the fault-indicating circuit.

The fault counter shall accumulate the faults as a numerically increasing sequence and shall display the accumulated total. The response time of the fault counter shall result in the counter registering faults spaced no farther than 610 mm apart for any combination of product speed and counter response time. This distance is to be calculated as follows:

$$D = S \times t$$

Where:

D = distance between faults

S = product speed as 0,656 × m/min

t = counter response time in seconds

For a d.c. test using a link- or bead-chain electrode, the surface of the insulated conductor(s) shall be in intimate contact with the link or bead chains for a distance of 125 mm ± 25 mm.

The length of a link- or bead-chain electrode is not specified for an a.c. test; however, the rate of speed at which the insulated conductor travels through the electrode shall keep any point on the product in contact with the electrode for not less than a total of 18 positive and negative crests of the a.c. supply voltage (the equivalent of a full 9 cycles of the a-c supply voltage). The maximum speed V of the product is to be determined for an a.c. test by means of the following formula:

$$V = (F \times L) / 150$$

Where:

V = speed in m/min

F = frequency in Hz

L = electrode length in mm

For convenience, Table D.2 shows the formulas for seven frequencies.

Table D.2 – Formula for maximum speed of wire in terms of electrode length L of link- or bead-chain electrode

Nominal supply frequency F (Hz)	Speed V (m/min) with electrode length L (mm)
50	$0,333 \cdot L$
60	$0,400 \cdot L$
100	$0,667 \cdot L$
400	$2,67 \cdot L$
1 000	$6,67 \cdot L$
3 000	$20,9 \cdot L$
4 000	$26,7 \cdot L$

The conductor being tested shall be earthed during the spark test. Where the conductor coming from the pay-off reel is bare, the conductor shall be earthed at the pay-off reel or at another point at which continuous contact with the bare conductor, prior to the insulating process, is maintained and the conductor is not required to be tested for continuity or earthed at the take-up reel. Where the conductor coming from a pay-off reel is insulated, an earth connection shall be made at each pay-off reel and at the take-up reel. The earth connection shall be bonded to the protective earth TERMINAL in the spark tester.

D.3 Routine spark test method for PROBE WIRE

For single-conductor wires with other than extruded insulation, the potential shall be 1 500 V if the wire is RATED for 300 V and shall be 2 000 V if the wire is RATED for 600 V.

For all other wires and insulations, the potential shall be 10 times the voltage RATING of the wire, up to 1 000 V, with a minimum potential of 1 500 V. If the RATED voltage is not specified, the potential shall be 3 000 V. For wire RATED more than 1 000 V, the potential shall be two times the RATED voltage with a minimum potential of 10 000 V. Insulated conductors or the insulated conductors of a jacketed wire shall be tested. In the case of a jacketed wire, the insulated conductors shall be tested prior to the application of the overall jacket or covering.

The spark test shall be performed at some point prior to the wire being cut to its final length or before being cut into shipping lengths.

Any faults shall be cut out or repaired. The insulation at points of repair shall be retested.

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

Annex E (informative)

4 mm CONNECTORS

E.1 General

HAZARDS may arise from an OPERATOR's reliance on values displayed by the equipment when CONNECTORS appear to be in mated position but conductive parts are not in contact.

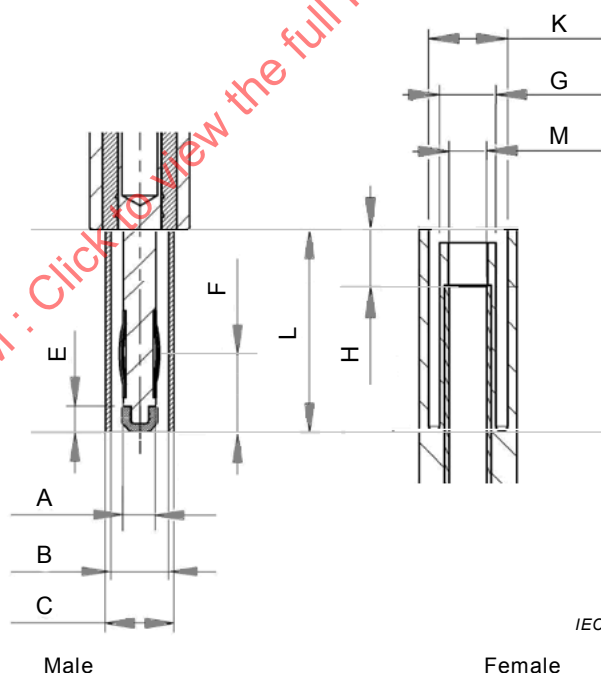
Annex E gives the recommended dimensions for safety purposes of 4 mm CONNECTORS when used on probe assemblies and equipment to which probe assemblies can be connected. These 4 mm CONNECTORS are often called "banana connectors" or "banana plugs".

E.2 Dimensions

The dimensions of Figure E.1 are compatible with 4 mm CONNECTORS RATED for MEASUREMENT CATEGORIES II, III or IV up to 1 000 V.

These dimensions ensure that SPACINGS of 6.4.2 are met when the CONNECTORS are mated, unmated or partially mated, and conductive parts of mated CONNECTORS are in contact.

NOTE Extraction or insertion forces and contact resistance values have not been considered.



Key:

A = 3,90 mm ± 0,05 mm (compressed)

B ≥ 6,6 mm

C ≤ 7,9 mm

2,6 mm ≤ E ≤ 6 mm

F ≤ 12 mm

M = 4,00 mm + 0,05 mm

G ≤ 6,4 mm

K ≥ 8,1 mm

4 mm ≤ H ≤ 6 mm

L ≥ 20 mm

Figure E.1 – Recommended dimensions of 4 mm CONNECTORS

Tolerances on dimensions without specific tolerances: $\pm 0,1$ mm

- F is the point where the best contact occurs
- A is the maximum diameter where the contact occurs
- Minimum value of E and H depends of the presence of plastic parts. SPACINGS shall be at least 2,6 mm

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV

Annex F (normative)

MEASUREMENT CATEGORIES

F.1 General

For the purposes of this standard, the following MEASUREMENT CATEGORIES are used. These MEASUREMENT CATEGORIES are not the same as the OVERVOLTAGE CATEGORIES according to Annex K of IEC 61010-1:2010 and IEC 60664-1, or the impulse withstand categories (overvoltage categories) according to IEC 60364-4-44.

NOTE 1 IEC 60664-1 and IEC 60364-4-44 categories are created to achieve an insulation coordination of the components and equipment used within the low-voltage MAINS supply system.

NOTE 2 MEASUREMENT CATEGORIES are based on locations on the MAINS supply system where measurements can be made.

F.2 MEASUREMENT CATEGORIES

F.2.1 MEASUREMENT CATEGORY II

MEASUREMENT CATEGORY II is applicable to test and measuring circuits connected directly to utilization points (socket outlets and similar points) of the low-voltage mains installation (see Table F.1 and Figure F.1).

EXAMPLE Measurements on MAINS CIRCUITS of household appliances, portable tools and similar equipment, and on the consumer side only of socket-outlets in the fixed installation.

F.2.2 MEASUREMENT CATEGORY III

MEASUREMENT CATEGORY III is applicable to test and measuring circuits connected to the distribution part of the building's low-voltage mains installation (see Table F.1 and Figure F.1).

To avoid risks caused by the HAZARDS arising from these higher short-circuit currents, additional insulation and other provisions are required.

EXAMPLE Measurements on distribution boards (including secondary meters), photovoltaic panels, circuit-breakers, wiring, including cables, bus-bars, junction boxes, switches, socket-outlets in the fixed installation, and equipment for industrial use and some other equipment such as stationary motors with permanent connection to the fixed installation.

NOTE For equipment that is part of a fixed installation, the fuse or circuit breaker of the installation can be considered to provide adequate protection against short-circuit currents.

F.2.3 MEASUREMENT CATEGORY IV

MEASUREMENT CATEGORY IV is applicable to test and measuring circuits connected at the source of the building's low-voltage mains installation (see Table F.1 and Figure F.1).

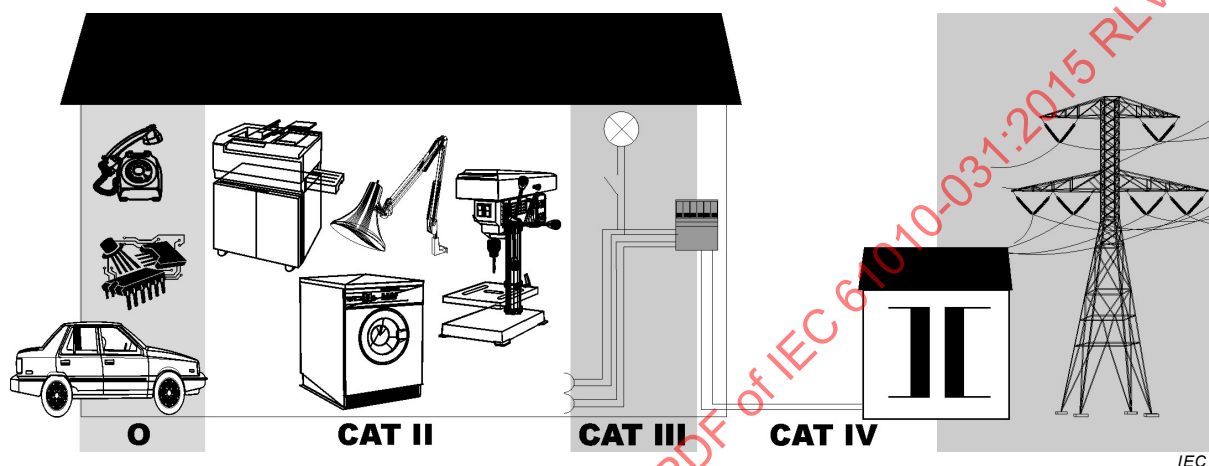
Due to these high short-circuit currents which can be followed by a high energy level, measurements made within these locations are extremely dangerous. Great precautions shall be made to avoid any chance of a short circuit.

EXAMPLE Measurements on devices installed before the main fuse or circuit breaker in the building installation.

F.2.4 Probe assemblies without a MEASUREMENT CATEGORY RATING

Many types of test and measuring circuits are not intended to be directly connected to the mains supply. Some of these measuring circuits are intended for very low energy applications, but others of these measuring circuits may experience very high amounts of available energy because of high short-circuit currents or high open-circuit voltages. There are no standard transient levels defined for these circuits. An analysis of the WORKING VOLTAGES, loop impedances, temporary overvoltages, and transient overvoltages in these circuits is necessary to determine the insulation requirements and short-circuit current requirements.

EXAMPLE Thermocouple measuring circuits, high-frequency measuring circuits, automotive testers, and testers used to characterize the mains installation before the installation is connected to the mains supply.



Key

- O Other circuits that are not directly connected to mains
- CAT II MEASUREMENT CATEGORY II
- CAT III MEASUREMENT CATEGORY III
- CAT IV MEASUREMENT CATEGORY IV

Figure F.1 – Example to identify the locations of MEASUREMENT CATEGORIES

Table F.1 – Characteristics of MEASUREMENT CATEGORIES

MEASUREMENT CATEGORY	Short-circuit current ^a (typical) kA	Location in the building installation
II	< 10	Circuits connected to mains socket outlets and similar points in the mains installation
III	< 50	Mains distribution parts of the building
IV	> 50	Source of the mains installation in the building
^a The values of loop impedances (installation impedances) do not take into account the resistance of the test leads and impedances internal to the measuring equipment. These short-circuit currents vary, depending on the characteristics of the installation.		

Annex G

Index of defined terms

Term	Definition
ACCESSIBLE (of a part)	3.4.1
BASIC INSULATION	3.5.1
CONNECTOR	3.1.5
CLEARANCE	3.5.10
CREEPAGE DISTANCE	3.5.11
DOUBLE INSULATION	3.5.3
ENCLOSURE	3.1.2
HAZARD	3.4.3
HAZARDOUS LIVE	3.4.2
MEASUREMENT CATEGORY	3.4.11
NORMAL CONDITION	3.4.6
NORMAL USE	3.4.5
OPERATOR	3.4.8
POLLUTION	3.5.5
POLLUTION DEGREE	3.5.6
POLLUTION DEGREE 1	3.5.7
POLLUTION DEGREE 2	3.5.8
POLLUTION DEGREE 3	3.5.9
PROBE TIP	3.1.4
PROBE WIRE	3.1.7
PROTECTIVE FINGERGUARD	3.1.3
PROTECTIVE IMPEDANCE	3.4.4
RATED (value)	3.2.1
RATING	3.2.2
REASONABLY FORESEEABLE MISUSE	3.4.12
REINFORCED INSULATION	3.5.4
RESPONSIBLE BODY	3.4.9
ROUTINE TEST	3.3.2
SINGLE FAULT CONDITION	3.4.7
SPACING	3.5.12
SPRING-LOADED CLIP	3.1.8
STACKABLE CONNECTOR	3.1.9
SUPPLEMENTARY INSULATION	3.5.2
TERMINAL	3.1.1
TOOL	3.1.6
TYPE TEST	3.3.1
WET LOCATION	3.4.10
WORKING VOLTAGE	3.2.3

Bibliography

IEC 60050-151:2001, *International Electrotechnical Vocabulary – Part 151: Electrical and magnetic devices*

IEC 60050-195:1998, *International Electrotechnical Vocabulary – Part 195: Earthing and protection against electric shock*

IEC 60065, *Audio, video and similar electronic apparatus – Safety requirements*

IEC 60270, *High-voltage test techniques – Partial discharge measurements*

IEC 60364-4-44, *Low-voltage electrical installations – Part 4-44: Protection for safety – Protection against voltage disturbances and electromagnetic disturbances*

IEC 60417, *Graphical symbols for use on equipment* (available at: <http://www.graphical-symbols.info/equipment>)

IEC 60664-1, *Insulation coordination for equipment within low-voltage systems – Part 1: Principles, requirements and tests*

IEC 60664-3:2003, *Insulation coordination for equipment within low-voltage systems – Part 3: Use of coating, potting or moulding for protection against pollution*
IEC 60664-3:2003/AMD1:2010

IEC 60664-4:2005, *Insulation coordination for equipment within low-voltage systems – Part 4: Consideration of high-frequency voltage stress*

IEC 60990, *Methods of measurement of touch current and protective conductor current*

IEC 61010 (all parts), *Safety requirements for electrical equipment for measurement, control and laboratory use*

IEC 61032:1997, *Protection of persons and equipment by enclosures – Probes for verification*

ISO 7000, *Graphical symbols for use on equipment* (available at: <http://www.iso.org/obp>)

SOMMAIRE

AVANT-PROPOS	93
1 Domaine d'application et objet	96
1.1 Domaine d'application	96
1.1.1 Sondes équipées incluses dans le domaine d'application	96
1.1.2 Sondes équipées exclues du domaine d'application	99
1.2 Objet	99
1.2.1 Aspects inclus dans le domaine d'application	99
1.2.2 Aspects exclus du domaine d'application	99
1.3 Vérification	99
1.4 Conditions d'environnement	99
1.4.1 Conditions normales d'environnement	99
1.4.2 Conditions d'environnement étendues	100
2 Références normatives	100
3 Termes et définitions	100
3.1 Parties et accessoires	100
3.2 Grandeurs	102
3.3 Essais	102
3.4 Termes de sécurité	102
3.5 Isolation	103
4 Tests	104
4.1 Généralités	104
4.2 Séquence d'essais	105
4.3 Conditions de référence pour les essais	105
4.3.1 Conditions d'environnement	105
4.3.2 État des sondes équipées	106
4.3.3 Position de la sonde équipée	106
4.3.4 Accessoires	106
4.3.5 Couvercles et parties amovibles	106
4.3.6 Tensions d'entrée et de sortie	106
4.3.7 Dispositifs de commande	106
4.3.8 Raccordements	106
4.3.9 Cycle de service	106
4.4 Essais en CONDITION DE PREMIER DEFAUT	106
4.4.1 Généralités	106
4.4.2 Application des conditions de défaut	107
4.4.3 Durée des essais	107
4.4.4 Conformité après application des conditions de défaut	108
4.5 Essais en MAUVAIS USAGE RAISONNABLEMENT PREVISIBLE	108
4.5.1 Généralités	108
4.5.2 Fusibles	108
5 Marquage et documentations	109
5.1 Marquage	109
5.1.1 Généralités	109
5.1.2 Identification	109
5.1.3 Fusibles	110
5.1.4 CONNECTEURS et dispositifs de manœuvre	110

5.1.5	CARACTÉRISTIQUES ASSIGNÉES	111
5.2	Marquages d'avertissement	111
5.3	Durabilité du marquage	111
5.4	Documentation	112
5.4.1	Généralités	112
5.4.2	CARACTÉRISTIQUES ASSIGNÉES des sondes équipées	112
5.4.3	Fonctionnement de sonde équipée	112
5.4.4	Maintenance et entretien des sondes équipées	113
6	Protection contre les chocs électriques	113
6.1	Généralités	113
6.2	Détermination des parties ACCESSIBLES	114
6.2.1	Généralités	114
6.2.2	Examen	114
6.2.3	Ouvertures d'accès aux commandes pré-réglées	115
6.3	Valeurs limites pour les parties ACCESSIBLES	116
6.3.1	Généralités	116
6.3.2	Niveaux en CONDITION NORMALE	116
6.3.3	Niveaux en CONDITION DE PREMIER DEFECT	116
6.3.4	Mesure de la tension et du courant de contact	119
6.4	Moyens de protection contre les chocs électriques	122
6.4.1	Généralités	122
6.4.2	CONNECTEURS	123
6.4.3	POINTES DE TOUCHE	124
6.4.4	Impédance	126
6.4.5	IMPÉDANCE DE PROTECTION	127
6.4.6	ISOLATION PRINCIPALE, ISOLATION SUPPLEMENTAIRE, DOUBLE ISOLATION et ISOLATION RENFORCEE	127
6.5	Exigences relatives à l'isolation	128
6.5.1	Nature de l'isolation	128
6.5.2	Exigences relatives à l'isolation des sondes équipées	132
6.6	Procédure pour les essais de tension	139
6.6.1	Généralités	139
6.6.2	Pré-conditionnement à l'humidité	139
6.6.3	Conduite des essais	139
6.6.4	Tensions d'essai	140
6.6.5	Procédures d'essai	142
6.7	Exigences relatives à la construction pour la protection contre les chocs électriques	143
6.7.1	Généralités	143
6.7.2	Matériaux isolants	143
6.7.3	ENVELOPPES des sondes équipées avec DOUBLE ISOLATION ou ISOLATION RENFORCEE	143
6.7.4	Attache de FIL DE SONDE	144
7	Protection contre les DANGERS mécaniques	147
8	Résistance aux contraintes mécaniques	147
8.1	Généralités	147
8.2	Essai de rigidité	148
8.3	Essai de chute	148
8.4	Essai d'oscillation	148

9	Limites de température et protection contre la propagation du feu	149
9.1	Généralités	149
9.2	Essais thermiques.....	150
10	Résistance à la chaleur	150
10.1	Intégrité des ESPACEMENTS.....	150
10.2	Résistance à la chaleur.....	150
11	Protection contre les DANGERS des fluides	150
11.1	Généralités	150
11.2	Nettoyage	151
11.3	Sondes équipées avec protection spéciale.....	151
12	Composants	151
12.1	Généralités	151
12.2	Fusibles	152
12.3	FIL DE SONDE	152
12.3.1	Généralités	152
12.3.2	CARACTERISTIQUE ASSIGNEE du FIL DE SONDE.....	152
12.3.3	Essai de pression à haute température pour les isolations.....	153
12.3.4	Essais de résistance de l'isolation à la fissuration.....	154
12.3.5	Tension d'essai.....	155
12.3.6	Essai de traction.....	156
13	Prévention du DANGER d'arc électrique et de courts-circuits	157
13.1	Généralités	157
13.2	Parties conductrices exposées.....	158
Annexe A (normative)	Circuits de mesure du courant de contact (voir 6.3).....	159
A.1	Circuits de mesure du courant alternatif à des fréquences jusqu'à 1 MHz et du courant continu	159
A.2	Circuits de mesure du courant alternatif à des fréquences sinusoïdales jusqu'à 100 Hz et du courant continu	160
A.3	Circuit de mesure du courant pour les brûlures électriques à des fréquences au-dessus de 100 kHz	160
A.4	Circuit de mesure du courant en EMBLEMENTS HUMIDES	161
Annexe B (normative)	Doigts d'épreuve normalisés	163
Annexe C (normative)	Mesure de DISTANCES D'ISOLEMENT et de LIGNES DE FUITE.....	166
ANNEXE D (normative)	Essais individuels de série aux étincelles sur FIL DE SONDE	168
D.1	Généralités	168
D.2	Procédure d'essai aux étincelles	168
D.3	Méthode d'essais individuels de série aux étincelles pour FIL DE SONDE.....	171
Annexe E (informative)	CONNECTEURS de 4 mm	172
E.1	Généralités	172
E.2	Dimensions	172
Annexe F (normative)	CATÉGORIES DE MESURE.....	174
F.1	Généralités	174
F.2	CATÉGORIES DE MESURE	174
F.2.1	CATÉGORIE DE MESURE II.....	174
F.2.2	CATÉGORIE DE MESURE III.....	174
F.2.3	CATÉGORIE DE MESURE IV.....	174
F.2.4	Sondes équipées sans CATEGORIE DE MESURE ASSIGNEE	175
Annexe G	Index des termes définis.....	176

Bibliographie.....	177
Figure 1 – Exemples de sondes équipées de Type A	97
Figure 2 – Exemples de sondes équipées de Type B	97
Figure 3 – Exemples de sondes équipées de Type C	98
Figure 4 – Exemples de sondes équipées de Type D	98
Figure 5 – Exemple de CONNECTEUR EMPILABLE avec un CONNECTEUR mâle et une BORNE femelle	101
Figure 6 – Méthodes pour la détermination des parties ACCESSIBLES (voir 6.2) et pour les essais de tension (voir 6.4.2)	115
Figure 7 – Niveau de capacité en fonction de la tension en CONDITION NORMALE et en CONDITION DE PREMIER DEFECT (voir 6.3.2 c) et 6.3.3 c))	118
Figure 8 – Mesure de la tension et du courant de contact	119
Figure 9 – Mesure de la tension et du courant de contact pour le CONNECTEUR de référence	120
Figure 10 – Mesure de la tension et du courant de contact avec sonde d'essai blindée.....	121
Figure 11 – Tension d'entrée maximale de la sonde d'essai pour un courant de contact de 70 mA	122
Figure 12 – Protection par un PROTEGE-DOIGTS	125
Figure 13 – Protection par la distance.....	126
Figure 14 – Protection par indicateur tactile	126
Figure 15 – Distance entre conducteurs sur une interface entre deux couches	130
Figure 16 – Distance entre conducteurs adjacents, le long de l'interface de deux couches	131
Figure 17 – Distance entre conducteurs adjacents situés sur les deux mêmes couches	132
Figure 18 – Exemple de tension de crête répétitive	136
Figure 19 – Essai de flexion.....	145
Figure 20 – Essai de flexion en rotation	147
Figure 21 – Essai d'oscillation.....	149
Figure 22 – Dispositif de pénétration.....	153
Figure A.1 – Circuit de mesure du courant alternatif à des fréquences jusqu'à 1 MHz et du courant continu.	159
Figure A.2 – Circuits de mesure d'un courant à des fréquences sinusoïdales jusqu'à 100 Hz et du courant continu.	160
Figure A.3 – Circuit de mesure du courant pour brûlures électriques.....	161
Figure A.4 – Circuit de mesure du courant pour les sondes d'essai à haute fréquence.....	161
Figure A.5 – Circuit de mesure du courant en EMBLEMENTS HUMIDES	162
Figure B.1 – Doigt d'épreuve rigide	163
Figure B.2 – Doigt d'épreuve articulé	164
Figure D.1 – Configuration de chaînes à boules (si applicable)	169
Figure E.1 – Dimensions recommandées pour les CONNECTEURS de 4 mm	173
Figure F.1 – Exemple d'identification des emplacements des CATEGORIES DE MESURE	175
Tableau 1 – Symboles	110

Tableau 2 – ESPACEMENTS pour CONNECTEURS découplés de tension ASSIGNEE inférieure ou égale à 1 000 V alternatifs ou 1 500 V continus avec des parties conductrices ACTIVES DANGEREUSES	124
Tableau 3 – Coefficient multiplicateur pour les DISTANCES D'ISOLEMENT d'une sonde équipée pour un fonctionnement jusqu' à 5 000 m d'altitude ASSIGNEE	129
Tableau 4 – Tensions d'essai pour l'essai de l'isolation solide	130
Tableau 5 – Valeurs minimales pour la distance ou l'épaisseur	131
Tableau 6 – DISTANCES D'ISOLEMENT des sondes équipées en CATEGORIES DE MESURE II, III et IV	133
Tableau 7 – Valeurs de la DISTANCE D'ISOLEMENT pour le calcul du 6.5.2.3.2	135
Tableau 8 – DISTANCES D'ISOLEMENT pour l'ISOLATION PRINCIPALE des sondes équipées soumises à des tensions de crête répétitives ou dont la fréquence des TENSIONS DE SERVICE est supérieure à 30 kHz	137
Tableau 9 – LIGNES DE FUITE pour L'ISOLATION PRINCIPALE ou L'ISOLATION SUPPLÉMENTAIRE	138
Tableau 10 – Tension d'essai en fonction des DISTANCES D'ISOLEMENT	141
Tableau 11 – Coefficients de correction des tensions d'essai des DISTANCES D'ISOLEMENT suivant l'altitude du site d'essai	142
Tableau 12– Forces de traction pour les essais d'attache de FIL DE SONDE	146
Tableau 13 – Diamètre de mandrin et nombre de tours	154
Tableau C.1– Dimension X	166
Tableau D.1 – Espacements maximaux entre les centres des chaînes à boules	169
Tableau D.2 – Formule pour la vitesse maximale du fil en fonction de la longueur d'électrode L d'une électrode du type chaîne à maillons ou chaîne à boules	170
Tableau F.1 – Caractéristiques des CATEGORIES DE MESURE	175

COMMISSION ÉLECTROTECHNIQUE INTERNATIONALE

**RÈGLES DE SÉCURITÉ POUR APPAREILS ÉLECTRIQUES
DE MESURAGE, DE RÉGULATION ET DE LABORATOIRE –****Partie 031: Exigences de sécurité pour sondes équipées
tenues à la main pour mesurage et essais électriques**

AVANT-PROPOS

- 1) La Commission Electrotechnique Internationale (IEC) est une organisation mondiale de normalisation composée de l'ensemble des comités électrotechniques nationaux (Comités nationaux de l'IEC). L'IEC a pour objet de favoriser la coopération internationale pour toutes les questions de normalisation dans les domaines de l'électricité et de l'électronique. A cet effet, l'IEC – entre autres activités – publie des Normes internationales, des Spécifications techniques, des Rapports techniques, des Spécifications accessibles au public (PAS) et des Guides (ci-après dénommés "Publication(s) de l'IEC"). Leur élaboration est confiée à des comités d'études, aux travaux desquels tout Comité national intéressé par le sujet traité peut participer. Les organisations internationales, gouvernementales et non gouvernementales, en liaison avec l'IEC, participent également aux travaux. L'IEC collabore étroitement avec l'Organisation Internationale de Normalisation (ISO), selon des conditions fixées par accord entre les deux organisations.
- 2) Les décisions ou accords officiels de l'IEC concernant les questions techniques représentent, dans la mesure du possible, un accord international sur les sujets étudiés, étant donné que les Comités nationaux de l'IEC intéressés sont représentés dans chaque comité d'études.
- 3) Les Publications de l'IEC se présentent sous la forme de recommandations internationales et sont agréées comme telles par les Comités nationaux de l'IEC. Tous les efforts raisonnables sont entrepris afin que l'IEC s'assure de l'exactitude du contenu technique de ses publications; l'IEC ne peut pas être tenue responsable de l'éventuelle mauvaise utilisation ou interprétation qui en est faite par un quelconque utilisateur final.
- 4) Dans le but d'encourager l'uniformité internationale, les Comités nationaux de l'IEC s'engagent, dans toute la mesure possible, à appliquer de façon transparente les Publications de l'IEC dans leurs publications nationales et régionales. Toutes divergences entre toutes Publications de l'IEC et toutes publications nationales ou régionales correspondantes doivent être indiquées en termes clairs dans ces dernières.
- 5) L'IEC elle-même ne fournit aucune attestation de conformité. Des organismes de certification indépendants fournissent des services d'évaluation de conformité et, dans certains secteurs, accèdent aux marques de conformité de l'IEC. L'IEC n'est responsable d'aucun des services effectués par les organismes de certification indépendants.
- 6) Tous les utilisateurs doivent s'assurer qu'ils sont en possession de la dernière édition de cette publication.
- 7) Aucune responsabilité ne doit être imputée à l'IEC, à ses administrateurs, employés, auxiliaires ou mandataires, y compris ses experts particuliers et les membres de ses comités d'études et des Comités nationaux de l'IEC, pour tout préjudice causé en cas de dommages corporels et matériels, ou de tout autre dommage de quelque nature que ce soit, directe ou indirecte, ou pour supporter les coûts (y compris les frais de justice) et les dépenses découlant de la publication ou de l'utilisation de cette Publication de l'IEC ou de toute autre Publication de l'IEC, ou au crédit qui lui est accordé.
- 8) L'attention est attirée sur les références normatives citées dans cette publication. L'utilisation de publications référencées est obligatoire pour une application correcte de la présente publication.
- 9) L'attention est attirée sur le fait que certains des éléments de la présente Publication de l'IEC peuvent faire l'objet de droits de brevet. L'IEC ne saurait être tenue pour responsable de ne pas avoir identifié de tels droits de brevets et de ne pas avoir signalé leur existence.

La Norme internationale IEC 61010-031 a été établie par le comité d'études 66 de l'IEC: Sécurité des appareils de mesure, de commande et de laboratoire.

Elle a le statut d'une publication groupée de sécurité conformément au Guide 104 de l'IEC.

L'IEC 61010-031 est une norme autonome. Cette deuxième édition annule et remplace la première édition parue en 2002 et l'Amendement 1:2008. Cette édition constitue une révision technique.

Cette édition inclut les modifications techniques majeures suivantes par rapport à la première édition, ainsi que de nombreuses autres modifications:

- a) Les tensions au-dessus des niveaux de 30 V efficaces (eff), 42,4 V crête ou 60 V continu (c.c.) sont réputées être des tensions ACTIVES DANGEREUSES au lieu des tensions 33 V eff, 46,7 V crête, ou 70 V c.c.
- b) L'entretien est désormais inclus dans le domaine d'application.
- c) Des conditions d'environnement étendues sont incluses dans le domaine d'application.
- d) De nouveaux termes ont été définis.
- e) Des essais relatifs à un MAUVAIS USAGE RAISONNABLEMENT PREVISIBLE ont été ajoutés, en particulier pour les fusibles.
- f) Des exigences complémentaires relatives aux instructions concernant l'exploitation des sondes équipées ont été spécifiées.
- g) Des valeurs limites pour les parties ACCESSIBLES et pour la mesure de la tension et du courant de contact ont été modifiées.
- h) Les exigences relatives aux ESPACEMENTS pour l'emboîtement des CONNECTEURS ont été modifiées.
- i) Les exigences relatives aux POINTES DE TOUCHE et aux PINCES A RESSORT ont été modifiées. Le PROTEGE-DOIGTS remplace la BARRIERE avec de nouvelles exigences.
- j) Les exigences relatives à l'isolation (6.5) et les procédures d'essai (6.6.5) ont été réécrites et alignées avec la Partie 1 lorsque c'est pertinent. Des exigences spécifiques ont été ajoutées pour l'isolation solide et l'isolation en couches minces.
- k) La terminologie pour la CATEGORIE DE MESURE I a été remplacée par la dénomination "non ASSIGNEE pour les mesures en CATEGORIES DE MESURE II, III, ou IV".
- l) L'essai de traction/flexion (6.7.4.3) a été partiellement réécrit.
- m) Les limites de température de surface (Article 10) ont été modifiées pour se conformer aux limites du Guide 117 de l'IEC.
- n) Des exigences relatives à la résistance des FILS DE SONDE aux contraintes mécaniques ont été ajoutées à l'Article 12 et à une nouvelle Annexe D.
- o) Des exigences ajoutées se rapportent à la prévention du DANGER d'explosion due à un flash d'arc électrique et de courts-circuits pour les PINCES A RESSORT.
- p) Une nouvelle Annexe E informative définit les dimensions des CONNECTEURS banane de 4 mm.

Le texte de cette norme est issu des documents suivants:

FDIS	Rapport de vote
66/569/FDIS	66/571/RVD

Le rapport de vote indiqué dans le tableau ci-dessus donne toute information sur le vote ayant abouti à l'approbation de cette norme.

Cette publication a été rédigée selon les Directives ISO/IEC, Partie 2.

Une liste de toutes les parties de la série IEC 61010, publiées sous le titre général, *Règles de sécurité pour appareils électriques de mesurage, de régulation et de laboratoire*, peut être consultée sur le site web de l'IEC.

Dans la présente norme, les caractères d'imprimerie suivants sont utilisés:

- exigences et définitions: caractères romains;
- NOTES et EXEMPLES: petits caractères romains;
- *conformité et essais: caractères italiques;*
- termes définis à l'Article 3 et utilisés dans toute cette norme: CARACTERES ROMAINS EN PETITES CAPITALES.

Le comité a décidé que le contenu de cette publication ne sera pas modifié avant la date de stabilité indiquée sur le site web de l'IEC sous "<http://webstore.iec.ch>" dans les données relatives à la publication recherchée. A cette date, la publication sera

- reconduite,
- supprimée,
- remplacée par une édition révisée, ou
- amendée.

IMPORTANT – Le logo "colour inside" qui se trouve sur la page de couverture de cette publication indique qu'elle contient des couleurs qui sont considérées comme utiles à une bonne compréhension de son contenu. Les utilisateurs devraient, par conséquent, imprimer cette publication en utilisant une imprimante couleur.

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 PLV

RÈGLES DE SÉCURITÉ POUR APPAREILS ÉLECTRIQUES DE MESURAGE, DE RÉGULATION ET DE LABORATOIRE –

Partie 031: Exigences de sécurité pour sondes équipées tenues à la main pour mesurage et essais électriques

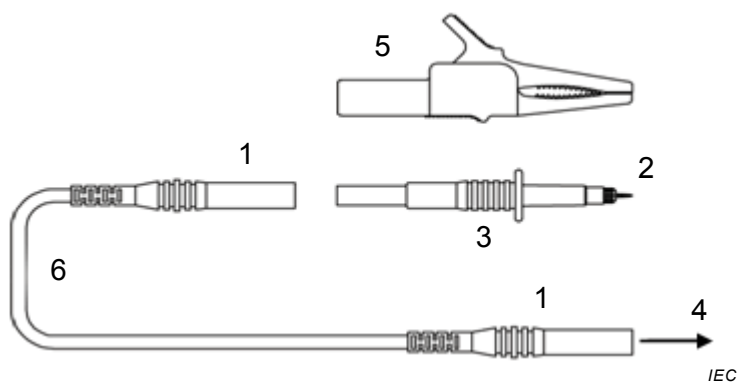
1 Domaine d'application et objet

1.1 Domaine d'application

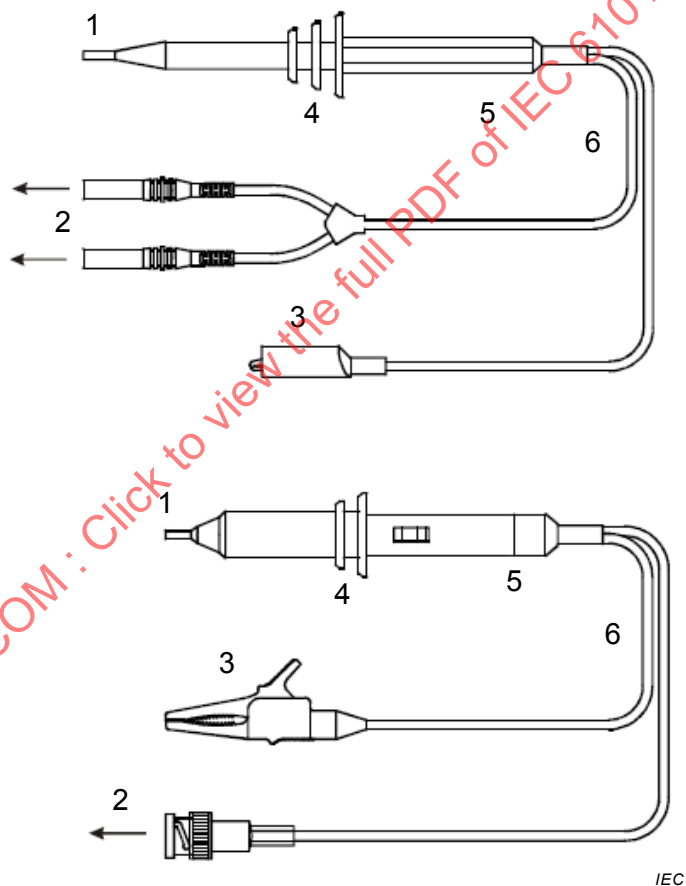
1.1.1 Sondes équipées incluses dans le domaine d'application

La présente partie de l'IEC 61010 spécifie les exigences de sécurité relatives aux sondes portatives et manipulées à la main correspondant aux types décrits ci-dessous, ainsi que leurs accessoires connexes. Ces sondes équipées sont prévues pour la connexion électrique directe entre une partie et un appareil de mesure et d'essai électrique. Elles peuvent être solidaires de l'appareil ou en être des accessoires détachables.

- a) Type A: sondes équipées, sans atténuation, à basse tension et à haute tension. Sondes équipées sans atténuation, ASSIGNEES pour connexion directe à des tensions supérieures à 30 V efficaces ou à 42,4 V crête ou à 60 V continus, mais ne dépassant pas 63 kV. Elles ne comportent pas de composants qui sont prévus pour assurer une fonction de diviseur de tension ou une fonction de mise en forme de signaux, mais elles peuvent contenir des composants ne provoquant pas d'atténuation tels que des fusibles (voir la Figure 1).
- b) Type B: sondes équipées à atténuateur ou diviseur à haute tension. Sondes équipées à atténuateur ou diviseur ASSIGNEES pour connexion directe sur des tensions secondaires supérieures à 1 kV efficaces ou 1,5 kV continus mais n'excédant pas 63 kV efficaces ou continus. La fonction de diviseur peut être réalisée dans sa totalité à l'intérieur de la sonde équipée, ou en partie dans l'appareil de mesure ou d'essai destiné à être utilisé avec la sonde équipée (voir la Figure 2).
- c) Type C: sondes équipées à atténuateur ou diviseur à basse tension. Sondes équipées à atténuateur ou diviseur pour connexion directe sur des tensions ne dépassant pas 1 kV efficaces ou 1,5 kV continus. La fonction de mise en forme de signaux peut être réalisée dans sa totalité à l'intérieur de la sonde équipée, ou en partie dans l'appareil de mesure ou d'essai destiné à être utilisé avec la sonde équipée (voir la Figure 3).
- d) Type D: sondes équipées à basse tension à atténuateurs, sans atténuation ou autres sondes de mise en forme de signaux qui ont des CARACTERISTIQUES ASSIGNEES pour connexion directe uniquement à des tensions n'excédant pas 30 V efficaces ou 42,4 V crête ou 60 V continus, et qui sont adaptées pour des courants dépassant 8 A (voir la Figure 4).

**Légende**

- | | | | |
|---|----------------------|---|-------------------|
| 1 | CONNECTEURS typiques | 4 | vers l'équipement |
| 2 | POINTE DE TOUCHE | 5 | PINCE A RESSORT |
| 3 | corps de sonde | 6 | FIL DE SONDE |

Figure 1 – Exemples de sondes équipées de Type A**Légende**

- | | | | |
|---|-------------------------|---|---|
| 1 | POINTE DE TOUCHE | 4 | PROTÈGE-DOIGTS |
| 2 | vers l'équipement | 5 | partie du corps de la sonde tenue à la main |
| 3 | CONNECTEUR de référence | 6 | FIL DE SONDE |

Figure 2 – Exemples de sondes équipées de Type B

1.1.2 Sondes équipées exclues du domaine d'application

La présente norme ne s'applique pas aux capteurs de courant relevant du domaine d'application de l'IEC 61010-2-032 (capteurs de courant portatifs et manipulés à la main), mais peut s'appliquer à leurs cordons d'entrée de circuit de mesure et à leurs accessoires.

1.2 Objet

1.2.1 Aspects inclus dans le domaine d'application

Les exigences de la présente norme ont pour but d'assurer que les DANGERS pour l'OPERATEUR et la zone alentour sont réduits à un niveau tolérable.

Les exigences relatives à la protection contre des types particuliers de DANGERS sont présentées dans les Articles 6 à 13, comme suit:

- a) les chocs électriques et les brûlures (voir les Articles 6, 10 et 11);
- b) les DANGERS mécaniques (voir les Articles 7, 8 et 11);
- c) les températures excessives (voir l'Article 9);
- d) la propagation du feu à partir de la sonde équipée (voir l'Article 9);
- e) flash d'arc électrique (voir l'Article 13).

Les exigences supplémentaires relatives aux sondes équipées qui sont conçues pour être alimentées à partir d'une alimentation réseau à basse tension, ou comportent d'autres caractéristiques qui ne sont pas spécifiquement traitées dans la présente norme, sont données dans d'autres parties de l'IEC 61010.

NOTE L'attention est attirée sur l'existence possible d'exigences supplémentaires relatives à la santé et à la sécurité des travailleurs.

1.2.2 Aspects exclus du domaine d'application

La présente norme ne couvre pas:

- a) la fiabilité de fonctionnement, les qualités de fonctionnement ou autres propriétés de la sonde équipée;
- b) l'efficacité de l'emballage de transport.

1.3 Vérification

La présente norme spécifie également les méthodes de vérification, par examen, par ESSAIS DE TYPE et par ESSAIS INDIVIDUELS DE SERIE, la conformité de la sonde équipée aux exigences de cette norme.

1.4 Conditions d'environnement

1.4.1 Conditions normales d'environnement

Cette norme est applicable aux sondes équipées conçues pour être sûres au moins dans les conditions suivantes:

- a) altitude inférieure ou égale à 2 000 m;
- b) température ambiante comprise entre 5 °C et 40 °C;
- c) humidité relative maximale de 80 % pour des températures jusqu'à 31 °C, avec décroissance linéaire jusqu'à 50 % d'humidité relative à 40 °C;
- d) DEGRE DE POLLUTION applicable de l'environnement prévu.

1.4.2 Conditions d'environnement étendues

Cette norme est applicable aux sondes équipées conçues pour être sûres non seulement dans les conditions d'environnement spécifiées en 1.4.1, mais aussi dans n'importe laquelle des conditions suivantes telles qu'ASSIGNEES par le fabricant des sondes équipées:

- a) usage en extérieur;
- b) altitudes au-dessus de 2 000 m;
- c) températures ambiantes inférieures à 5 °C ou supérieures à 40 °C;
- d) humidités relatives supérieures aux niveaux spécifiés en 1.4.1;
- e) EMPLACEMENTS HUMIDES.

2 Références normatives

Les documents suivants sont cités en référence de manière normative, en intégralité ou en partie, dans le présent document et sont indispensables pour son application. Pour les références datées, seule l'édition citée s'applique. Pour les références non datées, la dernière édition du document de référence s'applique (y compris les éventuels amendements).

IEC 60027 (toutes les parties), *Symboles littéraux à utiliser en électrotechnique*

IEC 60529, *Degrés de protection procurés par les enveloppes (Code IP)*

IEC 61010-1:2010, *Règles de sécurité pour appareils électriques de mesurage, de régulation et de laboratoire – Partie 1: Exigences générales*

IEC 61180-1:1992, *Techniques des essais à haute tension pour matériels à basse tension – Partie 1: Définitions, prescriptions et modalités relatives aux essais*

IEC 61180-2, *Techniques des essais à haute tension pour matériel à basse tension – Partie 2: Matériel d'essai*

IEC GUIDE 104, *The preparation of safety publications and the use of basic safety publications and group safety publications* (disponible en anglais seulement)

ISO/IEC GUIDE 51, *Aspects liés à la sécurité – Principes directeurs pour les inclure dans les normes*

3 Termes et définitions

Pour les besoins du présent document, les termes et définitions suivants s'appliquent.

3.1 Parties et accessoires

3.1.1

BORNE

composant destiné à raccorder un dispositif (appareil) à des conducteurs extérieurs

Note 1 à l'article: La BORNE peut comporter un ou plusieurs contacts, ce terme inclut donc les prises, les connecteurs, etc.

3.1.2

ENVELOPPE

partie assurant la protection d'une sonde équipée contre certaines influences extérieures et, dans toutes les directions, la protection contre le contact direct

3.1.3**PROTEGE-DOIGTS**

partie de l'ENVELOPPE qui indique la limite de l'accès sûr et qui réduit le risque que l'OPERATEUR touche des parties ACTIVES DANGEREUSES

3.1.4**POINTE DE TOUCHE**

partie d'une sonde équipée ou d'un accessoire qui établit une connexion au point mesuré ou soumis à essai

Note 1 à l'article: Le terme "POINTE DE TOUCHE" inclut les parties conductrices des mâchoires ou crochets des PINCES A RESSORT.

3.1.5**CONNECTEUR**

composant qui est lié au FIL DE SONDE, pour la connexion à une BORNE du matériel ou à un CONNECTEUR d'une autre sonde équipée

3.1.6**OUTIL**

dispositif extérieur, englobant les clés et les pièces de monnaie, utilisé pour aider quelqu'un à réaliser une fonction mécanique

3.1.7**FIL DE SONDE**

fil ou câble souple utilisé comme partie de la sonde équipée ou de ses accessoires, consistant en un ou plusieurs conducteurs et l'isolation associée

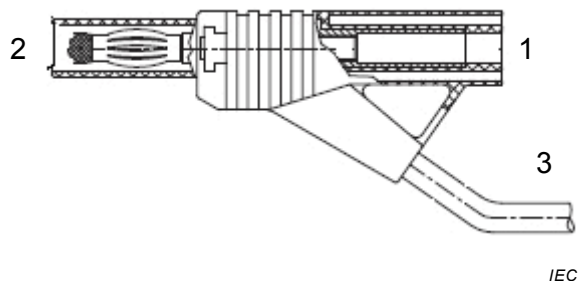
3.1.8**PINCE A RESSORT**

sonde ou accessoire de sonde avec un(e) ou plusieurs crochets ou mâchoires contrain(t)e(s) par un ressort pour agripper la partie mesurée ou soumise à essai

3.1.9**CONNECTEUR EMPILABLE**

assemblage de CONNECTEUR qui contient une BORNE supplémentaire

EXEMPLE: La Figure 5 est un exemple de CONNECTEUR EMPILABLE avec un CONNECTEUR mâle et une BORNE femelle.

**Légende**

- 1 BORNE pour CONNECTEUR supplémentaire
- 2 CONNECTEUR
- 3 FIL DE SONDE

**Figure 5 – Exemple de CONNECTEUR EMPILABLE
avec un CONNECTEUR mâle et une BORNE femelle**

3.2 Grandeurs

3.2.1

(condition ou valeur) **ASSIGNÉE**

condition ou valeur de grandeur assignée, généralement par un fabricant, correspondant à une condition de fonctionnement spécifiée d'un composant, d'un dispositif ou d'une sonde équipée

3.2.2

CARACTERISTIQUES ASSIGNEES

ensemble des valeurs ASSIGNEES et des conditions de fonctionnement

[SOURCE: IEC 60050-151:2001, 151-16-11]

3.2.3

TENSION DE SERVICE

valeur efficace la plus élevée de la tension alternative (c.a.) ou continue (c.c.) pouvant être présente de façon permanente en UTILISATION NORMALE sur n'importe quelle isolation particulière

Note 1 à l'article: Les transitoires et les fluctuations de tension ne sont pas considérés comme faisant partie de la TENSION DE SERVICE.

3.3 Essais

3.3.1

ESSAI DE TYPE

essai effectué sur un ou plusieurs échantillons d'une sonde équipée (ou parties d'une sonde équipée) réalisés selon une conception donnée, pour vérifier que cette conception et la construction répondent aux exigences de la présente norme

Note 1 à l'article: Cette définition développe celle de l'IEC 60050-151:2001, 151-16-16 pour tenir compte des exigences de conception comme de construction.

3.3.2

ESSAI INDIVIDUEL DE SÉRIE

essai de conformité effectué sur chaque entité en cours ou en fin de fabrication

[SOURCE: IEC 60050-151:2001, 151-16-17]

3.4 Termes de sécurité

3.4.1

ACCESSIBLE

pouvant être touché au moyen du doigt d'épreuve normalisé ou d'une broche d'essai comme spécifié en 6.2

3.4.2

ACTIVE DANGEREUSE

capable de causer un choc électrique ou une brûlure électrique

3.4.3

DANGER

phénomène dangereux
source potentielle de dommage

3.4.4

IMPEDANCE DE PROTECTION

composant, ensemble de composants, dont l'impédance, la construction et la fiabilité sont aptes à assurer la protection contre les chocs électriques

3.4.5**UTILISATION NORMALE**

fonctionnement y compris en position d'attente, conformément aux instructions d'utilisation ou à l'usage prévu évident

3.4.6**CONDITION NORMALE**

état dans lequel tous les moyens de protection contre les DANGERS sont intacts

3.4.7**CONDITION DE PREMIER DEFAUT**

état dans lequel un seul moyen de protection contre un DANGER est défectueux ou un seul défaut est présent ce qui pourrait entraîner un DANGER

3.4.8**OPERATEUR**

personne qui utilise la sonde équipée pour l'usage auquel elle est destinée

3.4.9**AUTORITE RESPONSABLE**

individu ou groupe responsable de l'utilisation et de la maintenance des sondes équipées en sécurité

3.4.10**EMPLACEMENT HUMIDE**

emplacement où peuvent être présents de l'eau ou d'autres liquides conducteurs et qui risquent de réduire l'impédance du corps humain à cause du mouillage du contact entre le corps humain et la sonde équipée, ou du mouillage du contact entre le corps humain et l'environnement

3.4.11**CATEGORIE DE MESURE**

classification des circuits d'essai et de mesure selon le type de circuits réseau auxquels ils sont prévus d'être reliés

3.4.12**MAUVAIS USAGE RAISONNABLEMENT PREVISIBLE**

utilisation d'un produit dans des conditions ou à des fins non prévues par le fournisseur, mais qui peut provenir d'un comportement humain envisageable

3.5 Isolation**3.5.1****ISOLATION PRINCIPALE**

isolation des parties ACTIVES DANGEREUSES qui assure la protection principale

[SOURCE: IEC 60050-195:1998, 195-06-06]

3.5.2**ISOLATION SUPPLEMENTAIRE**

isolation indépendante appliquée en plus de l'ISOLATION PRINCIPALE afin d'assurer une protection contre les chocs électriques en cas de défaillance de l'ISOLATION PRINCIPALE

3.5.3**DOUBLE ISOLATION**

isolation comprenant à la fois une ISOLATION PRINCIPALE et une ISOLATION SUPPLEMENTAIRE

[SOURCE: IEC 60050-195:1998, 195-06-08]

3.5.4

ISOLATION RENFORCEE

isolation qui assure un degré de protection contre les chocs électriques qui n'est pas inférieur à celui assuré par l'ISOLATION DOUBLE

3.5.5

POLLUTION

toute addition de corps étrangers, solides, liquides ou gazeux (gaz ionisés), qui peut produire une réduction de rigidité diélectrique ou de résistivité superficielle

3.5.6

DEGRE DE POLLUTION

nombre indiquant le niveau de POLLUTION qui peut être présent dans l'environnement

3.5.7

DEGRE DE POLLUTION 1

pas de POLLUTION ou uniquement une POLLUTION sèche, non conductrice qui n'a pas d'influence

3.5.8

DEGRE DE POLLUTION 2

POLLUTION non conductrice seulement, pouvant occasionnellement présenter une conductivité temporaire provoquée par la condensation

3.5.9

DEGRE DE POLLUTION 3

présence d'une POLLUTION conductrice ou d'une POLLUTION sèche, non conductrice, qui devient conductrice par suite de la condensation qui peut se produire

3.5.10

DISTANCE D'ISOLEMENT (dans l'air)

distance la plus courte dans l'air entre deux parties conductrices

3.5.11

LIGNE DE FUITE

distance la plus courte, le long de la surface d'un isolant solide, entre deux parties conductrices

[SOURCE: IEC 60050-151:2001, 151-15-50]

3.5.12

ESPACEMENT

toute combinaison de DISTANCES D'ISOLEMENT et de LIGNES DE FUITE

4 Tests

4.1 Généralités

Tous les essais dans la présente norme sont des ESSAIS DE TYPE qui doivent être effectués sur des échantillons de sondes équipées ou de parties de sondes équipées. Leur seule fin est de vérifier que la conception et la construction garantissent la conformité à cette norme. En outre, les ESSAIS INDIVIDUELS DE SERIE selon l'Annexe D doivent être réalisés sur le FIL DE SONDE.

La sonde équipée doit au moins satisfaire aux exigences de la présente norme. Il est permis de dépasser les exigences. Si la présente norme spécifie une limite inférieure pour une valeur de conformité, la sonde équipée peut démontrer une valeur plus élevée. Si une limite

supérieure est spécifiée pour une valeur de conformité, la sonde équipée peut démontrer une valeur inférieure. Les variations et les tolérances de fabrication doivent être prises en compte.

Les essais réalisés sur des composants ou parties de la sonde équipée qui satisfont aux exigences des normes applicables spécifiées dans la présente norme, et qui sont utilisé(e)s conformément à celles-ci, peuvent ne pas être répétés au cours des ESSAIS DE TYPE de la sonde équipée au complet.

Si une sonde équipée est de plusieurs types (voir 1.1.1), chaque type doit être soumis à essai selon les exigences appropriées.

La conformité aux exigences de la présente norme est vérifiée en effectuant tous les essais applicables, mais un essai peut être omis lorsque l'examen de la sonde équipée et de la documentation relative à la conception démontre de façon incontestable que la sonde équipée en question serait en mesure de subir cet essai avec succès. Les essais sont effectués tant dans des conditions de référence pour essais (voir 4.3) que dans des conditions de défaut (voir 4.4).

Lorsque les énoncés de conformité dans la présente norme exigent une inspection, cela peut inclure l'examen de la sonde équipée par mesure, l'examen des marquages sur la sonde équipée, l'examen des instructions livrées avec la sonde équipée, l'examen des fiches techniques des matériaux ou des composants qui ont servi à fabriquer la sonde équipée, etc. Dans chaque cas, l'inspection démontrera que la sonde équipée satisfait aux exigences applicables ou indiquera que des essais complémentaires sont requis.

Si, en effectuant un essai de conformité, il y a une incertitude quelconque à propos de la valeur exacte d'une grandeur appliquée ou mesurée (la tension, par exemple), en raison de la tolérance, il convient que:

- a) les fabricants s'assurent qu'au moins la valeur d'essai spécifiée est appliquée;*
- b) les laboratoires d'essai s'assurent qu'il n'est pas appliqué plus que la valeur d'essai spécifiée.*

Si la plage ASSIGNEE des conditions d'environnement pour la sonde équipée est plus large que celle qui est énoncée en 1.4.1, il convient que le fabricant s'assure (par exemple, par une modification appropriée des exigences d'essai ou par la réalisation d'essais supplémentaires) que les exigences de sécurité de la présente norme sont encore respectées.

Les sondes équipées qui ont subi les ESSAIS DE TYPE peuvent ne plus être adaptées à leur fonction prévue en raison des contraintes résiduelles résultant de certains de ces essais. Par conséquent, une sonde équipée qui a subi des ESSAIS DE TYPE ne doit pas être utilisée.

4.2 Séquence d'essais

La séquence d'essais est facultative, sauf exigences contraires. La sonde équipée soumise aux essais doit être soigneusement examinée après chaque essai. Si le résultat d'un essai engendre un doute sur la question de savoir si des essais antérieurs ont été subis avec succès en cas d'inversion de la séquence, ces essais préalables doivent être répétés.

4.3 Conditions de référence pour les essais

4.3.1 Conditions d'environnement

Sauf spécification contraire dans la présente norme, les conditions d'environnement suivantes (qui ne doivent cependant pas être en contradiction avec celles en 1.4.1) doivent prévaloir dans le local d'essai:

- a) température comprise entre 15 °C et 35 °C;
- b) humidité relative non supérieure à 75 %;

- c) pression d'air comprise entre 75 kPa et 106 kPa;
- d) pas de gelée blanche, de rosée, d'eau d'infiltration, de pluie, de rayonnement solaire, etc.

4.3.2 État des sondes équipées

Sauf exigence contraire, les essais doivent être effectués sur la sonde équipée complète pour une UTILISATION NORMALE, et suivant la combinaison la moins favorable des conditions données de 4.3.3 à 4.3.9.

En cas de doute, les essais doivent être effectués suivant plus d'une combinaison de conditions.

S'il n'est pas approprié, en raison des dimensions ou de la masse, d'effectuer des essais particuliers sur une sonde équipée, les essais sur des sous-ensembles sont admis, pourvu qu'il soit vérifié que la sonde équipée complète satisfera aux exigences de la présente norme.

4.3.3 Position de la sonde équipée

Toutes les orientations possibles de la sonde équipée sont considérées comme étant des positions d'UTILISATION NORMALE.

4.3.4 Accessoires

Les accessoires et parties interchangeables par un OPERATEUR, mis à disposition ou recommandés par le fabricant pour utilisation avec la sonde équipée objet de l'essai, doivent être raccordés ou non à la sonde équipée.

4.3.5 Couvercles et parties amovibles

Les couvercles ou les parties qui peuvent être retirés sans utiliser d'OUTIL doivent être retirés ou non retirés suivant la pire des conditions.

4.3.6 Tensions d'entrée et de sortie

Les tensions d'entrée et de sortie, y compris les tensions flottantes, doivent être ajustées à n'importe quelle tension dans la plage de tensions ASSIGNEES.

4.3.7 Dispositifs de commande

Les dispositifs de commande qu'un OPERATEUR peut manipuler sans l'aide d'un OUTIL doivent être réglés sur n'importe quelle position sauf pour les combinaisons de présélections interdites par un marquage apposé par le fabricant sur la sonde équipée.

4.3.8 Raccordements

La sonde équipée doit être connectée pour une UTILISATION NORMALE ou non connectée suivant la pire des conditions.

4.3.9 Cycle de service

Les sondes équipées destinées à être utilisées en fonctionnement intermittent ou de durée limitée doivent être mises en service pendant la période ASSIGNEE la plus longue et avoir la période de récupération ASSIGNEE la plus courte qui soit conforme aux instructions du fabricant.

4.4 Essais en CONDITION DE PREMIER DEFAUT

4.4.1 Généralités

Les exigences suivantes s'appliquent.

- a) L'examen de la sonde équipée et de son schéma de circuit indiquera généralement les conditions de défaut qui sont susceptibles de provoquer des DANGERS et qui doivent par conséquent être appliquées.
- b) Les essais de défauts doivent être effectués comme spécifié lors de la vérification de conformité, sauf s'il peut être démontré qu'aucun DANGER ne pourra résulter d'une condition de défaut particulière.
- c) La sonde équipée doit être utilisée suivant la combinaison la moins favorable des conditions de référence pour les essais (voir 4.3). Ces combinaisons peuvent être différentes pour des défauts différents et elles doivent être enregistrées pour chaque essai.

4.4.2 Application des conditions de défaut

4.4.2.1 Généralités

Les conditions de défaut doivent inclure celles qui sont spécifiées de 4.4.2.2 à 4.4.2.5. Elles doivent être appliquées à tour de rôle selon l'ordre le plus pratique. Des défauts multiples ne doivent pas être appliqués simultanément, à moins qu'ils ne soient une conséquence du défaut appliqué.

Après chaque application d'une condition de défaut, la sonde équipée ou la partie doit subir avec succès les essais applicables de 4.4.4

4.4.2.2 IMPÉDANCE DE PROTECTION

Les exigences suivantes s'appliquent.

- a) Si une IMPÉDANCE DE PROTECTION est formée par une combinaison de composants, chaque composant doit être court-circuité ou déconnecté selon la condition la moins favorable.
- b) Si une IMPÉDANCE DE PROTECTION est formée d'un seul composant qui satisfait aux exigences de 6.4.5, elle n'a pas à être court-circuitée ou déconnectée.

4.4.2.3 Sondes équipées ou parties de sondes équipées à fonctionnement de courte durée ou intermittent

Elles doivent être mises en fonctionnement en permanence si le fonctionnement continu peut se produire lors d'une CONDITION DE PREMIER DEFAUT.

4.4.2.4 Sorties

Les sorties des sondes équipées de Type B et de Type C doivent être court-circuitées.

4.4.2.5 Isolation entre circuits et parties

L'isolation entre les circuits et les parties qui est en dessous du niveau spécifié pour l'ISOLATION PRINCIPALE doit être pontée pour vérifier la propagation du feu si la méthode en 9.1 est utilisée.

4.4.3 Durée des essais

La sonde équipée doit fonctionner jusqu'à ce qu'il soit improbable qu'un changement ultérieur ne se produise par suite du défaut appliqué. La durée de chaque essai est normalement limitée à 1 h car un défaut secondaire occasionné par une CONDITION DE PREMIER DEFAUT se manifeste habituellement dans ce délai. S'il y a une indication qu'un DANGER de choc électrique, de propagation du feu ou de préjudice à des personnes puisse finalement se produire, l'essai doit être poursuivi pendant une durée maximale de 4 h.

4.4.4 Conformité après application des conditions de défaut

4.4.4.1 Choc électrique

La conformité aux exigences de protection contre les chocs électriques après application des conditions de premier défaut est vérifiée comme suit:

- a) *en effectuant les mesures indiquées en 6.3.3 pour vérifier qu'aucune partie conductrice ACCESSIBLE n'est devenue ACTIVE DANGEREUSE, sauf dans les conditions permises en 6.1;*
- b) *en réalisant un essai de tension sur la DOUBLE ISOLATION ou sur l'ISOLATION RENFORCEE pour vérifier que la protection est encore au moins au niveau de l'ISOLATION PRINCIPALE. Les essais de tension sont effectués comme spécifié en 6.6 (sans l'essai de pré-conditionnement à l'humidité) avec la tension d'essai de l'ISOLATION PRINCIPALE.*

4.4.4.2 Température

La conformité aux exigences de protection thermique est vérifiée en déterminant la température de la surface extérieure de la sonde équipée (voir l'Article 9).

Cette température est déterminée en mesurant l'échauffement de la surface ou de la partie et en l'ajoutant à la température ambiante maximale ASSIGNEE.

4.4.4.3 Propagation du feu

La conformité aux exigences de protection contre la propagation du feu est vérifiée en plaçant la sonde équipée sur du papier mousseline blanc couvrant une surface en bois tendre et en recouvrant la sonde équipée de gaze. Ni métal en fusion, ni isolant en combustion, ni particules enflammées etc., ne doivent tomber sur la surface sur laquelle se trouve la sonde équipée et il ne doit y avoir ni carbonisation, ni incandescence, ni embrasement du papier mousseline ou de la gaze. Une fusion de matière isolante ne doit pas être prise en compte si aucun DANGER ne peut se produire.

4.4.4.4 Autres DANGERS

La conformité aux exigences de protection contre les autres DANGERS est vérifiée conformément aux spécifications des Articles 7 à 13.

4.5 Essais en MAUVAIS USAGE RAISONNABLEMENT PREVISIBLE

4.5.1 Généralités

Les essais nécessaires pour venir à l'appui d'une appréciation du risque relatif à un MAUVAIS USAGE RAISONNABLEMENT PREVISIBLE sont réalisés dans les combinaisons de conditions et de fonctionnements déterminées au cours de l'appréciation du risque.

4.5.2 Fusibles

Les sondes équipées avec fusible sont utilisées quand l'appareil, auquel les sondes équipées tenues à la main sont connectées, apporte une protection insuffisante en particulier dans les conditions de MAUVAIS USAGE RAISONNABLEMENT PREVISIBLE qui pourrait provoquer un incendie ou une explosion due à un arc.

Pour les besoins de cet essai, il est supposé que l'appareil auquel les sondes équipées avec fusible sont connectées constitue une condition de court-circuit. On suppose en outre que les sondes équipées avec fusible peuvent être connectées à n'importe quelle source de tension suivant les CARACTERISTIQUES ASSIGNEES de la sonde équipée. Cela conduit à une condition d'essai où n'importe quelle valeur de courant pouvant atteindre le courant éventuel maximal de court-circuit peut être appliquée. En ce qui concerne les courants éventuels de court-circuit liés aux installations du réseau, la caractéristique du fusible doit être ASSIGNEE selon 12.2 et aucun essai supplémentaire liée à la CARACTERISTIQUE ASSIGNEE du courant de coupure n'est nécessaire. Cependant, les essais sont nécessaires aux niveaux actuels

proches de la CARACTERISTIQUE ASSIGNEE du fusible qui pourrait potentiellement conduire à une augmentation excessive de la température sur les parties tenues à la main ainsi qu'à des dommages aux parties isolantes, ENVELOPPES, et les barrières.

Il doit être prouvé que la température maximum du fusible de la sonde équipée avec fusible ne conduit pas à un DANGER lorsque toutes les conditions de charge du courant jusqu'à 5 fois la CARACTERISTIQUE ASSIGNEE du fusible sont appliquées.

La conformité est vérifiée par examen et mesure.

5 Marquage et documentations

5.1 Marquage

5.1.1 Généralités

Les sondes équipées doivent porter les marquages selon 5.1.2 à 5.2. Les marquages concernant la sonde équipée dans son ensemble ne doivent pas être apposés sur des parties qui peuvent être retirées par un OPERATEUR sans l'aide d'un OUTIL.

Les symboles littéraux pour les grandeurs et les unités doivent être conformes à l'IEC 60027. Les symboles graphiques doivent être conformes au Tableau 1, si applicable. Il n'y a aucune exigence relative à la taille ou à la couleur. S'il n'y a pas de symbole applicable dans le Tableau 1, tout autre symbole graphique peut être utilisé sur la sonde équipée, à condition de l'expliquer dans la documentation d'accompagnement (voir 5.4.1)

S'il n'est pas possible d'apposer tous les marquages qui sont requis sur la pièce, les informations nécessaires doivent être incluses dans la documentation. Le Symbole 7 du Tableau 1 peut aussi être utilisé.

La conformité est vérifiée par examen.

5.1.2 Identification

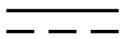
Chaque sonde équipée et, si possible, ses accessoires doivent être marqués avec:

- a) le nom ou la marque déposée du fabricant ou du fournisseur;
- b) en supplément pour le Type B et le Type C seulement, le numéro du modèle ou le nom ou tout autre moyen permettant d'identifier la sonde équipée ou la partie.

Si une sonde équipée est conçue pour n'être utilisée qu'avec un modèle d'appareil spécifique, cela doit apparaître de façon claire, et l'appareil ou le modèle spécifique doit être désigné soit par un marquage sur la sonde équipée, soit dans la documentation d'accompagnement.

La conformité est vérifiée par examen.

Tableau 1 – Symboles

Numéro	Symbole	Publication	Description
1		IEC 60417-5031 (2002-10)	Courant continu
2		IEC 60417-5032 (2002-10)	Courant alternatif
3		IEC 60417-5033 (2002-10)	Courant continu et courant alternatif
4		IEC 60417-5017 (2006-08)	BORNE de terre (masse)
5		IEC 60417-6042 (2010-11)	Attention, possibilité de choc électrique
6		IEC 60417-5041 (2002-10)	Attention, surface chaude
7		ISO 7000-0434 (2004-01)	Attention ^a
^a Voir 5.4.1 exigeant que les fabricants déclarent qu'il faut consulter la documentation chaque fois que ce symbole est marqué.			

5.1.3 Fusibles

Les sondes équipées contenant des fusibles conçus pour être remplacés par un OPERATEUR doivent être marquées avec tous les détails nécessaires pour que l'OPERATEUR puisse obtenir le fusible correct. Ces marquages doivent comprendre les CARACTERISTIQUES ASSIGNEES de tension ainsi que le pouvoir de coupure (courant maximal que le fusible peut interrompre de manière sûre à la tension ASSIGNEE la plus élevée). Si la place est insuffisante, le Symbole 7 du Tableau 1 doit être marqué sur la sonde équipée et les informations nécessaires doivent être incluses dans la documentation.

La conformité est vérifiée par examen.

5.1.4 CONNECTEURS et dispositifs de manœuvre

Si cela est nécessaire pour la sécurité, une indication doit être donnée sur le rôle des CONNECTEURS, des BORNES, des dispositifs de commande, y compris toutes les séquences de fonctionnement.

La conformité est vérifiée par examen.

5.1.5 CARACTÉRISTIQUES ASSIGNÉES

Les CARACTÉRISTIQUES ASSIGNÉES des sondes équipées doivent être marquées comme suit.

- a) Les sondes équipées qui n'ont pas de CARACTÉRISTIQUE ASSIGNÉE pour les CATEGORIES DE MESURE II, III, ou IV (voir 6.5.2) doivent être marquées avec la tension ASSIGNÉE à la terre et avec le Symbole 7 du Tableau 1 (voir aussi 5.4.3 f) et g)).
- b) Les sondes équipées prévues pour la mesure dans les CATEGORIES DE MESURE II, III et IV (voir 6.5.2) doivent être marquées avec les tensions ASSIGNÉES à la terre et avec les CATEGORIES DE MESURE pertinentes. Les marquages de la CATEGORIE DE MESURE doivent être «CAT II», «CAT III» ou «CAT IV» selon ce qui est applicable.

Le marquage sur une sonde équipée doit être préférentiellement apposé sur le corps de la sonde. La nature de la tension (courant alternatif, courant continu, etc.) doit également être marquée, sauf si la valeur marquée de tension s'applique à la fois au courant alternatif efficace (c.a. eff.) et au courant continu (c.c.). Si un CONNECTEUR de référence est conçu pour une connexion à des points d'un niveau de tension supérieur aux valeurs prévues en 6.3.2, la tension ASSIGNÉE doit être marquée sur le CONNECTEUR ou aussi près que possible du CONNECTEUR.

Pour les sondes équipées de Type A et de Type D seulement, la valeur ASSIGNÉE du courant de la sonde équipée doit être marquée conjointement avec la valeur ASSIGNÉE de la tension à la terre. La valeur ASSIGNÉE du courant peut ne pas être marquée sur les sondes équipées spécifiées pour une utilisation uniquement avec un appareil ayant des entrées à haute impédance ou des sorties limitées en courant.

La conformité est vérifiée par examen.

5.2 Marquages d'avertissement

Les marquages d'avertissement doivent être lisibles lorsque la sonde équipée est prête pour l'UTILISATION NORMALE.

S'il est nécessaire à l'OPERATEUR de se reporter aux instructions d'emploi pour conserver les protections offertes par la sonde équipée, la sonde équipée doit porter le Symbole 7 du Tableau 1. Si un avertissement s'applique à une partie particulière de la sonde équipée, cet avertissement doit être placé sur la partie en question ou à proximité de celle-ci.

Si les instructions d'utilisation énoncent que l'OPERATEUR est autorisé à avoir accès, en utilisant un OUTIL, à une partie qui peut être ACTIVE DANGEREUSE en UTILISATION NORMALE, un avertissement doit être marqué pour énoncer que la sonde équipée doit être isolée ou déconnectée de la tension ACTIVE DANGEREUSE avant l'accès ou le Symbole 7 du Tableau 1 peut être utilisé à condition que l'information soit comprise dans les instructions d'utilisation.

A moins que leur état chaud ne soit évident ou implicite d'après la fonction de la sonde équipée, les parties aisément touchées et aussi autorisées selon 9.1 à dépasser les limites de température indiquées en 9.1 doivent être marquées du Symbole 6 du Tableau 1.

La conformité est vérifiée par examen.

5.3 Durabilité du marquage

Les marquages exigés doivent rester nets et lisibles dans les conditions d'UTILISATION NORMALE et doivent résister aux effets des agents de nettoyage spécifiés par le fabricant.

La conformité est vérifiée en réalisant l'essai suivant pour la durabilité des marquages apposés sur l'extérieur de la sonde équipée. Les marquages sont frottés à la main, sans pression excessive pendant 30 s avec un tissu imbibé avec chacun des agents de nettoyage

spécifié, un à la fois, ou, si aucun agent n'est spécifié, avec une solution aqueuse contenant 70 % minimum d'alcool isopropylique.

Après le traitement ci-dessus, les marquages doivent rester clairement lisibles et les étiquettes adhésives ne doivent pas se décoller ni présenter de bords enroulés.

5.4 Documentation

5.4.1 Généralités

Les sondes équipées doivent être accompagnées de la documentation nécessaire à la sécurité. Une telle documentation doit au moins inclure:

- a) la spécification technique;
- b) les instructions d'utilisation;
- c) le nom et l'adresse du fabricant ou du fournisseur auprès duquel il est possible d'obtenir l'assistance technique nécessaire;
- d) les informations spécifiées de 5.4.2 à 5.4.4.

S'il y a lieu, des avis d'avertissement et une explication claire des symboles d'avertissement marqués sur les sondes équipées doivent être donnés dans la documentation ou doivent être marqués de façon durable et lisible sur les sondes équipées. En particulier, il doit y avoir un énoncé expliquant que la documentation a besoin d'être consultée chaque fois que le Symbole 7 du Tableau 1 est utilisé, afin de connaître la nature du DANGER potentiel et toutes les actions nécessaires à prendre.

La conformité est vérifiée par examen.

5.4.2 CARACTÉRISTIQUES ASSIGNÉES des sondes équipées

La documentation doit comporter les CARACTÉRISTIQUES ASSIGNÉES de tension et de courant (selon ce qui est approprié) et la CATÉGORIE DE MESURE ainsi qu'un énoncé de la plage des conditions d'environnement pour lesquelles la sonde équipée est conçue (voir 1.4).

La conformité est vérifiée par examen.

5.4.3 Fonctionnement de sonde équipée

Les instructions d'utilisation doivent inclure, lorsqu'elles s'appliquent:

- a) l'identification des dispositifs de commande et leur utilisation dans tous les modes opératoires;
- b) pour les sondes équipées conçues pour être utilisées seulement avec un modèle spécifique de matériel, une identification claire et nette du matériel;
- c) une explication des symboles relatifs à la sécurité qui sont utilisés sur la sonde équipée;
- d) une définition de la CATÉGORIE DE MESURE applicable si le marquage est exigé sur la sonde équipée (voir 5.1.5);
- e) une spécification des limites de fonctionnement intermittent, s'il y a lieu;
- f) les instructions pour l'interconnexion aux accessoires et à d'autres appareils, y compris l'indication des accessoires appropriés, pièces amovibles et tous matériaux spéciaux;
- g) les instructions pour le nettoyage;
- h) les instructions pour le remplacement des matières consommables;
- i) pour les sondes équipées qui n'ont pas de FIL DE SONDE avec un indicateur d'usure, les instructions pour l'examen périodique du FIL DE SONDE;

- j) pour les sondes équipées qui ont un FIL DE SONDE avec un indicateur d'usure, un avertissement interdisant d'utiliser la sonde équipée si l'indicateur d'usure est devenu visible (voir 12.3.2);
- k) pour les sondes équipées qui n'ont pas de CARACTERISTIQUE ASSIGNEE pour les CATEGORIES DE MESURE II, III et IV, un avertissement interdisant d'utiliser les sondes équipées pour des mesures sur les circuits de réseaux de distribution;
- l) pour les sondes équipées de Type B, si la tension ASSIGNEE du FIL DE SONDE est inférieure à la tension ASSIGNEE de la POINTE DE TOUCHE, un avertissement indiquant que le FIL DE SONDE peut ne pas fournir la protection adéquate s'il entre en contact avec une partie ACTIVE DANGEREUSE;
- m) un avertissement précisant que la CATEGORIE DE MESURE applicable d'un assemblage d'une sonde équipée et d'un accessoire est la CATEGORIE DE MESURE la plus basse entre la CATEGORIE DE MESURE de la sonde équipée et celle de l'accessoire.

Il doit y avoir dans les instructions un énoncé indiquant que, si la sonde équipée est utilisée d'une façon qui n'est pas spécifiée par le fabricant, la protection assurée par la sonde équipée peut être compromise.

La conformité est vérifiée par examen.

5.4.4 Maintenance et entretien des sondes équipées

L'AUTORITE RESPONSABLE doit recevoir des instructions suffisamment détaillées pour permettre la maintenance et l'examen en toute sécurité de la sonde équipée et d'assurer la sécurité permanente de la sonde équipée après la procédure de maintenance et d'examen.

Le fabricant doit spécifier toutes les parties qui ne doivent être vérifiées ou fournies que par le fabricant ou son représentant.

Les CARACTERISTIQUES ASSIGNEES et les caractéristiques des fusibles utilisés doivent être énoncées (voir 5.1.3).

Les instructions relatives aux sujets suivants doivent être fournies pour le personnel d'entretien, selon les besoins afin de permettre un entretien sûr et une sécurité permanente de la sonde équipée après l'entretien si la sonde équipée se prête à être entretenue:

- a) les risques spécifiques à un produit qui peuvent affecter le personnel d'entretien;
- b) les mesures de protection contre ces risques;
- c) la confirmation par vérification que la sonde équipée est dans un état sûr après réparation.

Les instructions pour le personnel d'entretien peuvent ne pas être fournies à l'AUTORITE RESPONSABLE, mais il convient qu'elles soient disponibles pour le personnel d'entretien.

La conformité est vérifiée par examen.

6 Protection contre les chocs électriques

6.1 Généralités

La protection contre les chocs électriques doit être maintenue en CONDITION NORMALE et en CONDITION DE PREMIER DEFAUT. Les parties ACCESSIBLES des sondes équipées ne doivent pas être ACTIVES DANGEREUSES (voir 6.3).

S'il n'est pas possible pour des raisons fonctionnelles d'éviter que les parties suivantes soient à la fois ACCESSIBLES et ACTIVES DANGEREUSES, elles peuvent néanmoins être ACCESSIBLES à l'OPERATEUR en UTILISATION NORMALE tout en étant ACTIVES DANGEREUSES:

- a) les parties destinées à être remplacées par l'OPERATEUR (par exemple, les fusibles) et qui peuvent être ACTIVES DANGEREUSES pendant leur remplacement, mais seulement si elles portent un marquage d'avertissement conforme à 5.2
- b) les POINTES DE TOUCHE, à condition qu'elles satisfassent aux exigences en 6.4.3;
- c) les CONNECTEURS découplés tels que spécifiés en 6.4.2 c).

La conformité est vérifiée par la détermination en 6.2 et les mesures en 6.3, suivies des essais de 6.4 à 6.7.

6.2 Détermination des parties ACCESSIBLES

6.2.1 Généralités

À moins que cela ne soit évident, la détermination pour savoir si une partie est ACCESSIBLE est effectuée telle que spécifiée en 6.2.2 et 6.2.3. Les doigts d'épreuve (voir Annexe B) et les broches d'essai sont appliqués sans effort. Des parties sont considérées comme étant ACCESSIBLES si elles peuvent être touchées par une partie quelconque d'un doigt d'épreuve ou d'une broche d'essai ou si elles peuvent être touchées en l'absence de couvercle considéré comme n'assurant pas une isolation appropriée (voir 6.7.2).

Si, en UTILISATION NORMALE, des actions quelconques prévues (avec ou sans l'aide d'un OUTIL) d'un OPERATEUR sont susceptibles d'augmenter l'accessibilité des parties, ces actions sont entreprises avant d'accomplir les examens en 6.2.2 et 6.2.3.

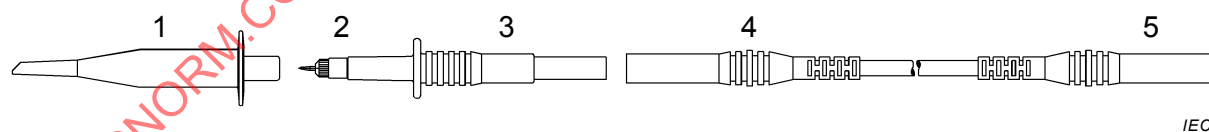
NOTE Exemples de ces actions:

- a) retrait des couvercles;
- b) réglage des dispositifs de commande;
- c) remplacement de matériaux consommables;
- d) dépose ou installation de parties et d'accessoires fournies.

La Figure 6 donne des méthodes pour la détermination des parties ACCESSIBLES des sondes équipées.

6.2.2 Examen

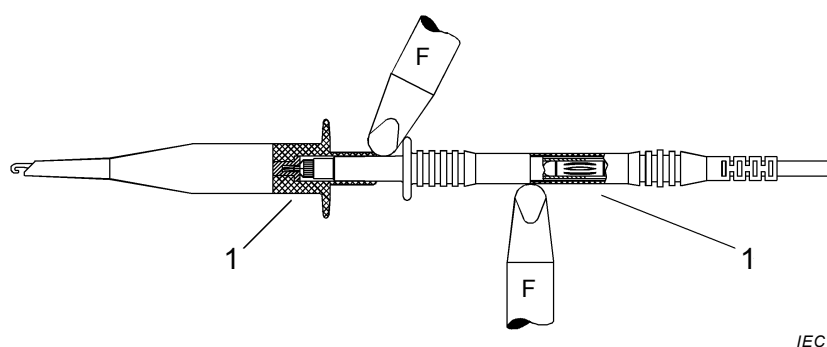
Le doigt d'épreuve articulé (voir la Figure B.2) est appliqué sans effort dans toutes les positions possibles. L'essai est appliqué à toutes les surfaces extérieures.



Légende

- | | | | |
|---|-------------------------------|---|------------------------------|
| 1 | POINTE DE TOUCHE d'accessoire | 4 | CONNECTEUR |
| 2 | POINTE DE TOUCHE | 5 | CONNECTEUR vers l'équipement |
| 3 | corps de sonde | | |

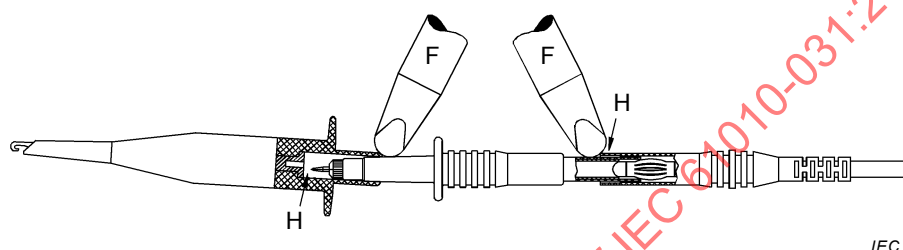
Figure 6a – Partie d'une sonde équipée



IEC

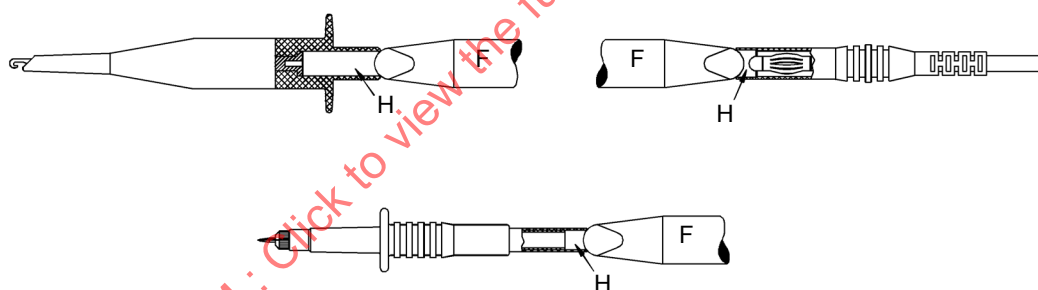
Légende

1 CONNECTEUR

Figure 6b – Sonde équipée totalement couplée (voir 6.2 et 6.4.2 a))

IEC

Les parties de connexion sont partiellement couplées pour juste réaliser un contact électrique tout en autorisant un accès maximal au doigt d'épreuve.

Figure 6c – Sonde équipée partiellement couplée (voir 6.2 et 6.4.2b))

IEC

Légende

F Doigt d'épreuve rigide (voir la Figure B.1)

H Partie potentiellement ACTIVE DANGEREUSE

Figure 6d – Parties découplées d'une sonde équipée (voir 6.2 et 6.4.2 c))**Figure 6 – Méthodes pour la détermination des parties ACCESSIBLES (voir 6.2) et pour les essais de tension (voir 6.4.2)****6.2.3 Ouvertures d'accès aux commandes prérégées**

Une broche d'essai métallique de 3 mm de diamètre est insérée à travers les orifices prévus pour l'accès aux commandes prérégées qui nécessitent l'utilisation d'un tournevis ou d'un autre OUTIL. La broche d'essai est appliquée dans toute direction possible à travers l'orifice. La pénétration ne doit pas dépasser trois fois la distance entre la surface de l'ENVELOPPE et l'axe de la commande ou 100 mm, la plus petite de ces deux valeurs étant retenue.

6.3 Valeurs limites pour les parties ACCESSIBLES

6.3.1 Généralités

À l'exception des cas permis en 6.1, la tension entre une partie ACCESSIBLE et la terre ou entre deux parties ACCESSIBLES quelconques de la même sonde équipée, ne doit pas dépasser les niveaux indiqués en 6.3.2 en CONDITION NORMALE ou indiqués en 6.3.3 en CONDITION DE PREMIER DEFAT.

Les conducteurs extérieurs (blindages) des sondes équipées, destinés à être flottants, sont considérés comme étant portés à la même tension que la POINTE DE TOUCHE.

La tension ACCESSIBLE doit être mesurée (voir 6.3.4). Si la tension est inférieure aux niveaux selon 6.3.2 a) ou 6.3.3 a), selon le cas, le courant de contact et la capacité peuvent ne pas être mesurés. Si la tension dépasse ce niveau, le courant de contact et la capacité doivent être mesurés. Pour les sondes de test à hautes fréquences, la méthode alternative de 6.3.4.3 peut aussi être utilisée.

La conformité est vérifiée par examen et de la manière spécifiée de 6.3.2 à 6.3.3.

6.3.2 Niveaux en CONDITION NORMALE

Les tensions supérieures aux niveaux selon a) sont réputées être ACTIVES DANGEREUSES si des niveaux en b) ou c) sont dépassés en même temps.

- a) Les niveaux de tension alternative sont 30 V efficaces, 42,4 V crête et le niveau de tension continue est 60 V. Pour ce qui concerne les sondes équipées destinées à être utilisées dans des EMBLEMENTS HUMIDES, les niveaux de tension alternative sont 16 V efficaces ou 22,6 V crête et le niveau de tension continue est 35 V.
- b) Les niveaux de courant de contact sont:
 - 1) 0,5 mA efficace pour la forme d'onde sinusoïdale, 0,7 mA crête pour les fréquences non sinusoïdales ou les fréquences mixtes, ou 2 mA continu, lorsque le courant est mesuré avec le circuit de la Figure A.1. Si la fréquence ne dépasse pas 100 Hz, le circuit de mesure de la Figure A.2 peut être utilisé. Le circuit de mesure de la Figure A.5 est utilisé pour les sondes équipées qui sont destinées à être utilisées dans des EMBLEMENTS HUMIDES.
 - 2) 70 mA efficaces, lorsque le courant est mesuré avec le circuit de mesure de la Figure A.3. Cela se rapporte aux brûlures possibles à des fréquences supérieures à 100 kHz.
- c) Les niveaux de charge capacitive ou d'énergie sont:
 - 1) une charge de 45 μC pour les tensions inférieures ou égales à 15 kV crête ou continu. La droite A de la Figure 7 montre la capacité en fonction de la tension dans les cas où la charge est de 45 μC .
 - 2) une énergie accumulée de 350 mJ pour les tensions supérieures à 15 kV crête ou courant continu.

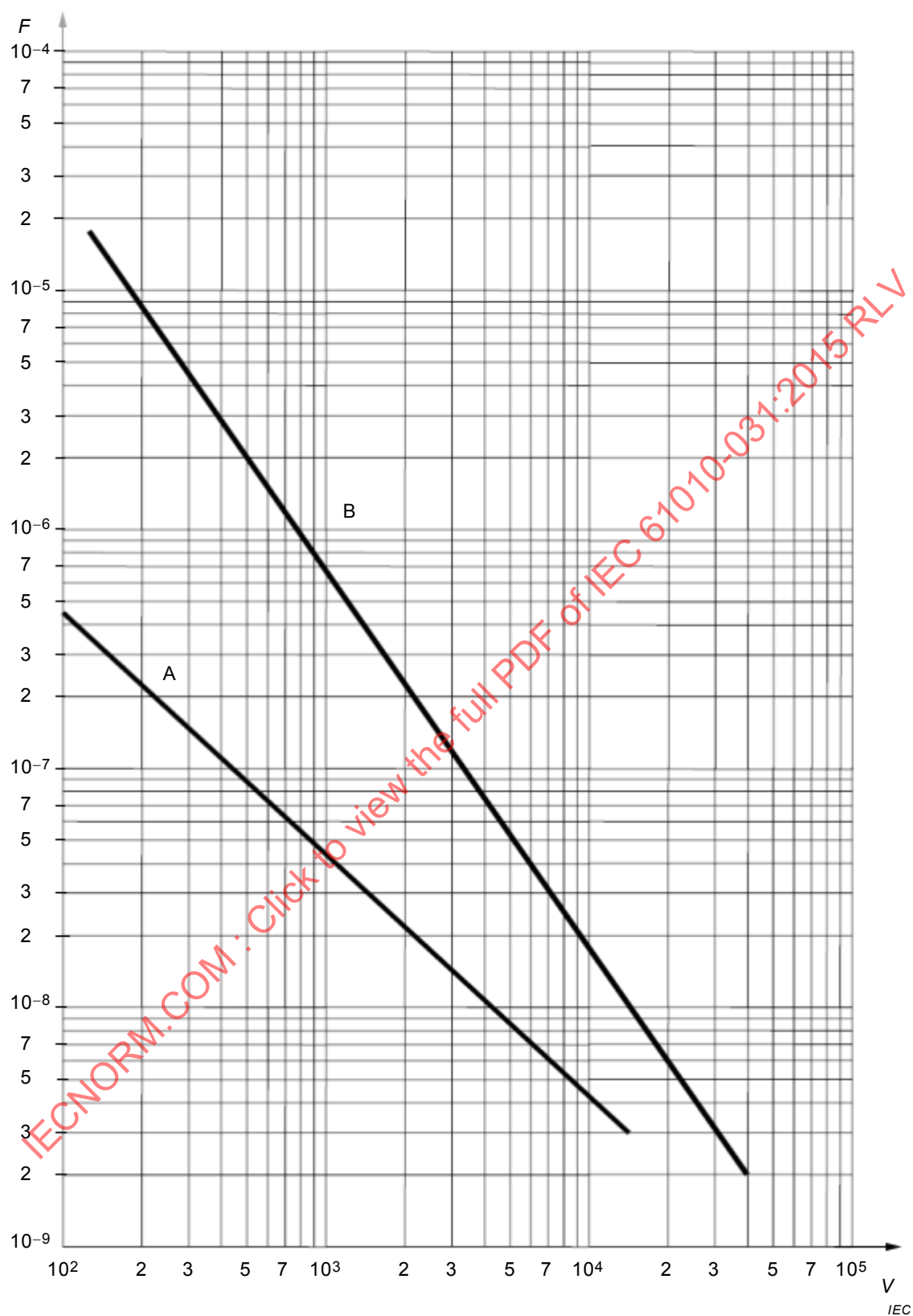
6.3.3 Niveaux en CONDITION DE PREMIER DEFAT

En CONDITION DE PREMIER DEFAT, les tensions supérieures aux niveaux selon a) sont réputées être ACTIVES DANGEREUSES si des niveaux en b) ou c) sont dépassés en même temps.

- a) Les niveaux de tension alternative sont 50 V efficaces, 70,7 V crête et le niveau de tension continue est 120 V. Pour ce qui concerne les sondes équipées destinées à être utilisées dans des EMBLEMENTS HUMIDES, les niveaux de tension alternative sont 33 V efficaces ou 46,7 V crête et le niveau de tension continue est 70 V.
- b) Les niveaux de courant de contact sont:

- 1) 3,5 mA efficaces pour la forme d'onde sinusoïdale, 5 mA crête pour les fréquences non sinusoïdales ou mixtes, ou 15 mA continu, lorsque le courant est mesuré avec le circuit de la Figure A.1. Si la fréquence n'est pas supérieure à 100 Hz; le circuit de mesure de la Figure A.2 peut être utilisé. Le circuit de mesure de la Figure A.5 est utilisé pour les sondes équipées qui sont destinées à être utilisées dans des EMPLACEMENTS HUMIDES.
 - 2) 500 mA efficaces, lorsque le courant est mesuré avec le circuit de mesure de la Figure A.3. Cela se rapporte aux brûlures possibles à des fréquences supérieures à 100 kHz.
- c) Le niveau de capacité est représenté par la droite B de la Figure 7.

IECNORM.COM : Click to view the full PDF of IEC 61010-031:2015 RLV



Légende

A = condition normale

B = condition de premier défaut

Figure 7 – Niveau de capacité en fonction de la tension en CONDITION NORMALE et en CONDITION DE PREMIER DEFAUT (voir 6.3.2 c) et 6.3.3 c))

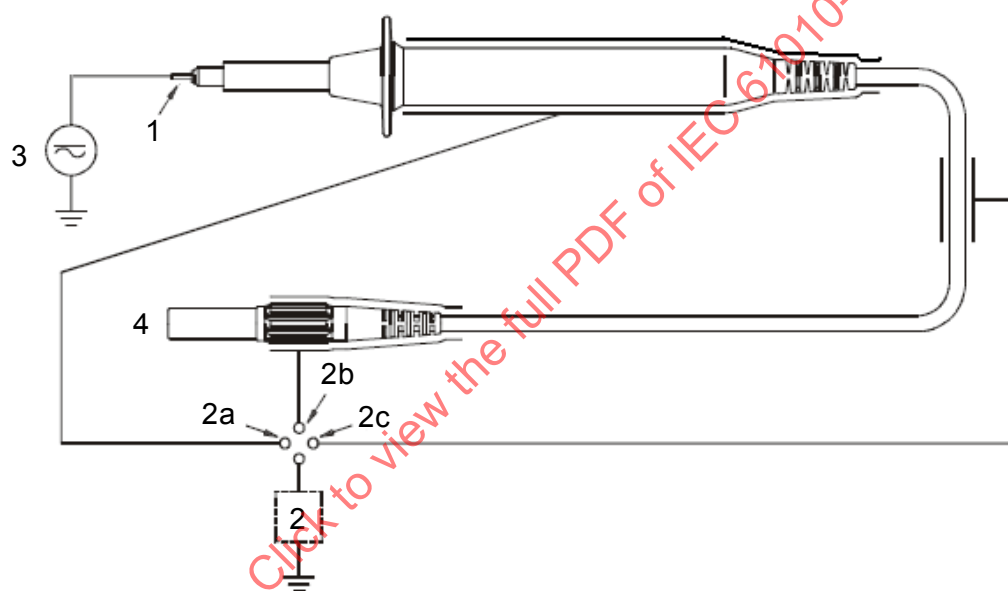
6.3.4 Mesure de la tension et du courant de contact

6.3.4.1 Généralités

La mesure de la tension et du courant de contact sur des parties ACCESSIBLES des sondes équipées est effectuée avec une feuille de métal serrée autour de chacune des parties, individuellement:

- a) autour du corps de sonde;
- b) 150 mm $\pm$ 20 mm du FIL DE SONDE ou sur toute la longueur du câble s'il est plus court;
- c) parties portatives ou manipulées à la main de chaque CONNECTEUR;
- d) autres parties portatives ou manipulées à la main.

La tension ASSIGNEE à la terre est appliquée entre la POINTE DE TOUCHE (1) et la terre. La tension est mesurée entre la feuille et la terre. S'il y a lieu, le circuit de mesure est raccordé tour à tour (2a – 2b – 2c) entre chacun des éléments enveloppés dans une feuille et la terre (voir les Figure 8 et Figure 9).

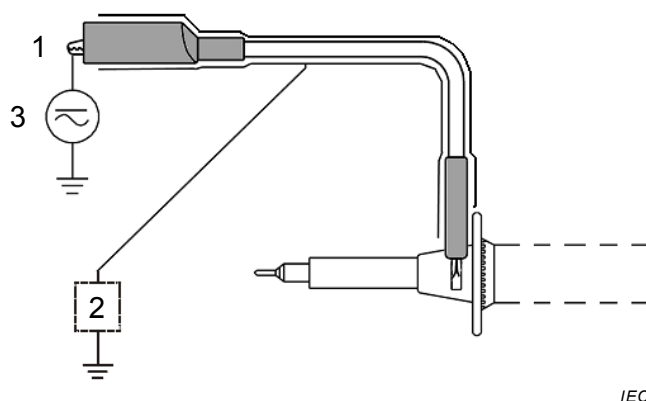


IEC

Légende

- 1 POINTE DE TOUCHE
- 2 Mesure de tension ou de courant de contact (voir l'Annexe A pour les circuits de mesure applicables aux mesures de courant de contact)
- 2a Connexion à la feuille métallique bien serrée autour des parties prévues pour être portatives ou manipulées à la main
- 2b Connexion à la feuille métallique bien serrée autour du CONNECTEUR
- 2c Connexion à la feuille métallique bien serrée autour du câble (voir 12.3.2)
- 3 Tension ASSIGNEE maximale avec connexion au conducteur interne du FIL DE SONDE
- 4 Non connecté au matériel d'essai ou de mesure

Figure 8 – Mesure de la tension et du courant de contact



Légende

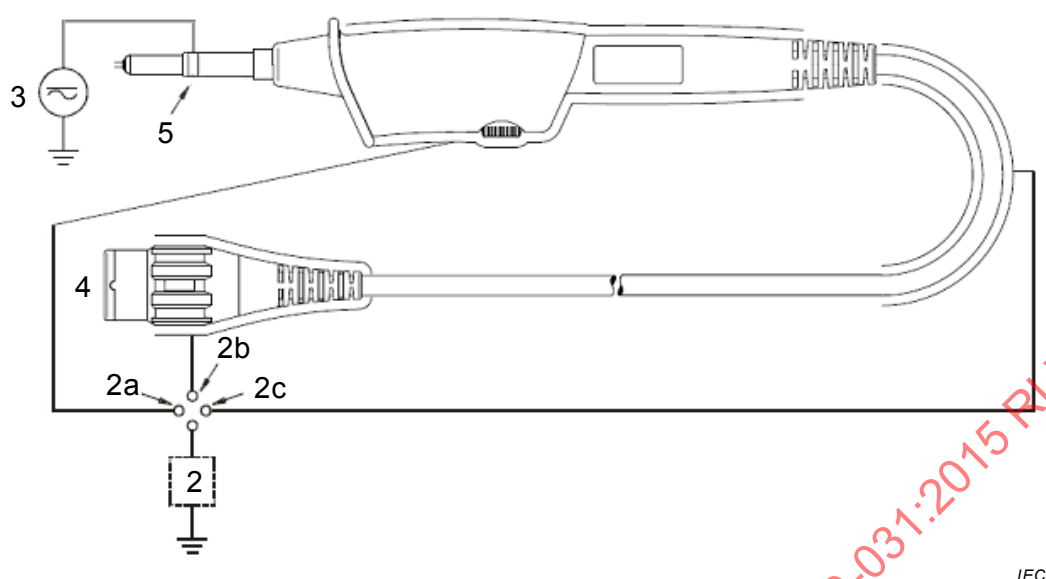
- 1 POINTE DE TOUCHE du CONNECTEUR de référence
- 2 Mesure de tension ou de courant de contact (voir l'Annexe A pour les circuits de mesure applicables aux mesures de courant de contact)
- 3 Tension ASSIGNEE maximale pour le CONNECTEUR de référence

Figure 9 – Mesure de la tension et du courant de contact pour le CONNECTEUR de référence

6.3.4.2 Sondes équipées avec connecteurs extérieurs flottants

Pour ce qui concerne les sondes équipées où la connexion du conducteur extérieur (blindage) peut être destinée à être flottante, l'essai est également effectué entre la POINTE DE TOUCHE (5) du conducteur extérieure et la terre (voir Figure 10).

Le courant de contact est déterminé en utilisant le circuit de mesure applicable selon l'Annexe A.



Légende

- 2 Mesure de tension ou de courant (voir l'Annexe A pour les circuits de mesure applicables aux mesures de courant de contact)
- 2a Connexion à la feuille métallique bien serrée autour des parties prévues pour être portatives ou manipulées à la main
- 2b Connexion à la feuille métallique bien serrée autour du CONNECTEUR
- 2c Connexion à la feuille métallique bien serrée autour du câble (voir 12.3.2)
- 3 Tension ASSIGNEE maximale avec connexion à la POINTE DE TOUCHE du conducteur extérieur
- 4 Non connecté au matériel d'essai ou de mesure
- 5 POINTE DE TOUCHE flottante connectée au blindage ou au conducteur extérieur du FIL DE SONDE

Figure 10 – Mesure de la tension et du courant de contact avec sonde d'essai blindée

6.3.4.3 Sondes de test à hautes fréquences

Dans le cas des sondes de test ASSIGNEES pour des fréquences supérieures à 100 kHz, avec un conducteur extérieur (blindage) flottant, il convient de déterminer la tension maximale admissible entre le blindage et les parties ACCESSIBLES pour éviter les brûlures électriques. Le courant de contact doit être mesuré dans toute la gamme de fréquence et à la tension maximale dans chaque gamme de fréquences.

Les mesures sont réalisées (voir la Figure 10):

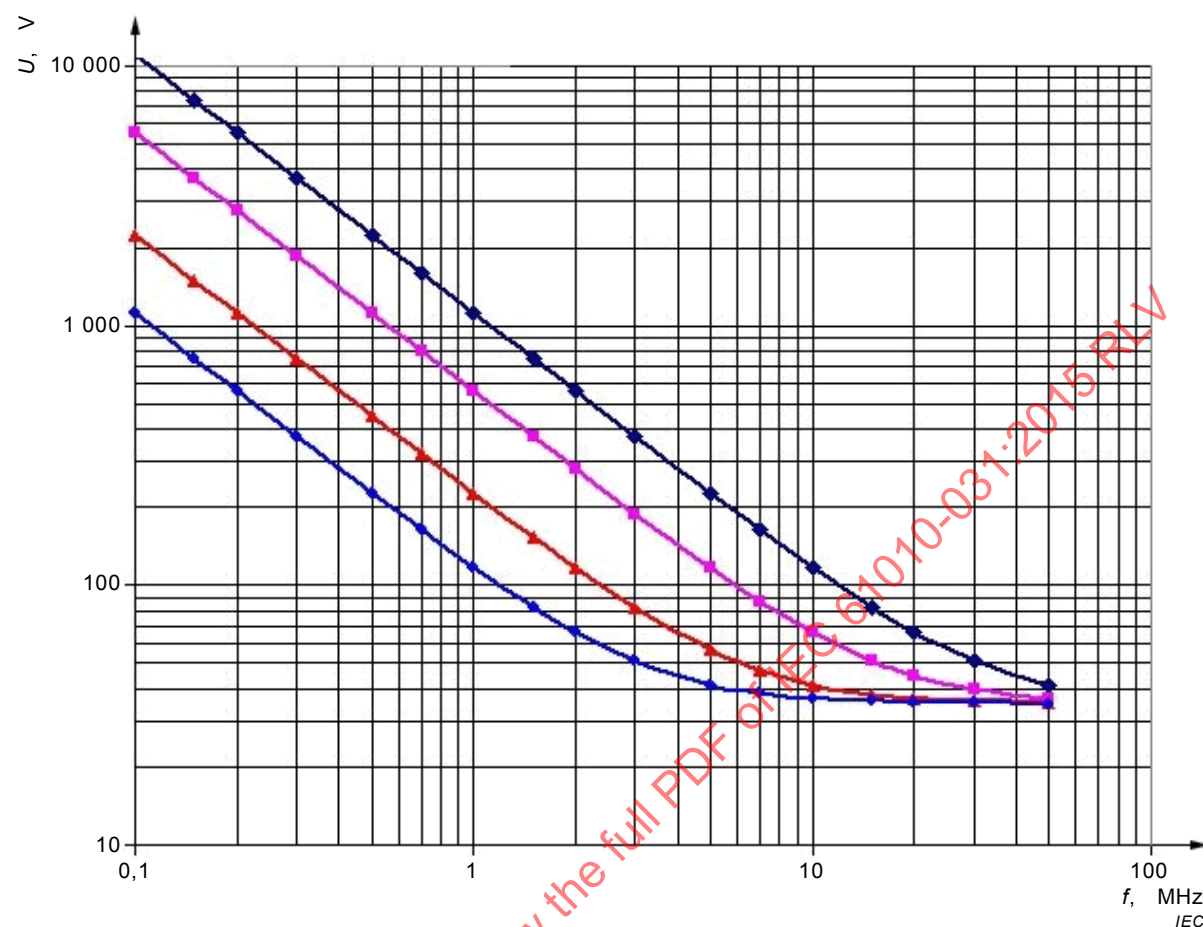
- entre le blindage et la feuille autour du corps de la sonde (2a), et
- entre le blindage et la feuille du CONNECTEUR coaxial (2b), et
- entre le blindage et la feuille autour du FIL DE SONDE (2c).

En alternative aux mesures de courant de contact, la capacité entre le blindage et la feuille peut être mesurée pour les cas a) à c).

La capacité C_s (capacité mesurée entre le blindage et la feuille) conjointement avec le circuit issu de l'Article A.3 crée l'impédance montrée à la Figure A.4. Les paramètres variables de cette impédance sont la capacité C_s et la fréquence (R_1 , C_1 et R_2 sont fixes). Au moyen de ces deux paramètres et concernant les brûlures électriques, la tension admissible maximale pour la sonde d'essai peut être calculée, par exemple pour un courant de contact admissible de 70 mA (c'est-à-dire 35 V sur R_2) comme le montre la Figure 11 pour un certain nombre de valeurs de la capacité C_s .

La tension maximale pour chaque fréquence peut alors être calculée.

NOTE En pratique, les valeurs de R_1 et C_1 peuvent être ignorées dans le calcul pour le cas des fréquences supérieures à 100 kHz.



Légende

- ◆ 10 pF entre sonde (blindage) et feuille
- 20 pF entre sonde (blindage) et feuille
- ▲ 50 pF entre sonde (blindage) et feuille
- 100 pF entre sonde (blindage) et feuille

Figure 11 – Tension d'entrée maximale de la sonde d'essai pour un courant de contact de 70 mA

6.4 Moyens de protection contre les chocs électriques

6.4.1 Généralités

Les CONNECTEURS doivent satisfaire aux exigences en 6.4.2.

Les POINTES DE SONDE doivent satisfaire aux exigences en 6.4.3.

Toutes les autres parties ACCESSIBLES des sondes équipées doivent être empêchées de devenir ACTIVES DANGEREUSES tant en CONDITION NORMALE qu'en CONDITION DE PREMIER DEFECT par l'un ou plusieurs des moyens suivants:

- a) une DOUBLE ISOLATION, constituée d'une ISOLATION PRINCIPALE plus une ISOLATION SUPPLEMENTAIRE (voir 6.4.6);
- b) une ISOLATION PRINCIPALE plus DES ENVELOPPES (voir 6.7.3) ou des PROTEGE-DOIGTS;
- c) une ISOLATION PRINCIPALE plus une impédance (voir 6.4.4);

- d) une ISOLATION RENFORCÉE (voir 6.4.6);
- e) une IMPEDANCE DE PROTECTION (voir 6.4.5).

NOTE Le FIL DE SONDE est considéré comme étant portatif. Voir également l'Article 12 pour ce qui concerne les exigences relatives au FIL DE SONDE.

La conformité est vérifiée par examen et de la manière spécifiée de 6.4.2 à 6.4.6, selon le cas.

6.4.2 CONNECTEURS

L'isolation, les parties ACCESSIBLES et les ESPACEMENTS pour les CONNECTEURS des sondes équipées doivent satisfaire aux exigences applicables indiquées en a) à c) ci-dessous.

L'Annexe E fournit des informations relatives aux dimensions recommandées des CONNECTEURS de 4 mm.

a) CONNECTEURS en position totalement couplée.

- 1) Les parties ACCESSIBLES des CONNECTEURS qui sont utilisés seulement pour la connexion de la sonde équipée à l'appareil d'essai ou de mesure et qui ne sont pas destinés à être tenus à la main pendant la mesure doivent être isolées des parties ACTIVES DANGEREUSES par une ISOLATION PRINCIPALE.
- 2) Les parties ACCESSIBLES des CONNECTEURS qui sont utilisés à d'autres fins ou qui sont destinés à être portatifs pendant la mesure doivent être isolées des parties ACTIVES DANGEREUSES par une DOUBLE ISOLATION ou par une ISOLATION RENFORCÉE.

La conformité est vérifiée par la détermination des parties ACCESSIBLES effectuée telle que spécifiée en 6.2 (voir la Figure 6 b)) et telle que spécifiée en 6.4.6 pour l'ISOLATION PRINCIPALE et l'ISOLATION RENFORCÉE.

b) CONNECTEURS en position partiellement couplée.

Les parties ACCESSIBLES des CONNECTEURS couplés partiellement doivent être isolées des parties ACTIVES DANGEREUSES par une ISOLATION PRINCIPALE.

La conformité est vérifiée par la détermination des parties ACCESSIBLES telle que spécifiée en 6.2 (voir la Figure 6 c)) et telle que spécifiée en 6.4.6 pour l'ISOLATION PRINCIPALE.

c) CONNECTEURS en position découplée.

Lorsque les tensions ASSIGNEES à la terre sont appliquées à d'autres CONNECTEURS ou POINTES DE TOUCHE de la sonde équipée,

- 1) les parties conductrices des CONNECTEURS à verrouillage ou à vis, y compris les CONNECTEURS qui n'exigent pas l'utilisation d'un OUTIL pour le déverrouillage ou le desserrage peuvent être accessibles tout en étant dans la position découplée,
- 2) les BORNES intégrées découplées des CONNECTEURS EMPILABLES doivent être protégées par une ISOLATION PRINCIPALE
- 3) les parties conductrices des autres connecteurs découplés doivent être empêchées de devenir ACTIVES DANGEREUSES par une IMPEDANCE DE PROTECTION (voir 6.4.5) ou doivent avoir des ESPACEMENTS conformes aux exigences suivantes:
 - i) pour les CONNECTEURS découplés avec des CARACTERISTIQUES ASSIGNEES de tension inférieures ou égales à 1 000 V, alternatifs ou 1 500 V continus les ESPACEMENTS applicables du Tableau 2 depuis la partie la plus proche du doigt d'épreuve touchant les parties externes du CONNECTEUR dans la position la moins favorable (voir la Figure 6 d)), ou;
 - ii) pour des CONNECTEURS découplés avec des CARACTERISTIQUES ASSIGNEES de tension supérieures à 1 000 V alternatifs ou 1 500 V continus, les ESPACEMENTS ne doivent pas être inférieurs à 2,8 mm et doivent supporter l'essai de tension du 6.6 avec une tension d'essai égale à la tension ASSIGNEE du CONNECTEUR multiplié par 1,25.